

AMSU-A VERIFICATION TEST REPORT
METSAT PHASE LOCKED OSCILLATOR ASSEMBLY

TEST ITEM:
AMSU-A PHASE LOCKED OSCILLATOR ASSEMBLY
P/N 1348360-1
SERIAL NUMBERS F09, F10

PREPARED FOR
NATIONAL AERONAUTICS AND SPACE ADMINISTRATION
GODDARD SPACE FLIGHT CENTER
GREENBELT, MARYLAND 20771

PREPARED BY
GENCORP AEROJET
POST OFFICE BOX 296
AZUSA, CALIFORNIA 91702-0296

Summary of Test Results for AMSU-A Phase Locked Oscillator Testing
Serial Numbers F09 and F10

Paragraph	Description	Requirements	F09	F10
3.2.1.1	Input Voltage and Current	600 mA max, +15V 100 mA max, -15V	522 mA for +15V, 64 mA for -15V	533 mA for +15V, 70 mA for -15V
3.2.1.2	Operating Temperature	+1°C to 44°C	-24°C to +60°C	0°C to 57°C
3.2.1.3	Start-up	All loads, +60°C and -30°C; in vacuum	Verified at +60 and -30°C, ambient	Verified at +60 and -30°C, ambient
3.2.1.4 & 3.2.1.5	Frequency Stability from 57.290344 GHz	±200 kHz	+0kHz, -33 kHz	+16 kHz, -0 kHz
3.2.1.6	RF Output Power	17 to 20 dBm	18.1 dBm	17.9 dBm
3.2.1.7	Output Power Stability	<1.5 dB	1.4 dB	1.5 dB
3.2.1.8	Load VSWR	2.01:1 or less	Verified	Verified
3.2.1.9	AM Noise	<-130 dBc/Hz @ 1 MHz	-145 dBc/Hz @ 1MHz	-140 dBc/Hz @ 1Mhz
3.2.1.10	FM Noise	<-100 dBc/Hz @ 1 MHz	-104 dBc/Hz @ 1 MHz	-105 dBc/Hz @ 1 MHz
3.2.1.11	Spurious and Sub-Harmonic Signals	<-90 dBc	< -90 dBc	< -90 dBc
3.2.1.12	Harmonics	<-30 dBc	-40 dBc	- 70 dBc
3.2.1.14	Warm-up Time	< 30 minutes	Verified	Verified
3.2.1.15	Grounding and Shielding		By Design	By Design
3.2.1.16	Input Voltage Protection		By Design	By Design
3.2.1.17	Reverse Polarity Protection		By Design	By Design
Environmental Testing				
Microphonics		AE-26633	TCXO Test	TCXO Test
Radiation Hardness		AE-26633	By Analysis	By Analysis
EMI/RFI		AE-26633	Not Required	Not Required
Vibration		AE-26633	Acceptance Level	Acceptance Level
Thermal Vacuum		AE-26633	Verified at Ambient Pressure Only	Verified at Ambient Pressure Only
Weight		2.0 lbs	2.0 lbs	2.0 lbs

1.0 SUMMARY

Two Flight Model AMSU-A Phase Locked Oscillators (P/N 1348360-1, S/N F09 and F10) have been tested per AES Test Procedure AE-26758 Rev. C, which includes full functional testing, vibration testing, thermal testing, and AM/FM Noise testing. Both assemblies satisfactorily passed all performance requirements of the AE-26633 Product Specification.

During the manufacture of PLO F09, the DRO CCA lid was rotated 180 degrees, which rendered the unit unable to lock. After removing the 10 fastening screws and installing the lid in the correct orientation, the unit functioned to all specifications. During the vibration of PLO F10, the dielectric puck of the DRO was dislodged from its bonded attachment to the CCA. The PLO and DRO were opened, the puck was re-attached, and the unit was restored to full operation. The MAI was enhanced to increase the reliability of the bonding.

2.0 REQUIREMENTS

The acceptance test procedure AE-26758C consists of tests designed to show compliance of the Phase Locked Oscillator with all requirements stated in the PLO Product Specification AE-26633. The tests reported herein demonstrate the acceptability of the AMSU-A PLO assemblies S/N's F09 and F10, and therefore compatibility with the AMSU-A Receiver Assembly.

3.0 RESULTS

The results of the required tests are presented in the following section as test data. As indicated on the test data sheets, all measured data passed all requirements associated with the product specification.

4.0 TEST DATA

A summary of the test data is provided at the start of each of the acceptance test sections. Furthermore, the raw data is reproduced as recorded, and is included in each section. The following table provides a concise summary of each unit's performance ability.

The remainder of this report contains the raw data taken during the tests of the two flight PLOs. The data is arranged by the following segmentation:

- Section 1A: Initial Functional Testing - F09
- 1B: Initial Functional Testing - F10

- Section 2A: Acceptance Level Vibration - F09
- 2B: Acceptance Level Vibration - F10

- Section 3A: Frequency and Power Hysteresis - F09
- 3B: Frequency and Power Hysteresis - F10

- Section 4A: EMI/RE02 Testing - F09 (not required)
- 4B: EMI/RE02 Testing - F10 (not required)

- Section 5A: Final Functional Testing - F09
- 5B: Final Functional Testing - F10

- Section 6A: AM/FM Noise Levels - F09
- 6B: AM/FM Noise Levels - F10

The remainder of this report contains the raw data taken during the tests of the two flight PLOs. The data is arranged by the following segmentation:

- Section 1A: Initial Functional Testing - F09
- 1B: Initial Functional Testing - F10

- Section 2A: Acceptance Level Vibration - F09
- 2B: Acceptance Level Vibration - F10

- Section 3A: Frequency and Power Hysteresis - F09
- 3B: Frequency and Power Hysteresis - F10

- Section 4A: EMI/RE02 Testing - F09 (not required)
- 4B: EMI/RE02 Testing - F10 (not required)

- Section 5A: Final Functional Testing - F09
- 5B: Final Functional Testing - F10

- Section 6A: AM/FM Noise Levels - F09
- 6B: AM/FM Noise Levels - F10

Section 1A: Initial Functional Testing - F09

This section contains the results of a full functional test over temperature taken before PLO F09 endured thermal cycling. All tests passed.

TEST DATA SHEET 6A (Sheet 1 of 4)
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Test Setup Verified: [Signature]
Signature

Paragraph 4.2.1.3, Functional Testing:

Step	Test	Expected	Measured	Pass/Fail
1	Potential Difference from ± 15 V RTN to:			
	PLO Base Plate	< 1.0 Vac	0.01	Pass
	Spectrum Analyzer	< 1.0 Vac	0.03	Pass
	Frequency Counter Chassis	< 1.0 Vac	0.01	Pass
	Power Meter Chassis	< 1.0 Vac	0.04	Pass
4	Evacuate vacuum chamber and record pressure	< 10^{-2} torr	N/A <i>OK AS IS SURVIVED 11-12-98</i>	N/A*
5	Thermal couple readings	TC1 = 22 ± 2 °C	TC1 = 22.3 °C	Pass
			TC2 = 22.5 °C	N/A
			TC3 = 21.8 °C	N/A
6	DRO L/A	0 to 1V	DRO L/A = 78 mV	Pass
	PLO L/A	4.3-4.7V 0 to 1V	PLO L/A = 4.52 V	Pass
	Is PLO locked?	Yes <i>10/12/98</i>	Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>	
7	PLO Frequency	57.290344 \pm .0002 GHz	Freq. = 57.290321180 GHz	Pass
	PLO Power	17 to 20 dBm	P = 17.77 dBm	Pass
8	Input Voltage and Current			
	VM1 Voltage	+15 \pm 0.1 V	VM1 = +15.10 V	Pass
	VM2 Voltage	-15 \pm 0.1 V	VM2 = -15.19 V	Pass
	IM1 Current	600 mA max.	IM1 = 522 mA	Pass
	IM2 Current	100 mA max.	IM2 = -64.7 mA	Pass
	DRO L/A Voltage	4.3-4.7V 0 to 1V	DRO L/A = 78 mV	Pass
	PLO L/A Voltage	0 to 1V <i>10/12/98</i>	PLO L/A = 4.52 V	Pass
12	RF Output Power and Frequency	17 to 20 dBm	P = 17.77 dBm	Pass
		57.290344 \pm .0002 GHz	Freq. = 57.290321180 GHz	Pass
	Baseplate Temp. (TC1)	TC1 = 22 ± 2 °C	TC1 = 22.3 °C	Pass
13	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 \pm 0.05 V	+Voltage = 15.20 V	Pass
		-15.2 \pm 0.05 V	-Voltage = 15.2 V	Pass
		57.290344 \pm .0002 GHz	Freq. = 57.290321322 GHz	Pass
		17 to 20 dBm	P = 17.67 dBm	Pass

*Record data only if performing test under vacuum

L 30.0dB

RL 0dBm

MKR -3.33dBm

57.29031GHz

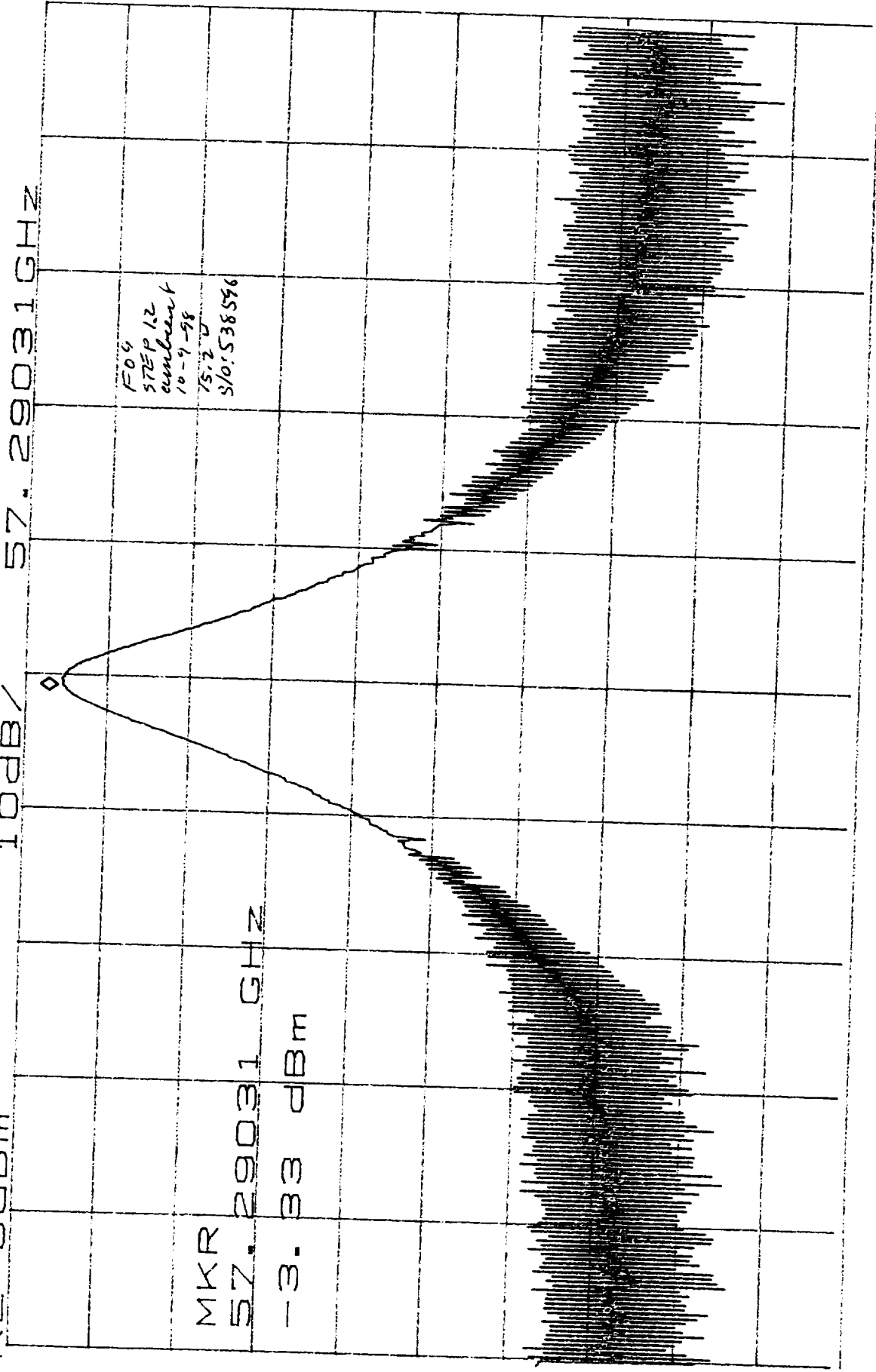
10dB/

MKR

57.29031 GHz

-3.33 dBm

F04
STEP 12
amplitude
10-9-98
15.2 V
S/O: 538546



CENTER 57.29034GHz

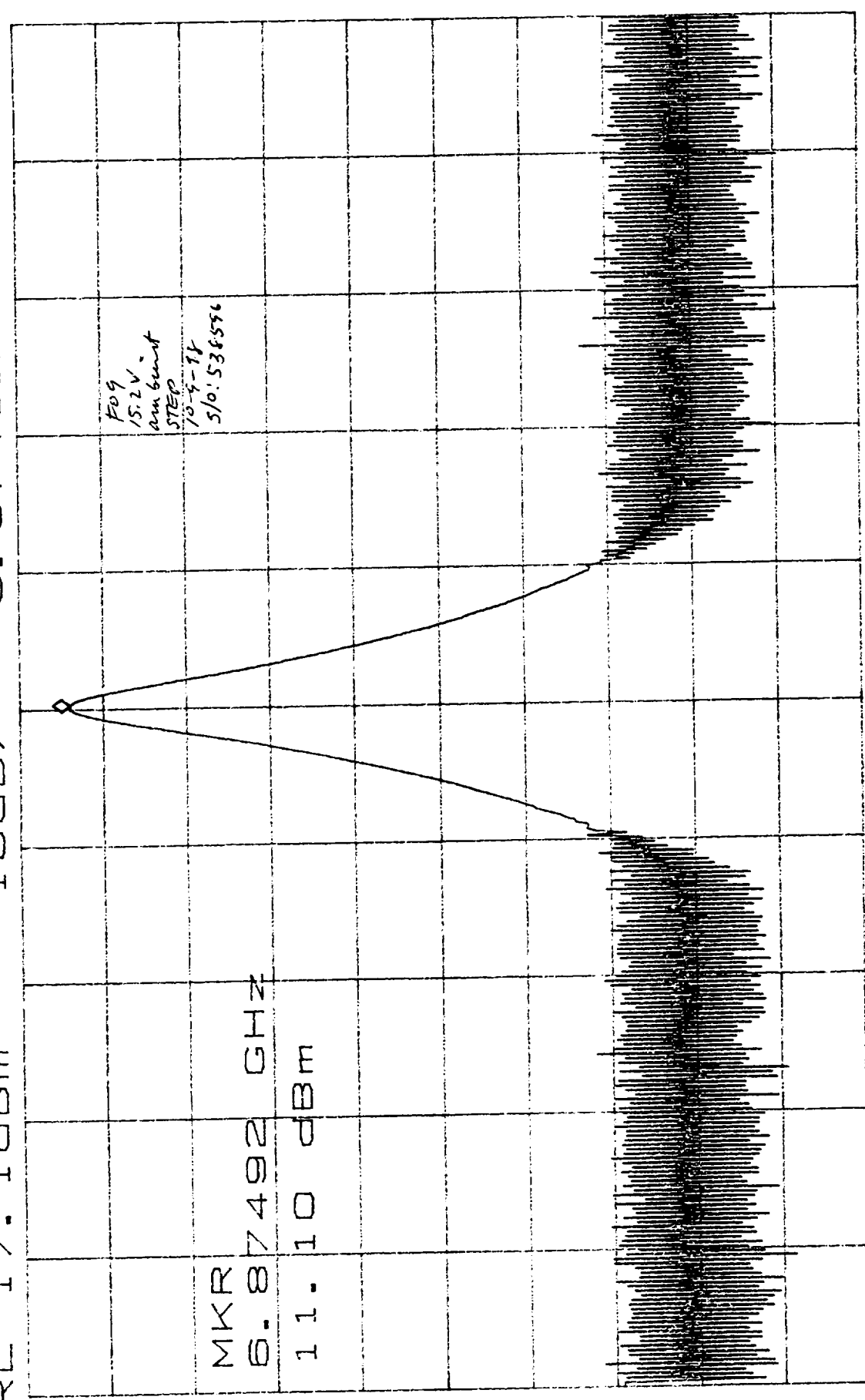
*RBW 300kHz

VBW 300kHz

SPAN 10.00MHz

SWP 50.0ms

ATTEN 30dB MKR 11.10dBm
RL 17.1dBm 6.87492GHz 10dB/



CENTER 6.87485GHz SPAN 20.00MHz
*RBW 300kHz *VBW 300kHz SWP 50.0ms

CL 30.0dB

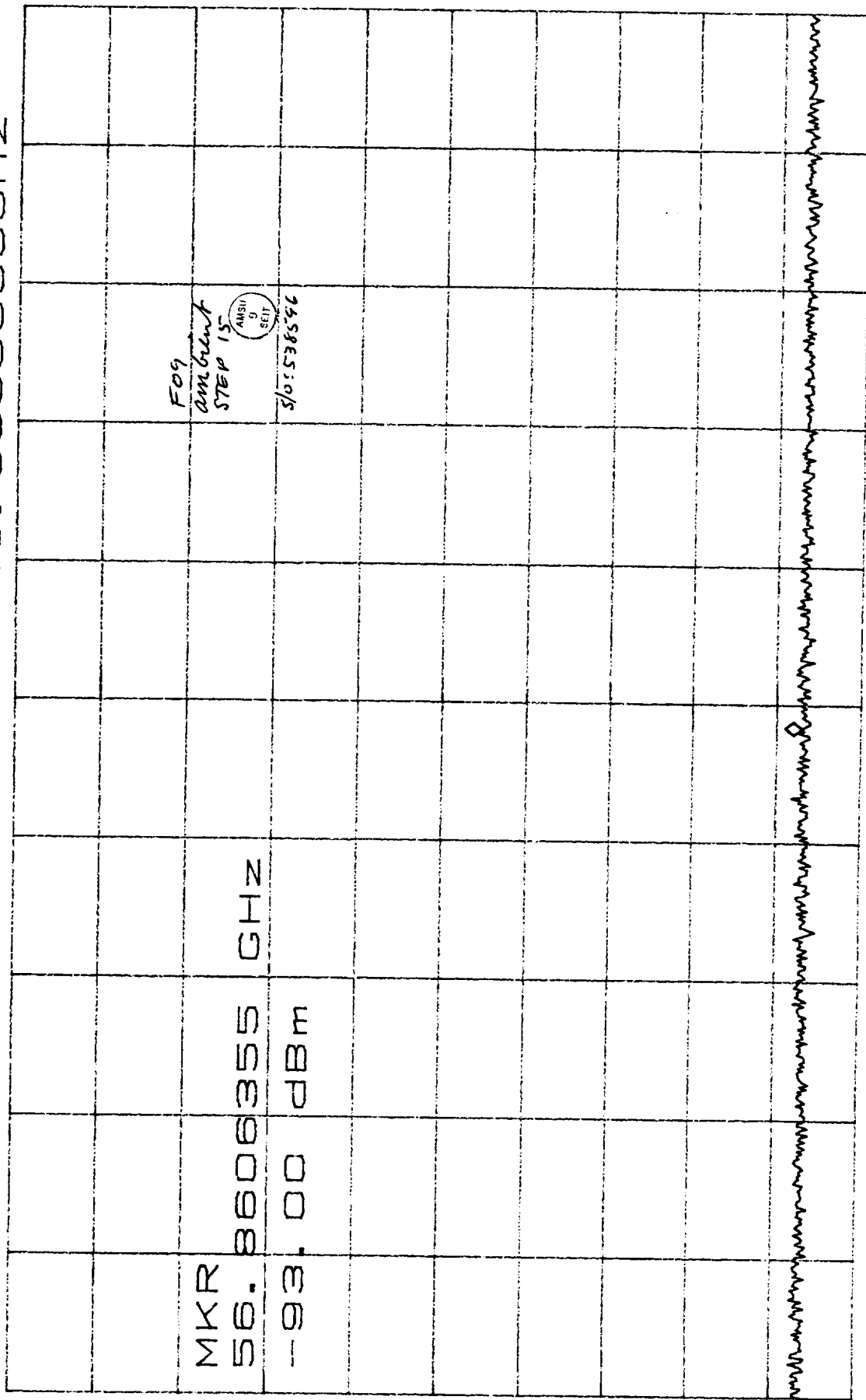
VAVG 6

MKR -93.00dBm

RL 0dBm

10dB/

56.8606355GHz



D

CENTER 56.8606439GHz

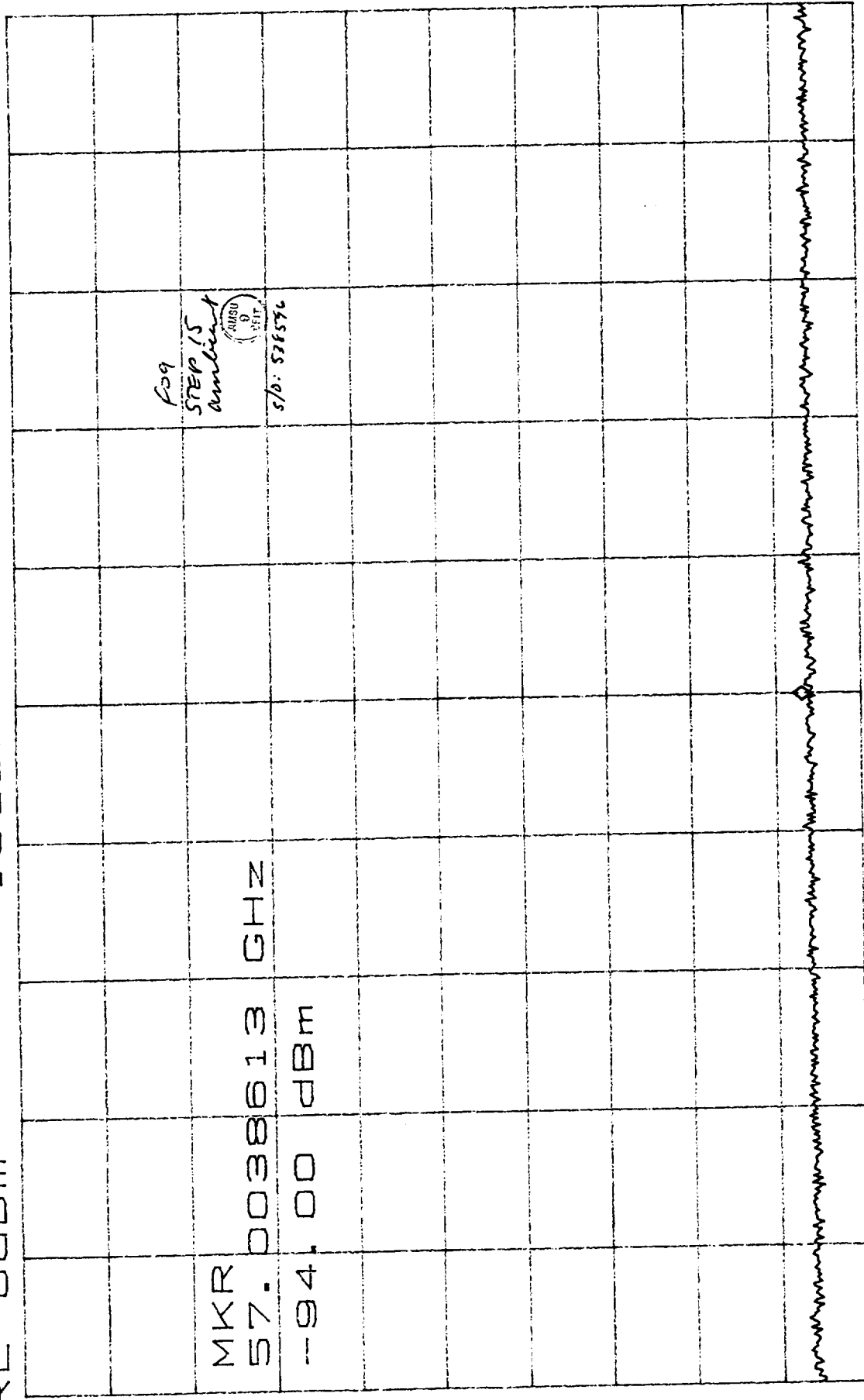
SPAN 500.0kHz

*RBW 3.0kHz

*VBW 1.0kHz

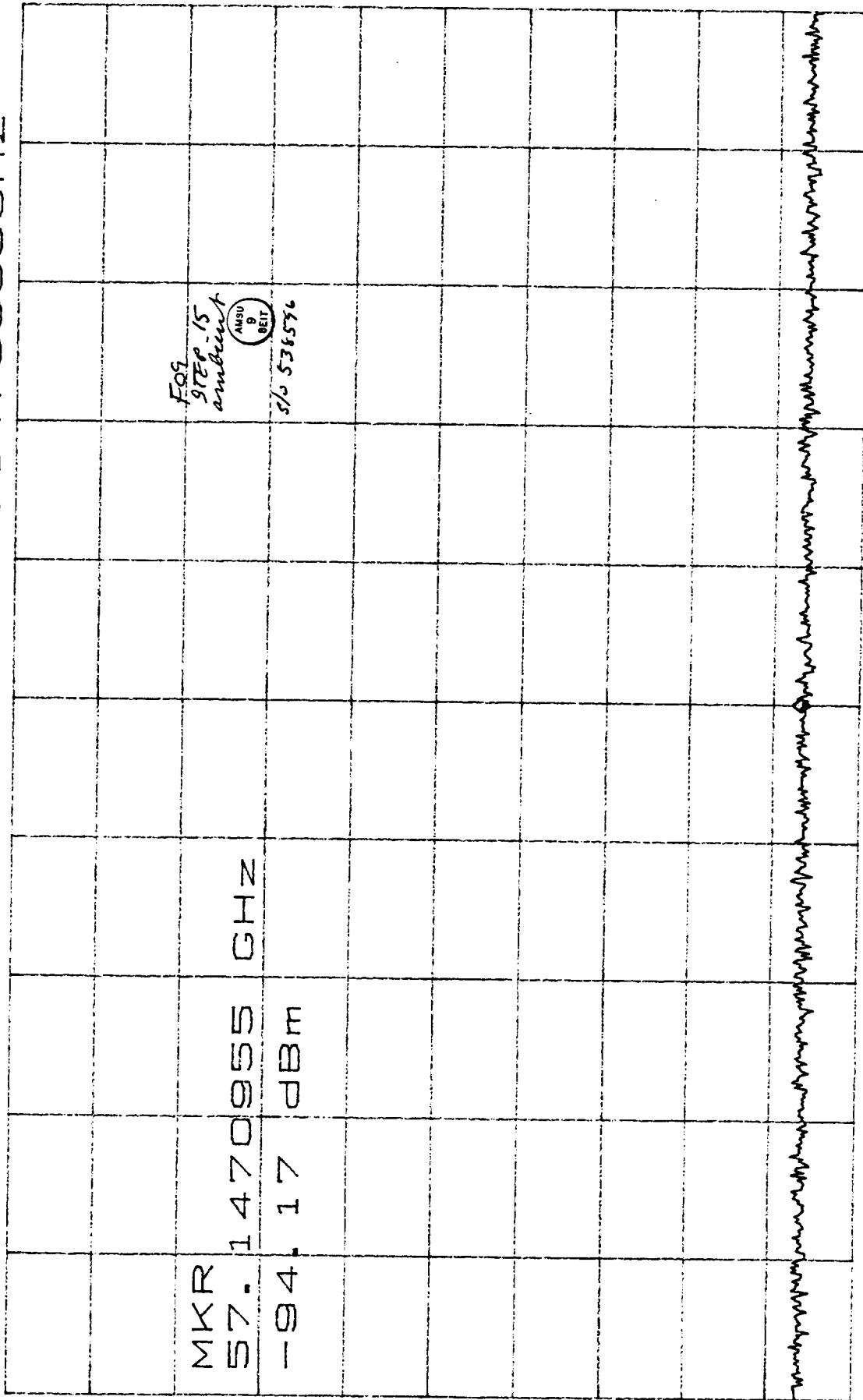
*SWP 2.00sec

CL 30.0dB VAVG 29 MKR -94.00dBm
RL 0dBm 10dB/



CENTER 57.0038613GHz SPAN 500.0KHZ
*RBW 3.0KHZ *VBW 1.0KHZ *SWP 2.00sec

CL 30.0dB VAVG 5 MKR -94.17dBm
 RL 0dBm 10dB/ 57.1470955GHz



D

CENTER 57.1470955GHz SPAN 500.0kHz
 *RBW 3.0kHz *VBW 1.0kHz *SWP 2.00sec

CL 30.0dB VAVG 5 MKR -93.17dBm
RL 0dBm 10dB/ 57.4335477GHz

MKR
57.4335477 GHz
-93.17 dBm

FO9
SEP 15
Amber
ANSI
9
BIT
3/6 53536

D

CENTER 57.4335477GHz SPAN 500.0kHz
*RBW 3.0kHz *VBW 1.0kHz *SWP 2.00sec

CL 30.0dB

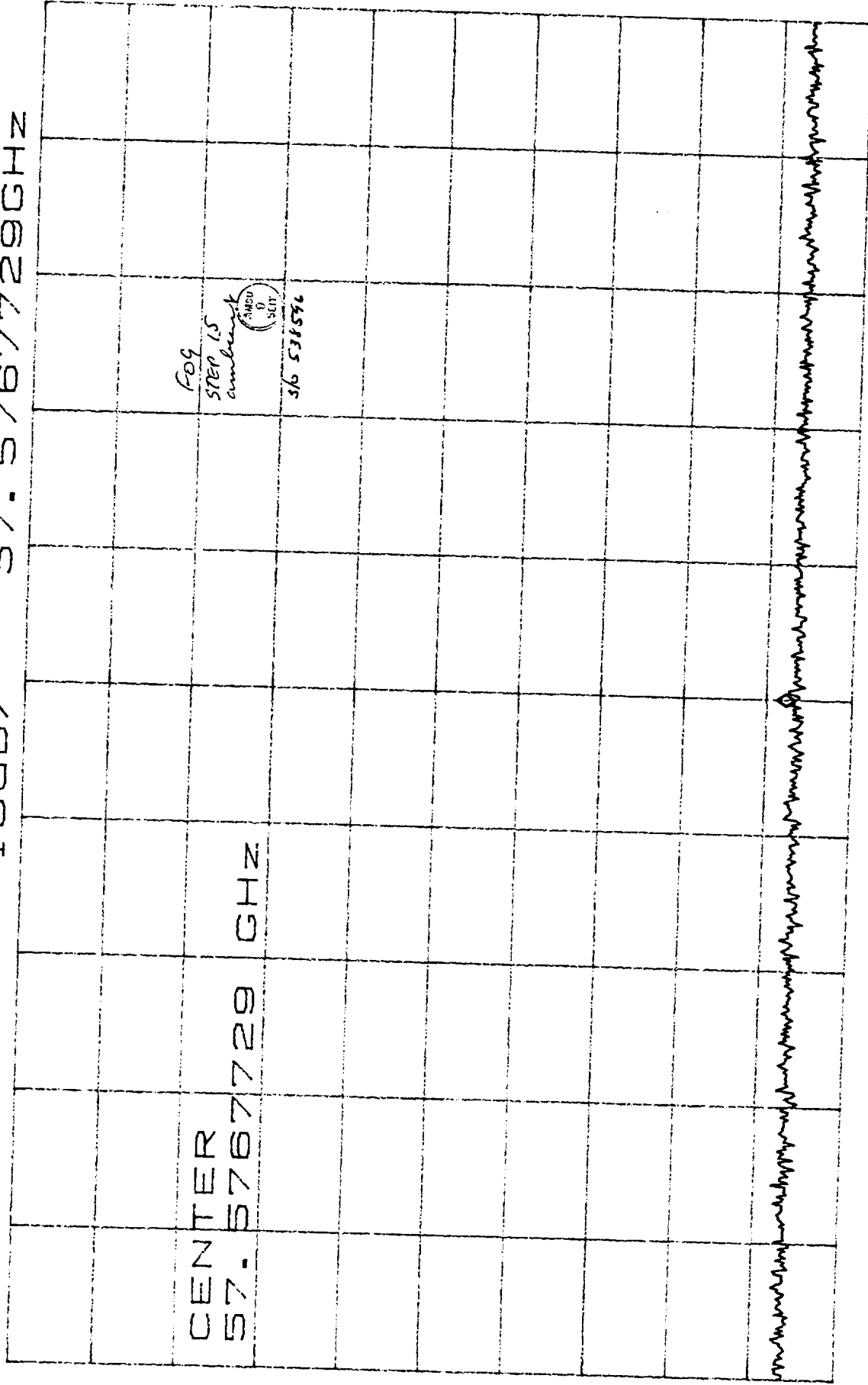
VAVG 5

MKR -93.17dBm

RL 0dBm

10dB/

57.5767729GHZ



D

CENTER 57.5767729GHZ

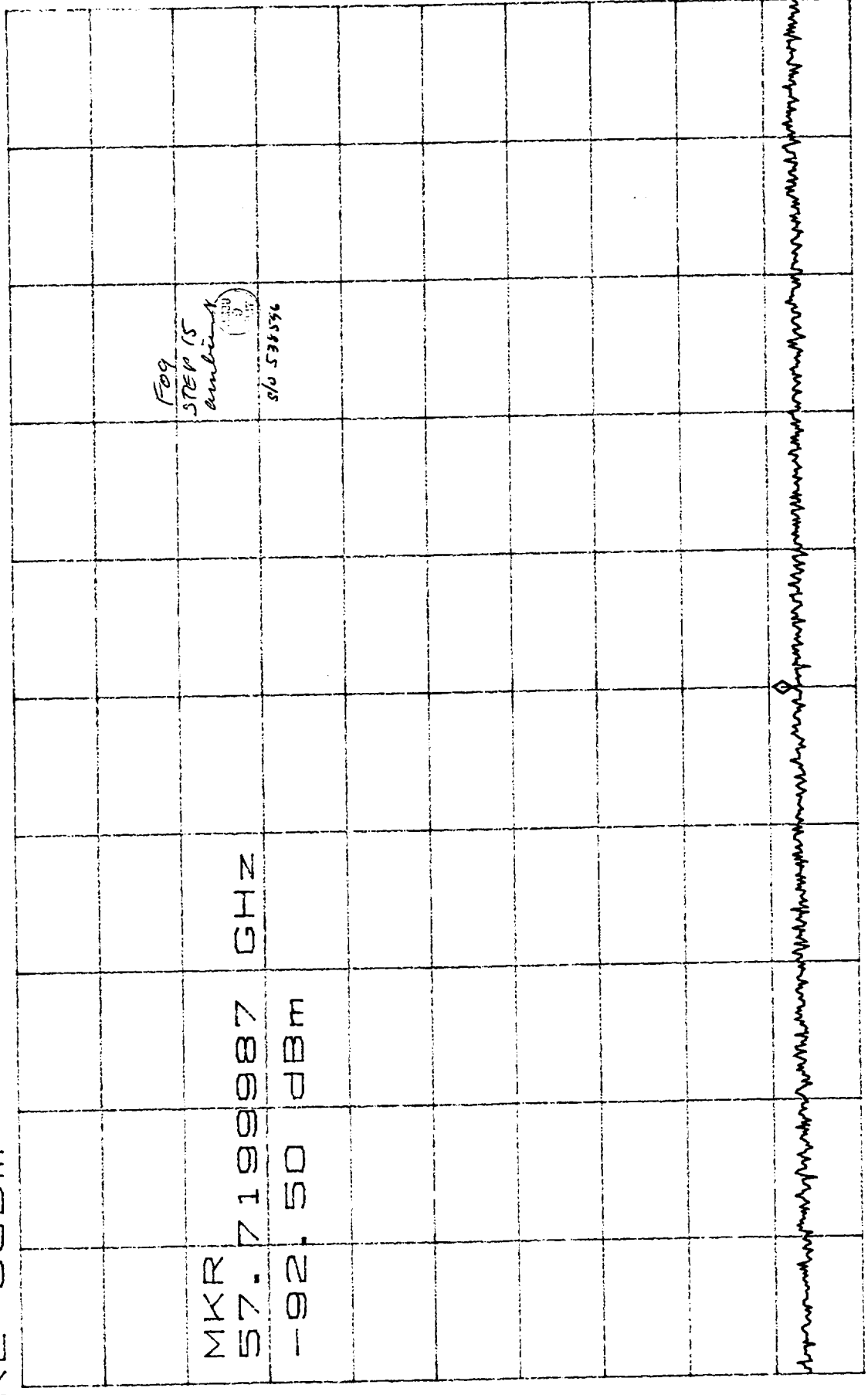
SPAN 500.0KHZ

*RBW 3.0KHZ

*VBW 1.0KHZ

*SWP 2.00sec

CL 30.0dB VAVG 6 MKR --92.50dBm
 RL 0dBm 10dB/ 57.7199987GHz



D

CENTER 57.7199987GHz SPAN 500.0kHz
 *RBW 3.0kHz *VBW 1.0kHz *SWP 2.00sec

CL 30.0dB

RL 0dBm

MKR -70.00dBm

10dB/

114.5806431GHz

MKR

114.5806431

GHz

-70.00 dBm

F09
STEP 14
ambient

ANAL
9
SET

5/6 538596

CENTER 114.5806434GHz

SPAN 100.0KHz

*RBW 300Hz

*VBW 1.0KHz

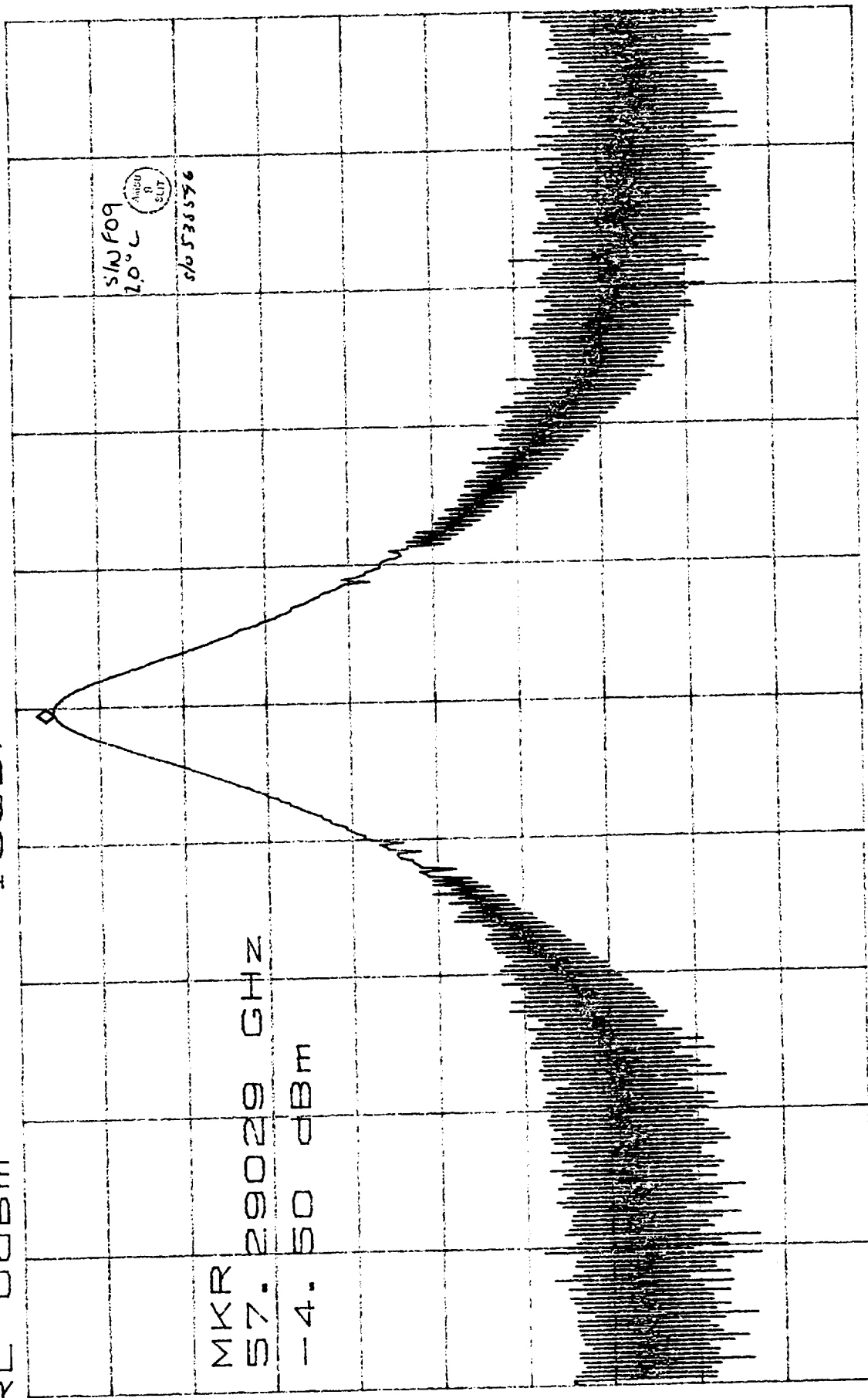
*SWP 2.80S000

CL 30.0dB MKR -4.50dBm
RL 0dBm 57.29029GHz

10dB/

MKR
57.29029 GHz
-4.50 dBm

510 F09
20°C
Audio
9
SUT
8/6 536596



CENTER 57.29034GHz SPAN 10.00MHz
*RBW 300kHz VBW 300kHz SWP 50.0ms

ATTEN 30dB
RL 17.1dBm

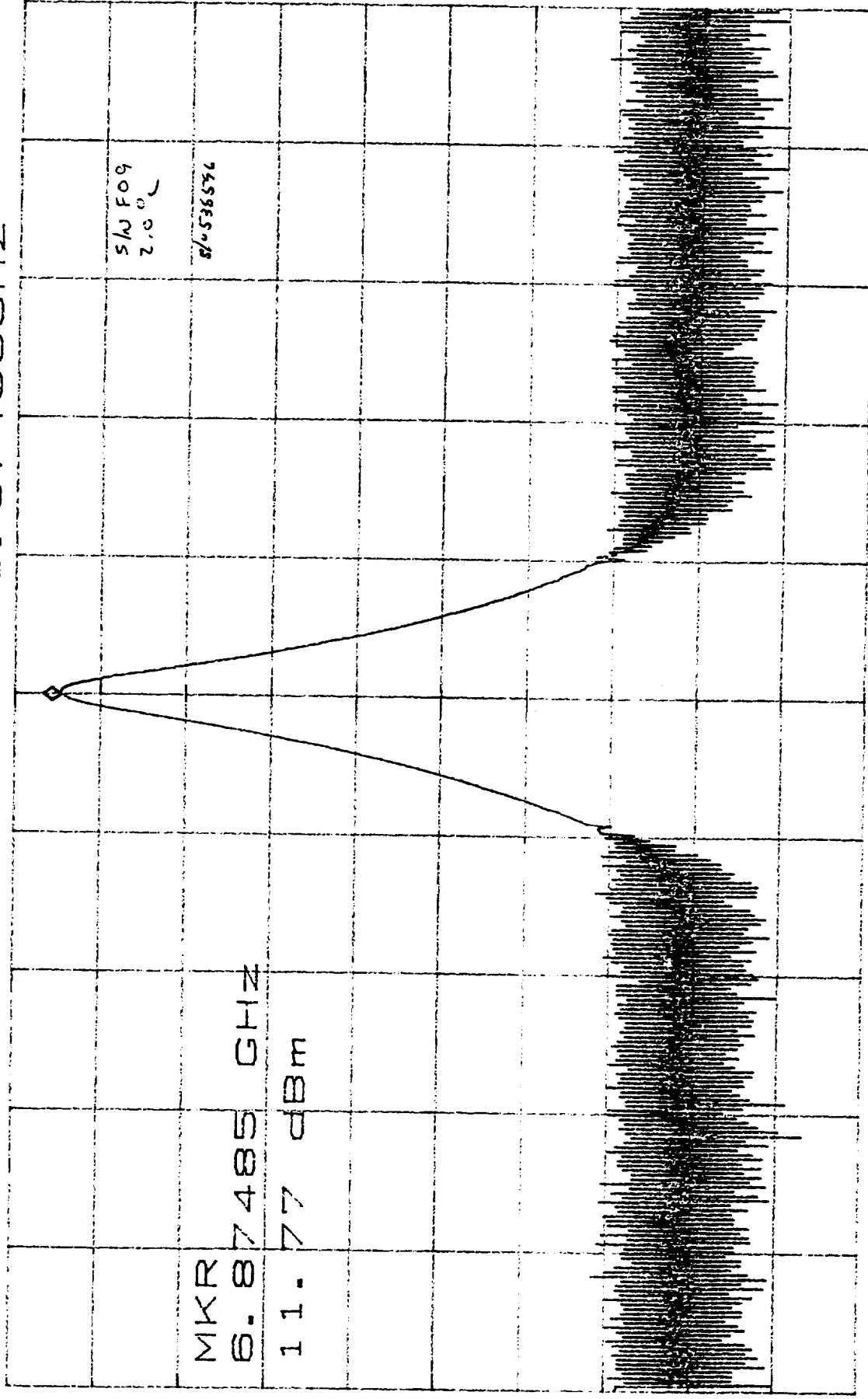
MKR 11.77dBm
6.87485GHz

10dB/

MKR
6.87485 GHz
11.77 dBm

5/3 F09
2.00

8/0536596



CENTER 6.87485GHz

SPAN 20.00MHz

*RBW 300kHz

*VBW 300kHz

SWP 50.0ms

TEST DATA SHEET 6A (Sheet 2 of 4)
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
14	Frequency vs. Voltage ± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	Pass
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.29034027</u> GHz	Pass
		17 to 20 dBm	P = <u>17.65</u> dBm	Pass
15	Spurious and Sub	-200 to -90 dBc	<u>See plots</u> <u>-70</u> dBm	Pass
16	Power level of 114.58 GHz signal	<-10 dBm		Pass
17	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>10 Hz</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>35</u> dB Peak	N/A
18	Operating Temperature @ 1°C baseplate	TC1 = 1 ± 2°C	TC1 = <u>2.3</u>	
			TC2 = <u>2.4</u>	N/A
			TC3 = <u>1.9</u>	N/A
		0 - 1V	DRO L/A = <u>64.9</u> mV	Pass
19	Input Voltage and Current <i>4.3 to 4.7 V</i> <i>10/19/98</i>			
	VM1 Voltage	+15 ± 0.1 V	VM1 = <u>15.0</u> V	
	VM2 Voltage	-15 ± 0.1 V	VM2 = <u>-15.0</u> V	
	IM1 Current	600 mA max.	IM1 = <u>508</u> mA	
	IM2 Current	100 mA max.	IM2 = <u>-63.2</u> mA	
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>64.9</u> mV	
	PLO L/A Voltage	<u>4.3 to 4.7 V</u>	PLO L/A = <u>4.6</u> V	
	RF Output Power	17 to 20 dBm	Power = <u>18.17</u> dBm	
	Frequency	57.290344 ± .0002 GHz	Freq. = <u>57.290311900</u> GHz	
	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>15.2</u> V	
		-15.2 ± 0.05 V	-Voltage = <u>-15.2</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290311595</u> GHz	
		17 to 20 dBm	Power = <u>18.26</u> dBm	
	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.29031877</u> GHz	
		17 to 20 dBm	Power = <u>18.20</u> dBm	Pass

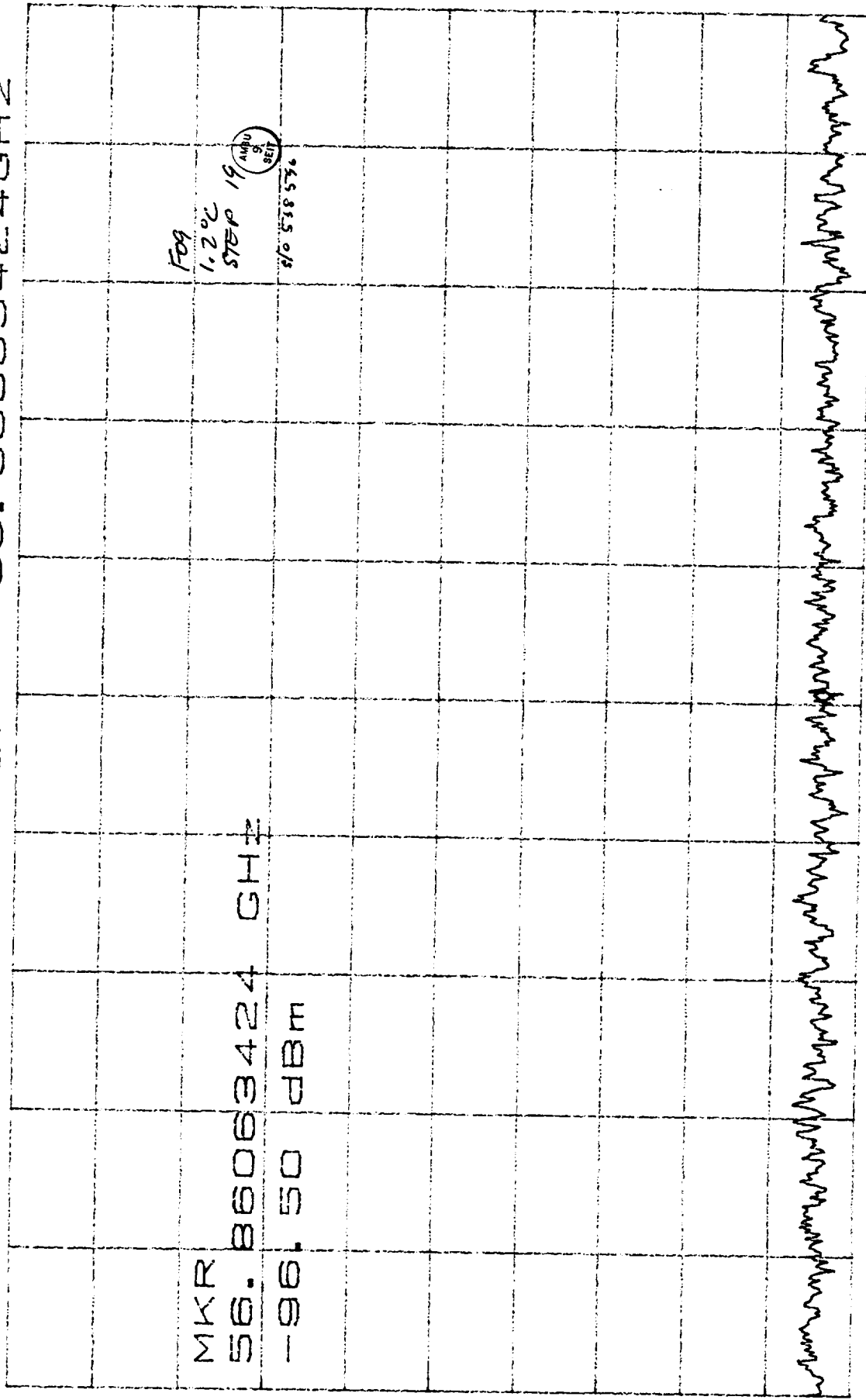
CL 30.0dB

RL 0dBm

MKR -96.50dBm

10dB/

56.86063424GHz



CENTER 56.86063391GHz

SPAN 50.00kHz

*RBW 1.0kHz

*VBW 1.0kHz

SWP 200ms

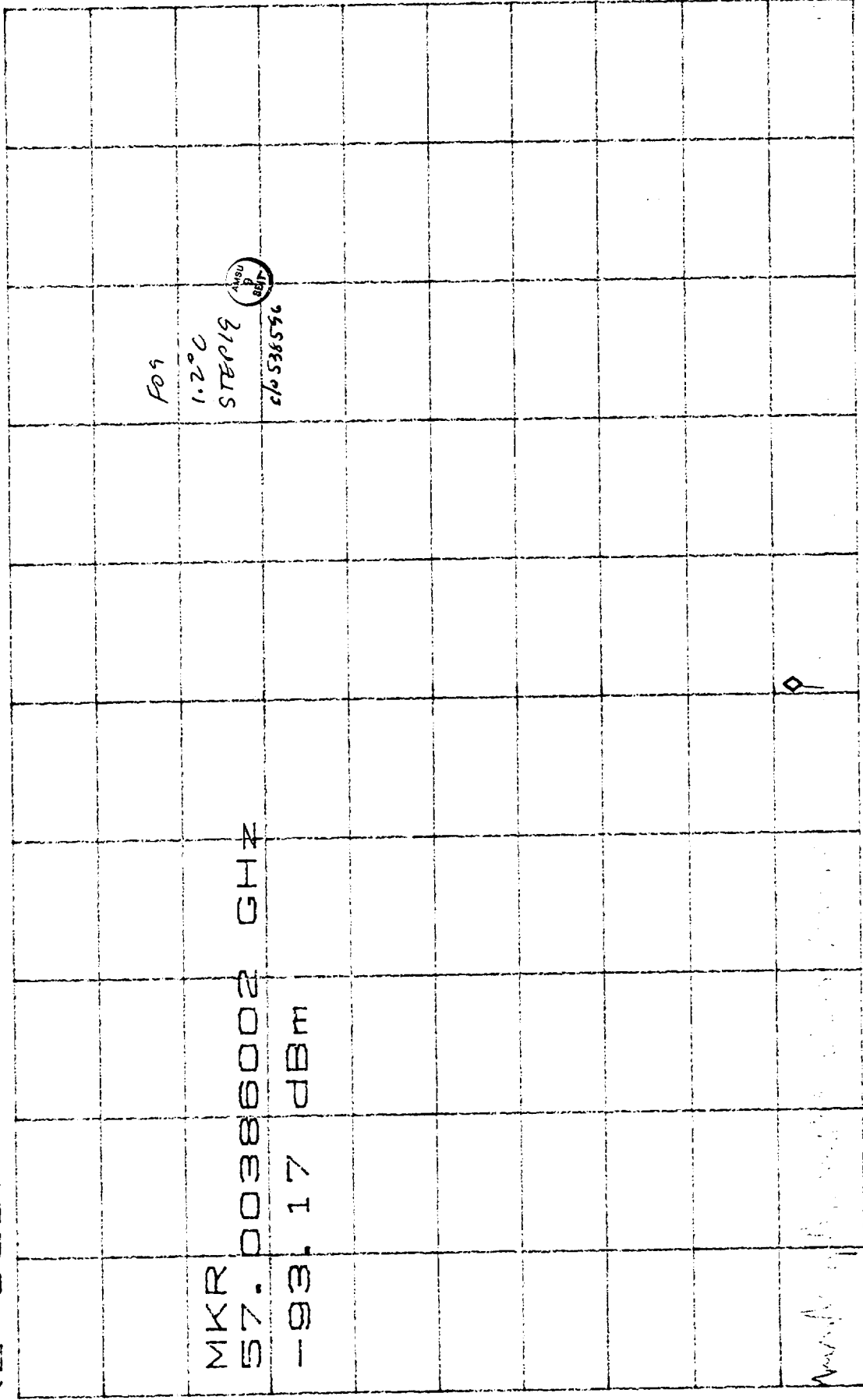
CL 30.0dB

MKR -93.17dBm

RL 0dBm

10dB/

57.00386002GHz



CENTER 57.00385969GHz SPAN 50.00kHz

*RBW 1.0kHz *VBW 1.0kHz SWP 200ms

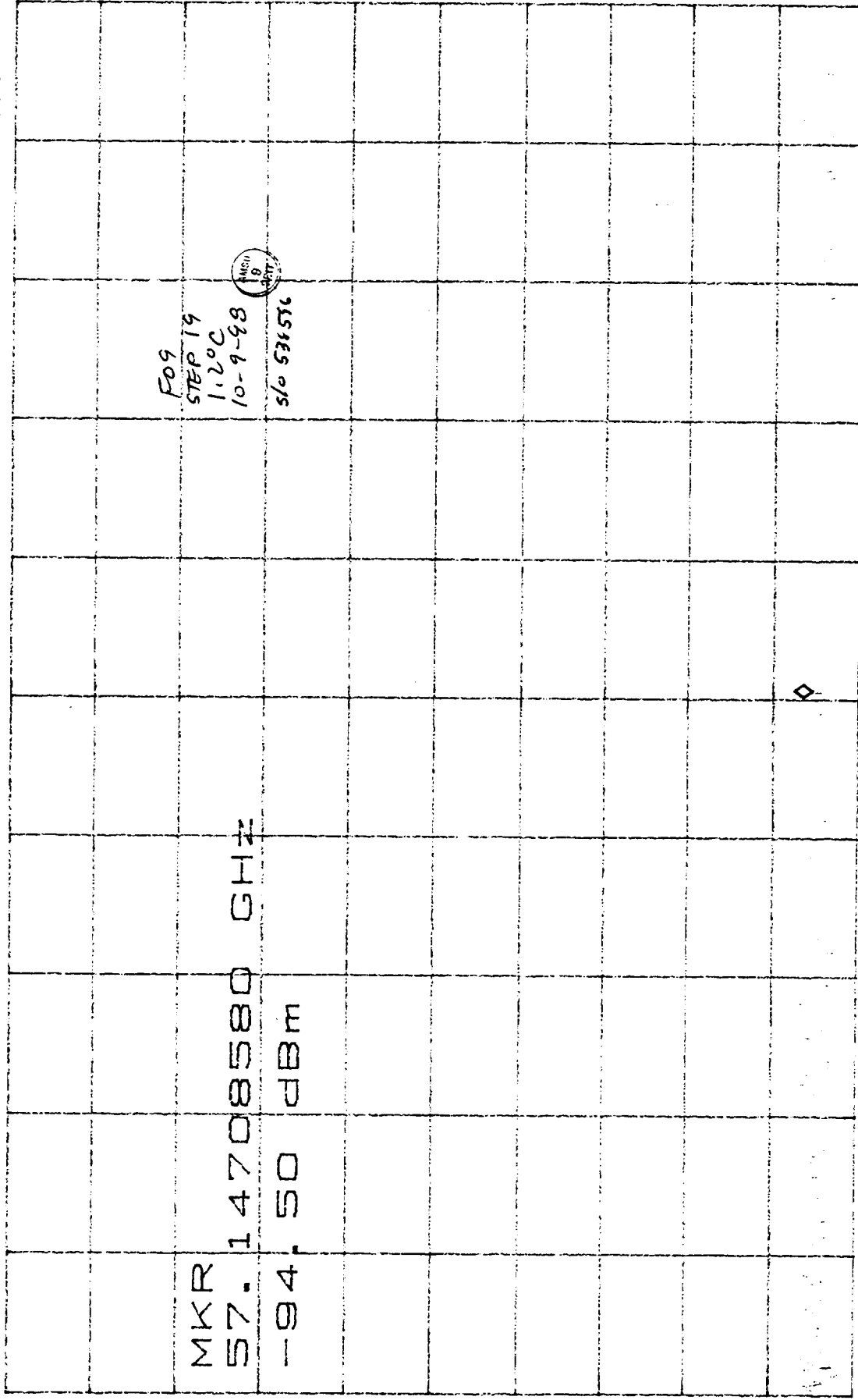
CL 30.0dB

RL 0dBm

MKR -94.50dBm

10dB/

57.14708580GHz



CENTER 57.14708546GHz

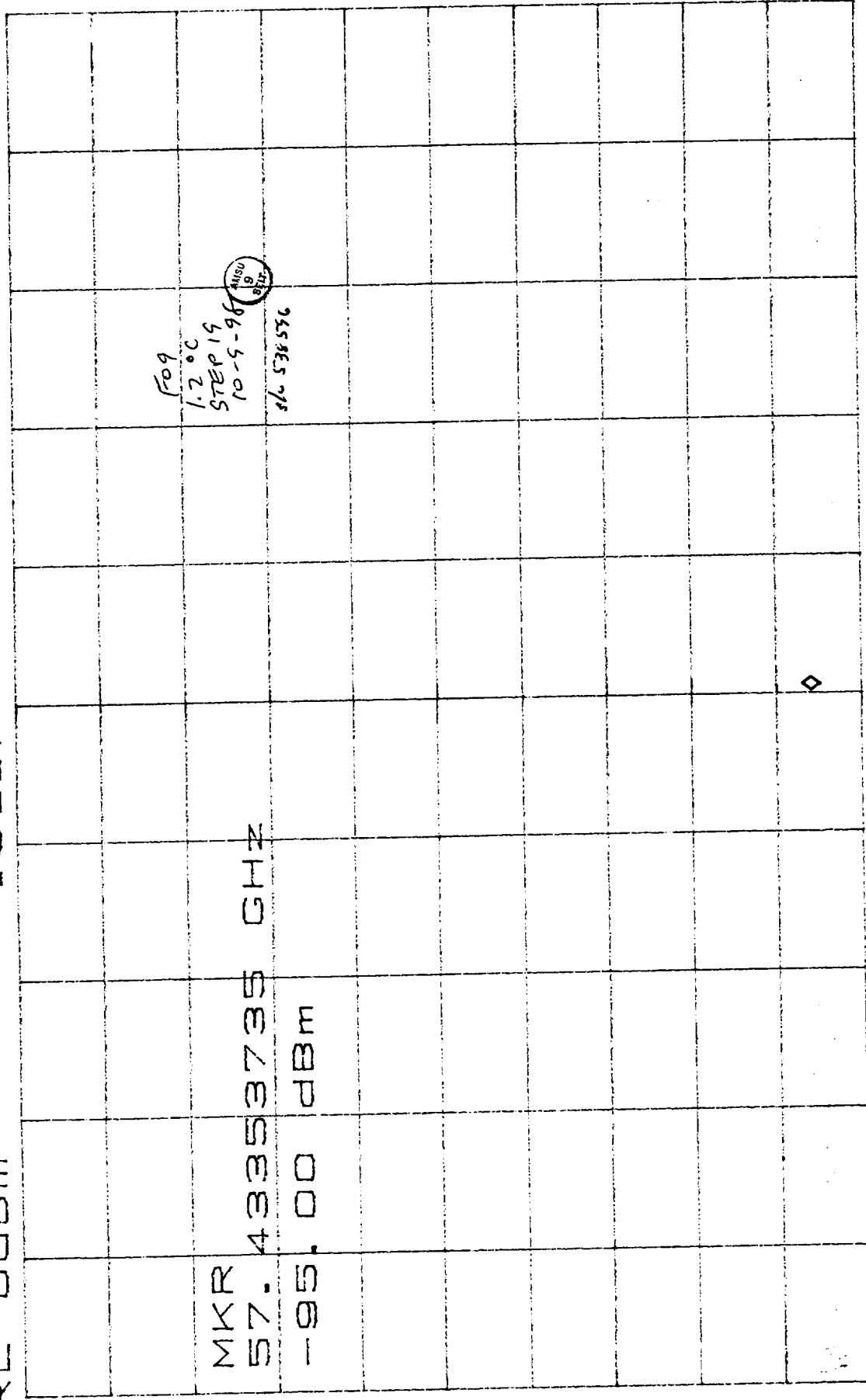
SPAN 50.00KHz

*RBW 1.0KHz

*VBW 1.0KHz

SWP 200ms

CL 30.0dB MKR -95.00dBm
 RL 0dBm 10dB/ 57.43353735GHz



CENTER 57.43353702GHz SPAN 50.00kHz
 *RBW 1.0kHz *VBW 1.0kHz SWP 200ms

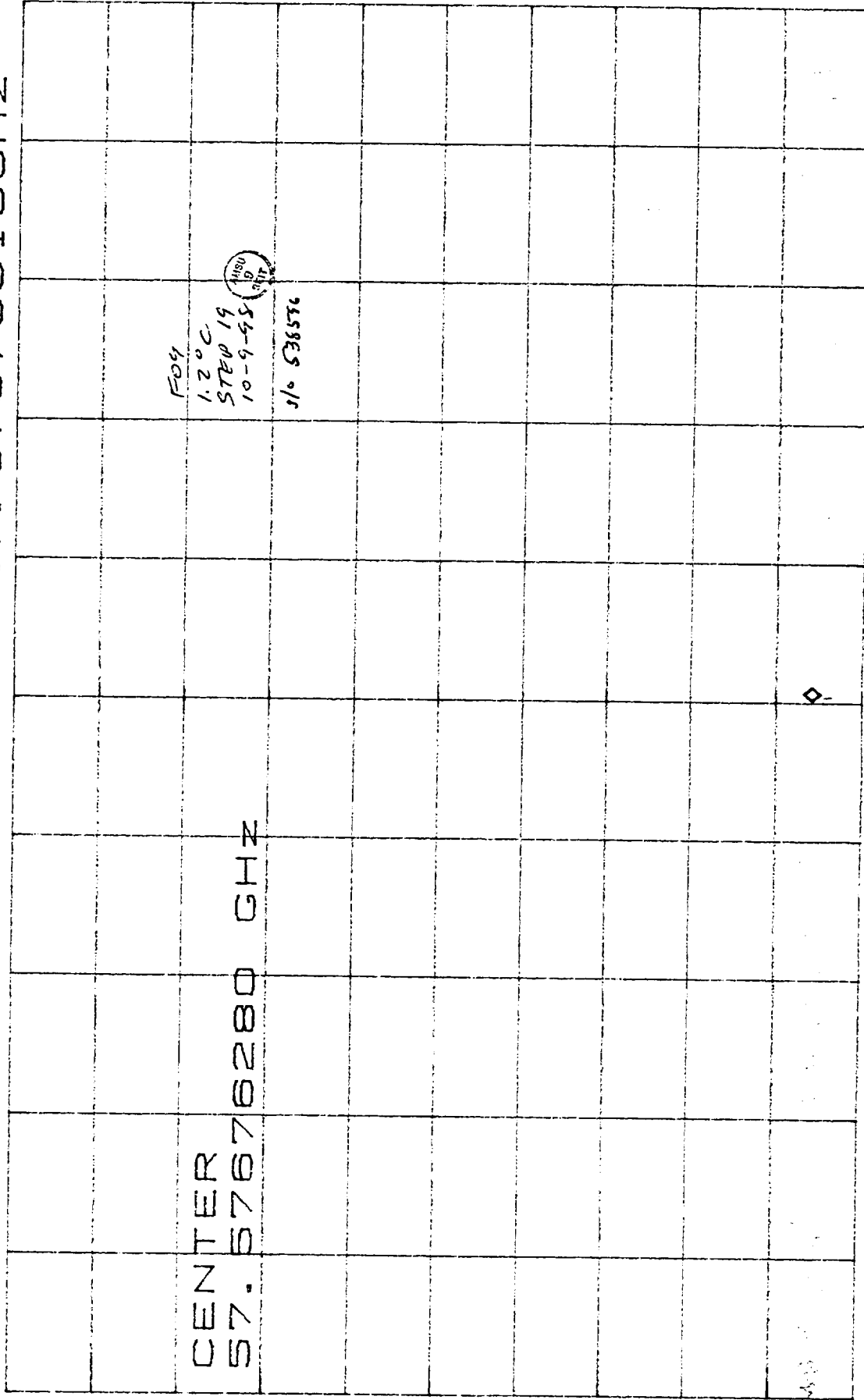
CL 30.0dB

RL 0dBm

10dB/

MKR -95.17dBm

57.57676313GHz



CENTER 57.57676280GHz

SPAN 50.00kHz

*RBW 1.0kHz

*VBW 1.0kHz

SWP 200ms

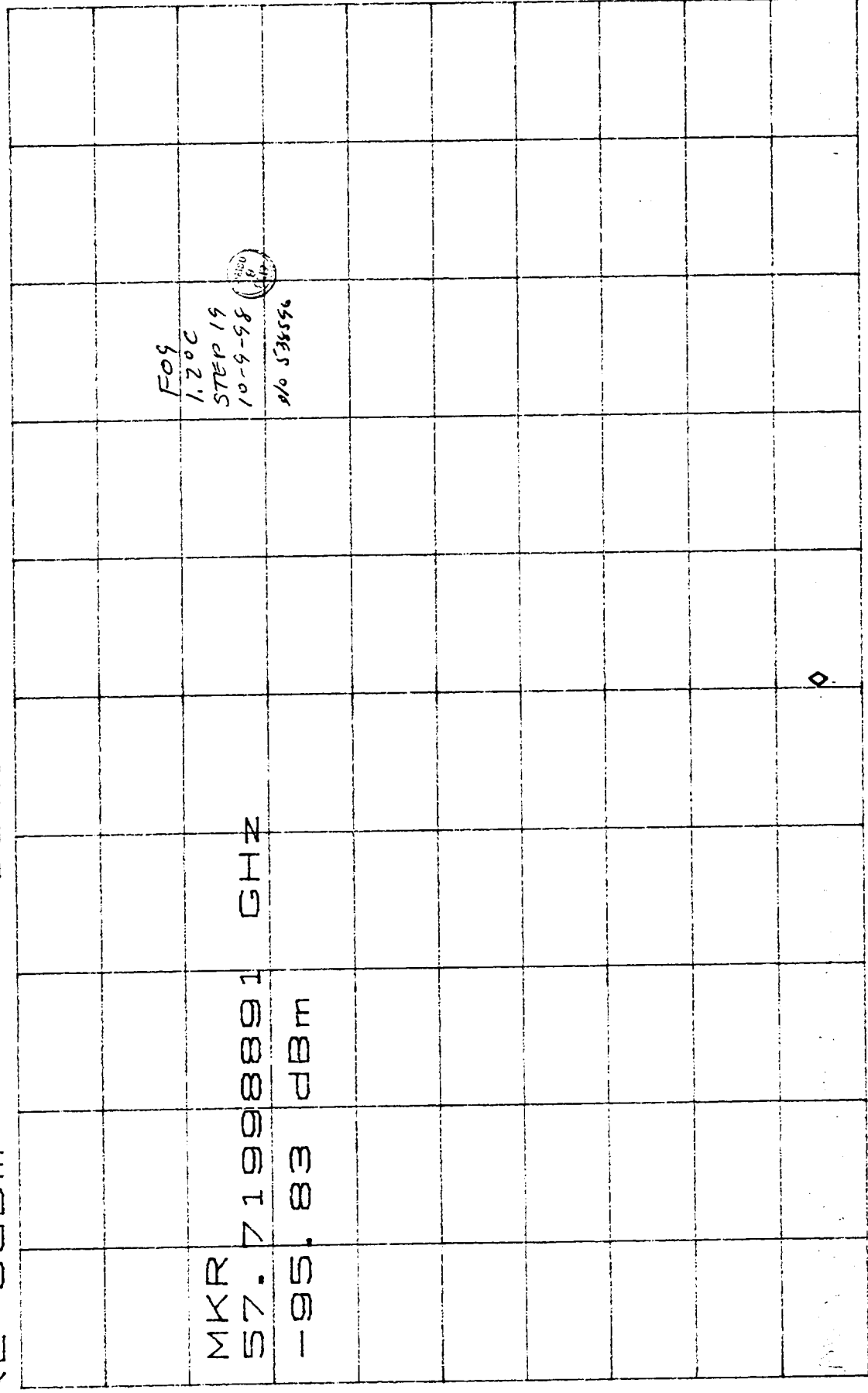
CL 30.0dB

MKR -95.83dBm

RL 0dBm

10dB/

57.71998891GHz



CENTER 57.71998858GHz SPAN 50.00kHz

*RBW 1.0kHz

*VBW 1.0kHz

SWP 200ms

CL 30.0dB

MKR -71.00dBm

RL 0dBm

10dB/

114.5806221GHz

MKR

114.5806221 GHz

-71.00 dBm

F09

1.20C

STEP 19

10-9-98



40 538596

CENTER 114.5806221GHz

SPAN 100.0KHz

*RBW 300Hz

*VBW 1.0KHz

*SWP 2.80Sec

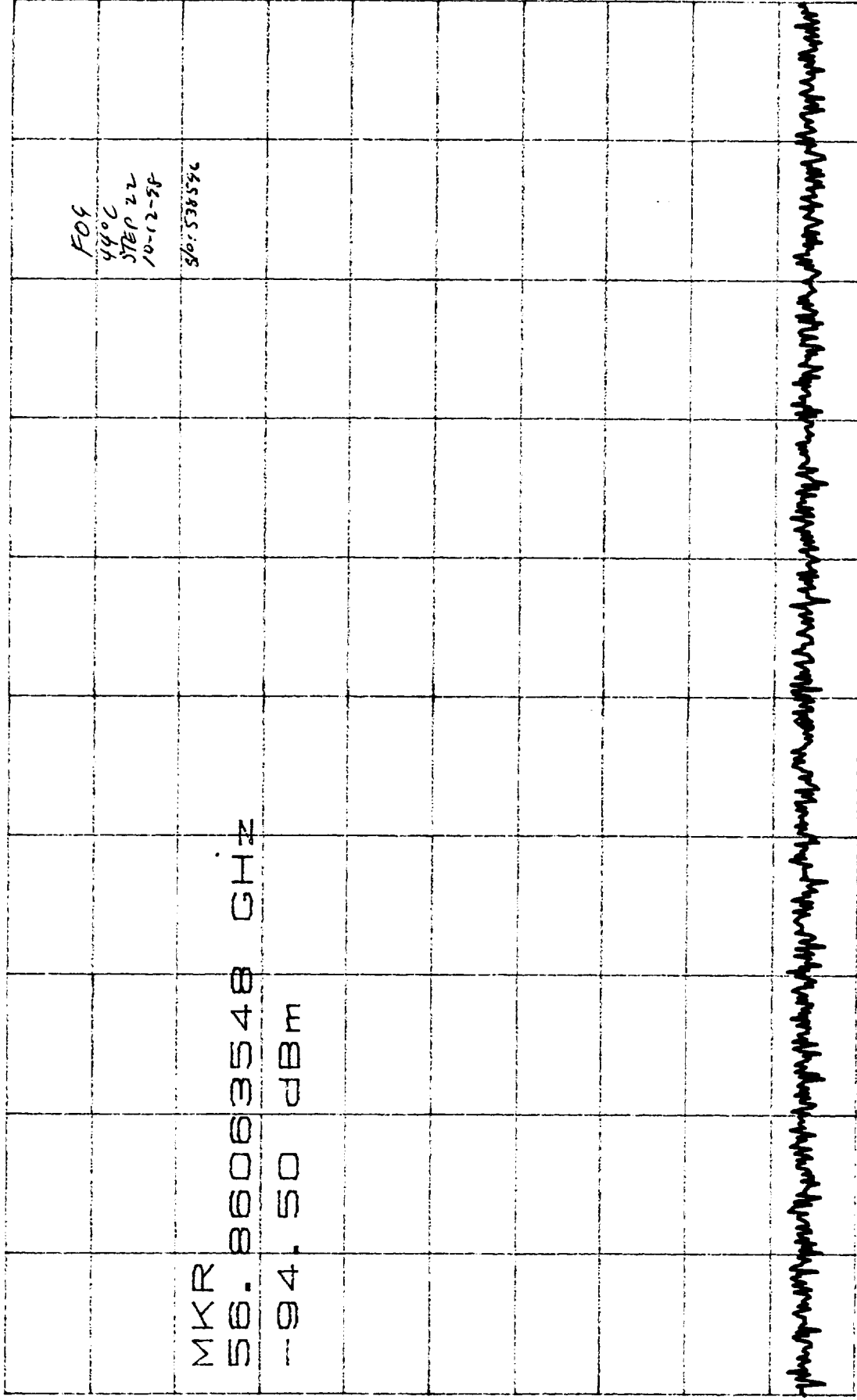
TEST DATA SHEET 6A (Sheet 3 of 4)
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Paragraph 4.2.1.3 (Cont):

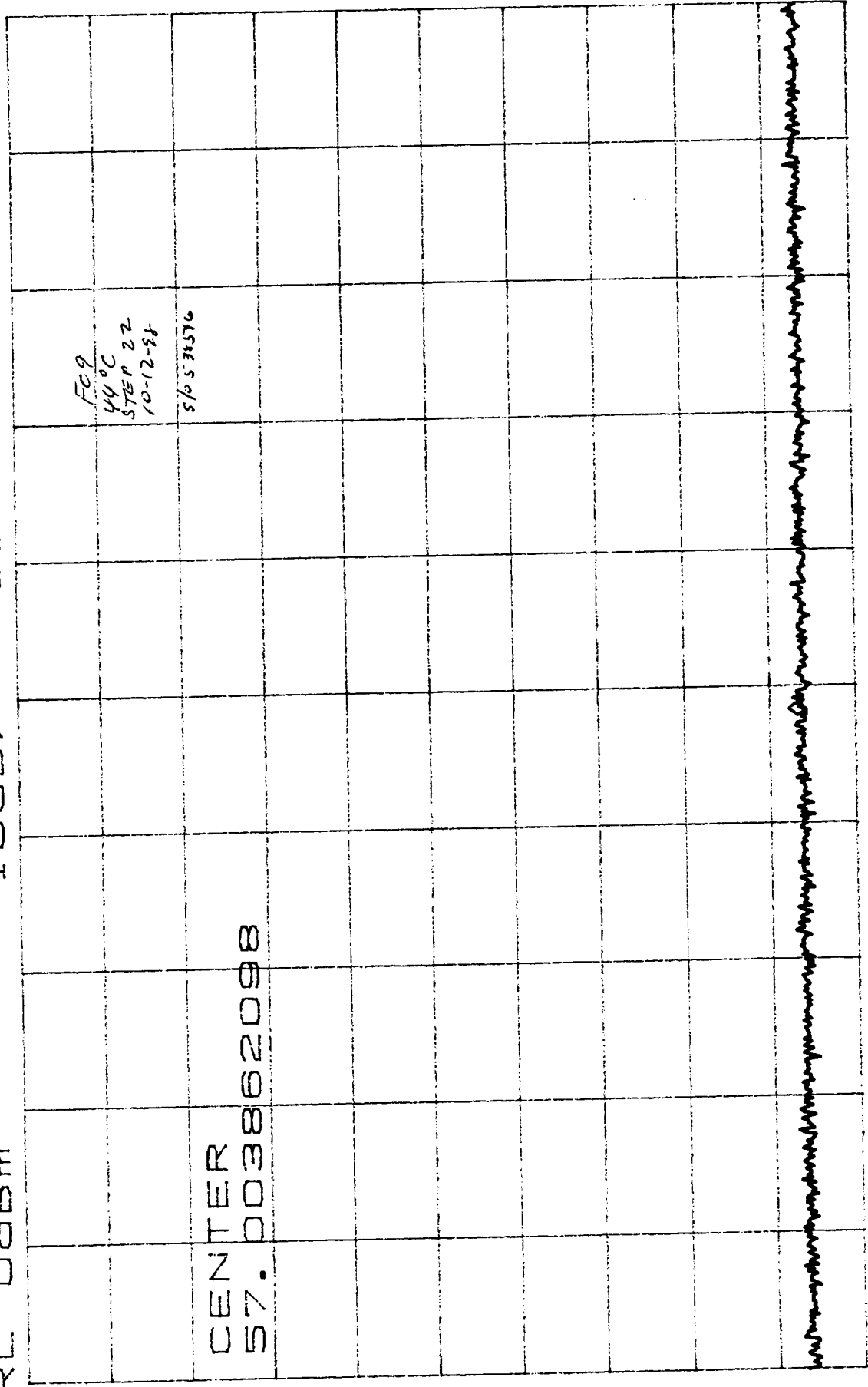
Step	Test	Expected	Measured	Pass/Fail
19	Spurious and Sub	-200 to -90 dBc	<i>see plots</i>	PASS
(Cont)	Power level of 114.58 GHz signal	<-10 dBm	<u>-71.0</u> dBm	PASS
Load VSWR and Frequency Pulling				
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>12.47</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>.23</u> dB	N/A
21	Operating Temperature @ +44°C Baseplate	TC1 = 44 ± 2°C	TC1 = <u>44.2°C</u>	Pass
			TC2 = <u>44.3°C</u>	N/A
			TC3 = <u>43.4°C</u>	N/A
		0 - 1V	DRO L/A = <u>120mV</u>	Pass
		<u>(229)</u> 0-1V 4.3-4.7V	PLO L/A = <u>4.5</u> V	Pass
22	Input Voltage and Current <i>10/12/98</i>			
	VM1 Voltage	+15 ± 0.1 V	VM1 = <u>+15.12</u> V	Pass
	VM2 Voltage	-15 ± 0.1 V	VM2 = <u>-15.12</u> V	Pass
	IM1 Current	600 mA max.	IM1 = <u>535</u> mA	Pass
	IM2 Current	100 mA max.	IM2 = <u>-66</u> mA	Pass
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>120mV</u>	Pass
	PLO L/A Voltage <u>(229)</u>	0 to 1V 4.3-4.7V	PLO L/A = <u>4.5</u> V	Pass
	RF Output Power and <i>10/12/98</i>	17 to 20 dBm	Power = <u>17.04</u> dBm	Pass
	Frequency	57.290344 ± .0002 GHz	Freq. = <u>57.290313666</u> GHz	Pass
Frequency vs. Voltage				
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>15.20</u> V	Pass
		-15.2 ± 0.05 V	-Voltage = <u>15.20</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.290313677</u> GHz	Pass
		17 to 20 dBm	Power = <u>17.02</u> dBm	Pass
Frequency vs. Voltage				
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	Pass
		-14.8 ± 0.05 V	-Voltage = <u>14.8</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.290313674</u> GHz	Pass
		17 to 20 dBm	Power = <u>17</u> dBm	Pass

CL 30.0dB VAVG 4 MKR -94.50dBm
RL 0dBm 10dB/ 56.86063548GHz



CENTER 56.86063548GHz SPAN 50.00kHz
*RBW 3.0kHz *VBW 3.0kHz *SWP 2.00sec

CL 30.0dB VAVG 42 MKR -94.17dBm
RL 0dBm 10dB/



D

CENTER 56.86063631GHZ SPAN 50.00KHZ
*RBW 3.0KHZ *VBW 3.0KHZ *SWP 2.00sec

CL 30.0dB

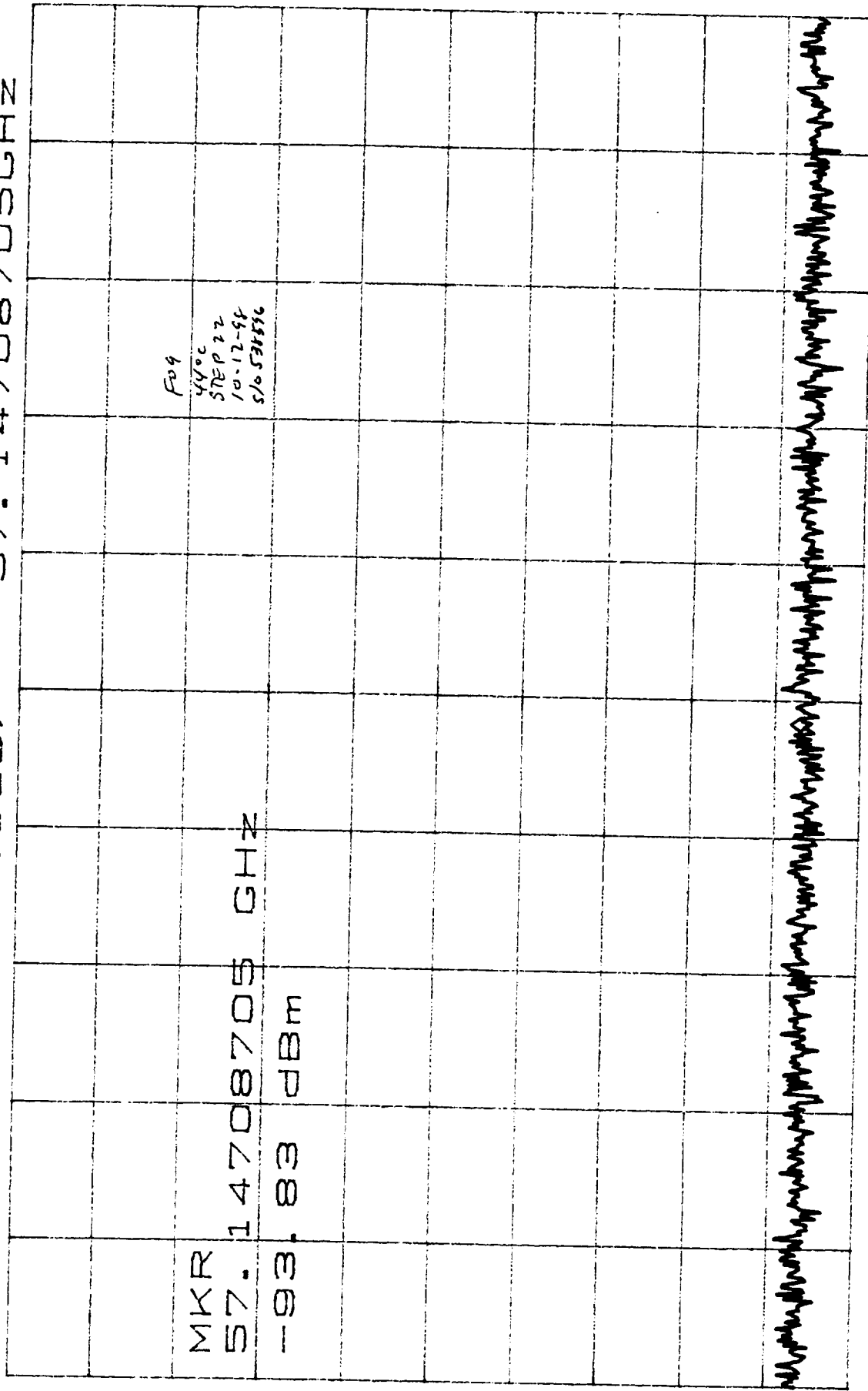
VAVG 3

MKR -93.83dBm

RL 0dBm

10dB/

57.14708705GHz



MKR

57.14708705 GHz

-93.83 dBm

D

CENTER 57.14708788GHz

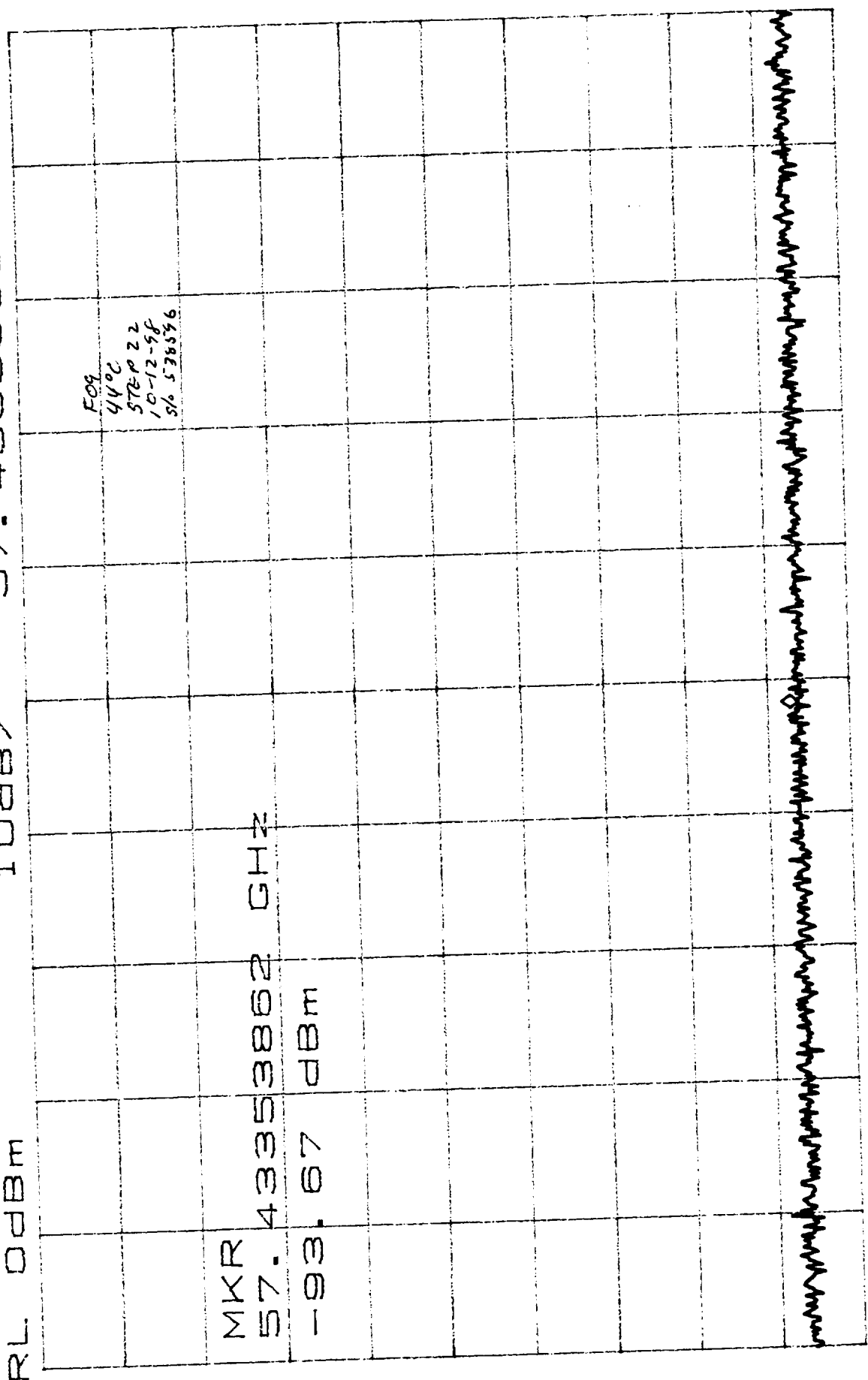
SPAN 50.00KHz

*RBW 3.0KHz

*VBW 3.0KHz

*SWP 2.00Sec

CL 30.0dB VAVG 9 MKR -93.67dBm
 RL 0dBm 10dB/ 57.43353862GHz



CENTER 57.43353862GHz SPAN 50.00kHz
 *RBW 3.0kHz *VBW 3.0kHz *SWP 2.00sec

CL 30.0dB

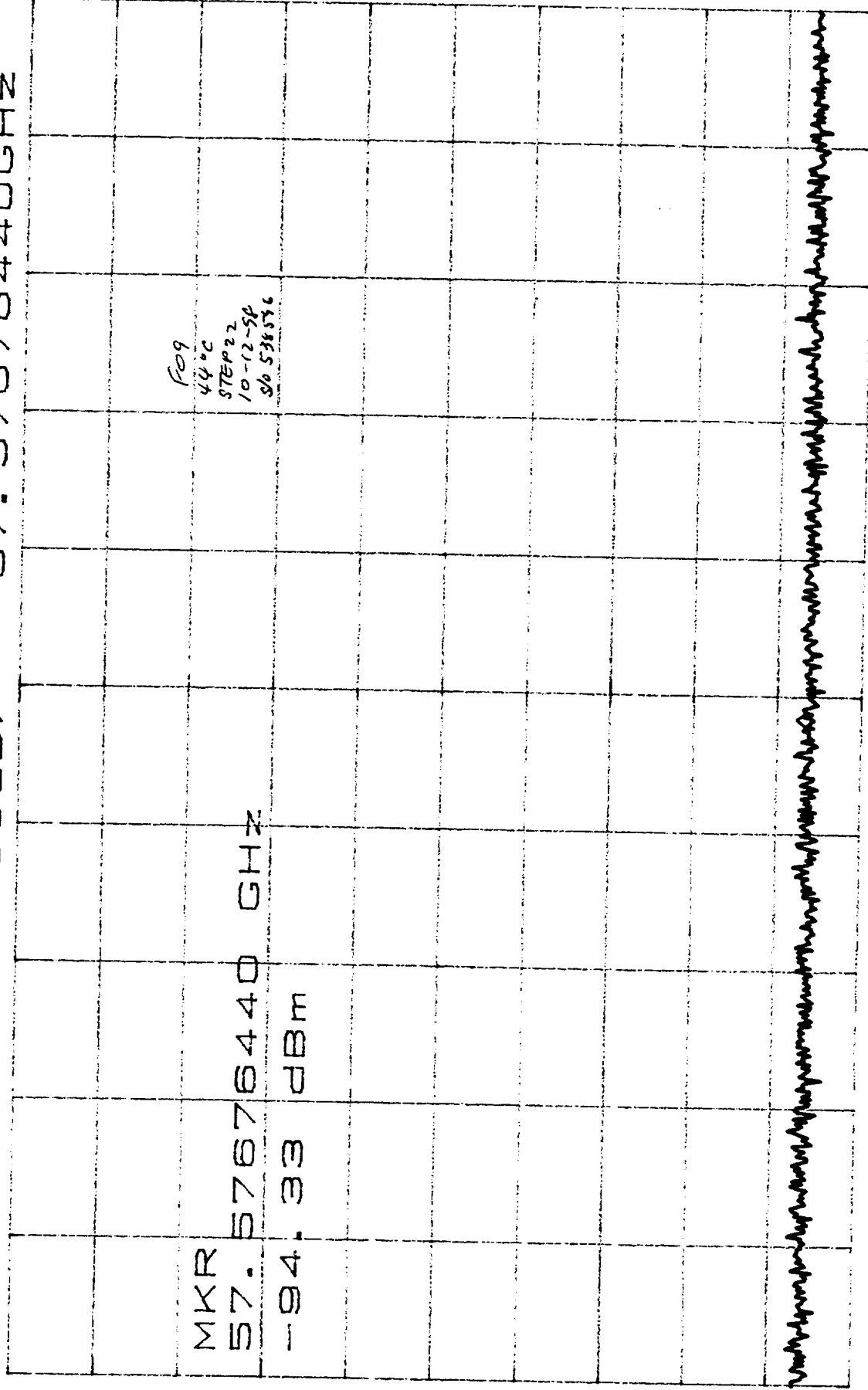
VAVG 9

MKR -94.33dBm

RL 0dBm

10dB/

57.57676440GHz



MKR

57.57676440 GHz

-94.33 dBm

109
44.0C
STEP 22
10-12-54
96 538536

D

CENTER 57.57676523GHz

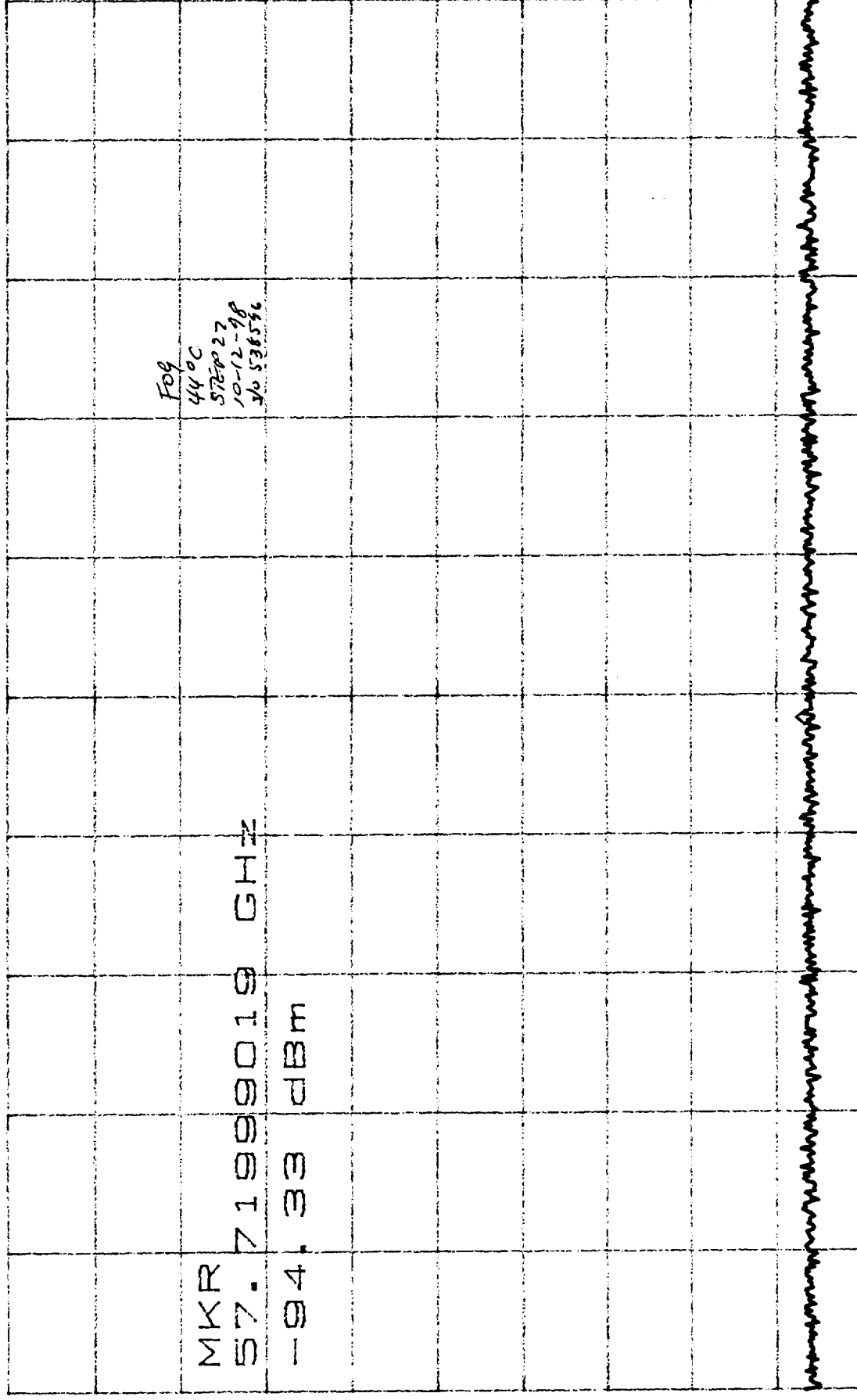
SPAN 50.00KHz

*RBW 3.0KHz

*VBW 3.0KHz

*SWP 2.00Sec

CL 30.0dB VAVG 23 MKR -94.33dBm
 RL 0dBm 10dB/ 57.71999019GHz



D

CENTER 57.71999102GHz SPAN 50.00kHz
 *RBW 3.0kHz *VBW 3.0kHz *SWP 2.00000

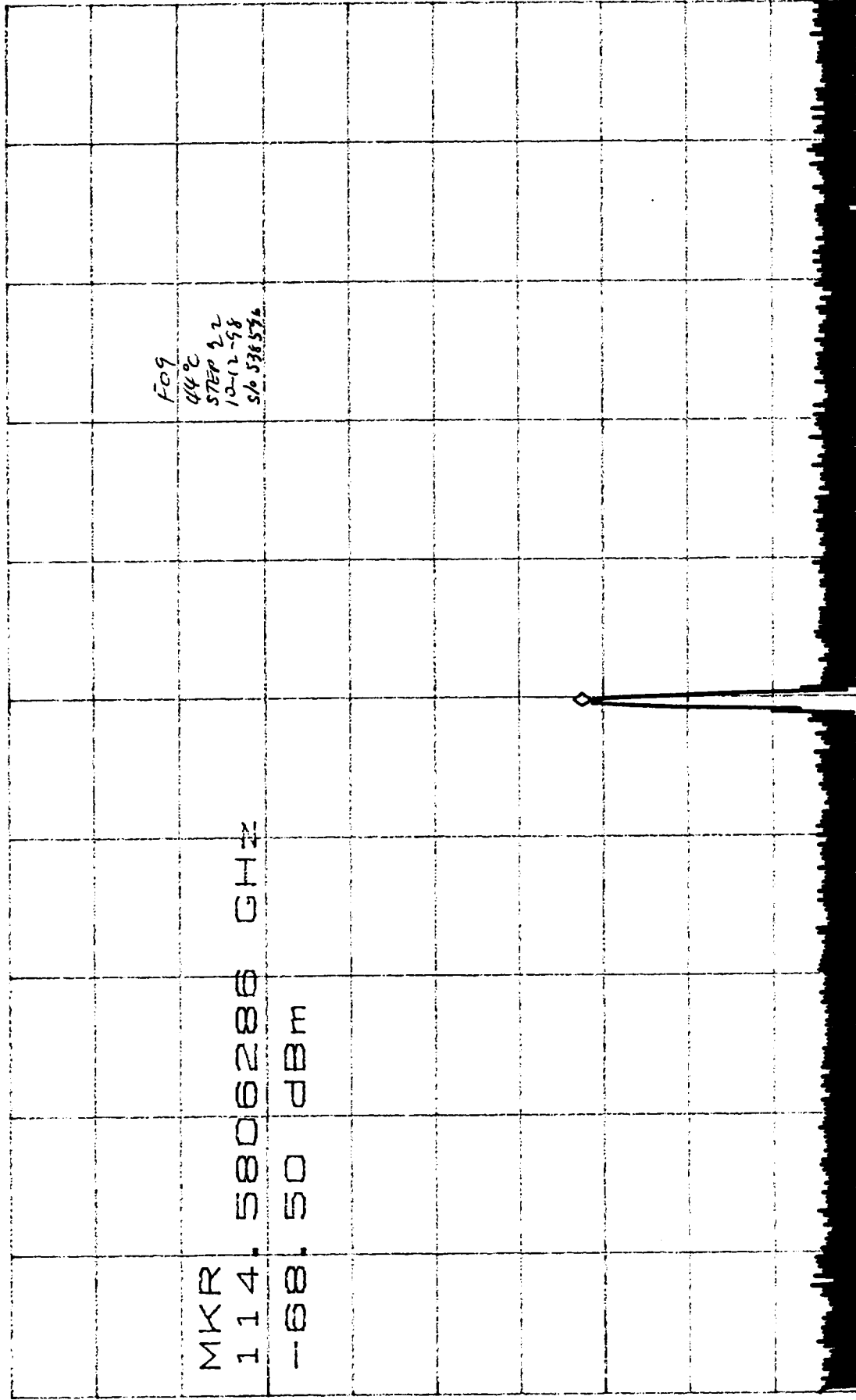
CL 30.0dB

MKR -68.50dBm

RL 0dBm

10dB/

114.5806286GHZ



CENTER 114.5806288GHZ

SPAN 100.0KHZ

*RBW 300HZ

*VBW 1.0KHZ

*SWP 2.80S



TEST DATA SHEET 6A (Sheet 4 of 4)
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
22	Spurious and Sub	-200 to -90 dBc	<i>see plots</i>	<i>Pass</i>
(Cont)	Power level of 114.58 GHz signal	<-10 dBm	<i>-62</i> dBm	<i>Pass</i>
Load VSWR and Frequency Pulling				
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <i>10.65</i>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <i>125</i> dB	N/A

Shop Order No.: 538596
Operation: 0110
Unit Serial No.: F09
Date: 10-12-98

Test Engineer: 
Quality Control:  *11-1*
Govt. Rep.: *[Signature]*

OCT 13 '98

Section 1B: Initial Functional Testing - F10

This section contains the results of a full functional test over temperature taken before PLO F10 endured thermal cycling. All tests passed.

TEST DATA SHEET 6A (Sheet 1 of 4)
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Test Setup Verified:

[Signature]
Signature

Paragraph 4.2.1.3, Functional Testing:

Step	Test	Expected	Measured	Pass/Fail
1	Potential Difference from ± 15 V RTN to:			
	PLO Base Plate	< 1.0 Vac	0.03	Pass
	Spectrum Analyzer	< 1.0 Vac	0.03	Pass
	Frequency Counter Chassis	< 1.0 Vac	0.02	Pass
	Power Meter Chassis	< 1.0 Vac	0.03	Pass
4	Evacuate vacuum chamber and record pressure	< 10^{-3} torr	N/A	N/A*
5	Thermal couple readings	TC1 = 22 ± 2 °C	TC1 = <u>21.8</u> °C	
			TC2 = <u>22.3</u> °C	N/A
			TC3 = <u>21.22</u> °C	N/A
6	DRO L/A	0 to 1V	DRO L/A = <u>54</u> mV	Pass
	PLO L/A	0 to 1V 4.3-4.7	PLO L/A = <u>4.49</u> V	
	Is PLO locked?	Yes	Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>	
7	PLO Frequency	57.290344 \pm .0002 GHz	Freq. = <u>57.290341378</u> GHz	
	PLO Power	17 to 20 dBm	P = <u>18.48</u> dBm	
8	Input Voltage and Current			
	VM1 Voltage	+15 \pm 0.1 V	VM1 = <u>15.0</u> V	
	VM2 Voltage	-15 \pm 0.1 V	VM2 = <u>-15.0</u> V	
	IM1 Current	600 mA max.	IM1 = <u>531</u> mA	
	IM2 Current	100 mA max.	IM2 = <u>-67</u> mA	
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>54</u> mV	
	PLO L/A Voltage	0 to 1V 4.3-4.7	PLO L/A = <u>4.49</u> V	
12	RF Output Power and Frequency	17 to 20 dBm	P = <u>18.48</u> dBm	
		57.290344 \pm .0002 GHz	Freq. = <u>57.290341378</u> GHz	
	Baseplate Temp. (TC1)	TC1 = 22 ± 2 °C	TC1 = <u>21.8</u> °C	
13	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 \pm 0.05 V	+Voltage = <u>15.2</u> V	
		-15.2 \pm 0.05 V	-Voltage = <u>-15.2</u> V	
		57.290344 \pm .0002 GHz	Freq. = <u>57.290341368</u> GHz	
		17 to 20 dBm	P = <u>18.40</u> dBm	Pass

*Record data only if performing test under vacuum

CL 30.0dB

RL 0dBm

MKR -3.17dBm

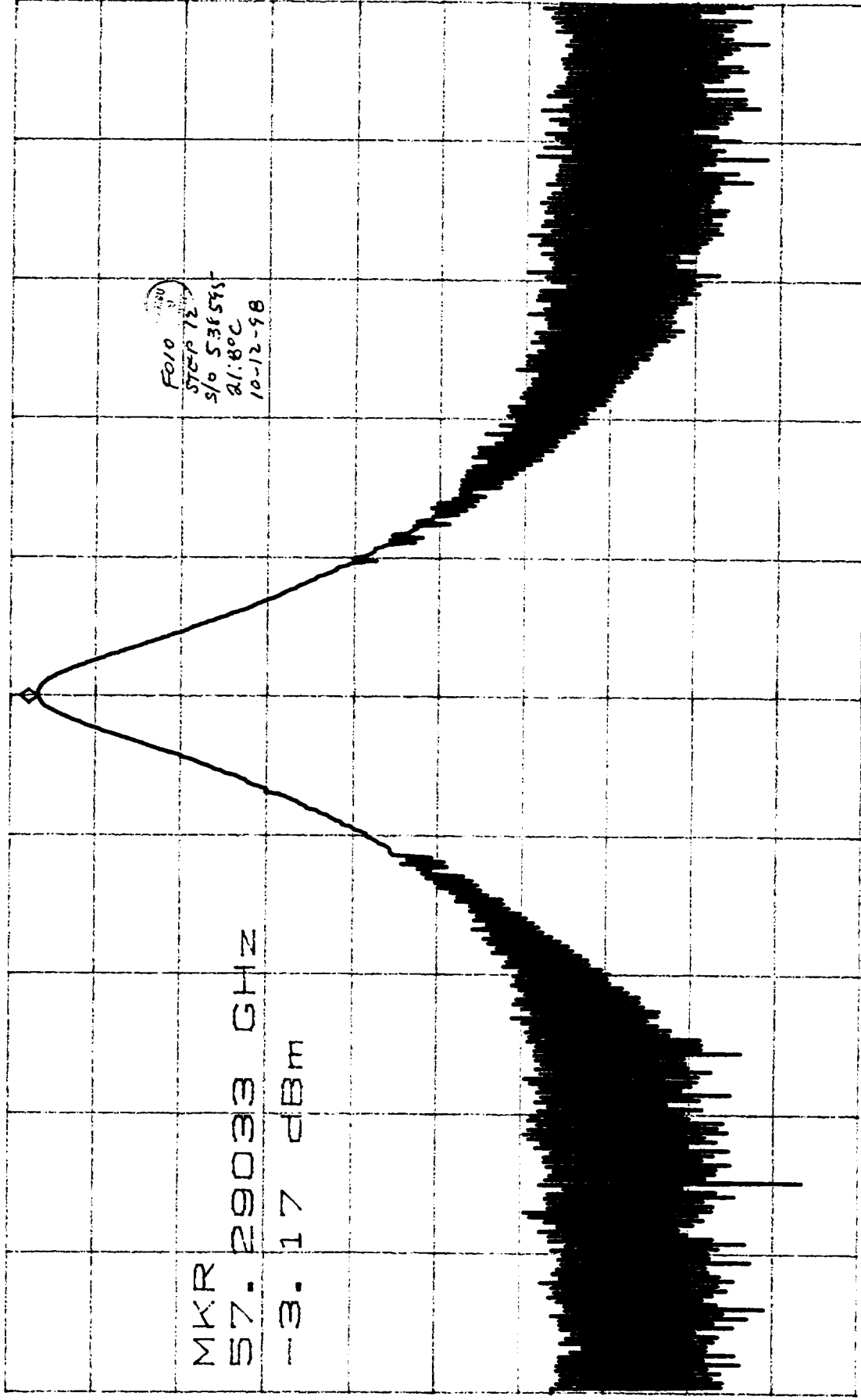
10dB/ 57.29033GHz

MKR

57.29033 GHz

-3.17 dBm

FOI 0
STEP 12
S/O 536545
21.8°C
10-12-98



CENTER 57.29033GHz

*RBW 300KHz

*VBW 300KHz

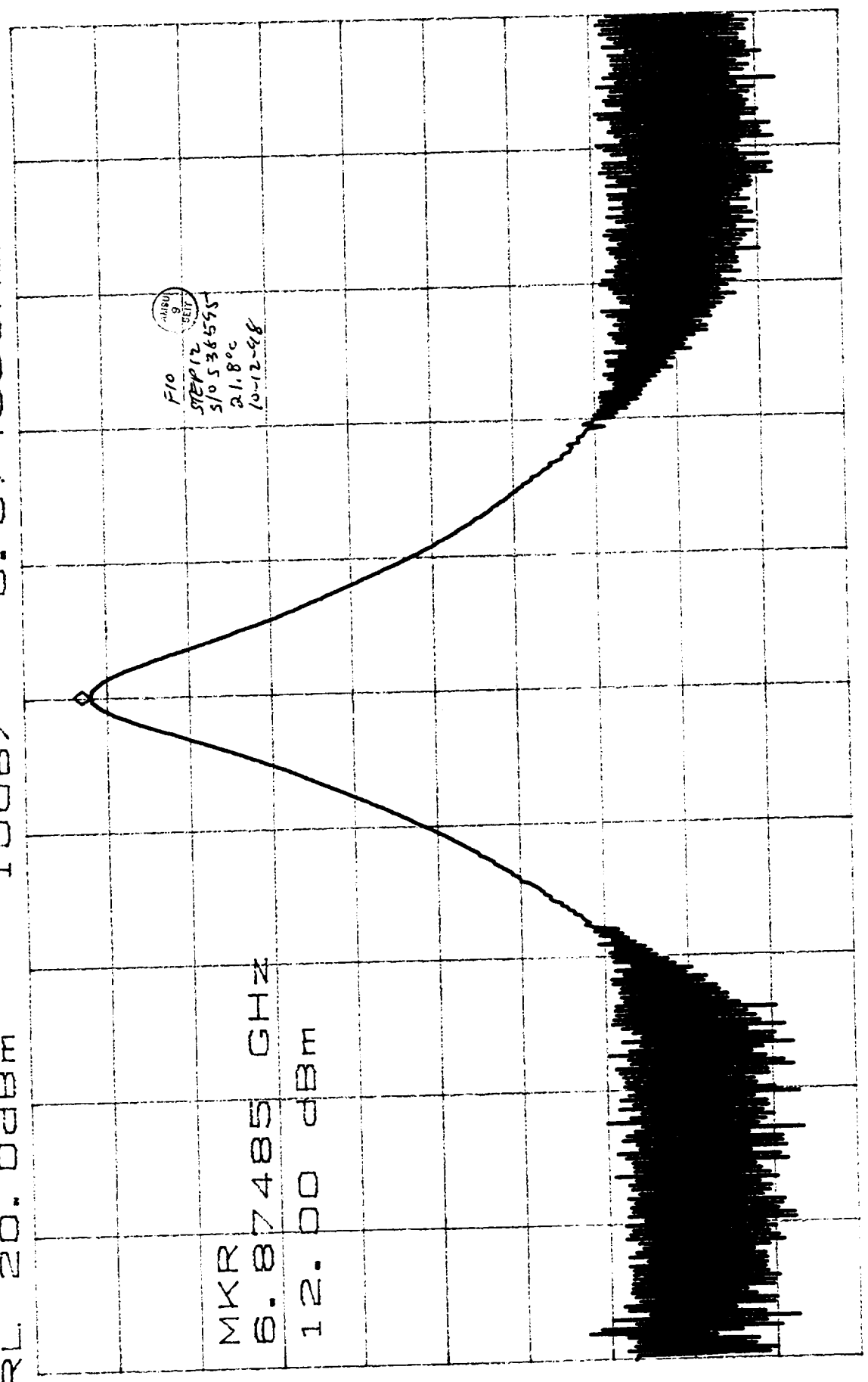
SPAN 10.00MHz

*SWP 50.0MHz

ATTEN 30dB MKR 12.00dBm
RL 20.00dBm 6.87485GHz 10dB/

MKR
6.87485 GHz
12.00 dBm

F10
SEP 12
S/O 53655
21.8°C
10-12-98



CENTER 6.87483GHz SPAN 10.00MHz
*RBW 300kHz VBW 300kHz SWP 50.0ms

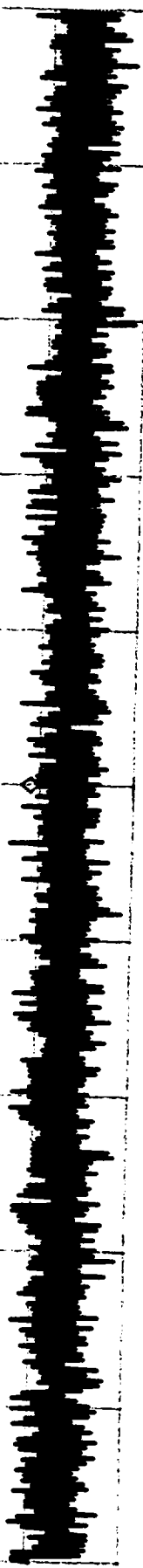
CL 30.0dB
RL 0dBm

MKR -90.00dBm
56.8607592GHz

10dB/

MKR
56.8607592 GHz
-90.00 dBm

F10
21.802
STEP 15
310538555
10-12-58

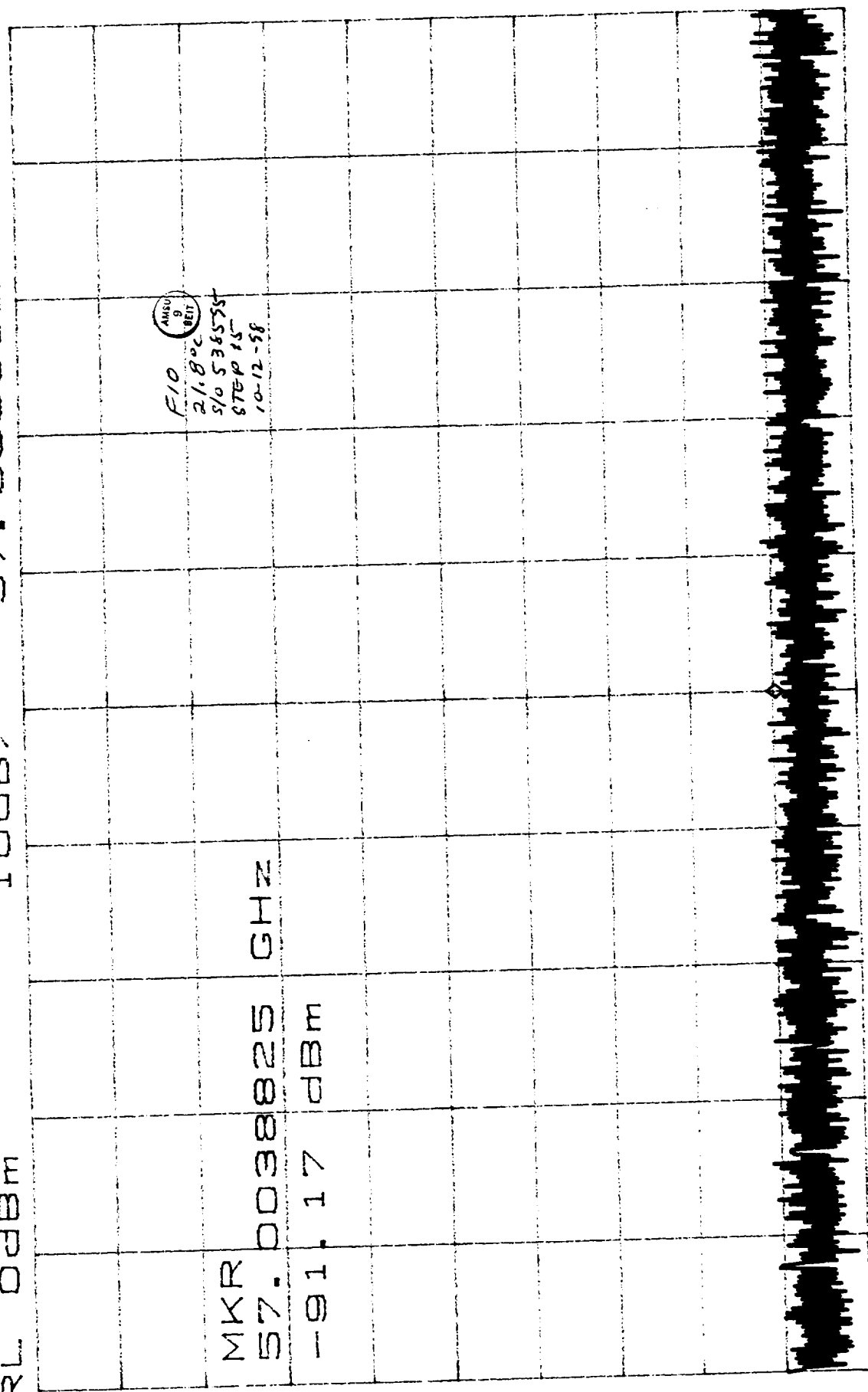


CENTER 56.8607592GHz
RBW 3.0kHz *VBW 1.0kHz
SPAN 500.0kHz
*SWP 1.00sec

CL 30.0dB
RL 0dBm

10dB/

MKR -91.17dBm
57.0038825GHz



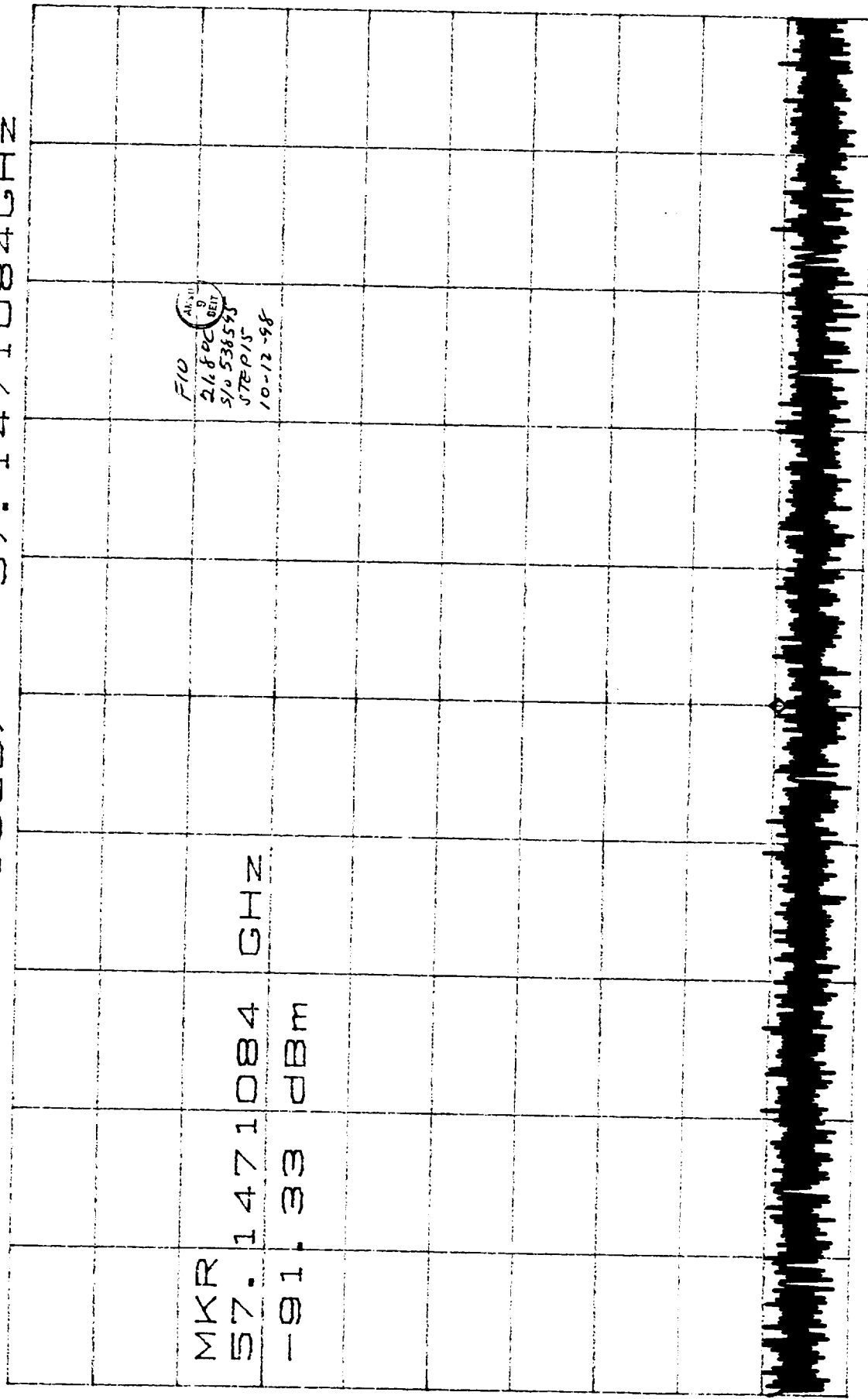
MKR
57.0038825 GHz
-91.17 dBm

CENTER 57.0038825GHz
SPAN 500.0KHz
RBW 3.0KHz
*VBW 1.0KHz
*SWP 1.00000

CL 30.0dB
RL 0dBm

MKR -91.33dBm
57.1471084GHz

10dB/



CENTER 57.1471084GHz
RBW 3.0KHz
SPAN 500.0KHz
*VBW 1.0KHz
*SWP 1.00Sec

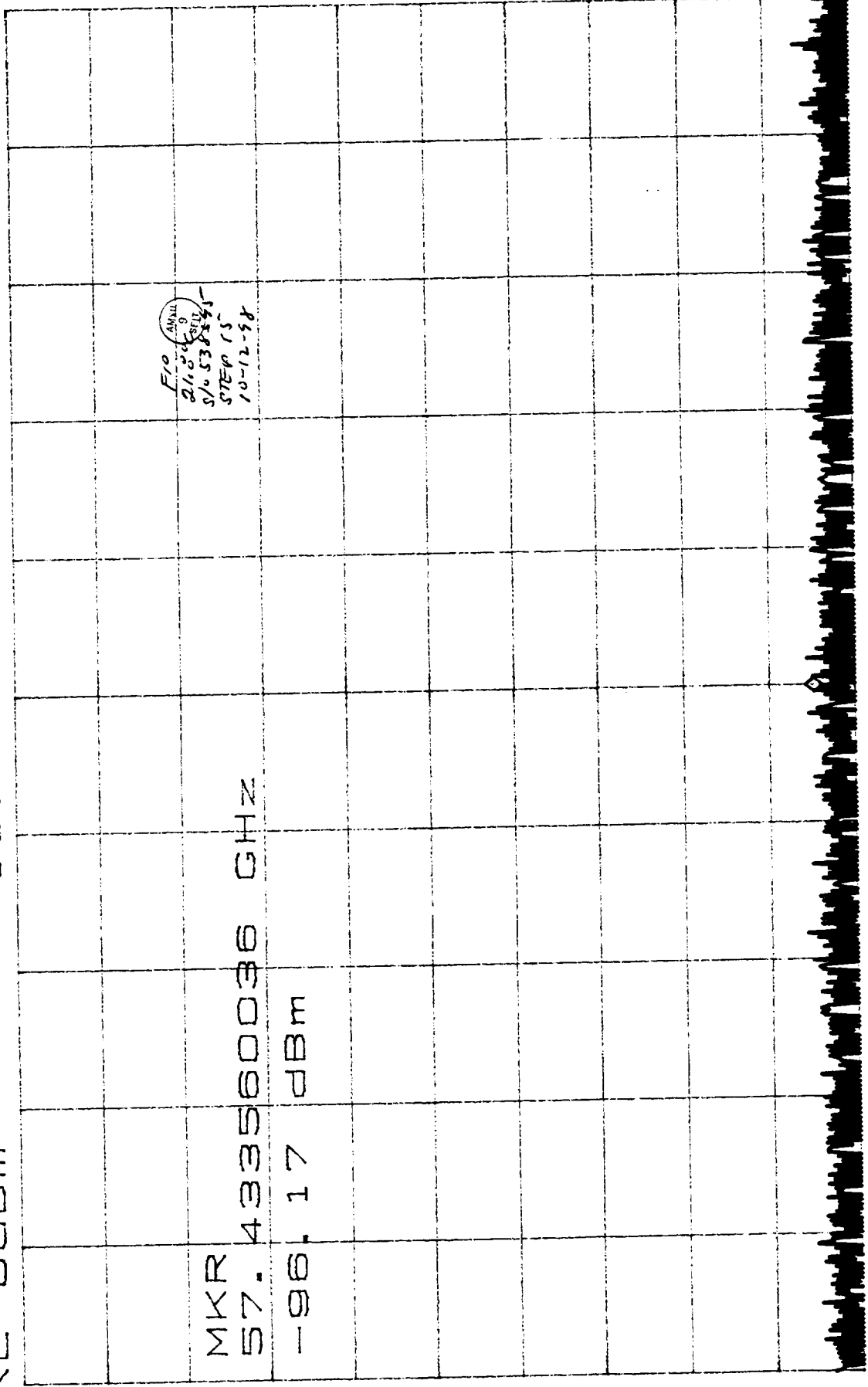
CL 30.0dB

RL 0dBm

MKR -96.17dBm

10dB/

57.433560036GHZ



MKR

57.433560036 GHZ

-96.17 dBm

CENTER 57.433560036GHZ SPAN 5.400KHZ
RBW 300HZ *VBW 1.0KHZ *SWP 1.00sec

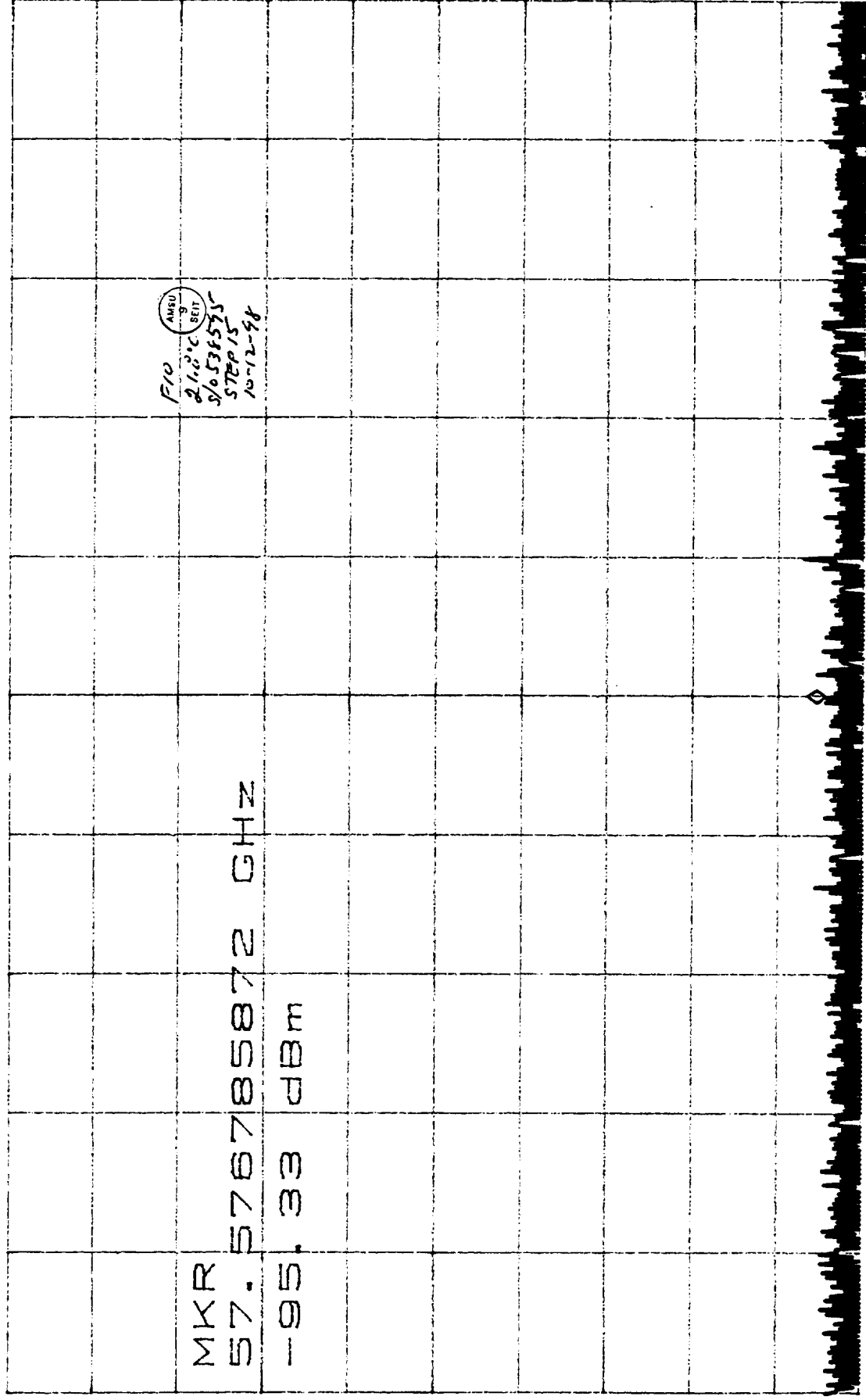
CL 30.0dB

RL 0dBm

MKR -95.33dBm

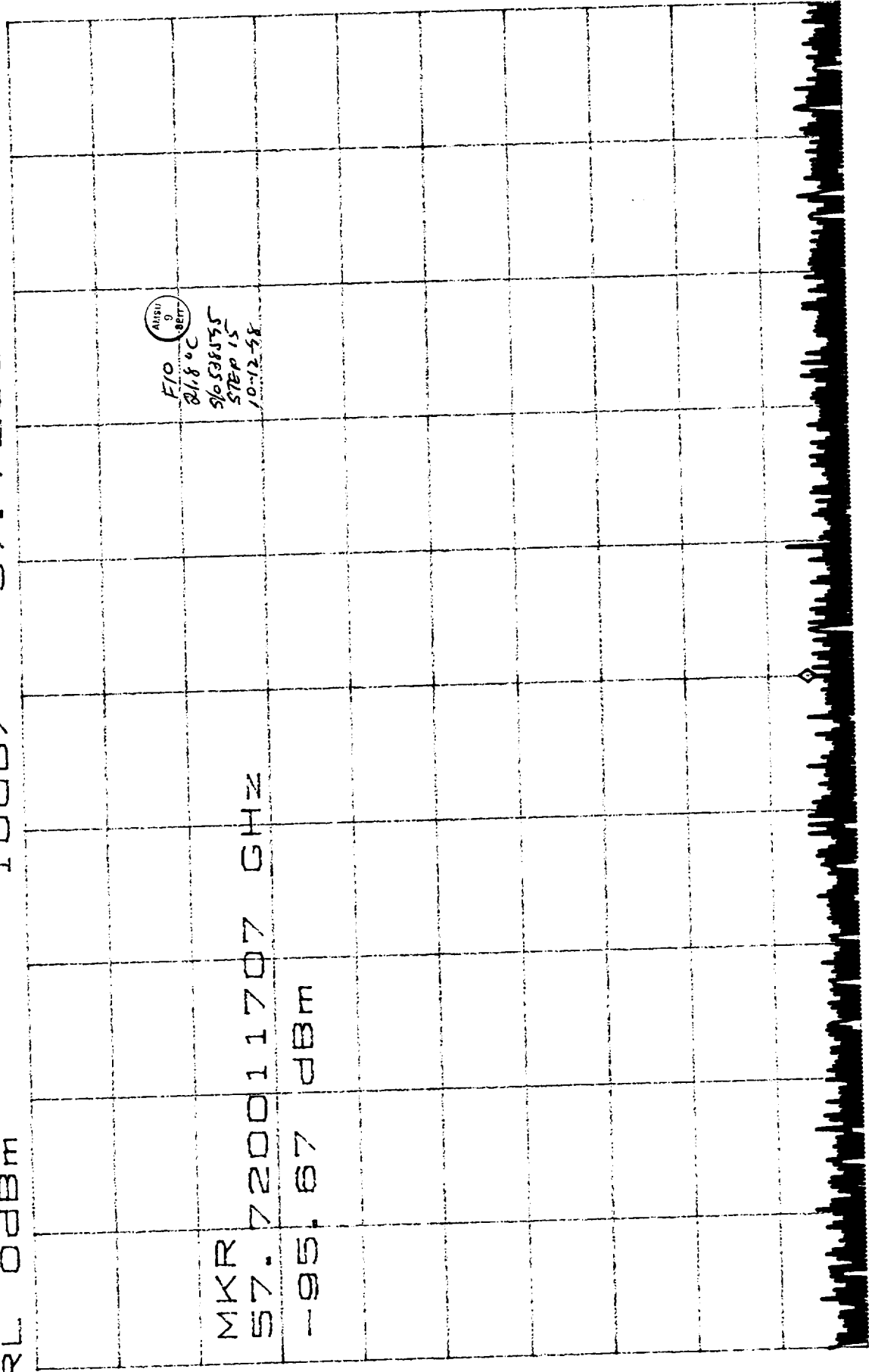
10dB/

57.576785872GHz



CENTER 57.576785872GHz SPAN 5.400kHz
RBW 300Hz *VBW 1.0kHz *SWP 1.00sec

CL 30.0dB
RL 0dBm
MKR -95.67dBm
57.720011707GHZ
10dB/



CENTER 57.720011707GHZ
RBW 300HZ
SPAN 5.400KHZ
*VBW 1.0KHZ
*SWP 1.00sec

CL 30.0dB

RL 0dBm

MKR -56.00dBm

10dB/

114.5806839GHz

MKR

114.5806839 GHz

-56.00 dBm

Fl
21.8°C
510538545-
STEP 15
10-12-58

ANAL
TO
BEIT

CENTER 114.5806839GHz

*RBW 300Hz

*VBW 1.0KHz

SPAN 100.0KHz

*SWP 2.80000

CL 30.0dB

RL 0dBm

MKR -2.00dBm

10dB/ 57.29033GHz

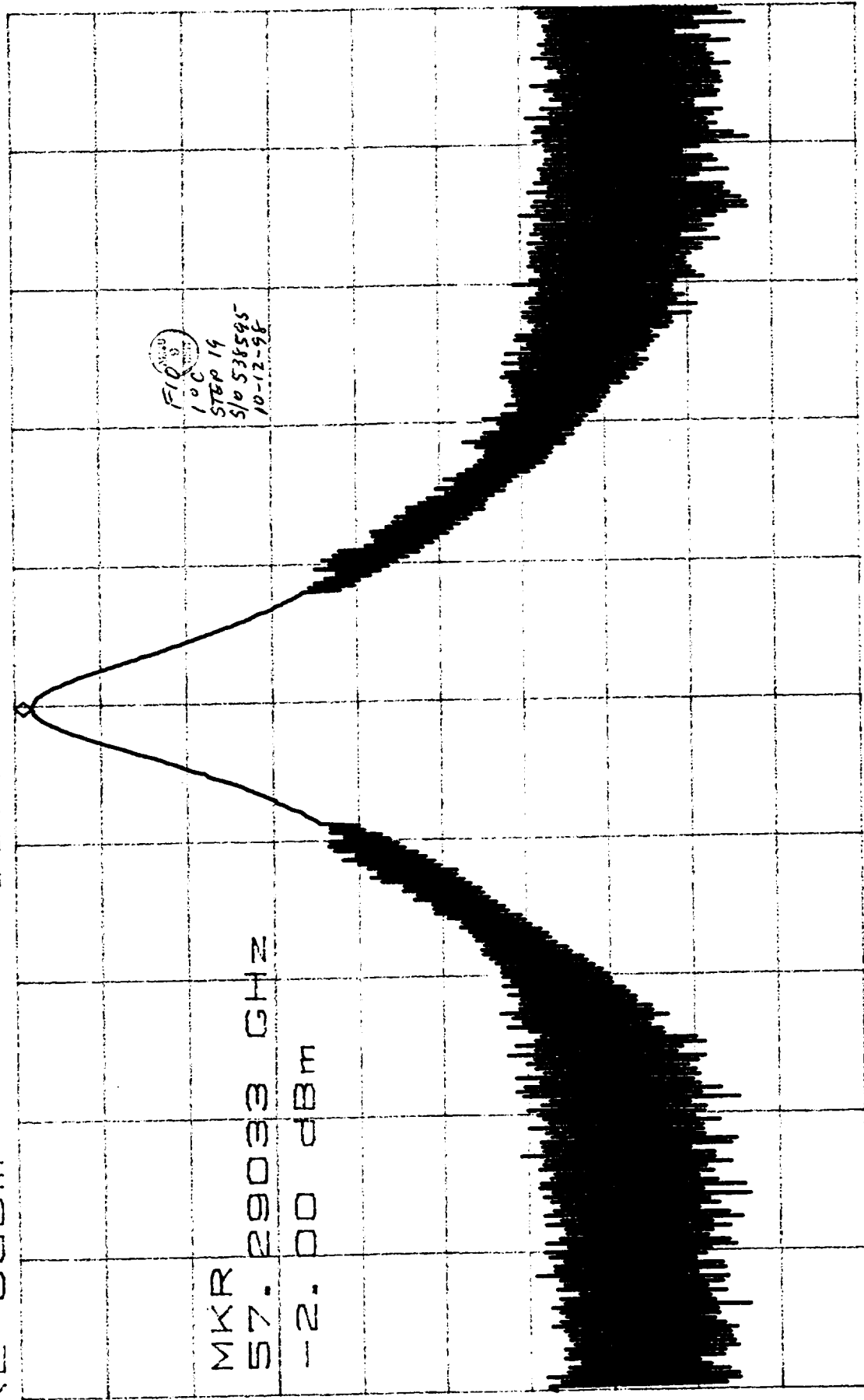
MKR

57.29033 GHz

-2.00 dBm

FIG 10
10C

STEP 14
SLO 538595
10-12-98



CENTER 57.29034GHz

SPAN 10.00MHz

*RBW 300kHz

*VBW 300kHz

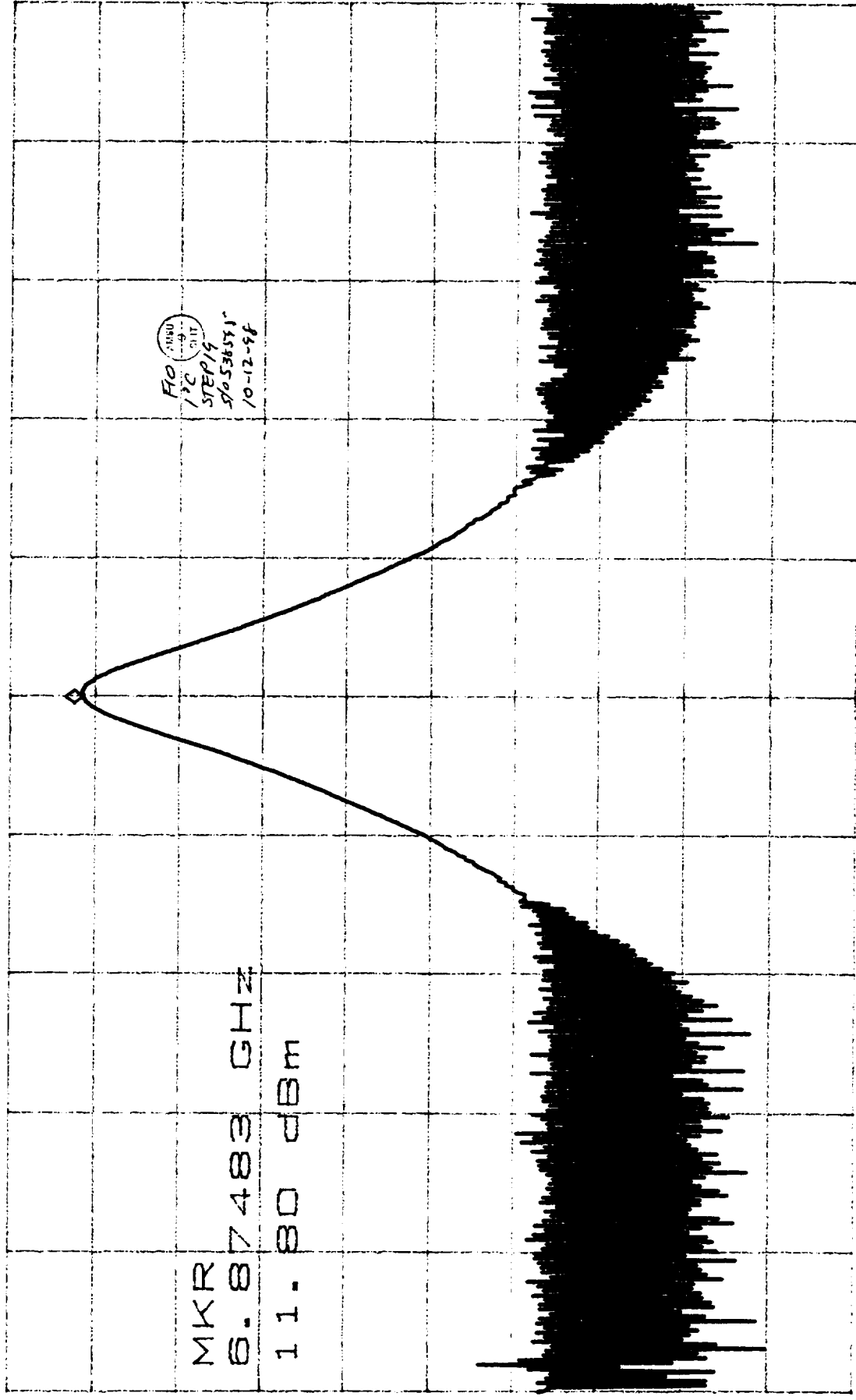
*SWP 50.0ms

ATTEN 40dB
RL 20.3dBm

MKR 11.80dBm
6.87483GHz
10dB/

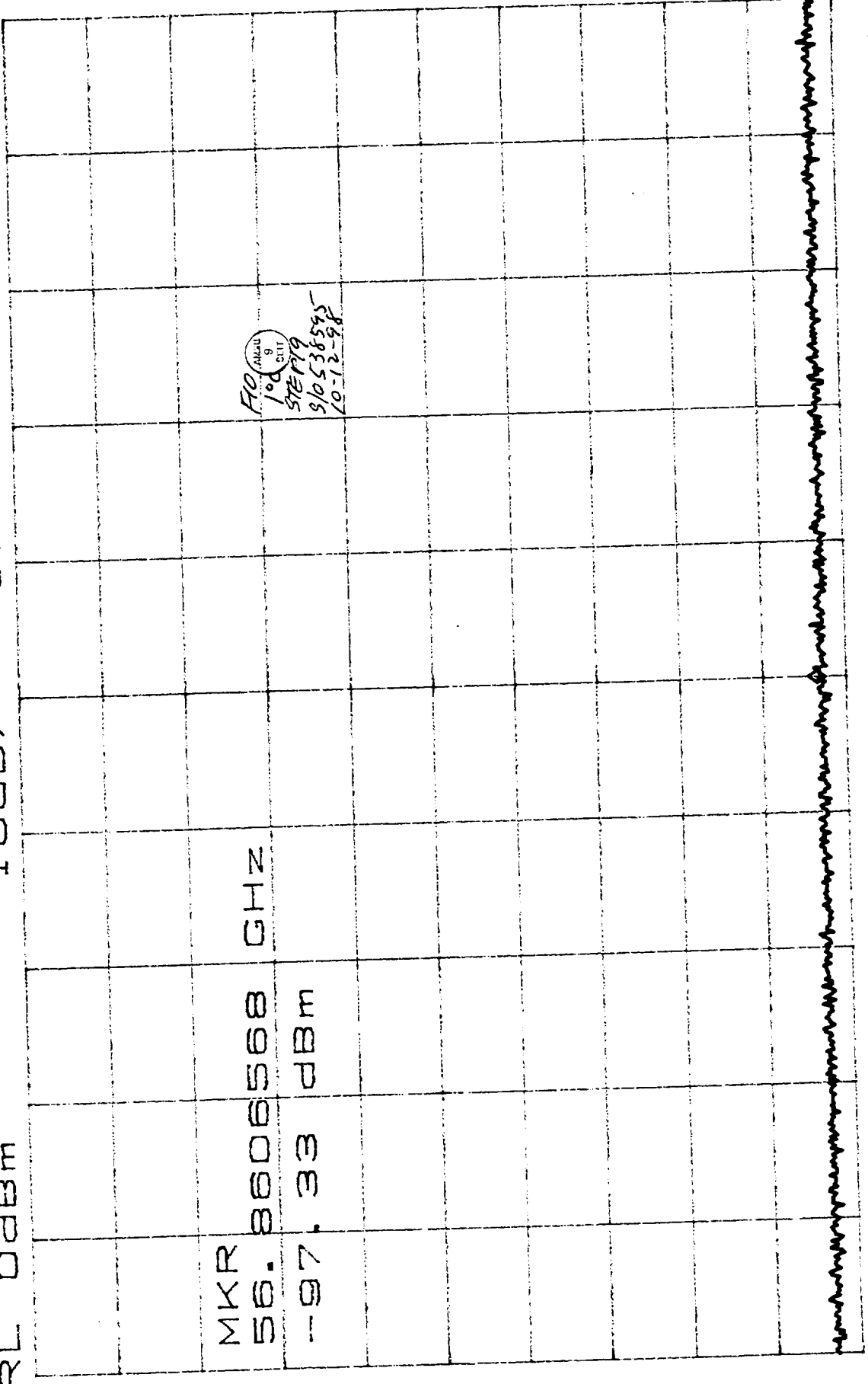
MKR
6.87483 GHz
11.80 dBm

FIG 10-12-98
STEP 19
SP053651
10-12-98



CENTER 6.87483GHz
*RBW 300kHz VBW 300kHz SPAN 10.00MHz
SWP 50.0ms

CL 30.0dB VAVG 26 MKR -97.33dBm
 RL 0dBm 10dB/ 56.8606568GHz



CENTER 56.8606568GHz SPAN 500.0kHz
 *RBW 1.0kHz VBW 1.0kHz SWP 1.30sec

CL 30.0dB

RL 0dBm

VAVG 5

10dB/

MKR -96.67dBm

57.0038826GHz

MKR

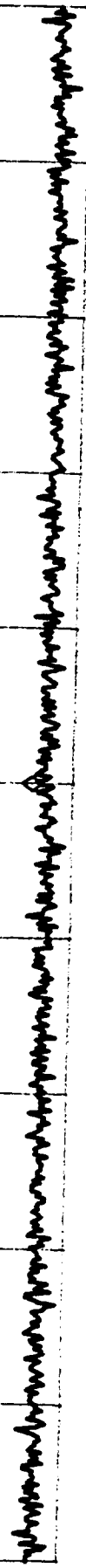
57.0038826

GHz

-96.67

dBm

F10
10C
STEP 9
S/O 53855-
10-12-98



CENTER 57.0038826GHz

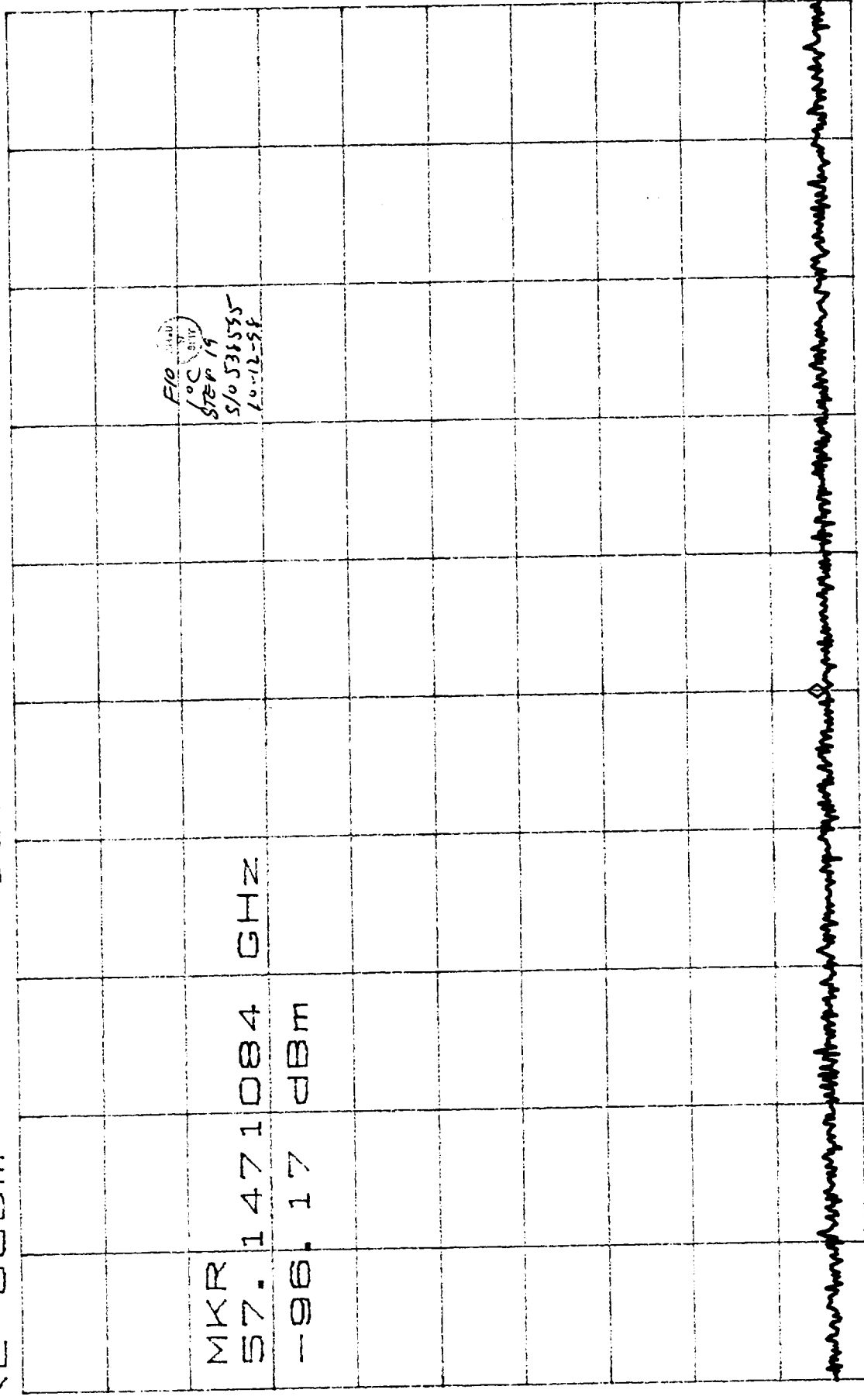
SPAN 500.0kHz

*RBW 1.0kHz

VBW 1.0kHz

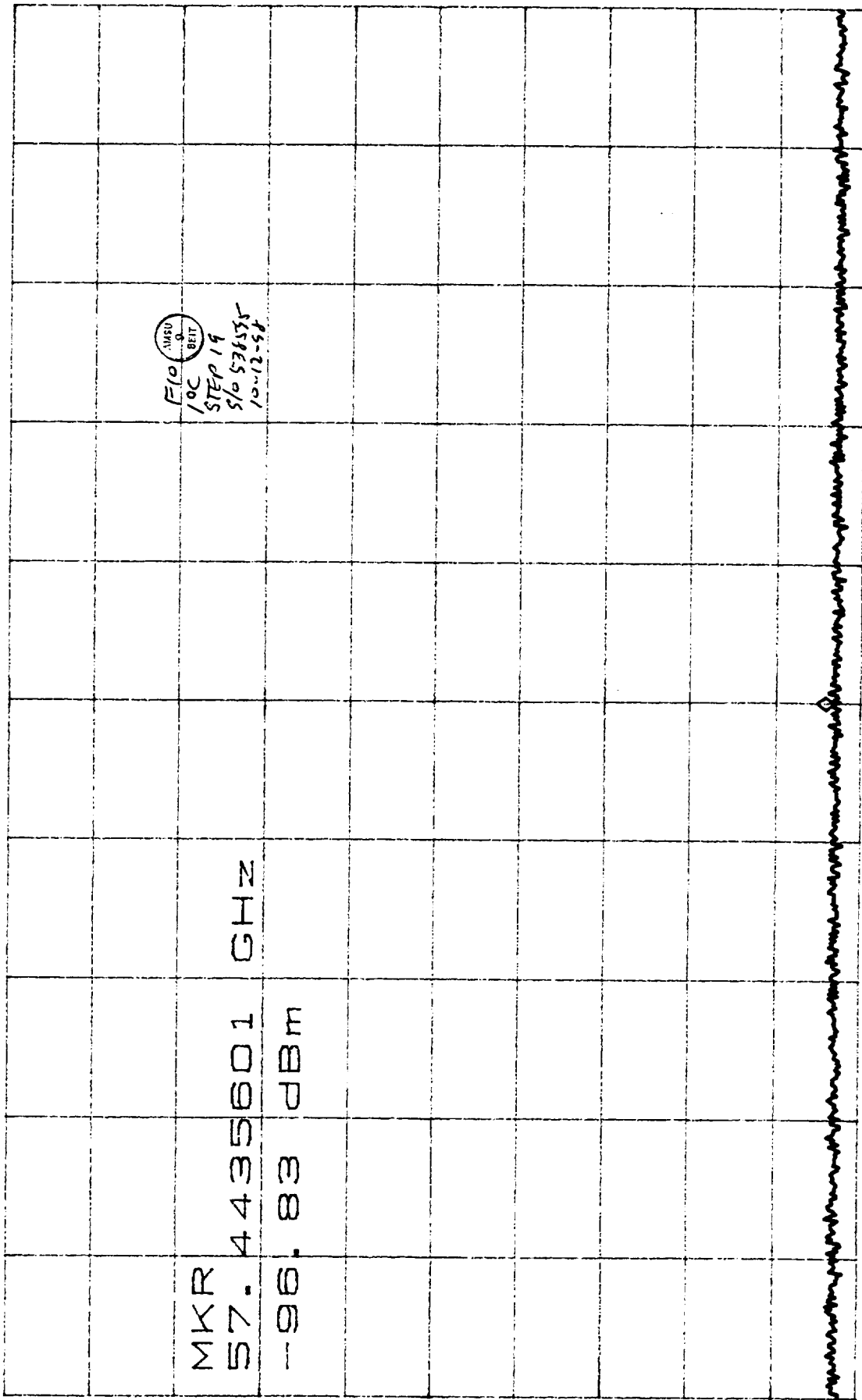
SWP 1.30sec

CL 30.0dB VAVG 6 MKR -96.17dBm
 RL 0dBm 10dB/ 57.1471084GHz



CENTER 57.1471084GHz SPAN 500.0kHz
 *RBW 1.0kHz VBW 1.0kHz SWP 1.30sec

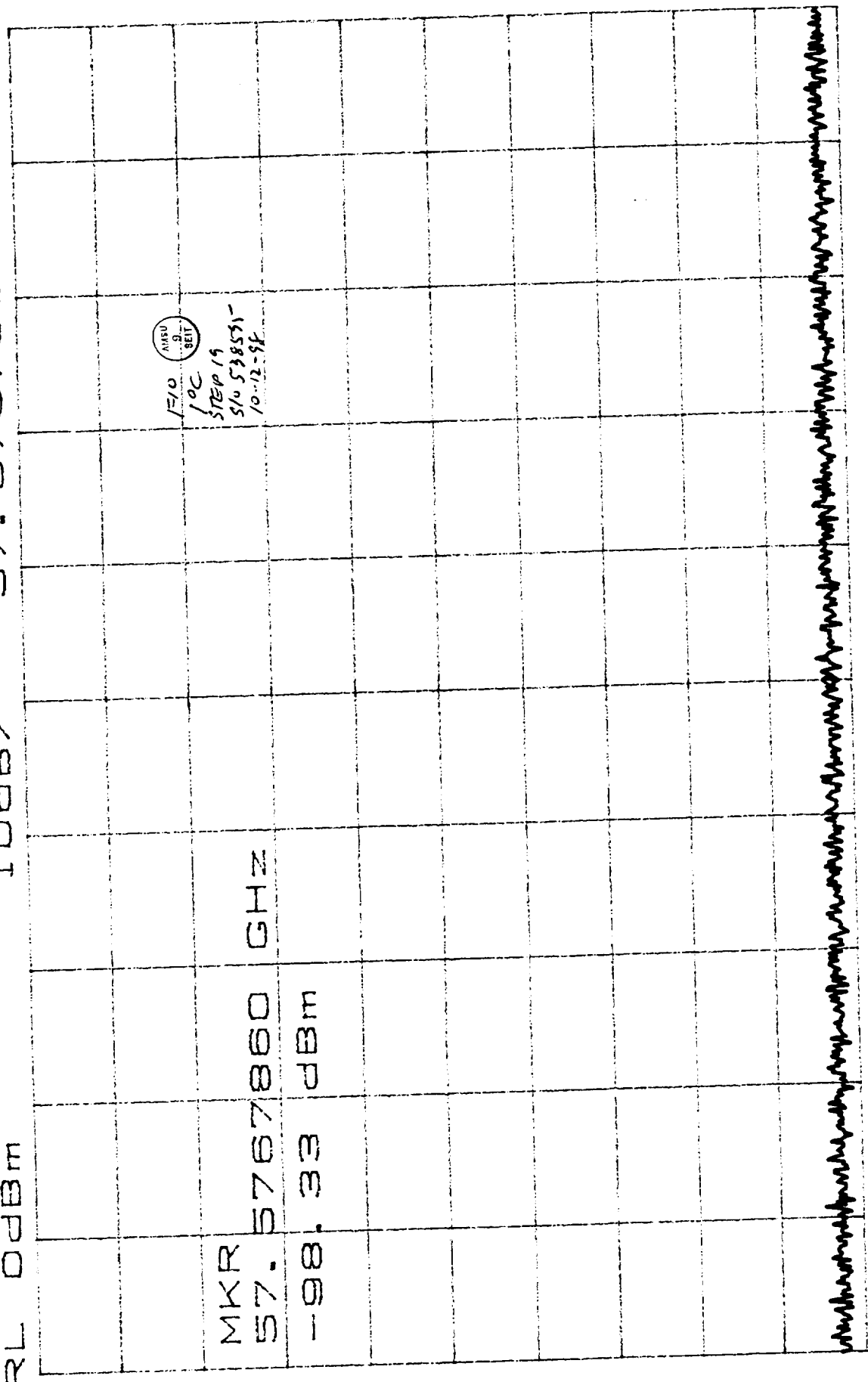
CL 30.0dB VAVG 45 MKR -96.83dBm
 RL 0dBm 10dB/ 57.4435601GHz



D

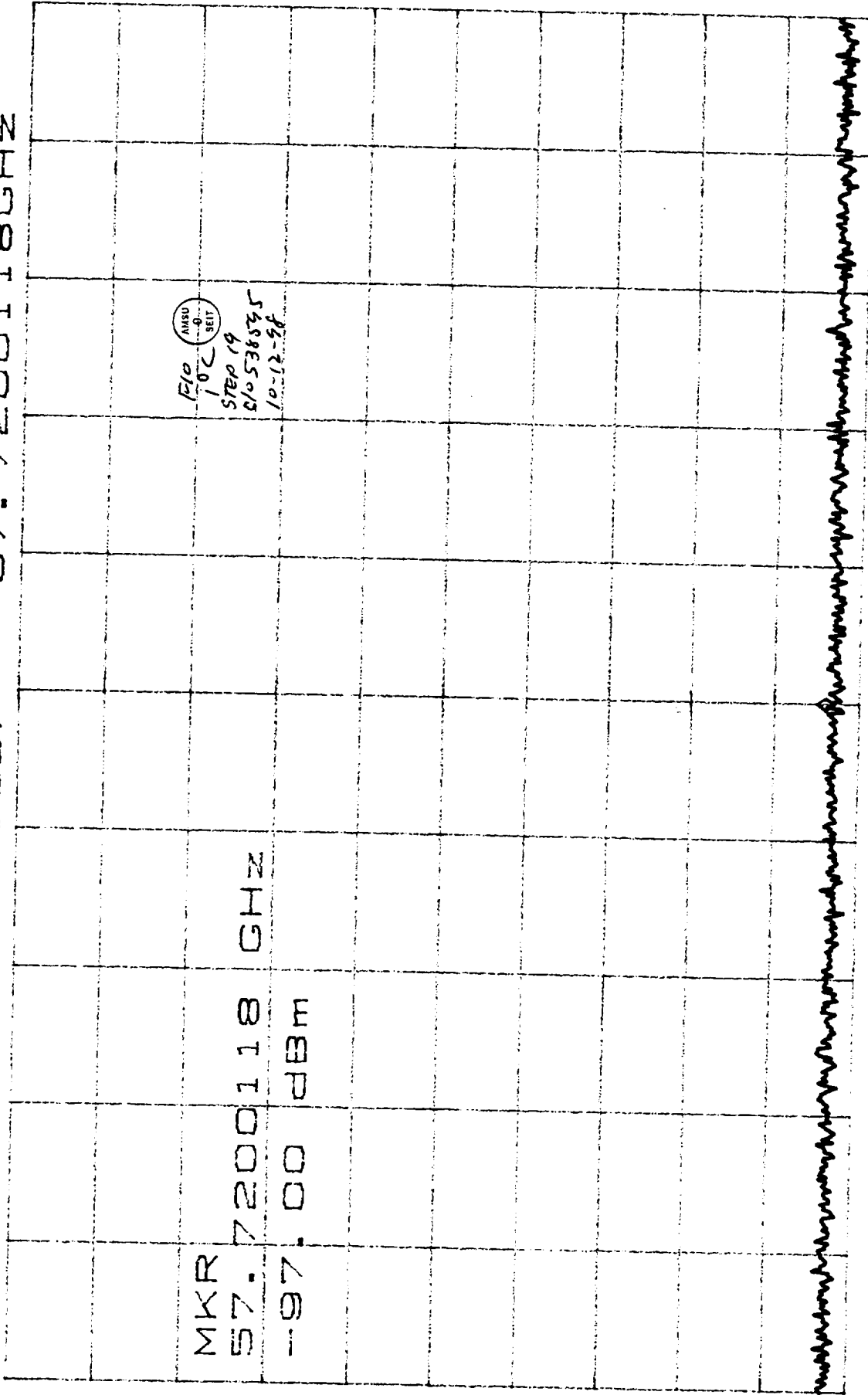
CENTER 57.4435601GHz SPAN 500.0kHz
 *RBW 1.0kHz VBW 1.0kHz SWP 1.30980

CL 30.0dB VAVG 5 MKR -98.33dBm
RL 0dBm 10dB/



CENTER 57.5767860GHZ SPAN 500.0KHZ
*RBW 1.0KHZ VBW 1.0KHZ SWP 1.30SSEC

CL 30.0dB VAVG 8 MKR -97.00dBm
RL 0dBm 10dB/ 57.7200118GHz



D

CENTER 57.7200118GHz

*RBW 1.0KHz VBW 1.0KHz SPAN 500.0KHz
SWP 1.30Sec

CL 30.0dB

RL 0dBm

MKR -55.83dBm

114.5806680GHz

10dB/

MKR

114.5806680 GHz

-55.83 dBm

AMSU
8
SET

F10

10C

STEP 19

SFO 53855

10-12-88

CENTER 114.5806680GHz

*RBW 300Hz

*VBW 1.0KHz

SPAN 100.0KHz

*SWP 2.80660

TEST DATA SHEET 6A (Sheet 2 of 4)
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
14	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	Pass
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290342</u> GHz	
		17 to 20 dBm	P = <u>18.47</u> dBm	
15	Spurious and Sub	-200 to -90 dBc	<u>see plots</u>	
16	Power level of 114.58 GHz signal	<-10 dBm	<u>-56</u> dBm	Pass
17	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>6 Hz</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>.5 dB</u> dB Peak	N/A
18	Operating Temperature @ 1°C baseplate	TC1 = 1 ± 2°C	TC1 = <u>1.0</u>	Pass
			TC2 = <u>2.5</u>	N/A
			TC3 = <u>1.0</u>	N/A
		0 - 1V	DRO L/A = <u>44</u> mV	Pass
		<u>0-1V 4.3-4.7V</u>	PLO L/A = <u>4.54</u> V	Pass
19	Input Voltage and Current			
	VM1 Voltage	+15 ± 0.1 V	VM1 = <u>15.0</u> V	Pass
	VM2 Voltage	-15 ± 0.1 V	VM2 = <u>-15.0</u> V	
	IM1 Current	600 mA max.	IM1 = <u>519</u> mA	
	IM2 Current	100 mA max.	IM2 = <u>-65</u> mA	
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>44</u> mV	
	PLO L/A Voltage	<u>0-1V 4.3-4.7V</u>	PLO L/A = <u>4.54</u> V	
	RF Output Power	17 to 20 dBm	Power = <u>19.36</u> dBm	
	Frequency	57.290344 ± .0002 GHz	Freq. = <u>57.29033424</u> GHz	
	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>15.2</u> V	
		-15.2 ± 0.05 V	-Voltage = <u>-15.2</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290333166</u> GHz	
		17 to 20 dBm	Power = <u>19.35</u> dBm	
	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290333951</u> GHz	
		17 to 20 dBm	Power = <u>19.35</u> dBm	Pass

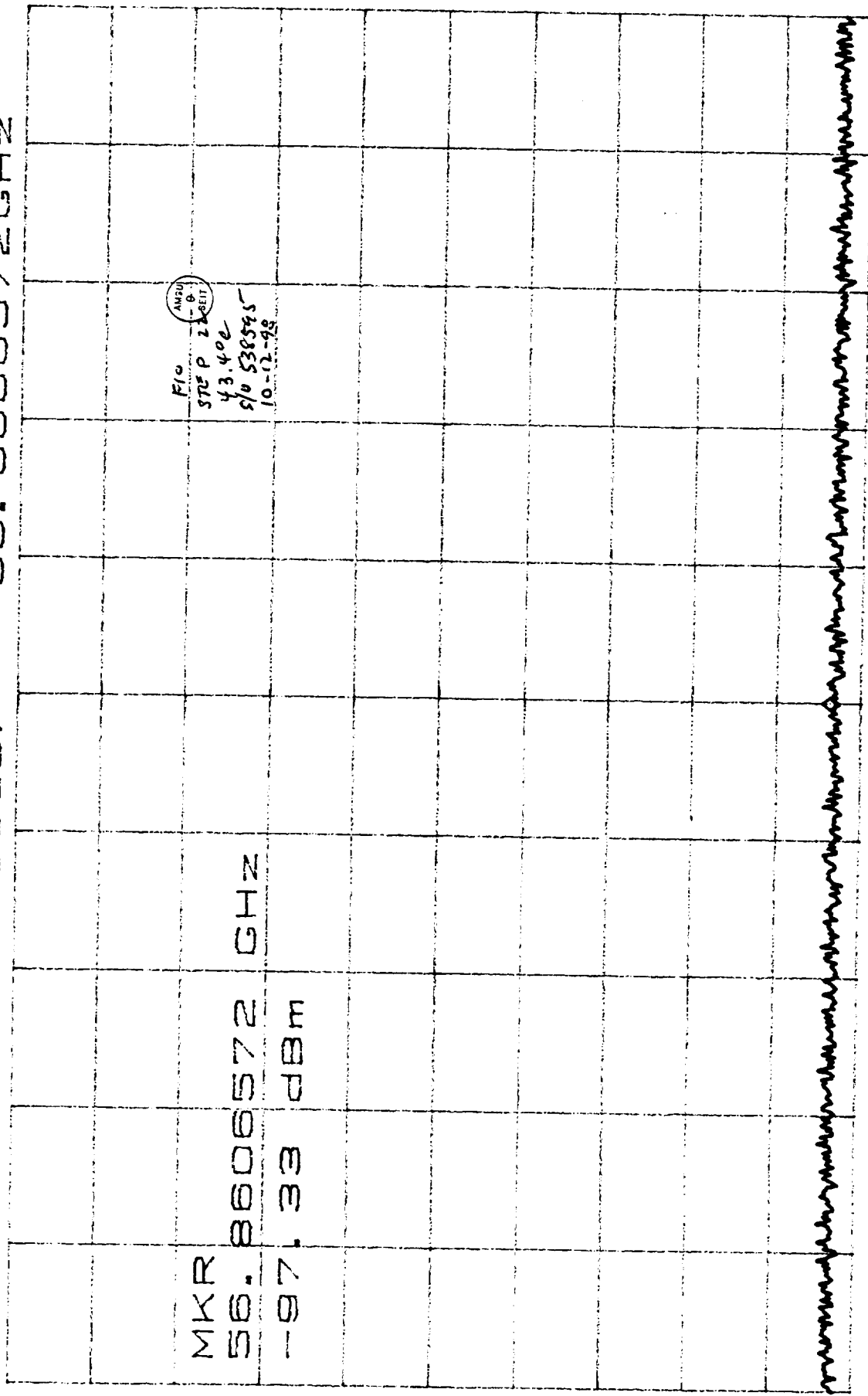
TEST DATA SHEET 6A (Sheet 3 of 4)
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
19 (Cont)	Spurious and Sub	-200 to -90 dBc	<i>see plots</i>	<i>Pass</i>
	Power level of 114.58 GHz signal	<-10 dBm	<i>-55.8</i> dBm	<i>Pass</i>
	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <i>643</i>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <i>138</i> dB	N/A
21	Operating Temperature @ +44°C Baseplate	TC1 = 44 ±2°C	TC1 = <i>43.3</i>	
			TC2 = <i>44.0</i>	N/A
			TC3 = <i>43.0</i>	N/A
		0 - 1V <i>0 to 1V 4.3-4.7V</i>	DRO L/A = <i>111 mV</i> PLO L/A = <i>4.52 V</i>	<i>Pass</i>
22	Input Voltage and Current			
	VM1 Voltage	+15 ± 0.1 V	VM1 = <i>15.0</i> V	
	VM2 Voltage	-15 ± 0.1 V	VM2 = <i>-15.0</i> V	
	IM1 Current	600 mA max.	IM1 = <i>542</i> mA	
	IM2 Current	100 mA max.	IM2 = <i>-68.7</i> mA	
	DRO L/A Voltage	0 to 1V	DRO L/A = <i>111 mV</i>	
	PLO L/A Voltage	<i>0 to 1V 4.3-4.7V</i>	PLO L/A = <i>4.52 V</i>	
	RF Output Power and	17 to 20 dBm	Power = <i>17.54</i> dBm	
	Frequency	57.290344 ± .0002 GHz	Freq. = <i>57.29033903</i> GHz	
	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <i>15.2</i> V	
		-15.2 ± 0.05 V	-Voltage = <i>-15.2</i> V	
		57.290344 ± .0002 GHz	Freq. = <i>57.290334133</i> GHz	
		17 to 20 dBm	Power = <i>17.53</i> dBm	
	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <i>14.8</i> V	
		-14.8 ± 0.05 V	-Voltage = <i>-14.8</i> V	
		57.290344 ± .0002 GHz	Freq. = <i>57.290334156</i> GHz	
		17 to 20 dBm	Power = <i>17.54</i> dBm	<i>Pass</i>

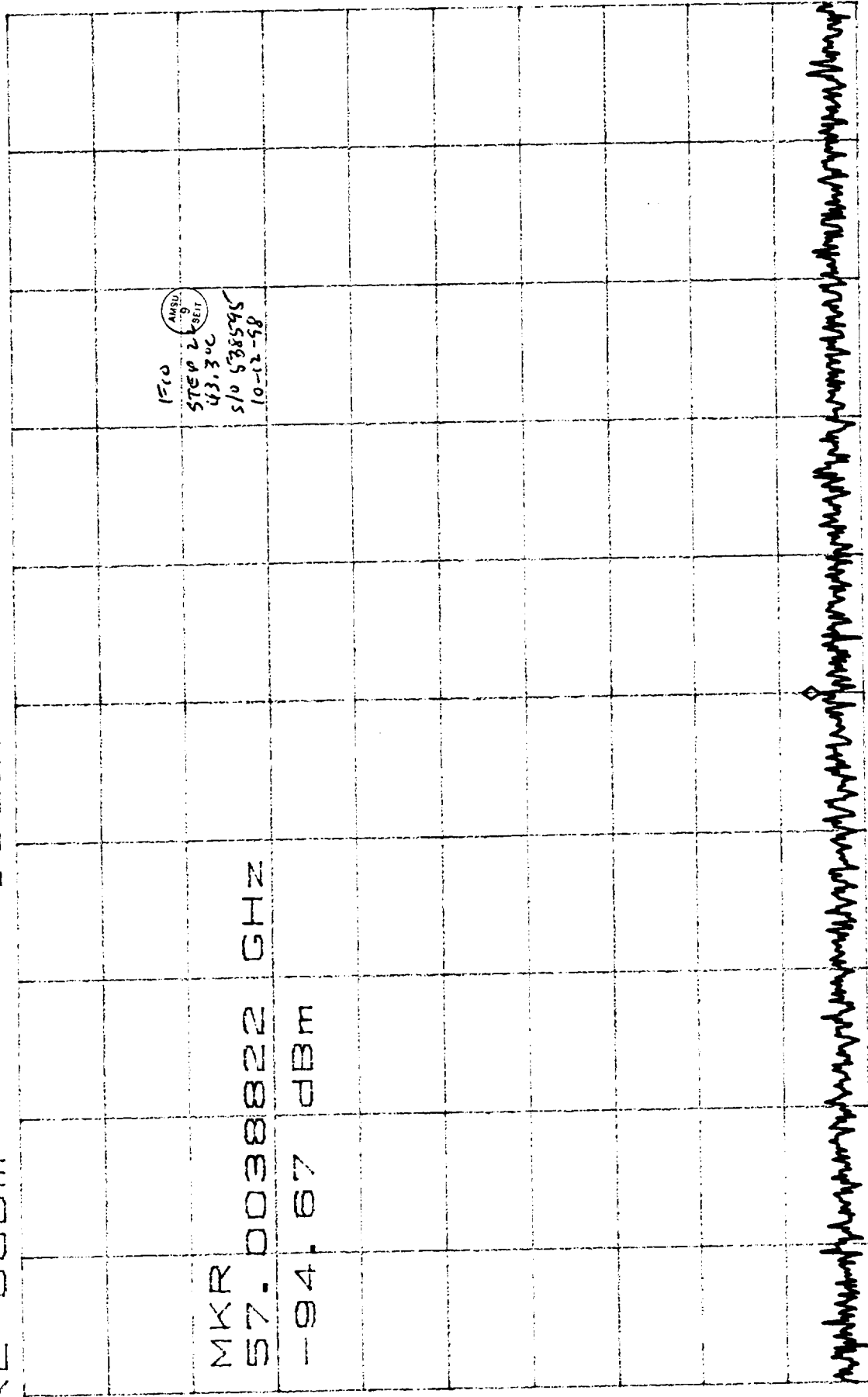
CL 30.0dB VAVG 10 MKR -97.33dBm
 RL 0dBm 10dB/ 56.8606572GHz



D

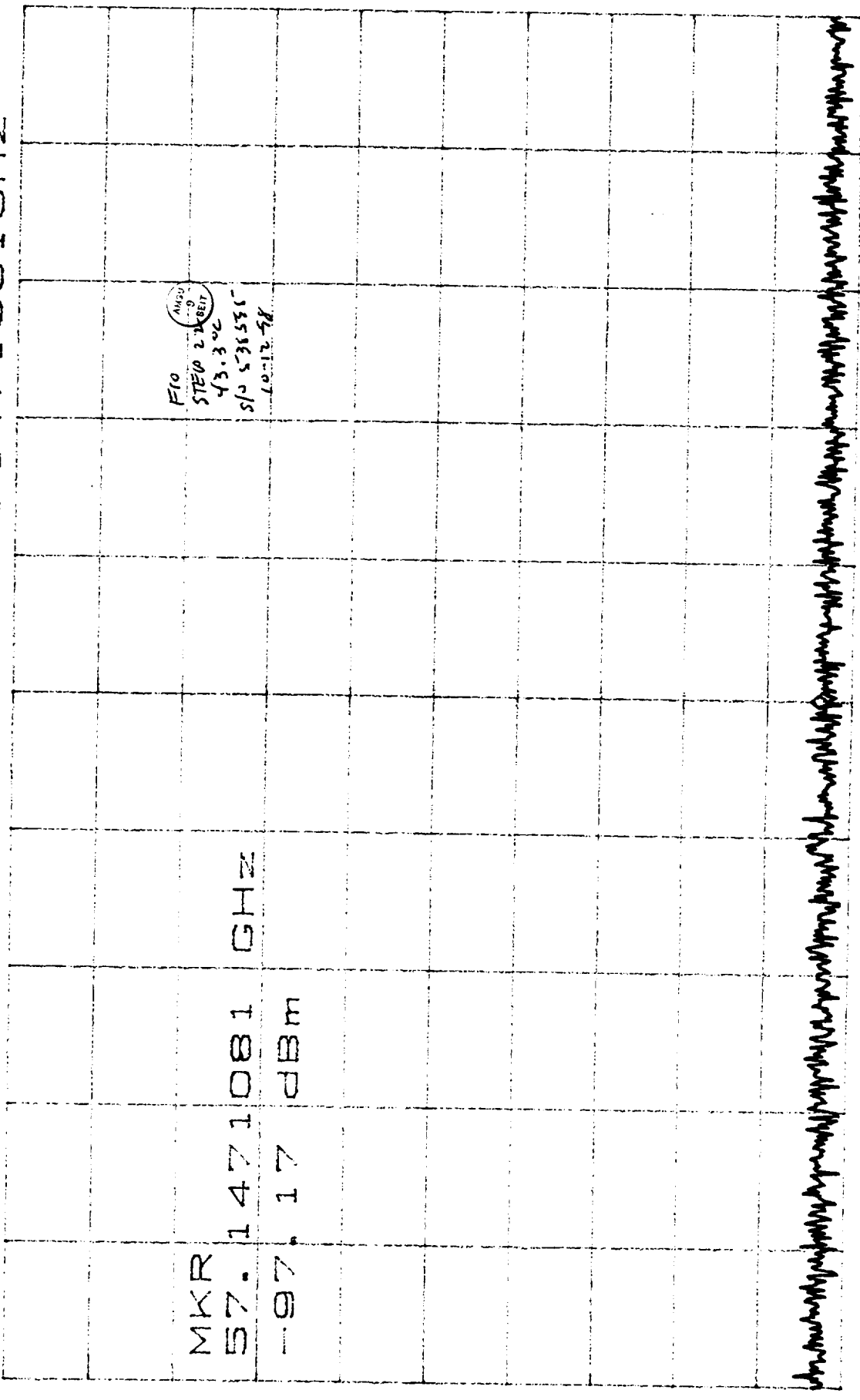
CENTER 56.8606572GHz SPAN 500.0KHz
 *RBW 1.0KHz *VBW 1.0KHz *SWP 1.30sec

CL 30.0dB VAVG 3 MKR -94.67dBm
 RL 0dBm 10dB/ 57.0038822GHz



CENTER 57.0038822GHz SPAN 500.0KHz
 *RBW 1.0KHz *VBW 1.0KHz *SWP 1.30sec

CL 30.0dB VAVG 2 MKR -97.17dBm
RL 0dBm 10dB/ 57.1471081GHz



CENTER 57.1471081GHz SPAN 500.0KHz
*RBW 1.0KHz *VBW 1.0KHz *SWP 1.30S00

CL 30.0dB VAVG 3 MKR -98.17dBm
RL 0dBm 10dB/ 57.4335597GHz

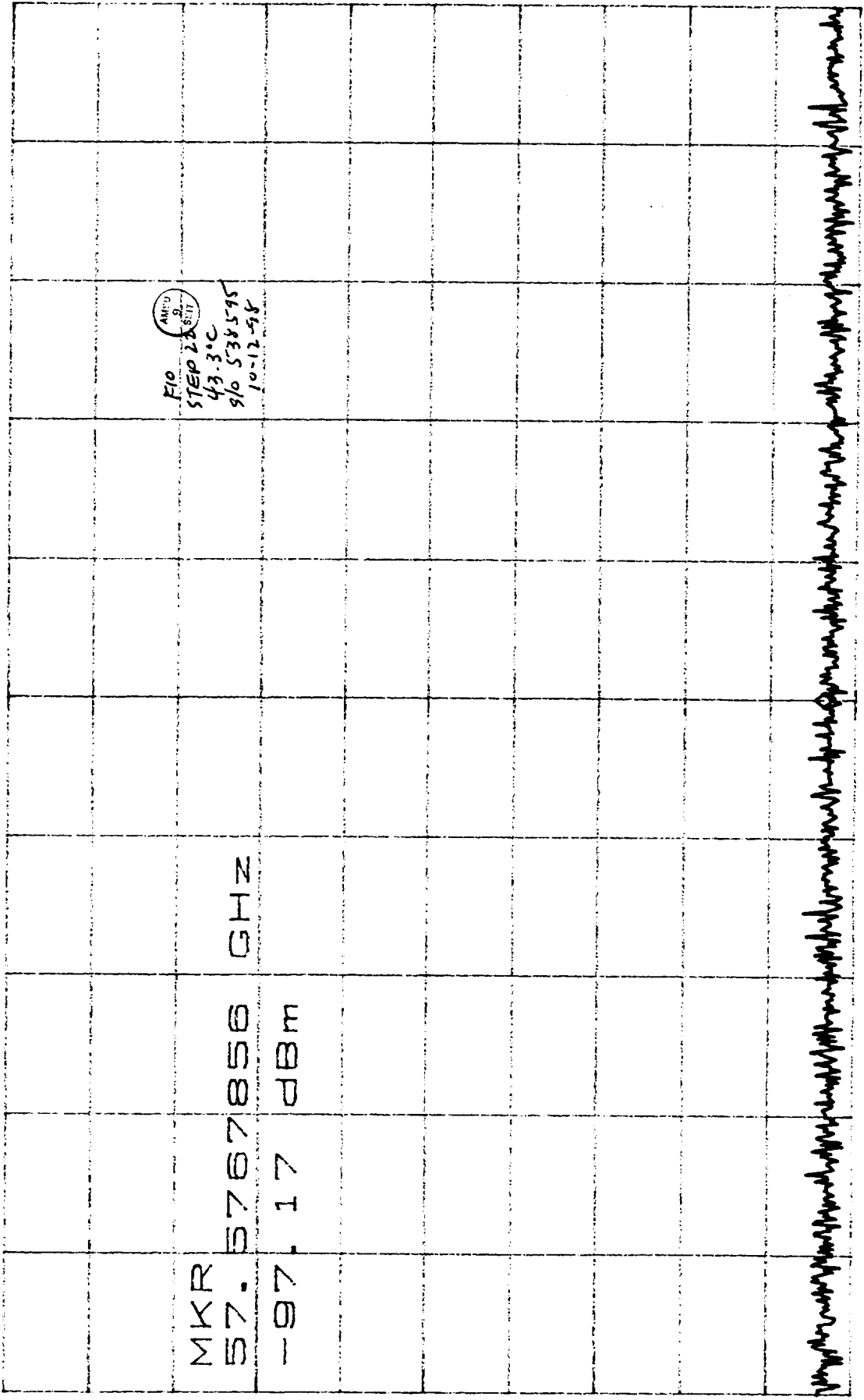
MKR
57.4335597 GHz
-98.17 dBm

F10
43.3°C
510538595
10-12-98

57.4335597GHz

CENTER 57.4335597GHz SPAN 500.0KHz
*RBW 1.0KHz *VBW 1.0KHz *SWP 1.30sec

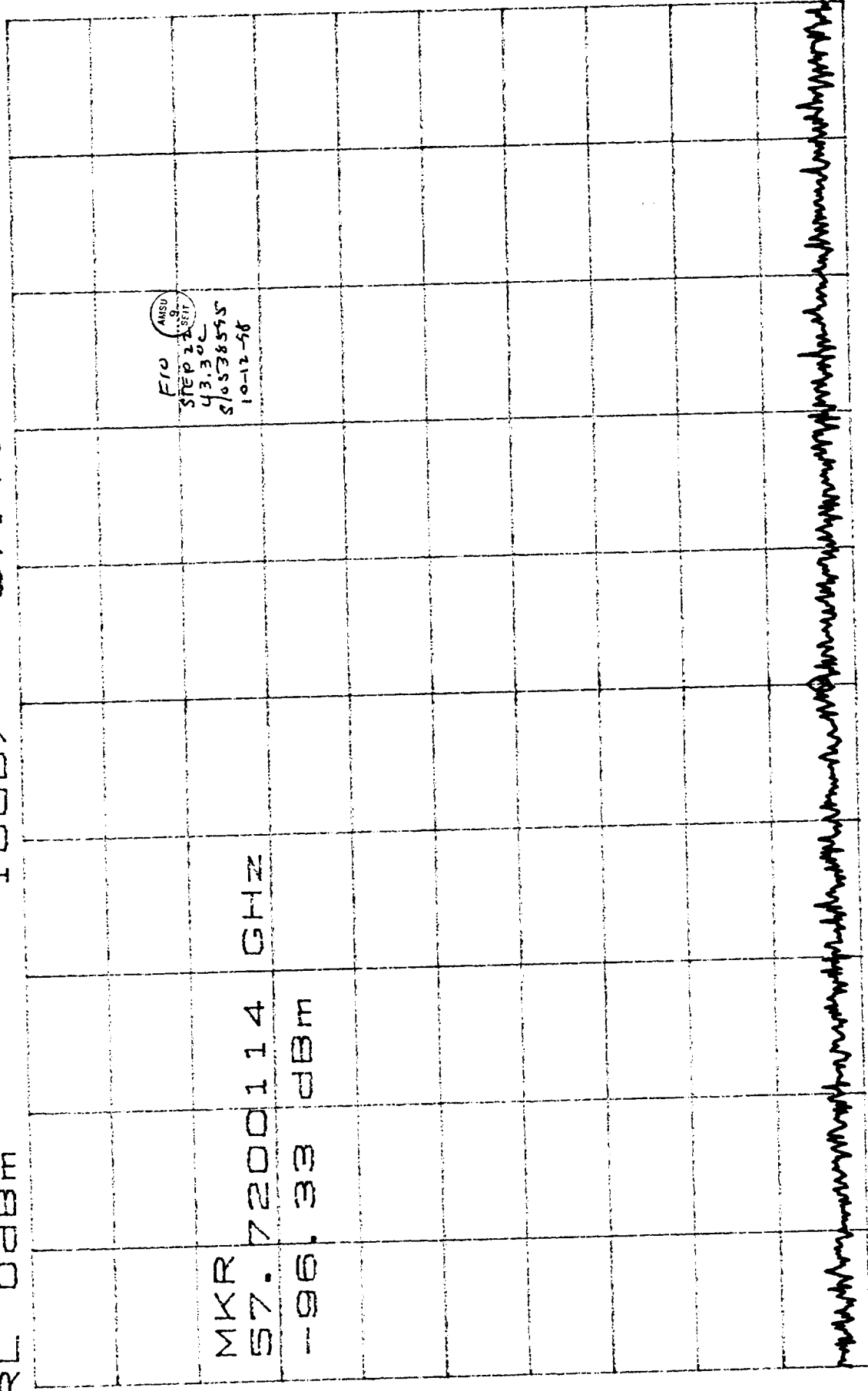
CL 30.0dB VAVG 3 MKR -97.17dBm
RL 0dBm 10dB/ 57.5767856GHz



MKR
57.5767856 GHz
-97.17 dBm

CENTER 57.5767856GHz SPAN 500.0KHz
*RBW 1.0KHz *VBW 1.0KHz *SWP 1.30sec

CL 30.0dB VAVG 4 MKR -96.33dBm
RL 0dBm 10dB/ 57.7200114GHz



D

CENTER 57.7200114GHz SPAN 500.0KHz
*RBW 1.0KHz *VBW 1.0KHz *SWP 1.30sec

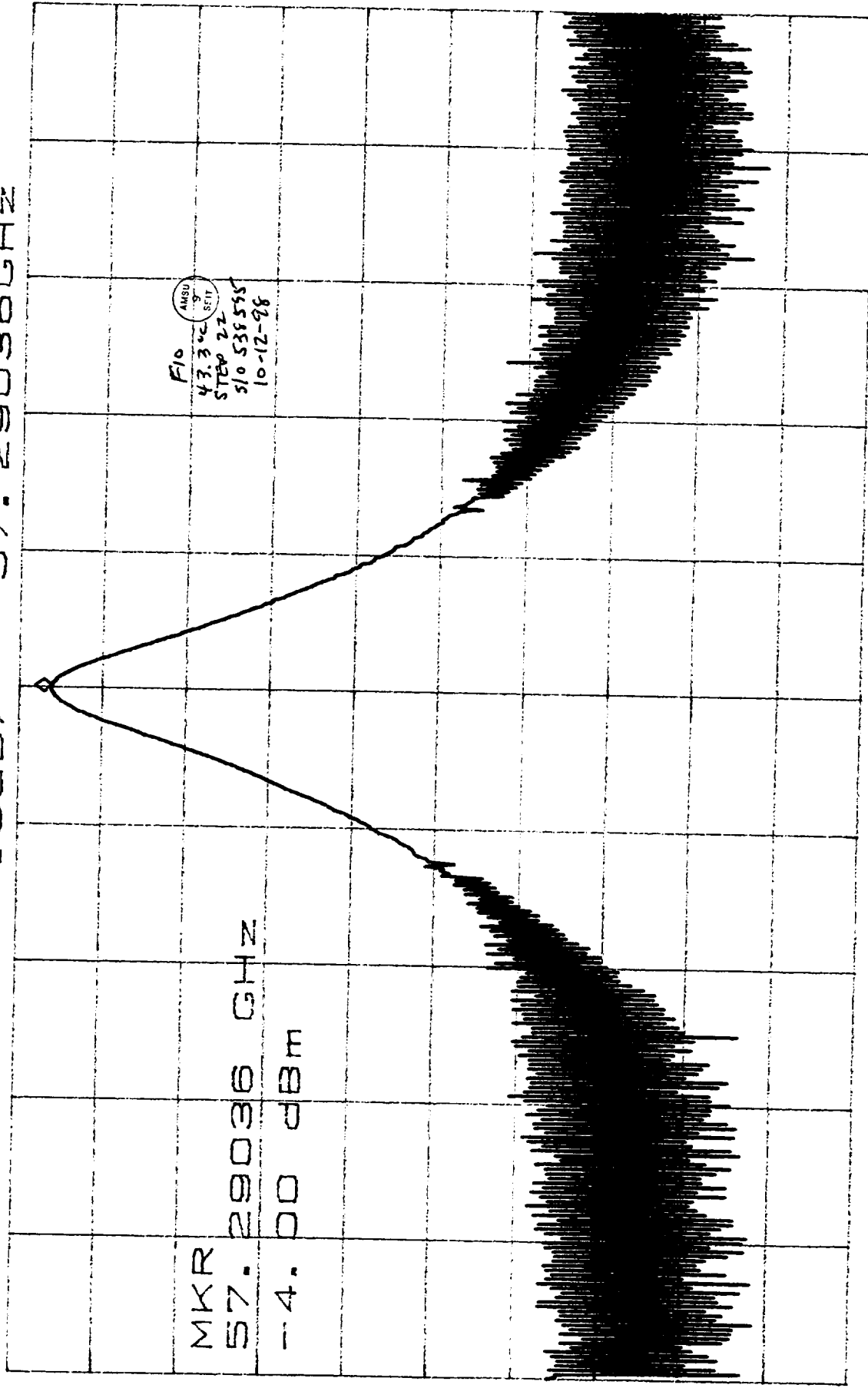
CL 30.0dB
RL 0dB

MKR -4.00dBm
57.29036GHz

10dB/

MKR
57.29036 GHz
-4.00 dBm

F10
43.3°C
STEP 22
S10 53555
10-12-98



CENTER 57.29036GHz

SPAN 10.00MHz
*SWP 50.0ms

*RBW 300kHz *VBW 300kHz

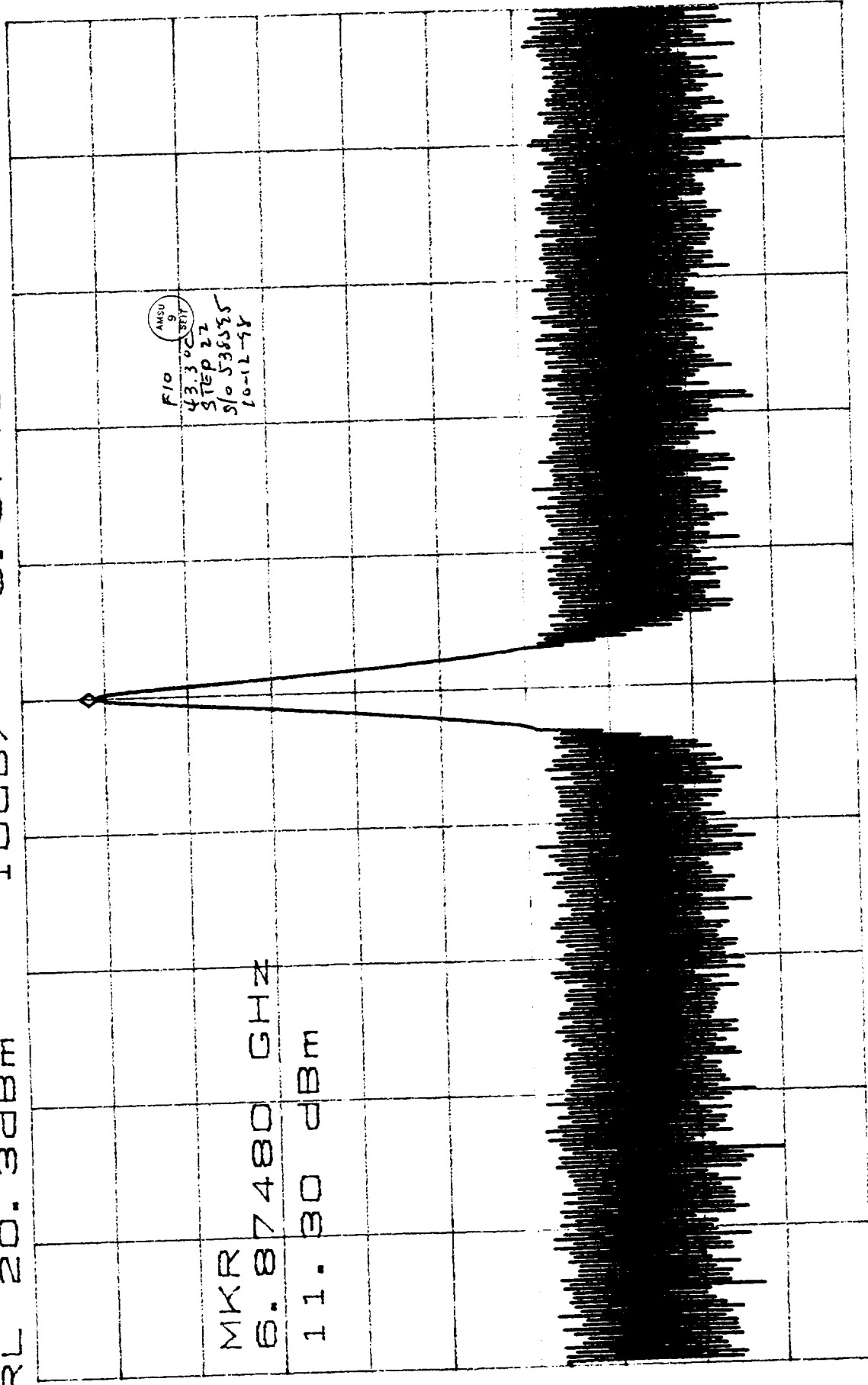
MKR 11.30dBm
6.87480GHZ

ATTEN 40dB
RL 20.3dBm

10dB/

MKR 6.87480 GHZ
11.30 dBm

F10
43.300
STEP 22
S/O 53835
10-12-98



CENTER 6.87480GHZ SPAN 50.00MHZ
*RBW 300KHZ VBW 300KHZ SWP 50.0ms

CL 30.0dB

RL 0dBm

MKR -47.33dBm

114.580673GHz

10dB/

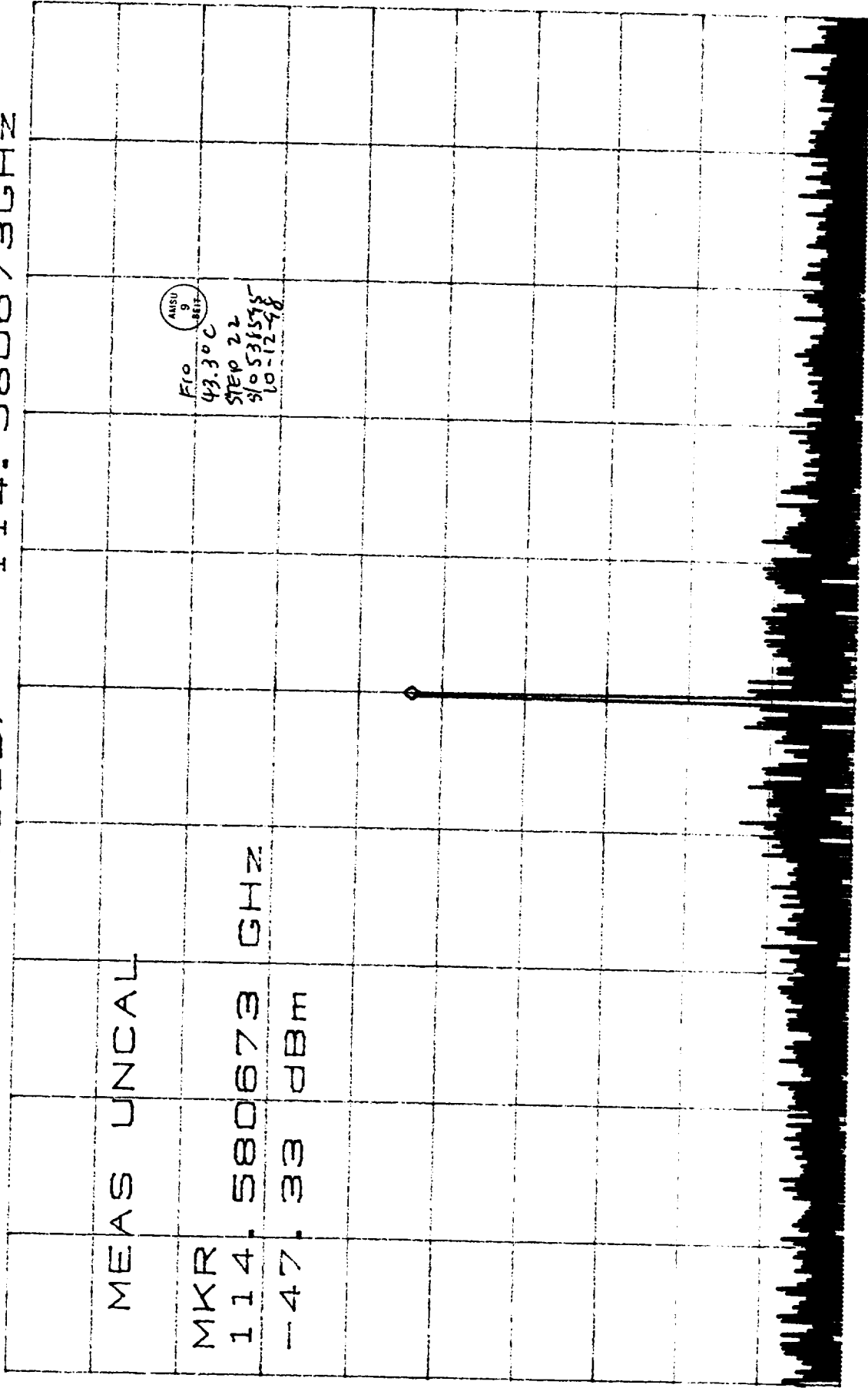
MEAS UNCAL

MKR

114.580673 GHz

-47.33 dBm

ANSU
9
BIT
Fro
43.30C
STEP 22
9/0538575
10-12-98



CENTER 114.580673GHz

*RBW 300Hz

*VBW 1.0KHz

SPAN 1.000MHz

*SWP 2.80Sec

TEST DATA SHEET 6A (Sheet 4 of 4)
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
22 (Cont)	Spurious and Sub	-200 to -90 dBc	<i>see plot 5</i>	<i>Pass</i>
	Power level of 114.58 GHz signal	<-10 dBm	<i>-47</i> dBm	<i>Pass</i>
	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <i>574</i>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <i>.4</i> dB	N/A

Shop Order No.: 538595
Operation: 0110
Unit Serial No.: F10
Date: 10-12-98

Test Engineer: _____
Quality Control: 7A 692 OCT 13 '98
Govt. Rep.: R. D. Brown 10/23/98

Section 2A: Acceptance Level Vibration - F09

This section includes the data from the limited functional tests which take place before and throughout vibration, and the vibration-specific. The following table summarizes the results of the limited functional test.

Test	Expected Value	Post X axis	Post Y axis	Post Z axis
Output Frequency	57290344 \pm 200 kHz	57290328 kHz	57290329 kHz	57290329 kHz
Output Power	18.5 dBm \pm 1.5 dB	18.1 dBm	18.0 dBm	18.0 dBm

The following pages contain the raw data.

TEST DATA SHEET 8B
Limited Functional Test (Paragraph 4.2.3)

Post X-Axis LPT

Test Setup Verified: *[Signature]*
Signature

Paragraph 4.2.3.2:

Step	Test		Required	Measurement	Pass/Fail
3	Potential Difference				
	From	To			
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	0.6 Vac	P
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	0.5 Vac	P

Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	+15.00 V	PASS
	Voltage Meter 2	-15 ± 0.1 V	-15.03 V	PASS
	Current Meter 1	600 mA max.	521 mA	PASS
	Current Meter 2	100 mA max.	64 mA	PASS
9	Output Frequency	57.290344 ± .0001 GHz	57.290328 GHz	PASS
10	Output Power	18.5 dBm ± 1.5 dB	18.07 dBm	PASS

* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

Shop Order No.: 538596
Operation: 0150
Unit Serial No.: F09
Date: 11/12/98

Test Engineer: *[Signature]*
Quality Control: *[Signature]* (7A 197) 11/12/98
Govt. Rep.: *[Signature]* 11-12-98

22 Oct 98

TEST DATA SHEET 8C
Limited Functional Test (Paragraph 4.2.3)

Post Y-Axis LPT

Test Setup Verified: *[Signature]*
 Signature

Paragraph 4.2.3.2:

Step	Test	Required	Measurement	Pass/Fail
3	Potential Difference			
	From	To		
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	0.5 Vac
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	0.6 Vac

Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.00 V	P
	Voltage Meter 2	-15 ± 0.1 V	-15.03 V	P
	Current Meter 1	600 mA max.	522 mA	P
	Current Meter 2	100 mA max.	64 mA	P
9	Output Frequency	57.290344 ± .0001 GHz	57.290329	P
10	Output Power	18.5 dBm ± 1.5 dB	18.02	P

* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

Shop Order No.: 538596
 Operation: 0150
 Unit Serial No.: FC9
 Date: 11/12/98

Test Engineer: *[Signature]*
 Quality Control: *[Signature]* 7A 197 11/12/98
 Govt. Rep.: *[Signature]* 11-12-98

TEST DATA SHEET 8D
Limited Functional Test (Paragraph 4.2.3)

Post Z-Axis LPT

Test Setup Verified: *[Signature]*
Signature

Paragraph 4.2.3.2:

Step	Test	Required	Measurement	Pass/Fail
3	Potential Difference			
	From	To		
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	0.5 Vac P
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	0.5 Vac P

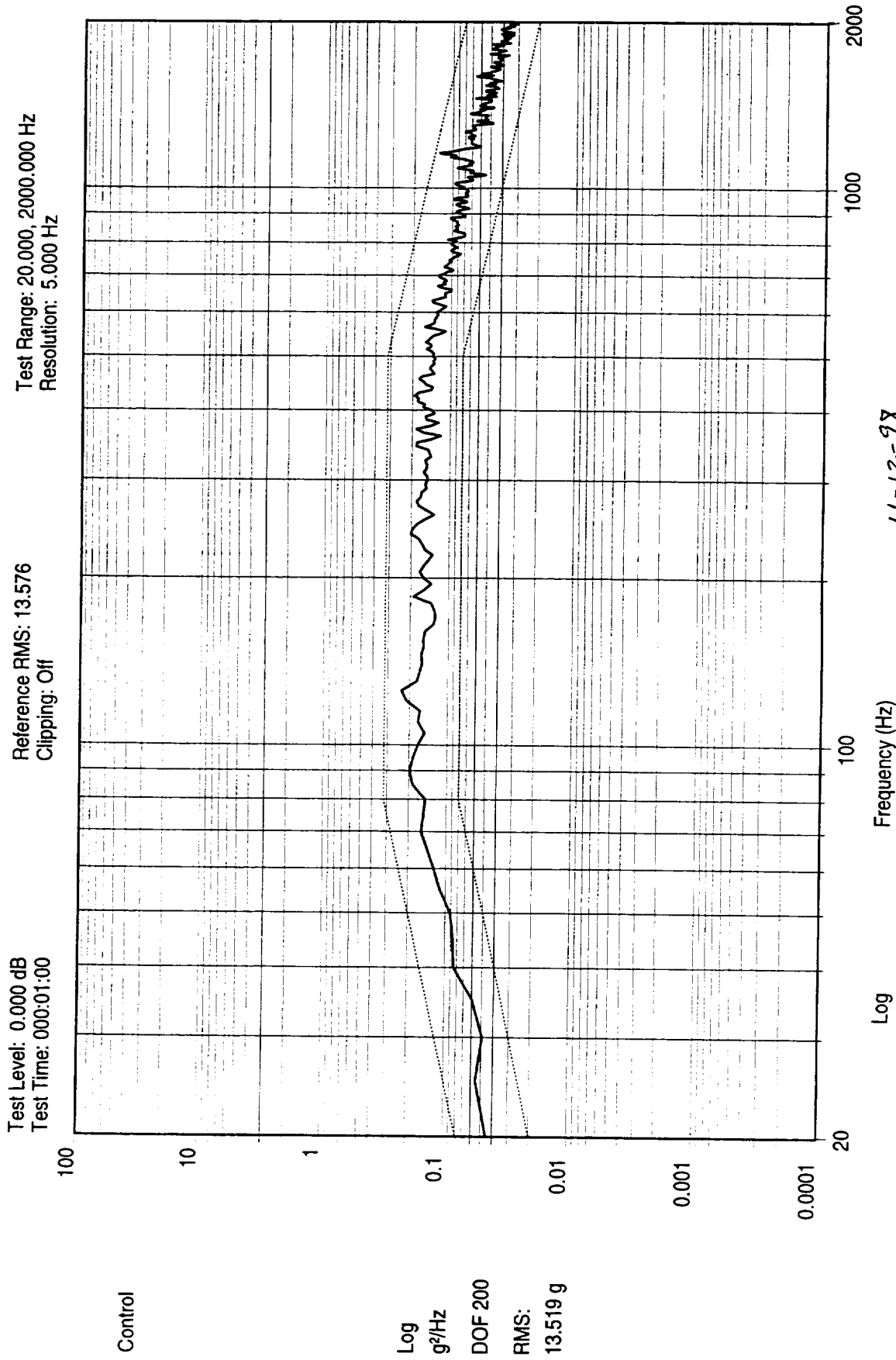
Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.00 V	P
	Voltage Meter 2	-15 ± 0.1 V	-15.02 V	P
	Current Meter 1	600 mA max.	522 mA	P
	Current Meter 2	100 mA max.	-64 mA	P
9	Output Frequency	57.290344 ± .0001 GHz	57.290329	P
10	Output Power	18.5 dBm ± 1.5 dB	18.0	P

* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

Shop Order No.: 538596
Operation: 0150
Unit Serial No.: F09
Date: 11/12/98

11/12/98

Test Engineer: *[Signature]*
Quality Control: *[Signature]* 7A 197 11/12/98
Govt. Rep.: *[Signature]* 11-12-98

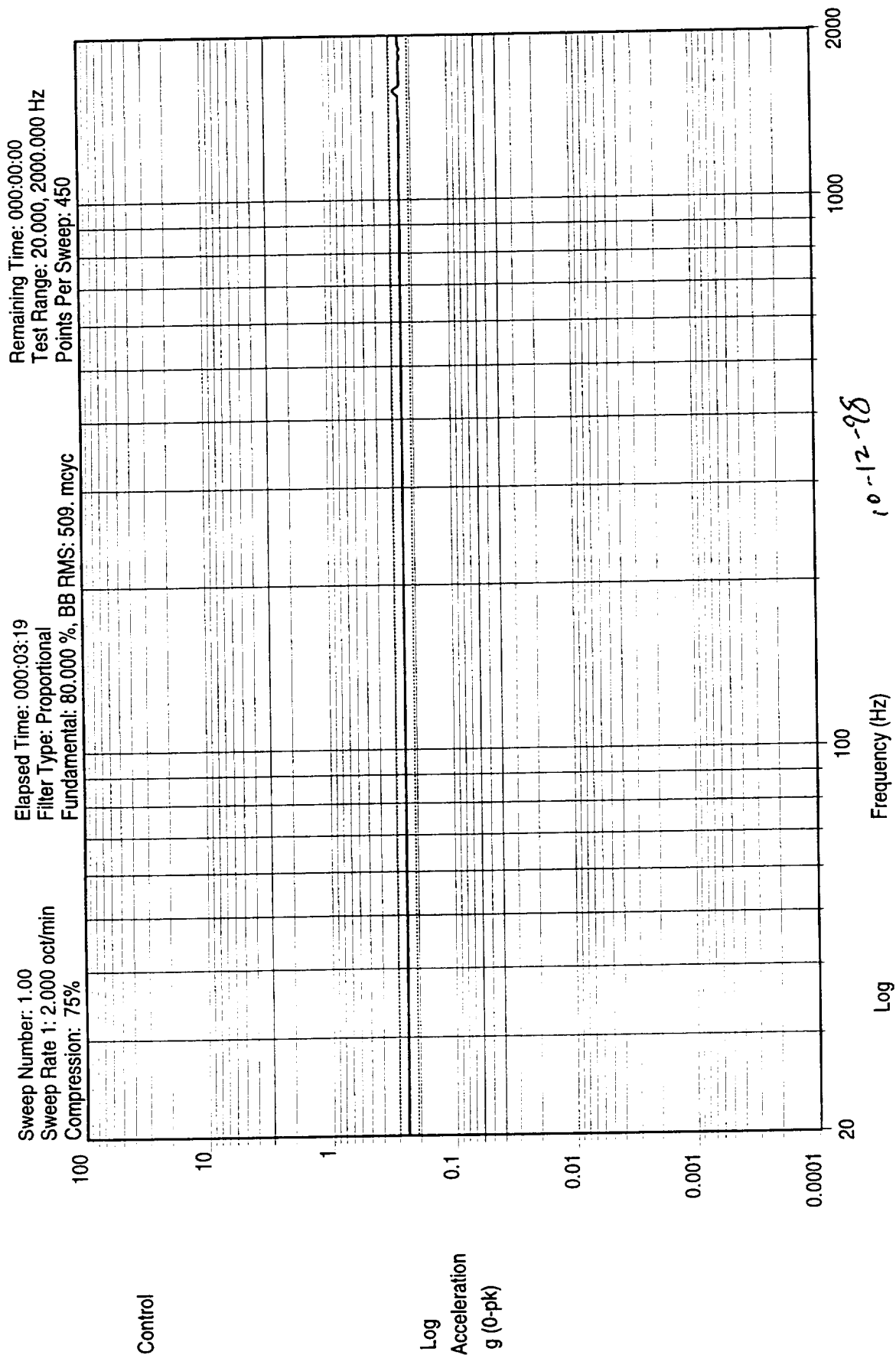


11:34:21
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538596-F09
X AXIS SYSTEM CHECKOUT P/N 1348360-1 S/N F09
Test Name: PLO.tmp

ENG 217
7A 267

11-12-98



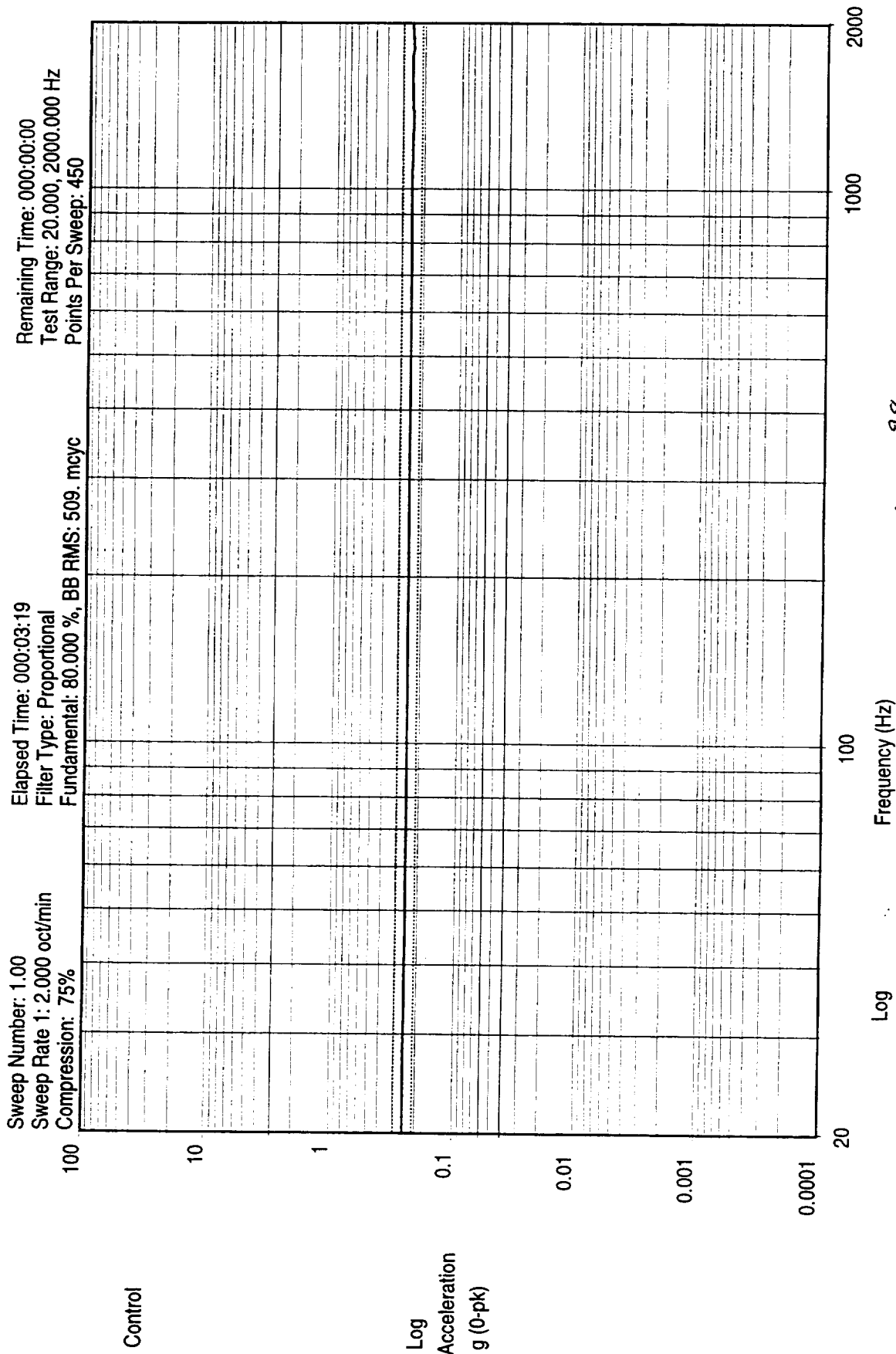
ENG 217

7A 267

11:51:43
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09
X AXIS CHECKOUT P/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

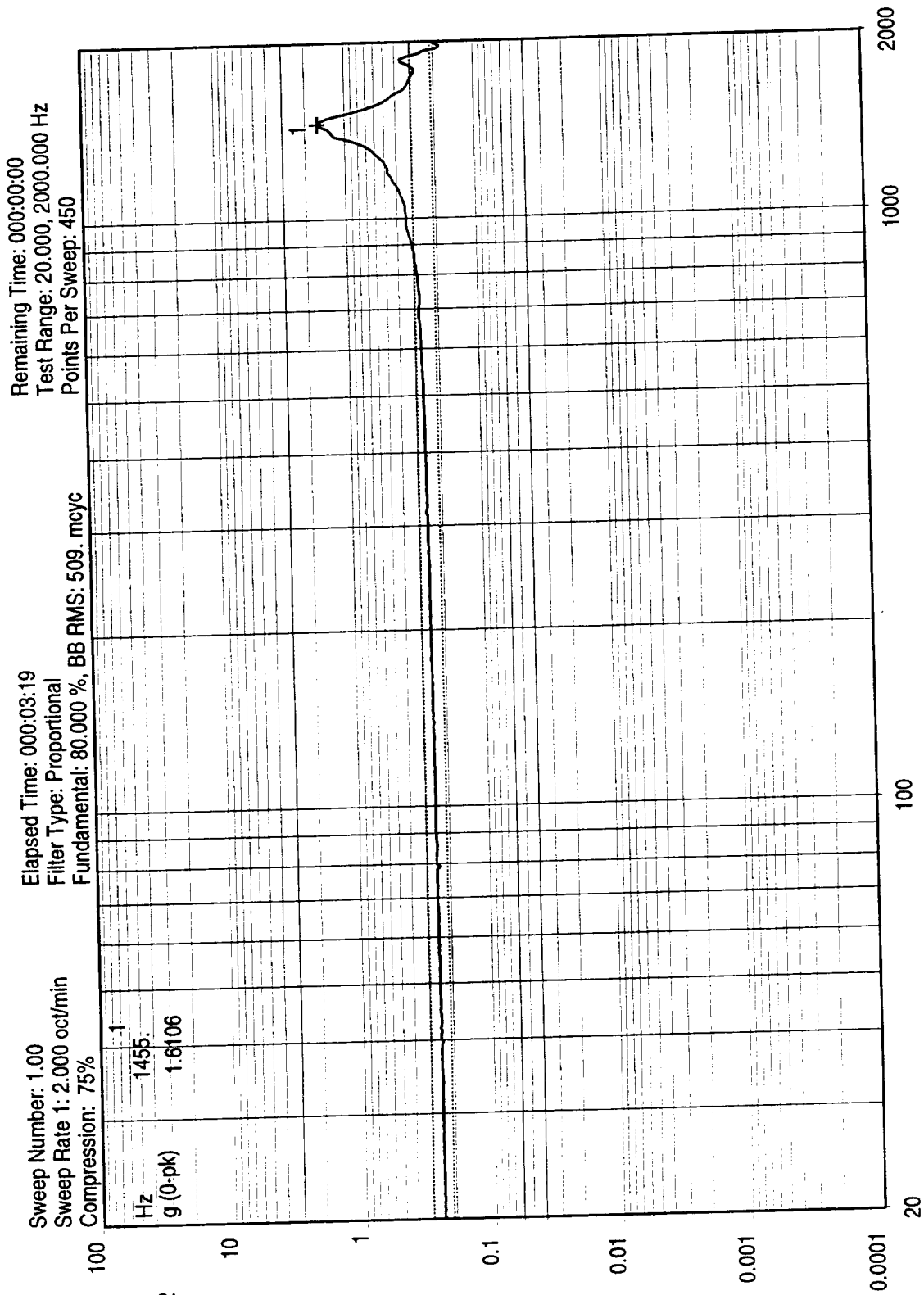


10-12-98



AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
X AXIS PRE SINE SWEEP/N 1348360-1 S/N F09
Sine Test Name: PLO.tmp

14:04:14
12-Nov-1998



UNIT X

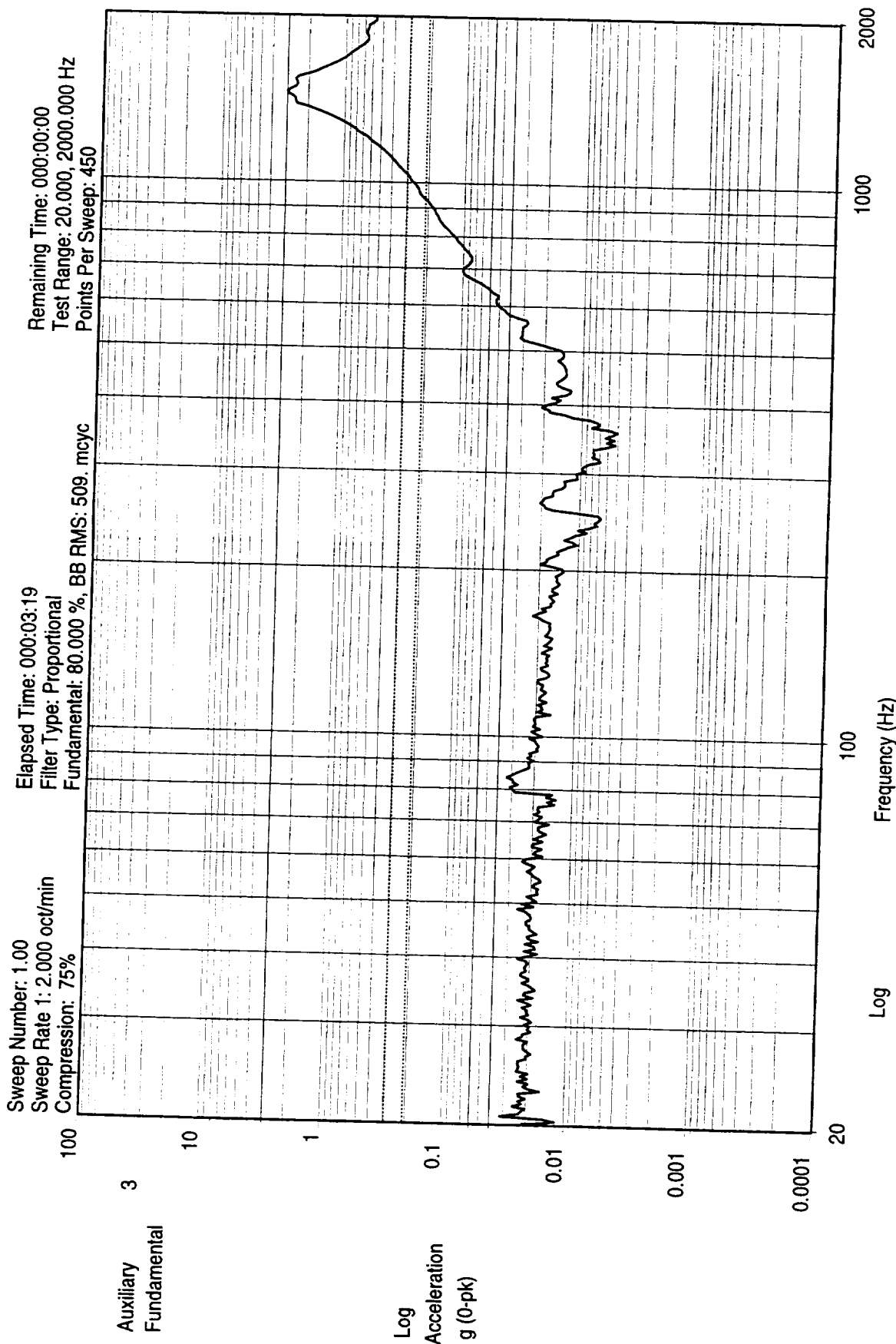
11-12-98



AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 X AXIS PRE SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

14:04:22
 12-Nov-1998



14:04:28
 12-Nov-1998

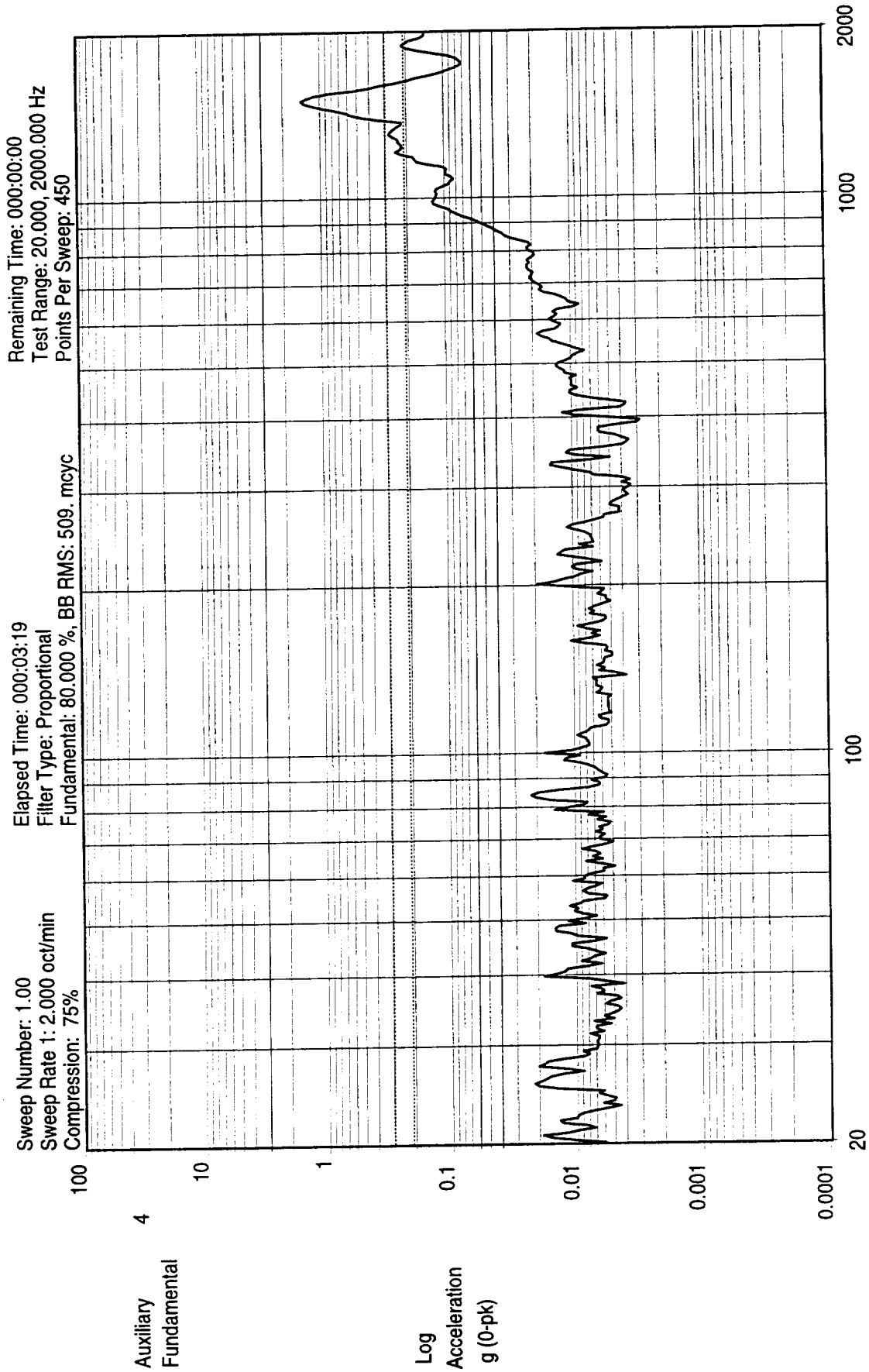
AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 X AXIS PRE SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

11-12-98

UNIT Z





UNIT Y

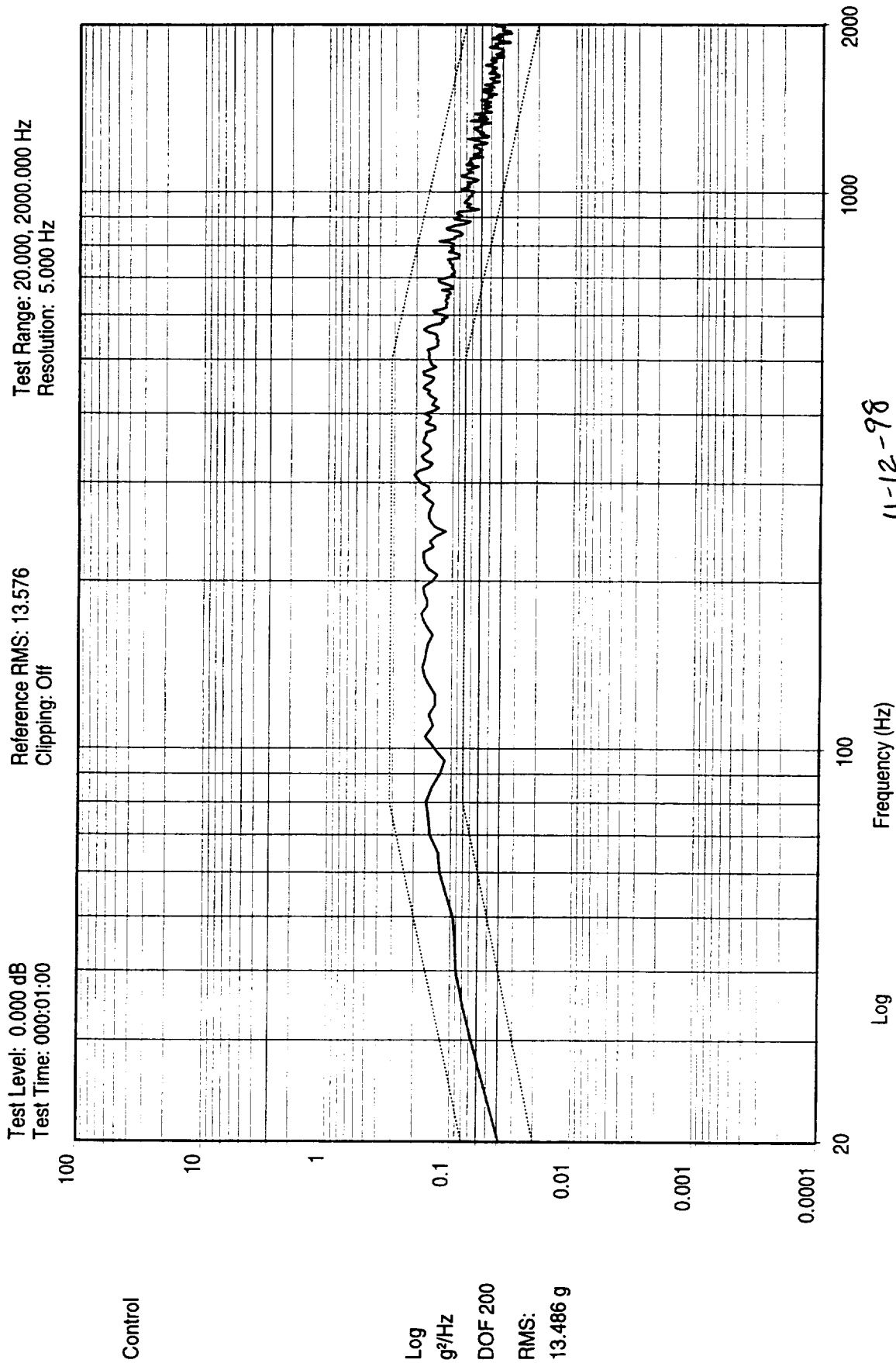
11-12-98



AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 X AXIS PRE SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

14:04:32
 12-Nov-1998



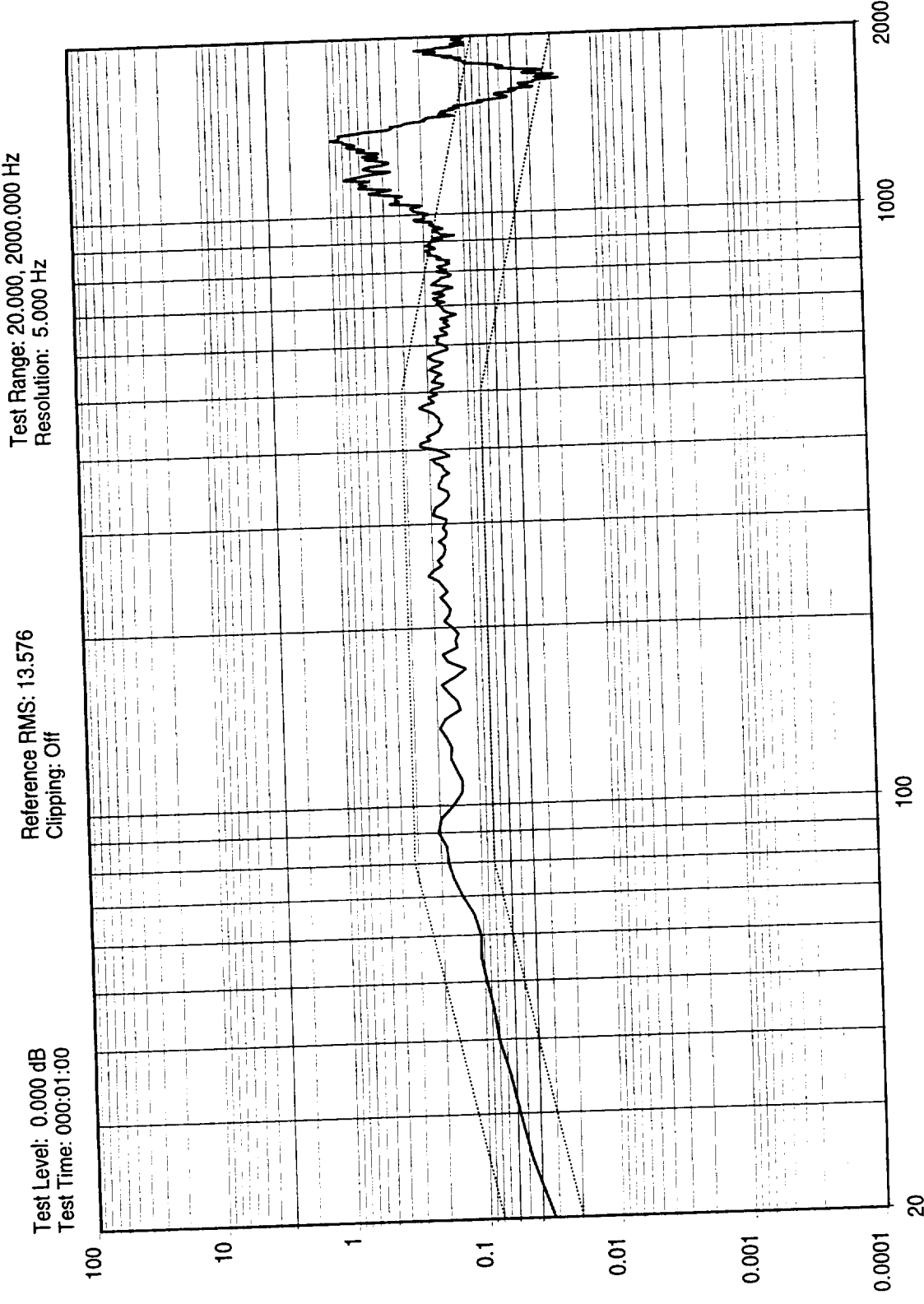
14:22:27
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
X AXIS TEST P/N 1348360-1 S/N F09

Test Name: PLO.tmp

11-12-98





Auxiliary 2

Log
g²/Hz
DOF 120
RMS:
20.562 g

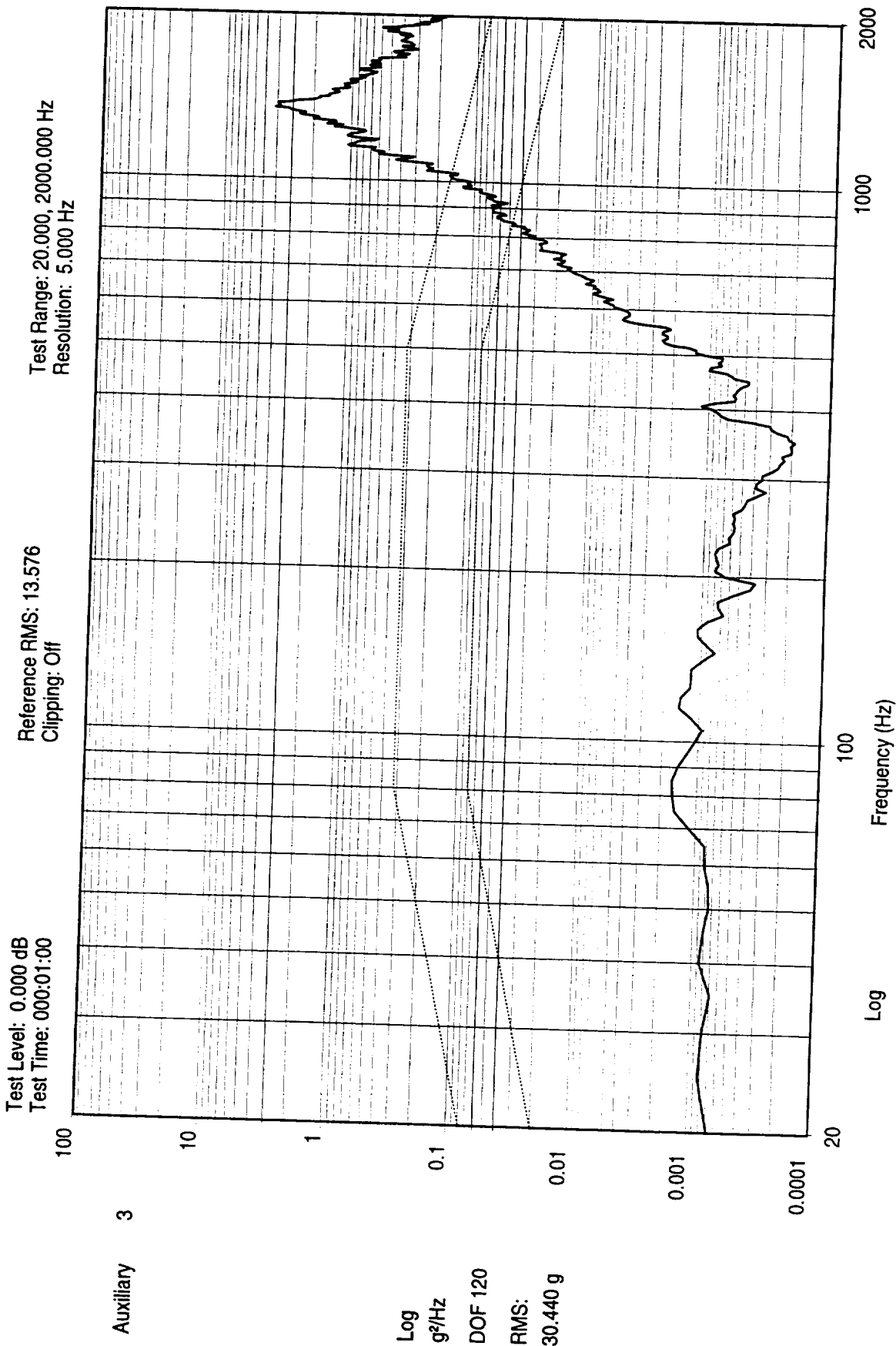
UNIT X AXIS
11-12-98

AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
X AXIS TEST P/N 1348360-1 S/N ,F09

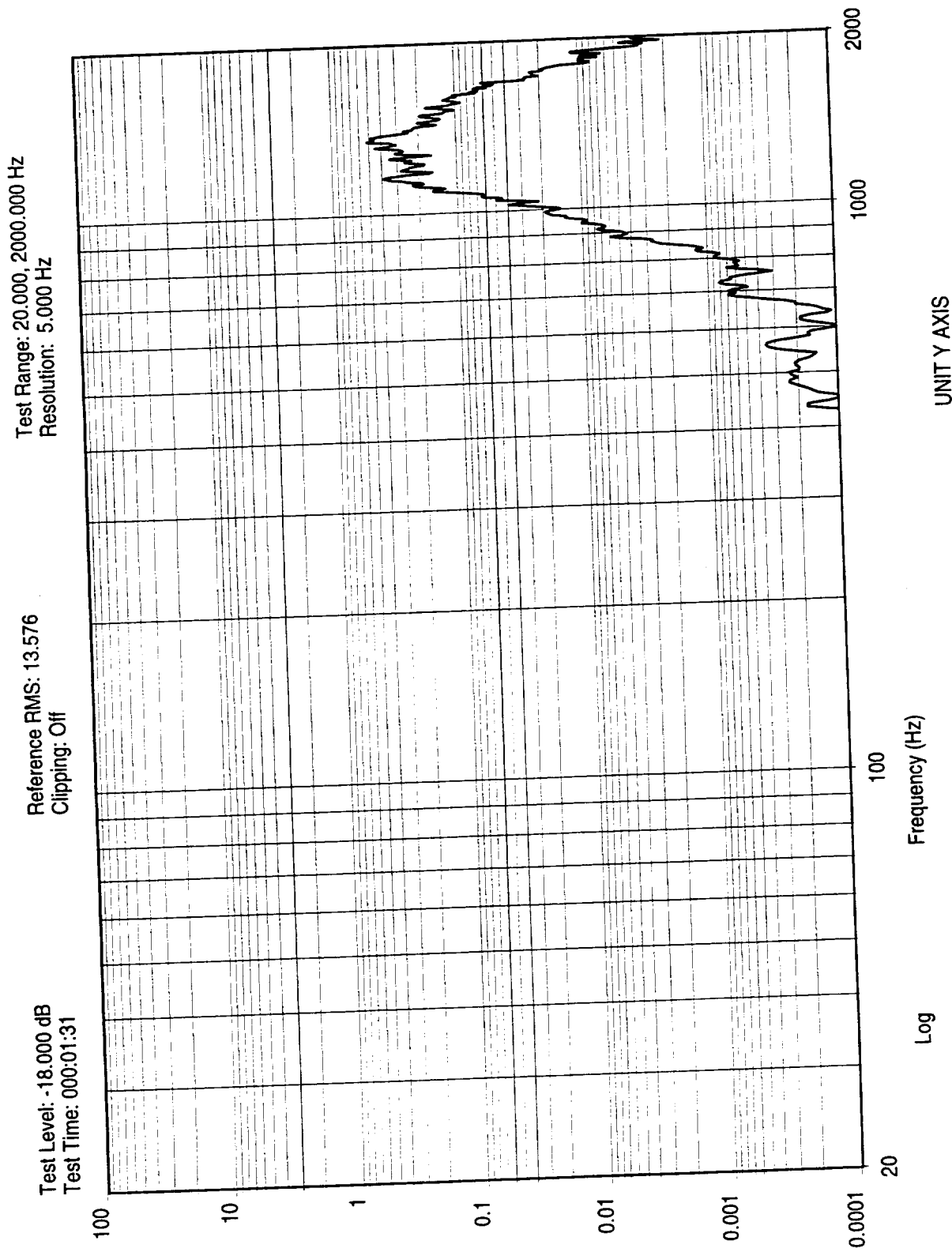


Test Name: PLO.tmp

14:17:40
12-Nov-1998



14:17:45
 12-Nov-1998
 AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
 X AXIS TEST P/N 1348360-1 S/N, F09
 Test Name: PLO.tmp
 11-12-98
 ENG 217
 002
 41



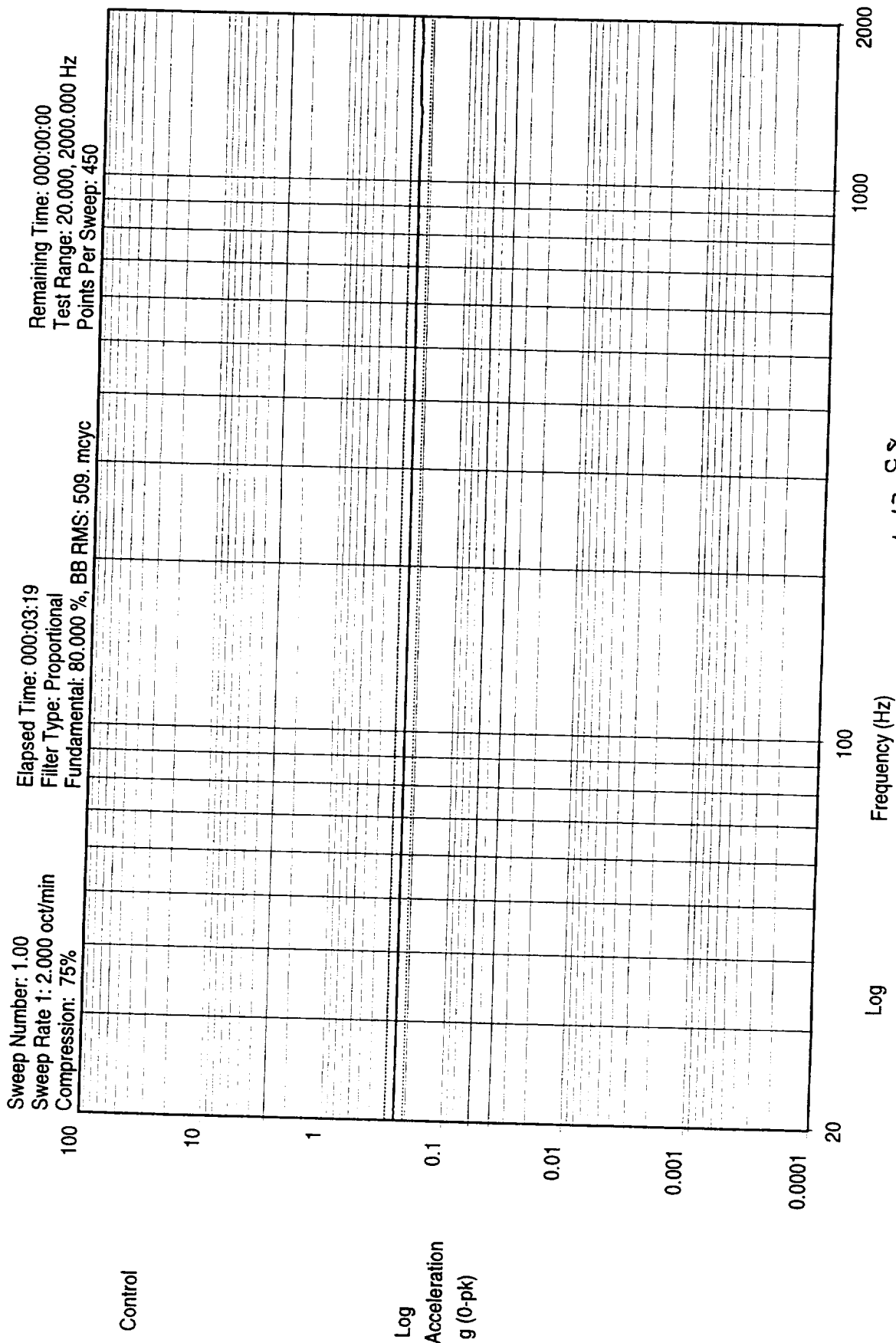
Auxiliary 4

Log
g²/Hz
DOF 120
RMS:
11.617 g

15:56:35
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
X AXIS TEST P/N 1348360-1 S/N,F09
Test Name: PLO.tmp

ENG 217
11-12-98



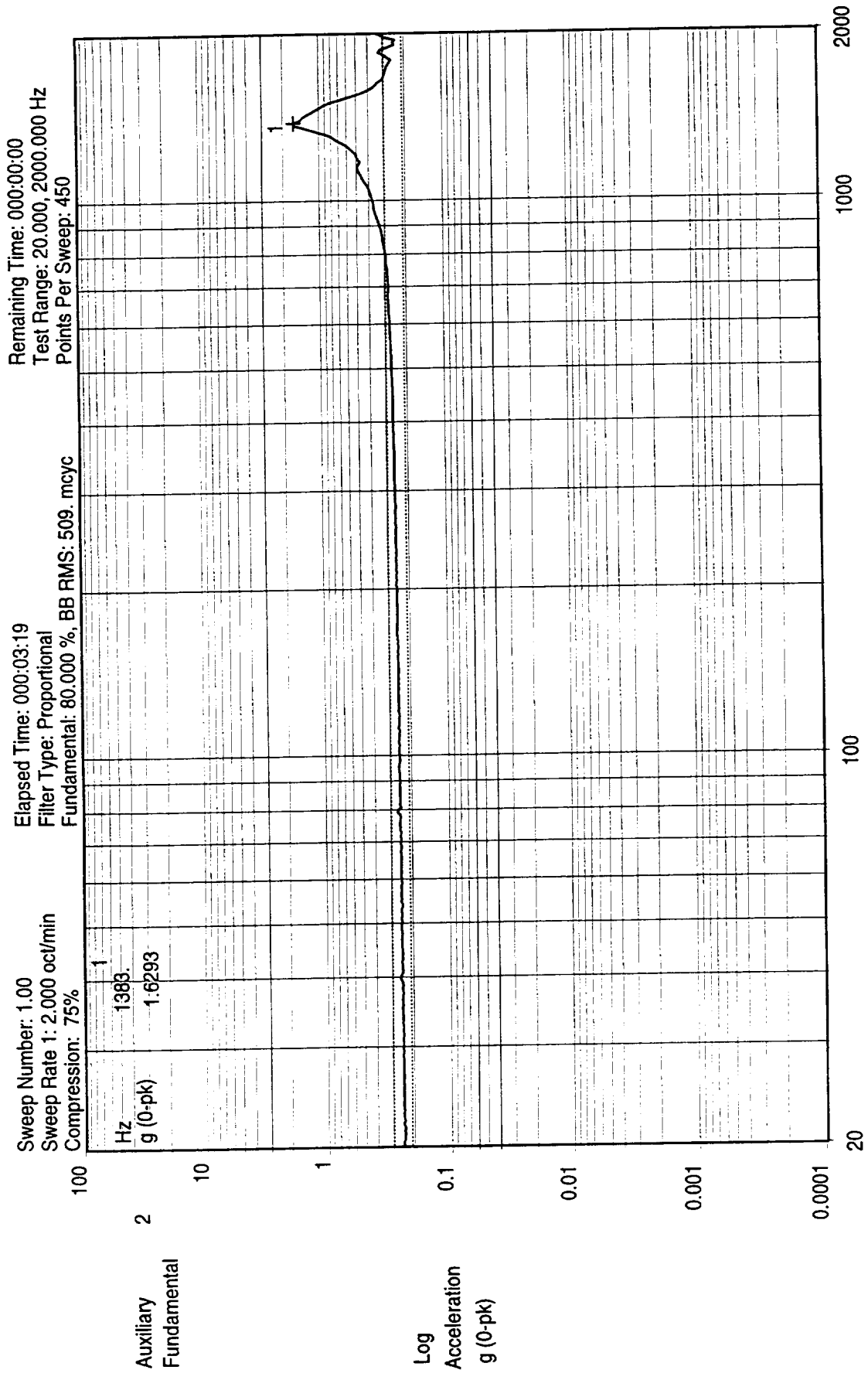
11-12-98

ENG 217
7A 200

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
X AXIS POST SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

14:41:10
12-Nov-1998

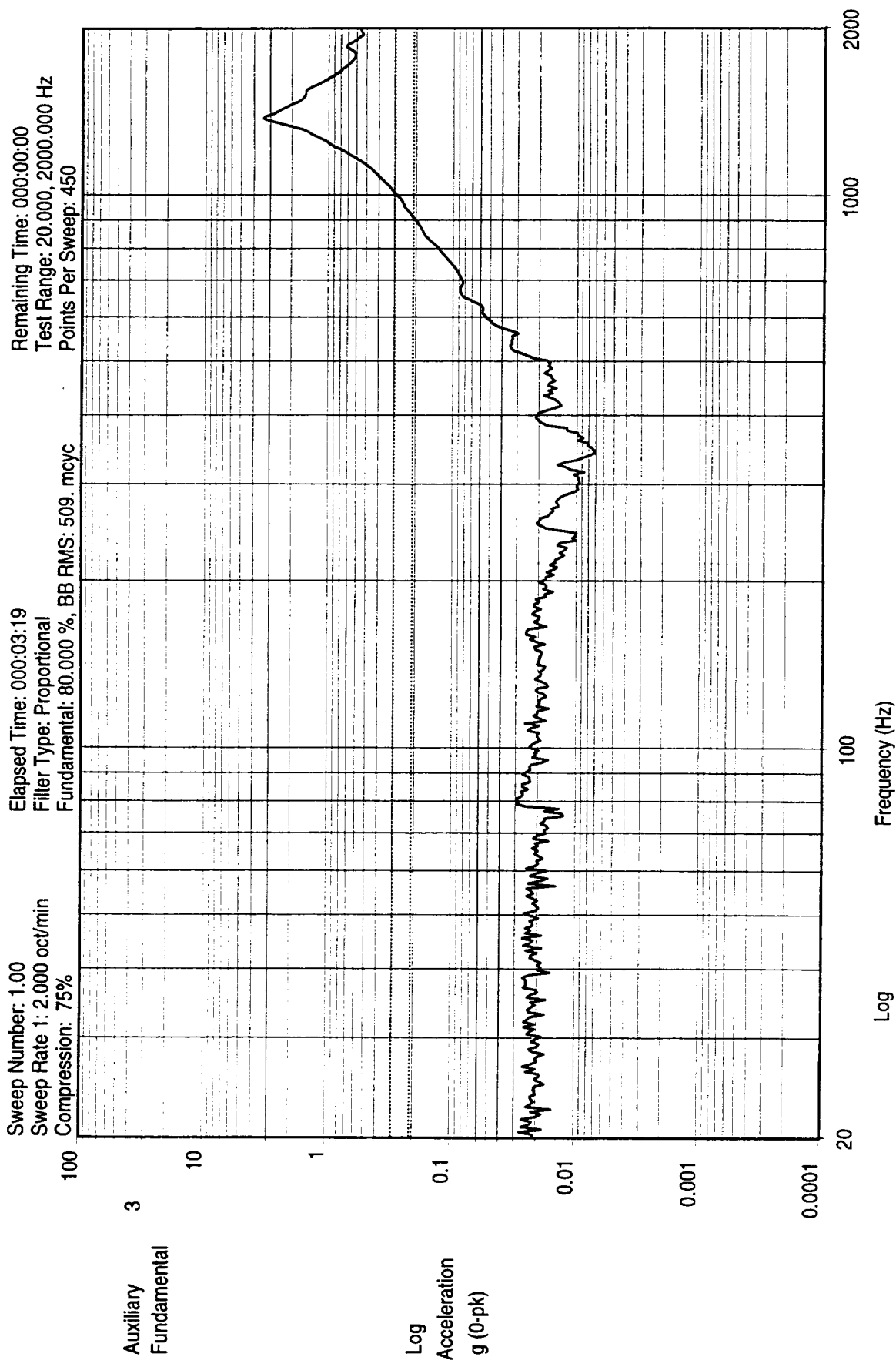


UNIT X

(1-12-98)
 ENG 7A
 217 200

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 X AXIS POST SINE SWEEP/N 1348360-1 S/N F09
 Sine Test Name: PLO.tmp

14:40:56
 12-Nov-1998



Sweep Number: 1.00
 Sweep Rate 1: 2.000 oct/min
 Compression: 75%

Elapsed Time: 000:03:19
 Filter Type: Proportional
 Fundamental: 80.000 %, BB RMS: 509. mcyc

Remaining Time: 000:00:00
 Test Range: 20.000, 2000.000 Hz
 Points Per Sweep: 450

14:41:00
 12-Nov-1998

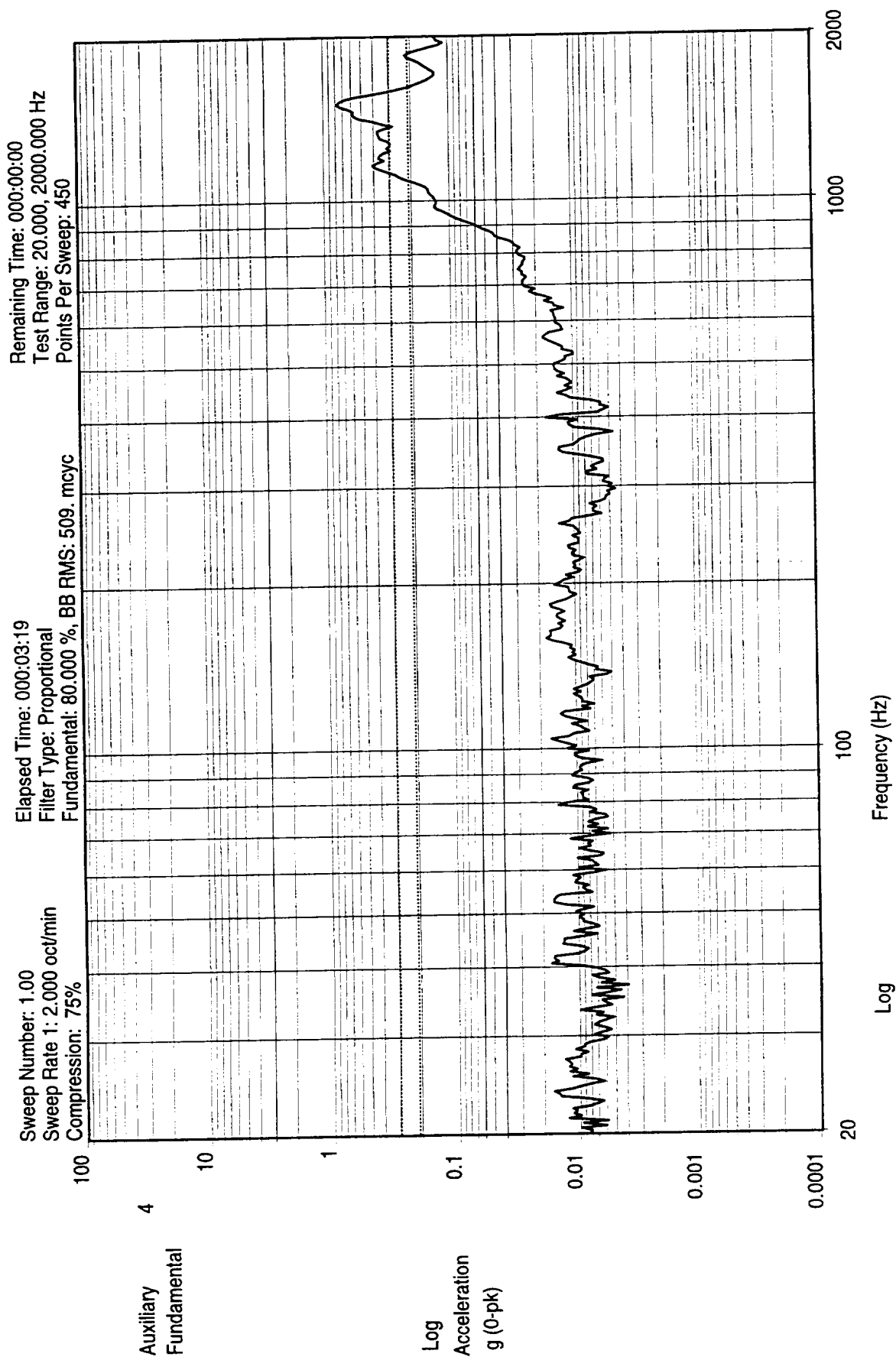
AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 X AXIS POST SINE SWEEP/P/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

UNIT Z

11-12-98

ENG 217 7A 200



UNIT Y

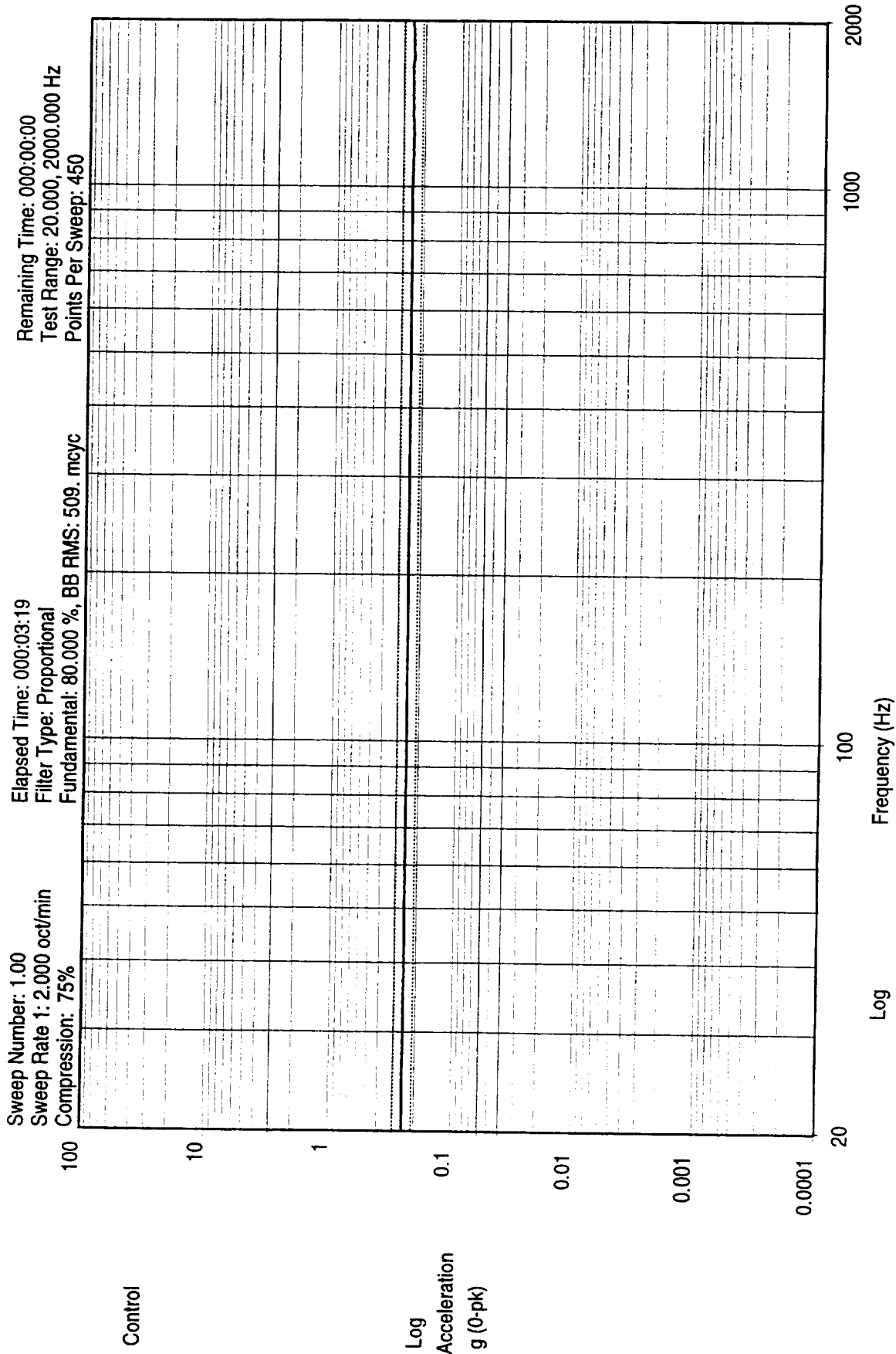
11-12-98



AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 X AXIS POST SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

14:41:04
 12-Nov-1998



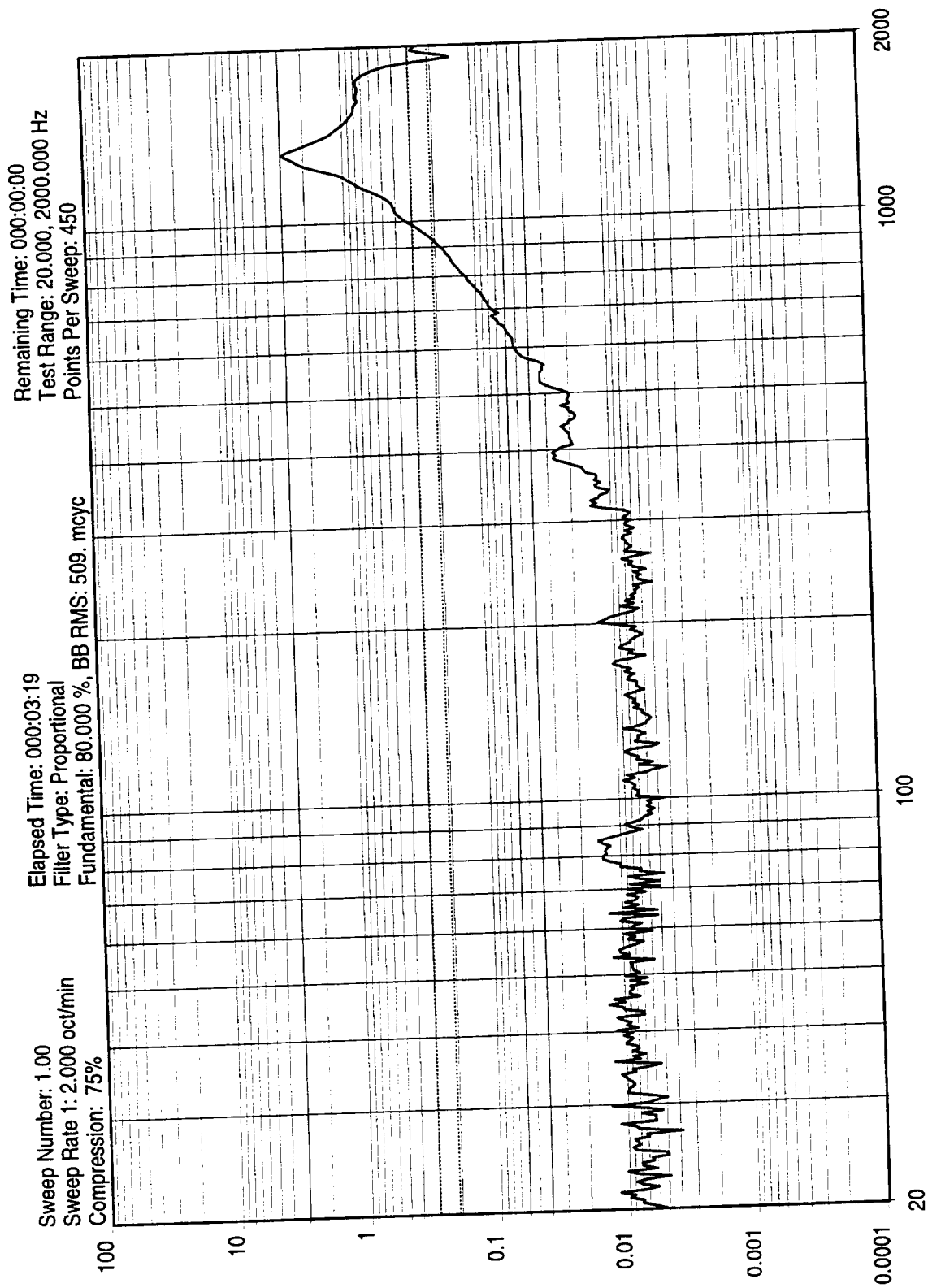
15:23:10
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
Y AXIS PRE SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

11-12-98

ENG 217 7A 200



UNIT X

11-12-98



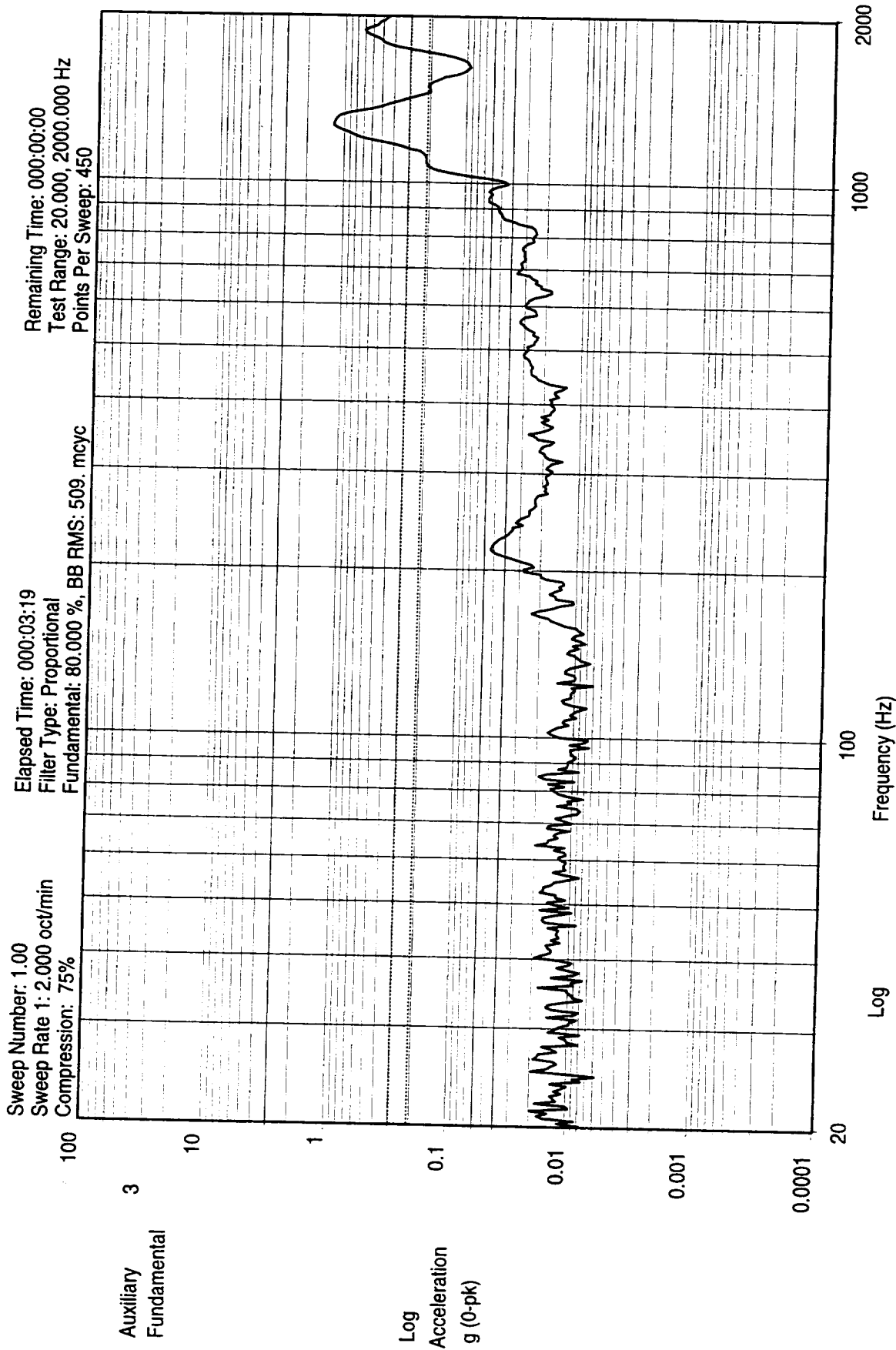
AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT

Y AXIS PRE SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

15:23:23

12-Nov-1998



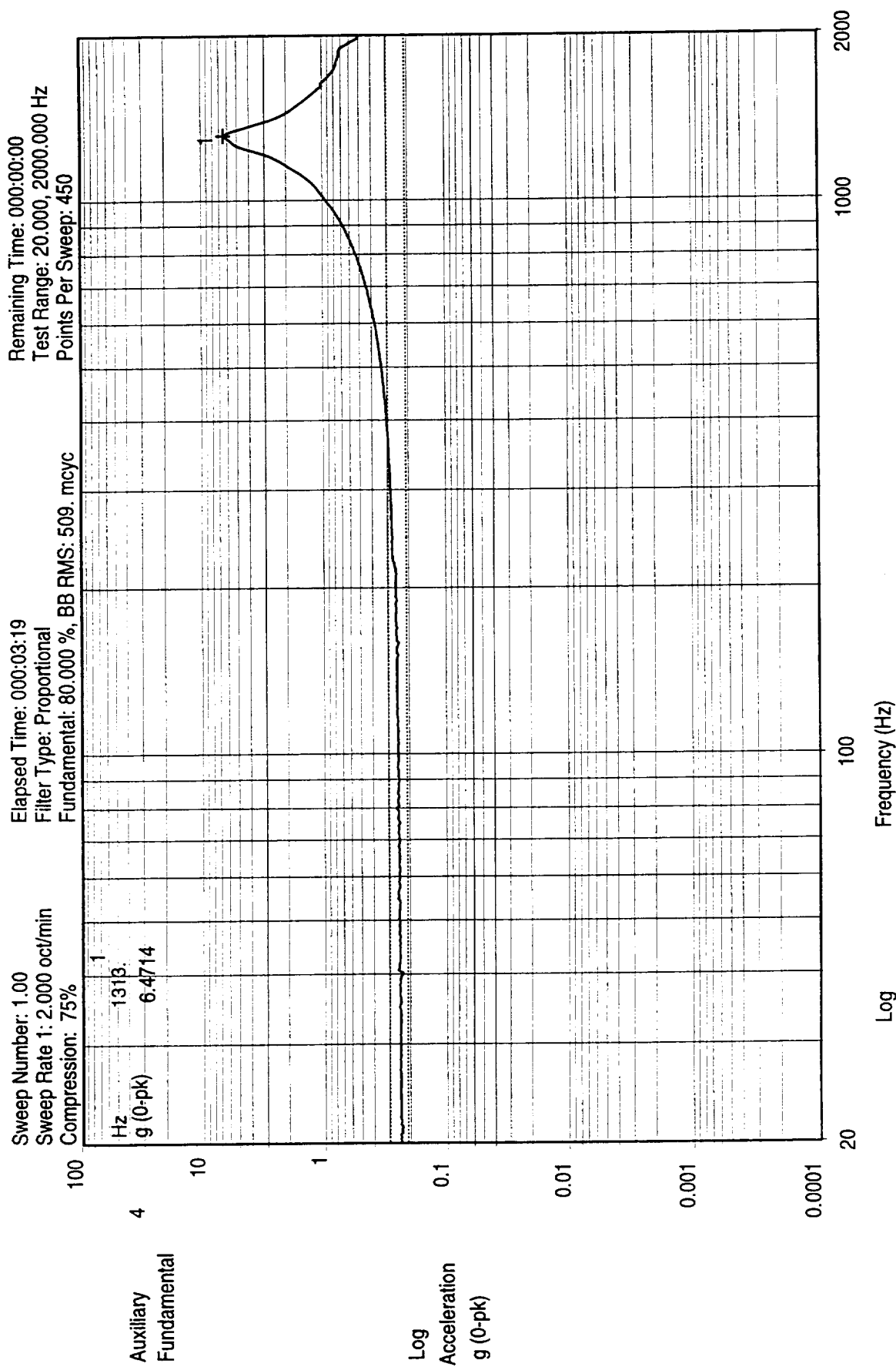
15:23:27
 12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 Y AXIS PRE SINE SWEEP/PN 1348360-1 S/N F09
 Sine Test Name: PLO.tmp

11-12-98



UNIT Z



UNIT Y

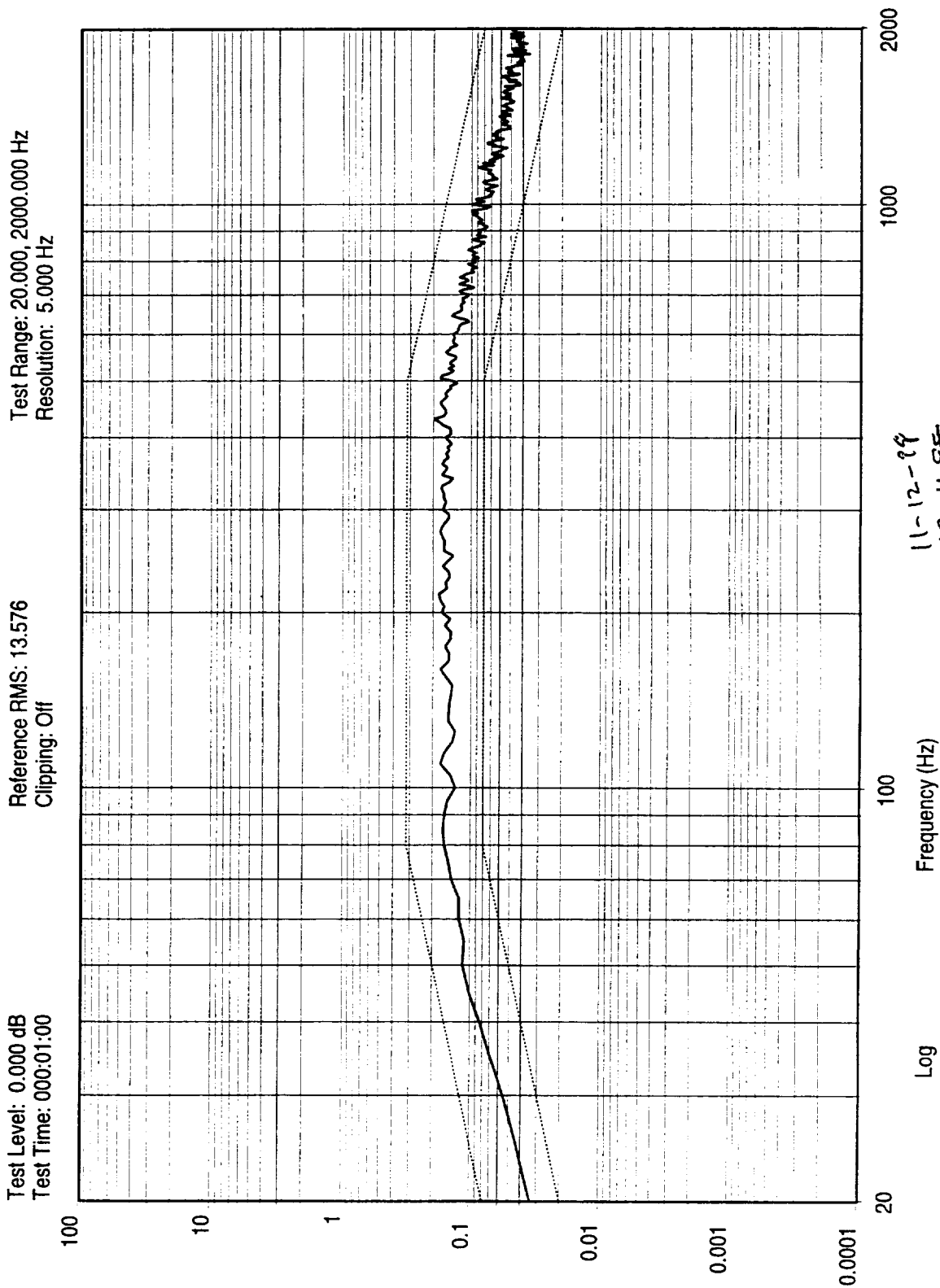
11-12-98



AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
Y AXIS PRE SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

15:23:44
12-Nov-1998



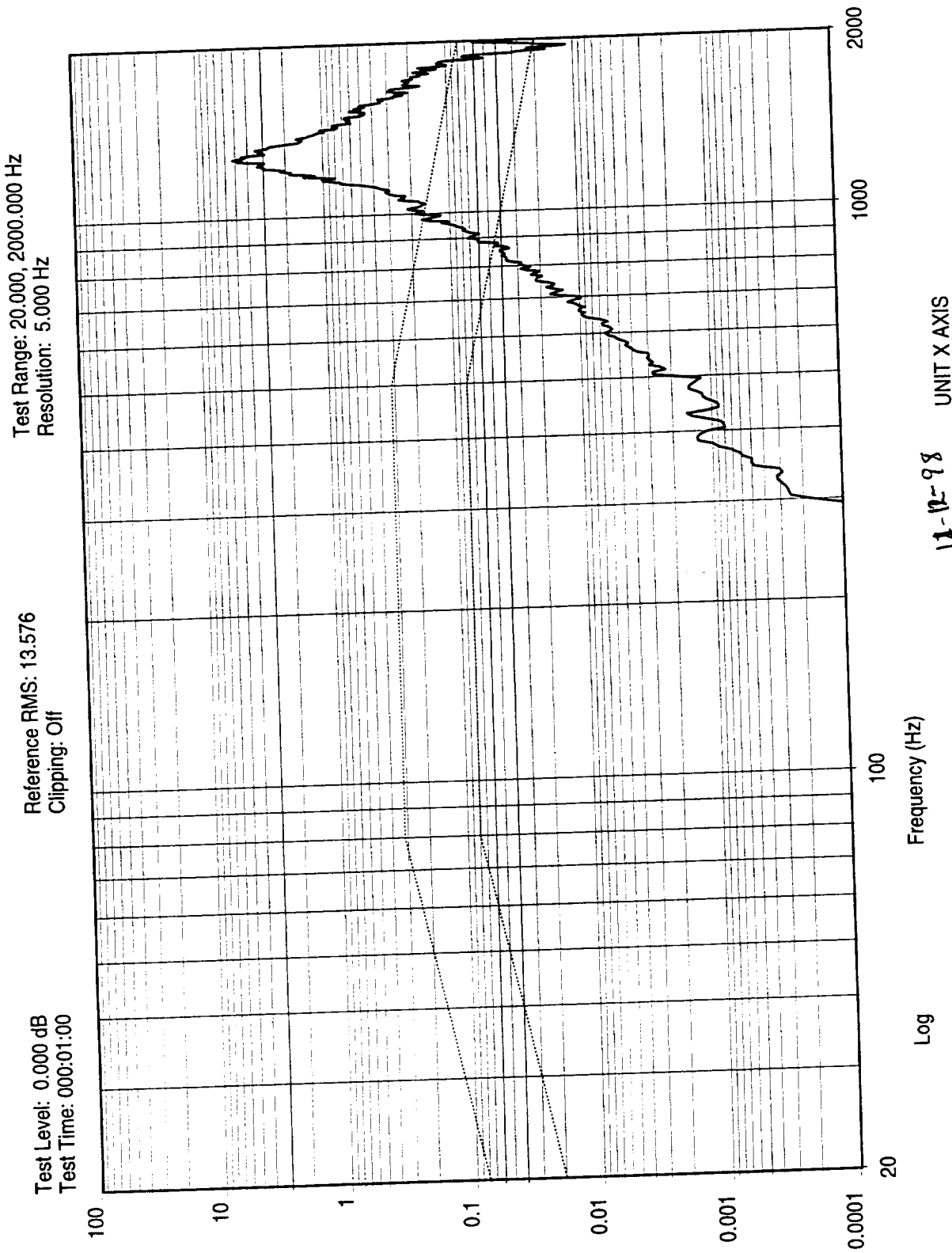
11-12-98
12-11-98



AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
Y AXIS TEST P/N 1348360-1 S/N F09

Test Name: PLO.tmp

15:35:59
12-Nov-1998



11-10-98

ENG A
217
0.00

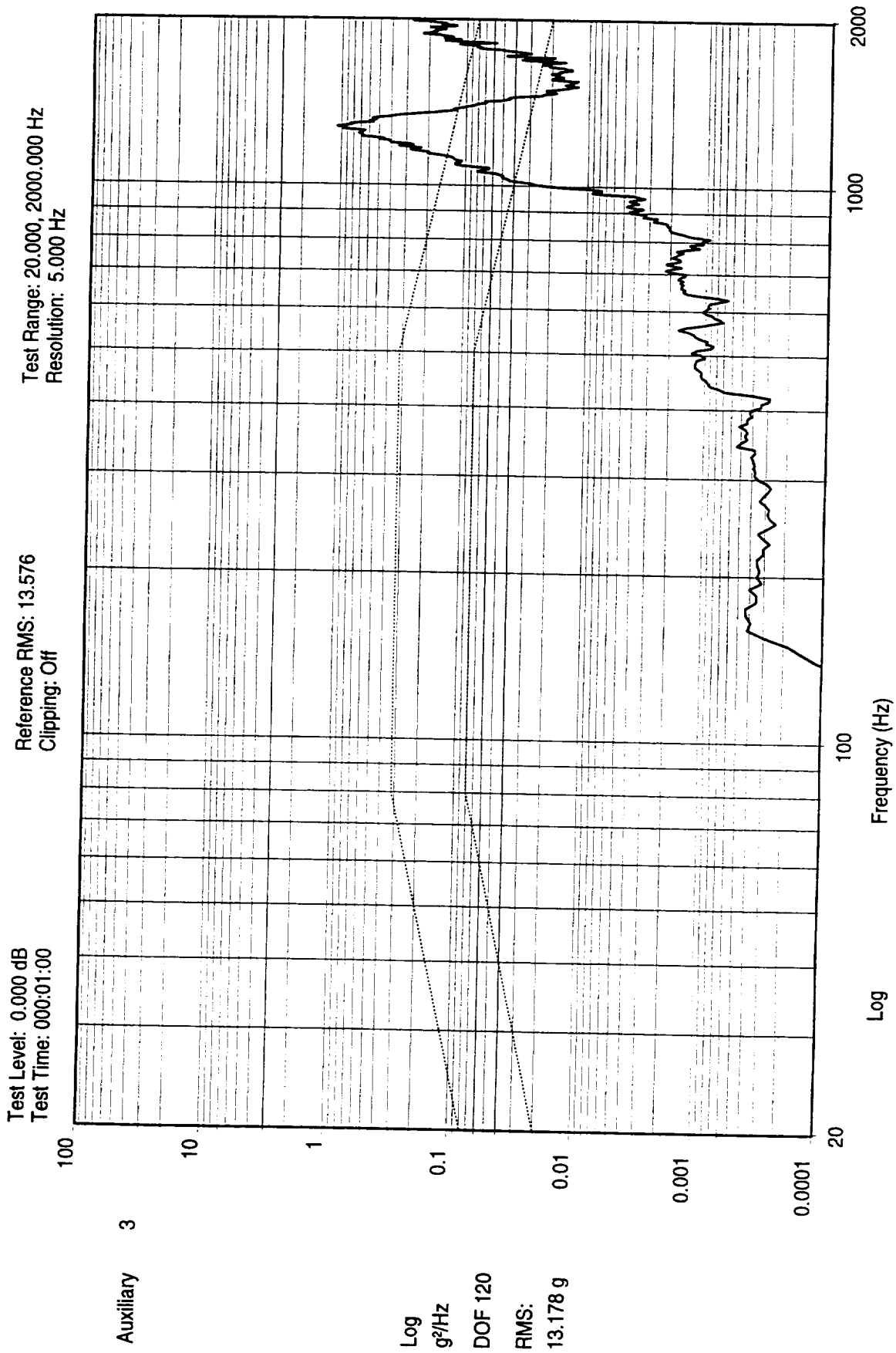
AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
Y AXIS TEST P/N 1348360-1 S/N F09

Test Name: PLO.tmp

15:36:11
12-Nov-1998

Auxiliary 2

Log
g²/Hz
DOF 120
RMS:
29.108 g



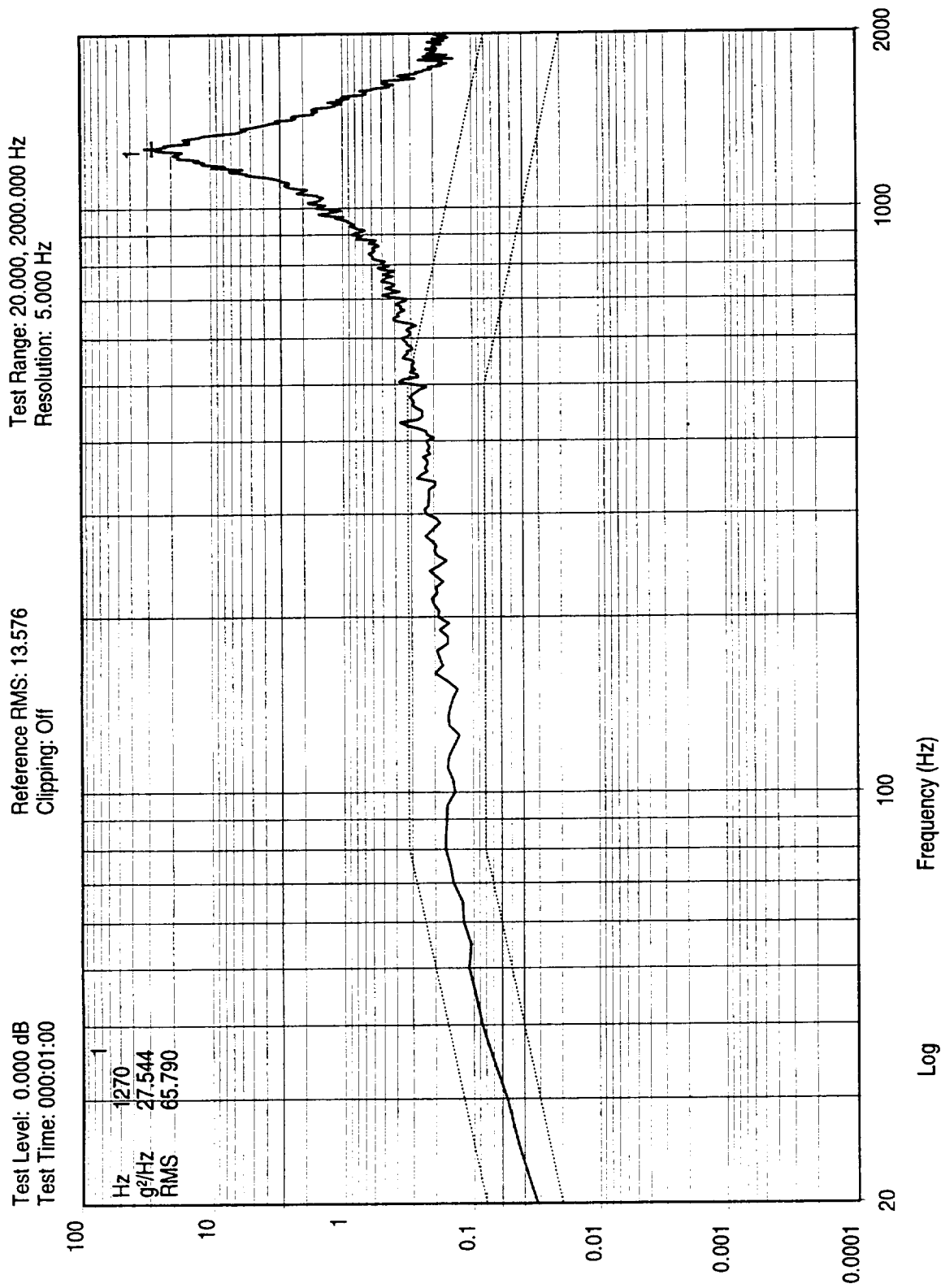
11-12-98



AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
Y AXIS TEST P/N 1348360-1 S/N F09

Test Name: PLO.tmp

15:36:15
12-Nov-1998



11-12-98 UNIT Y AXIS

METSAT

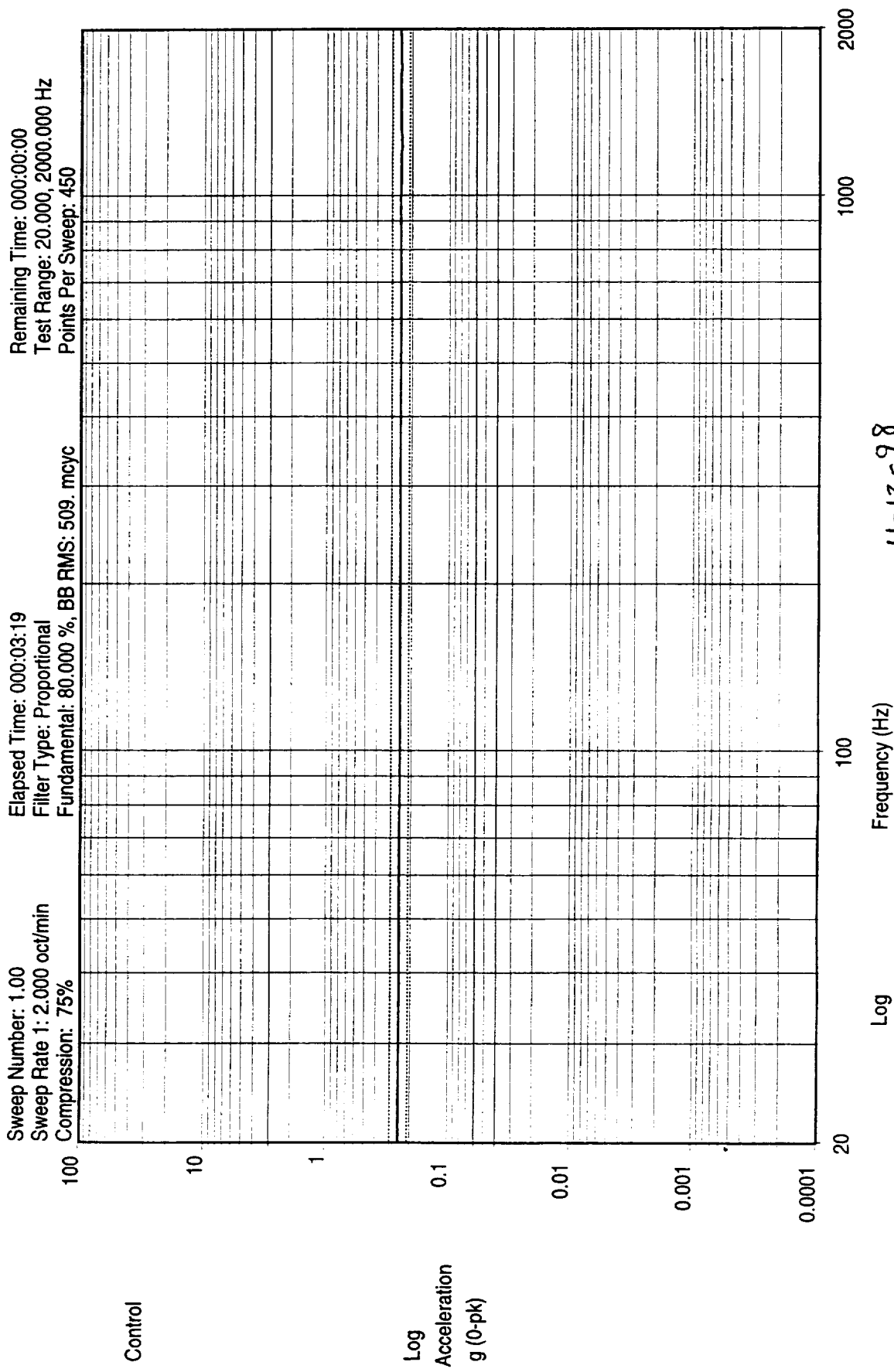
AMSU PHASE LOCK OSCILLATOR S/O538596-F09

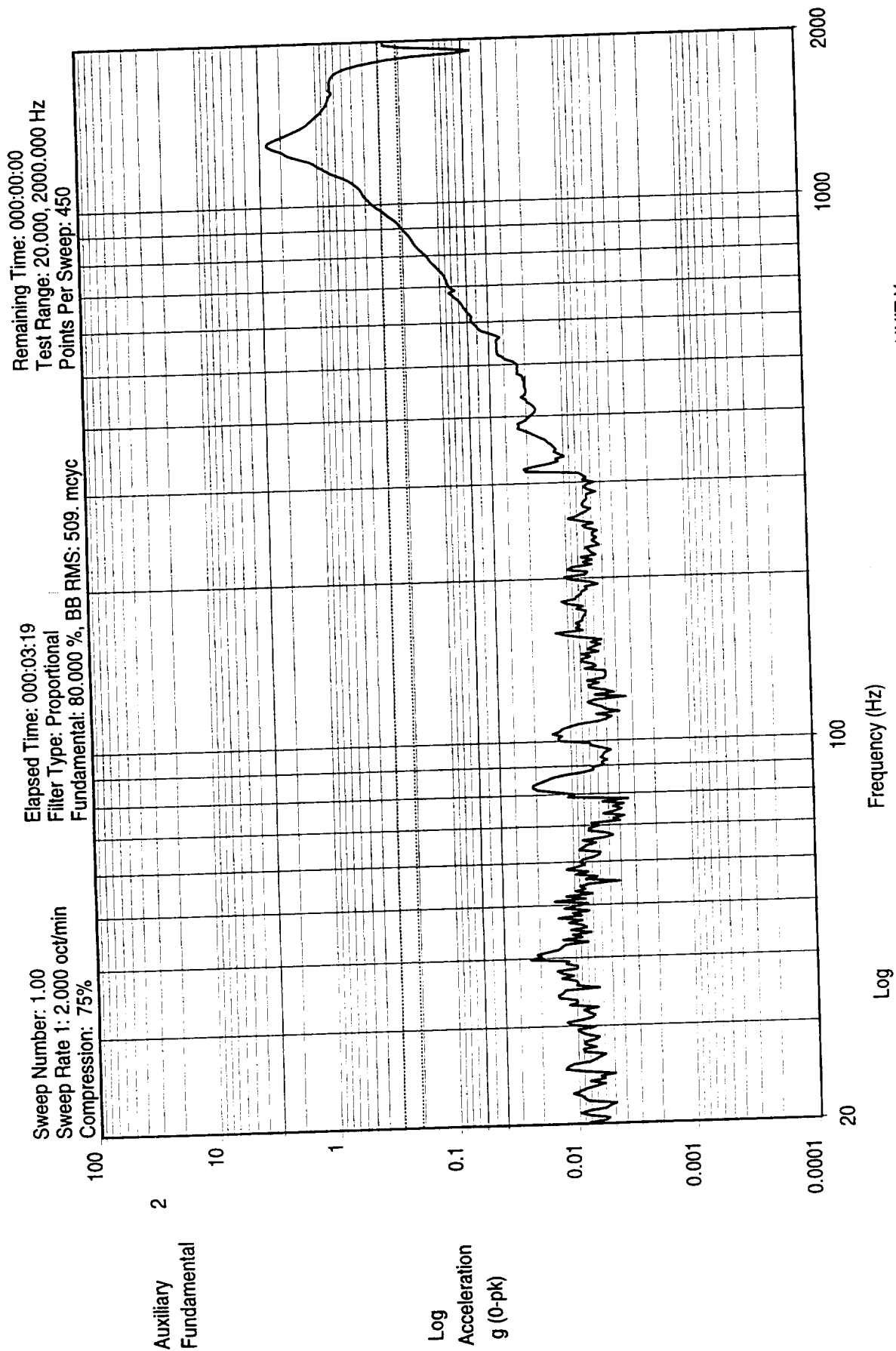
Y AXIS TEST P/N 1348360-1 S/N,F09

Test Name: PLO.tmp

15:36:25
12-Nov-1998







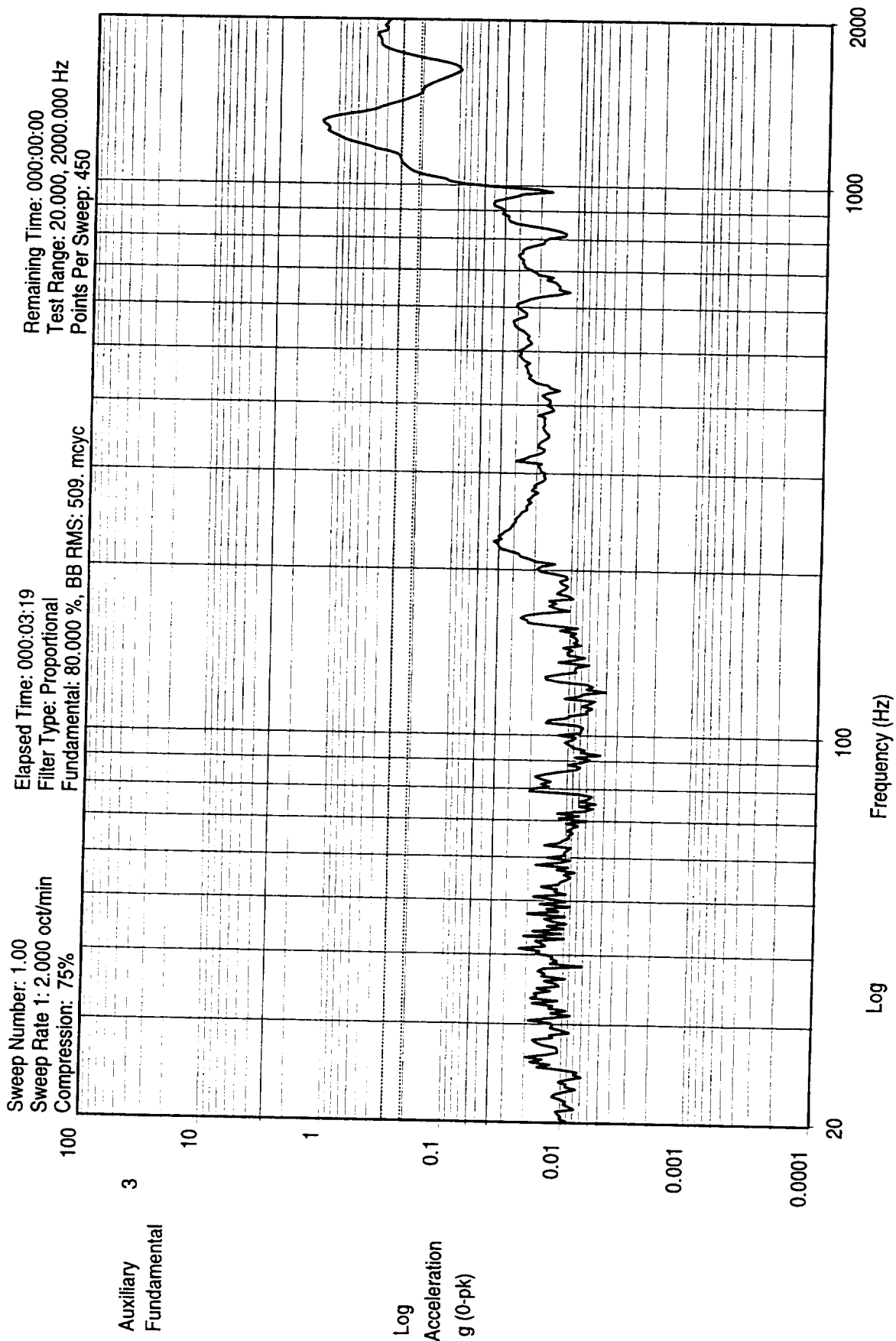
11-12-98



AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 Y AXIS POST SINE SWEEP/P/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

15:49:05
 12-Nov-1998



UNIT Z

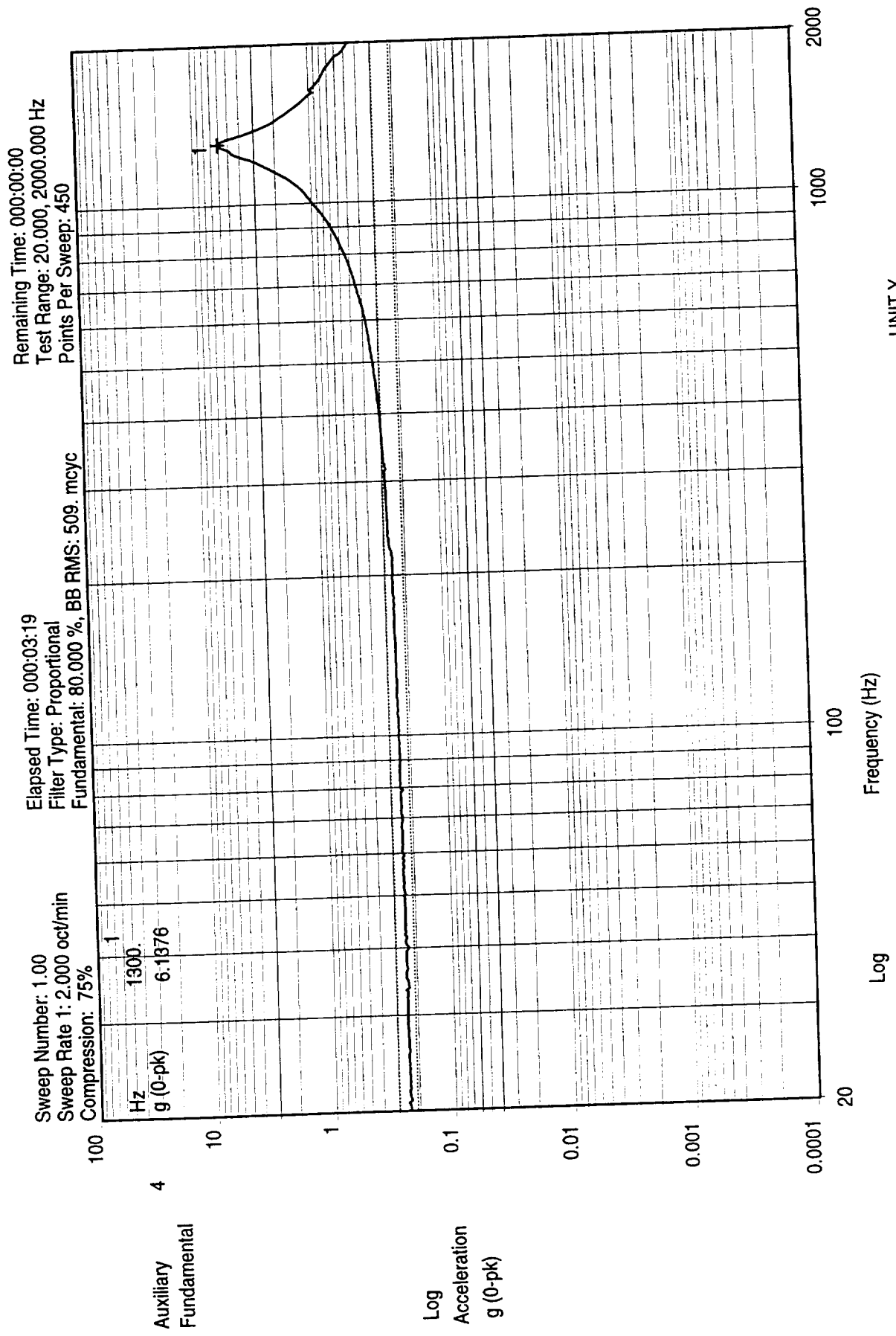
11-12-98



AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 Y AXIS POST SINE SWEEP/P/N 1348360-1 S/N F09

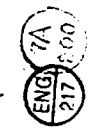
Sine Test Name: PLO.tmp

15:49:08
 12-Nov-1998

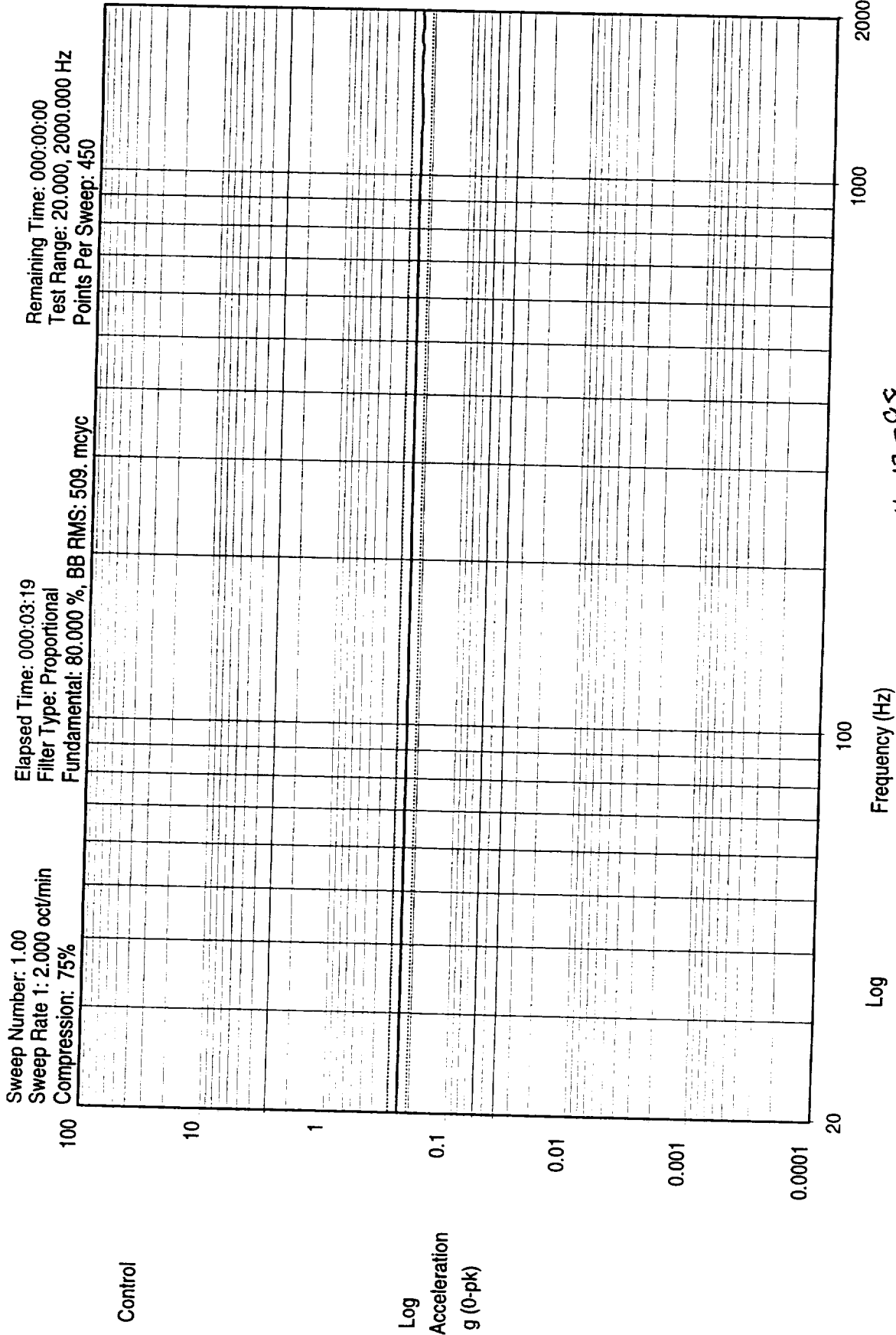


UNIT Y

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT 11-12-98
 Y AXIS POST SINE SWEEP/N 1348360-1 S/N F09
 Sine Test Name: PLO.tmp



15:49:25
 12-Nov-1998

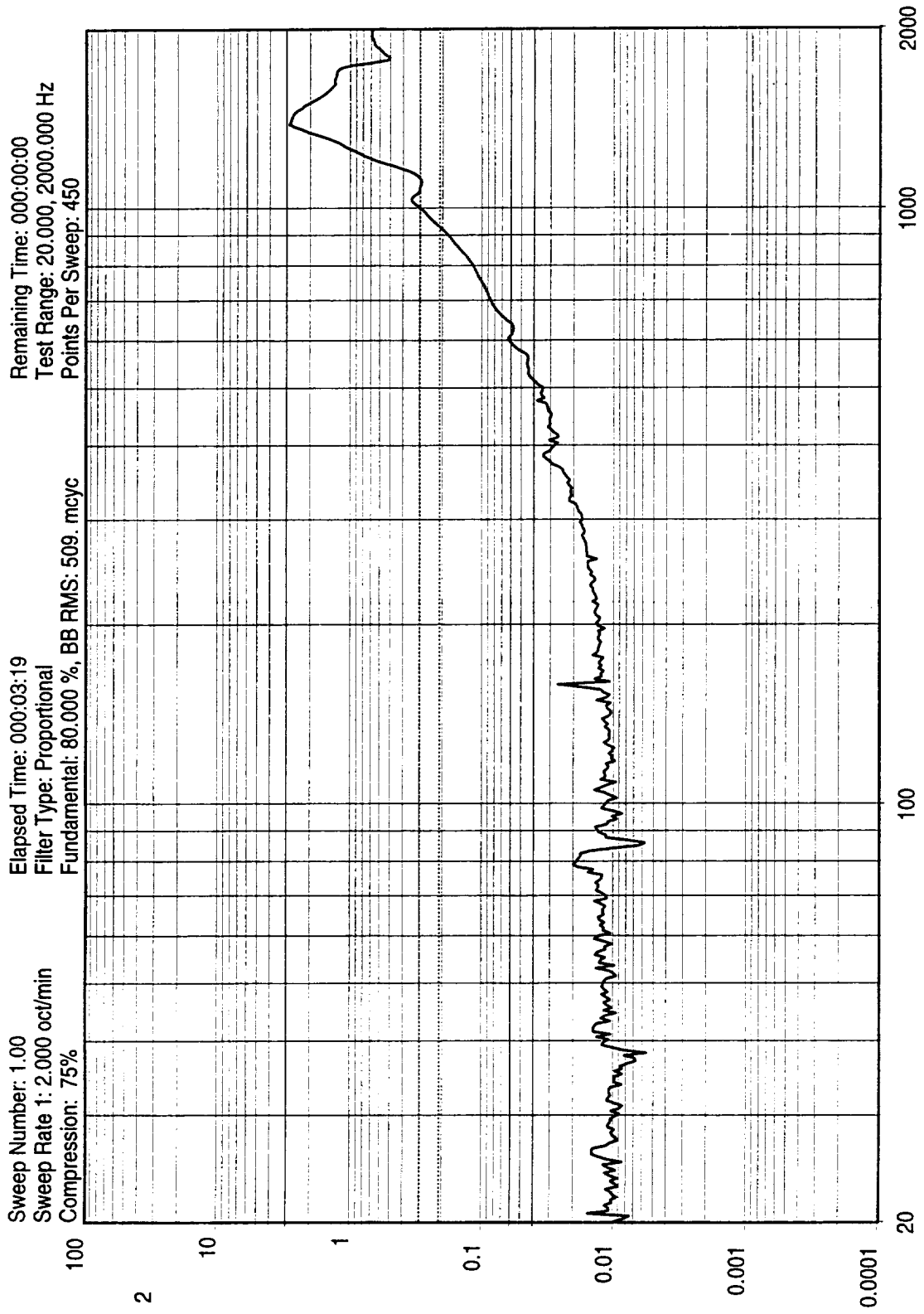


16:33:45
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
 Z AXIS PRE SINE SWEEP/N 1348360-1 S/N F09
 Sine Test Name: PLO.tmp

11-12-98





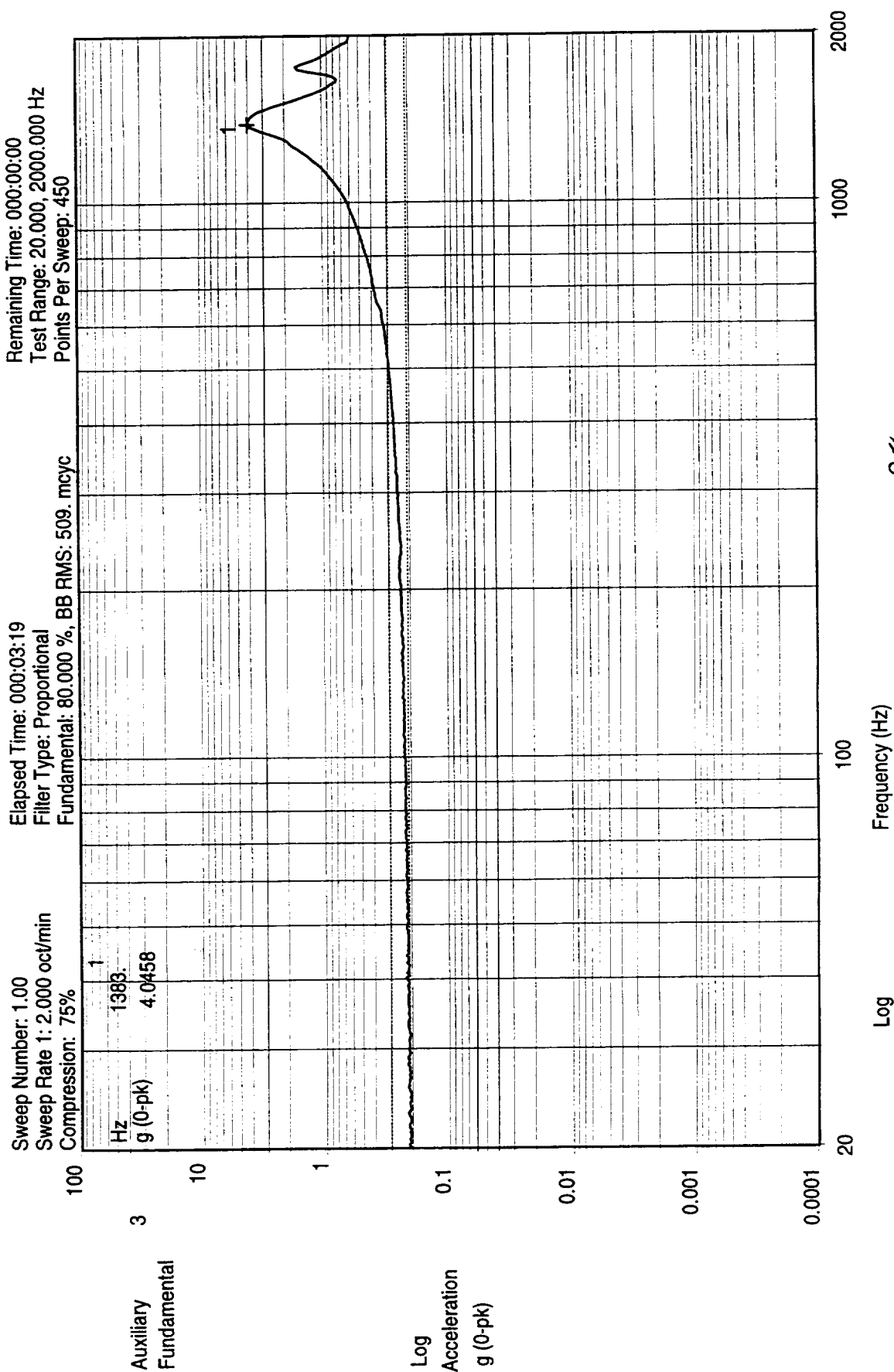
16:33:50
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
Z AXIS PRE SINE SWEEP/P/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

11-12-98 UNIT X





UNIT Z

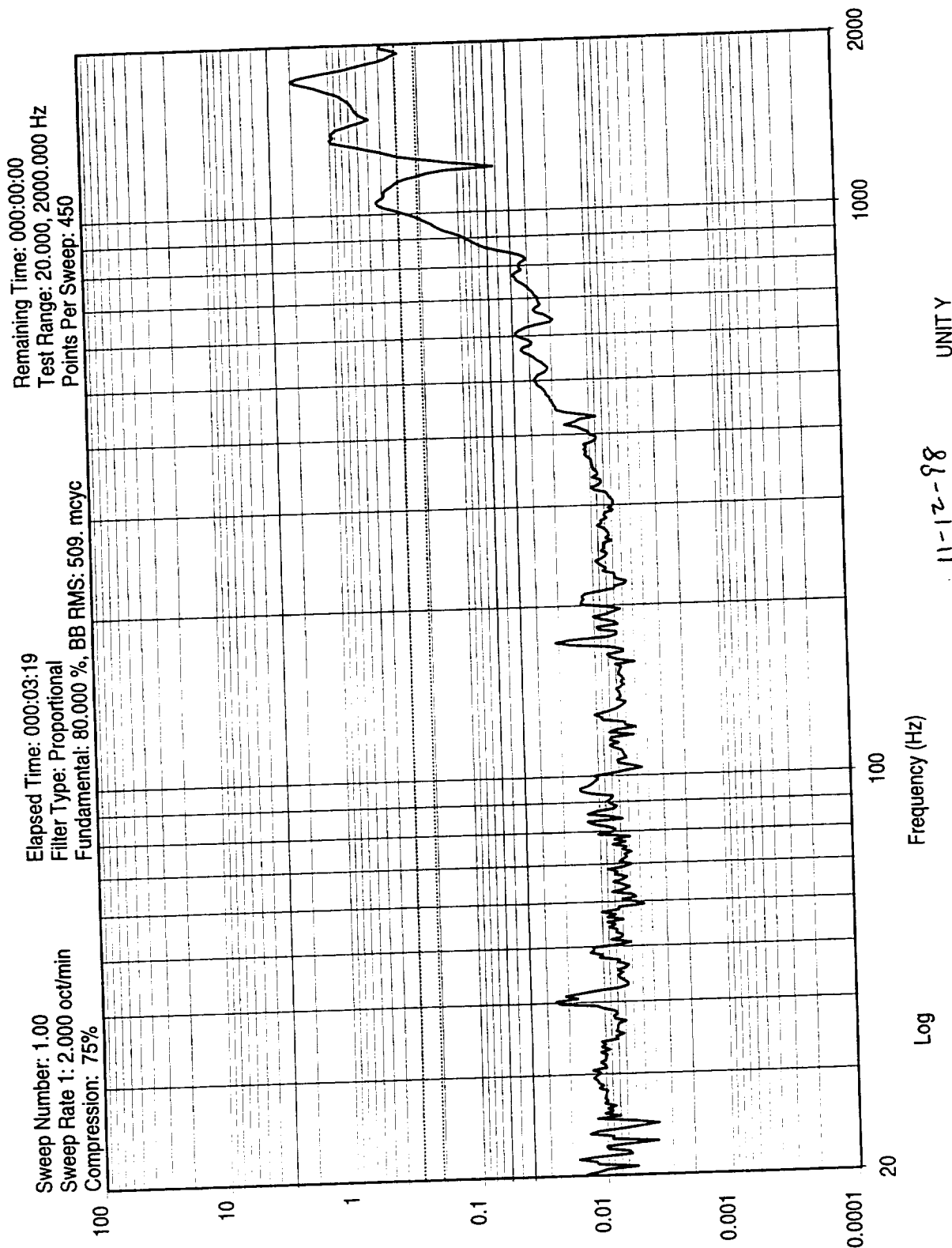
11-12-98



AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
Z AXIS PRE SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

16:34:10
12-Nov-1998



16:34:15
12-Nov-1998

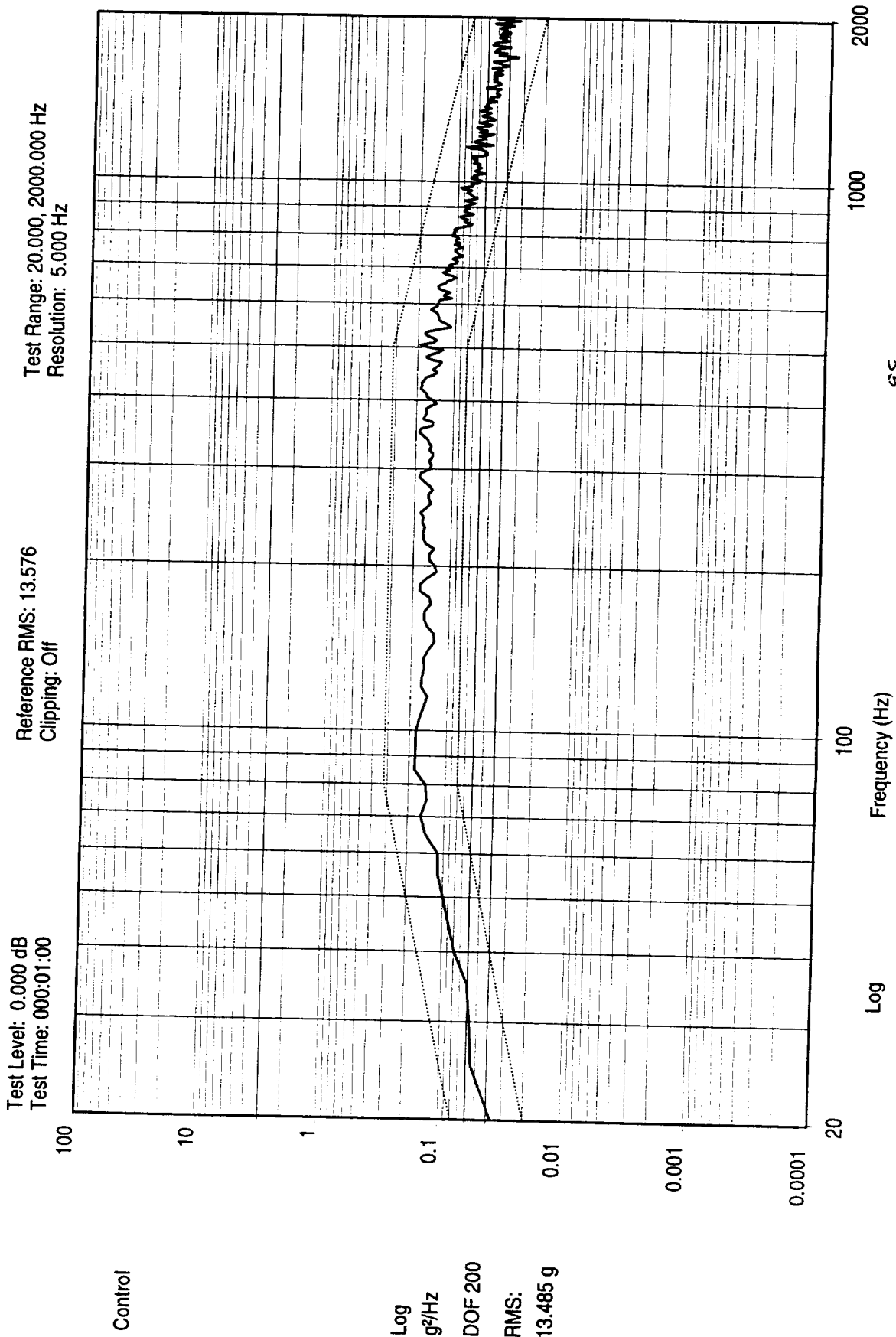
AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
Z AXIS PRE SINE SWEEP/PN 1348360-1 S/N F09

Sine Test Name: PLO.tmp

11-12-98



UNITY



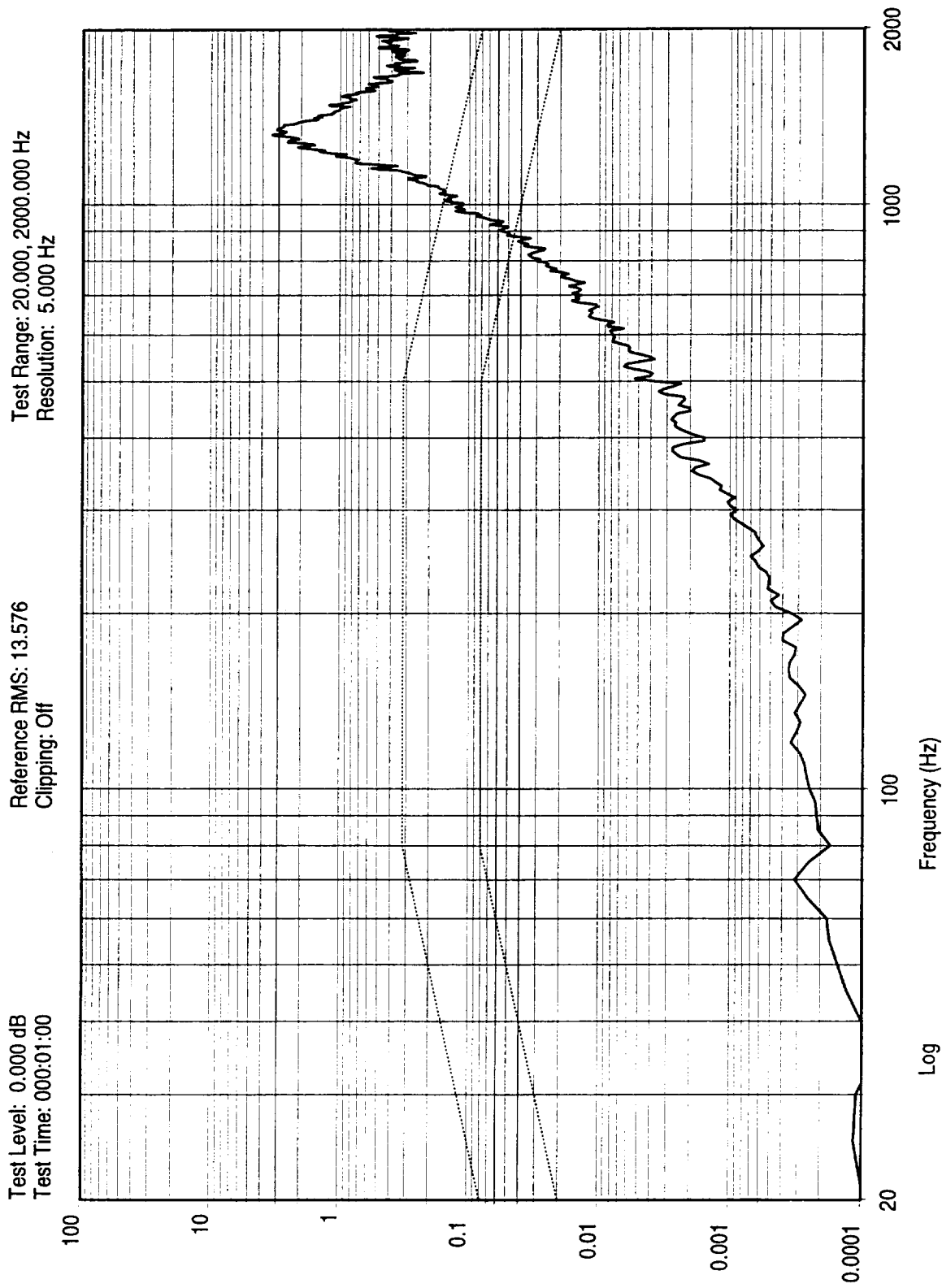
16:46:16
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
Z AXIS TEST P/N 1348360-1 S/N ,F09

Test Name: PLO.tmp

11-12-98





Auxiliary 2

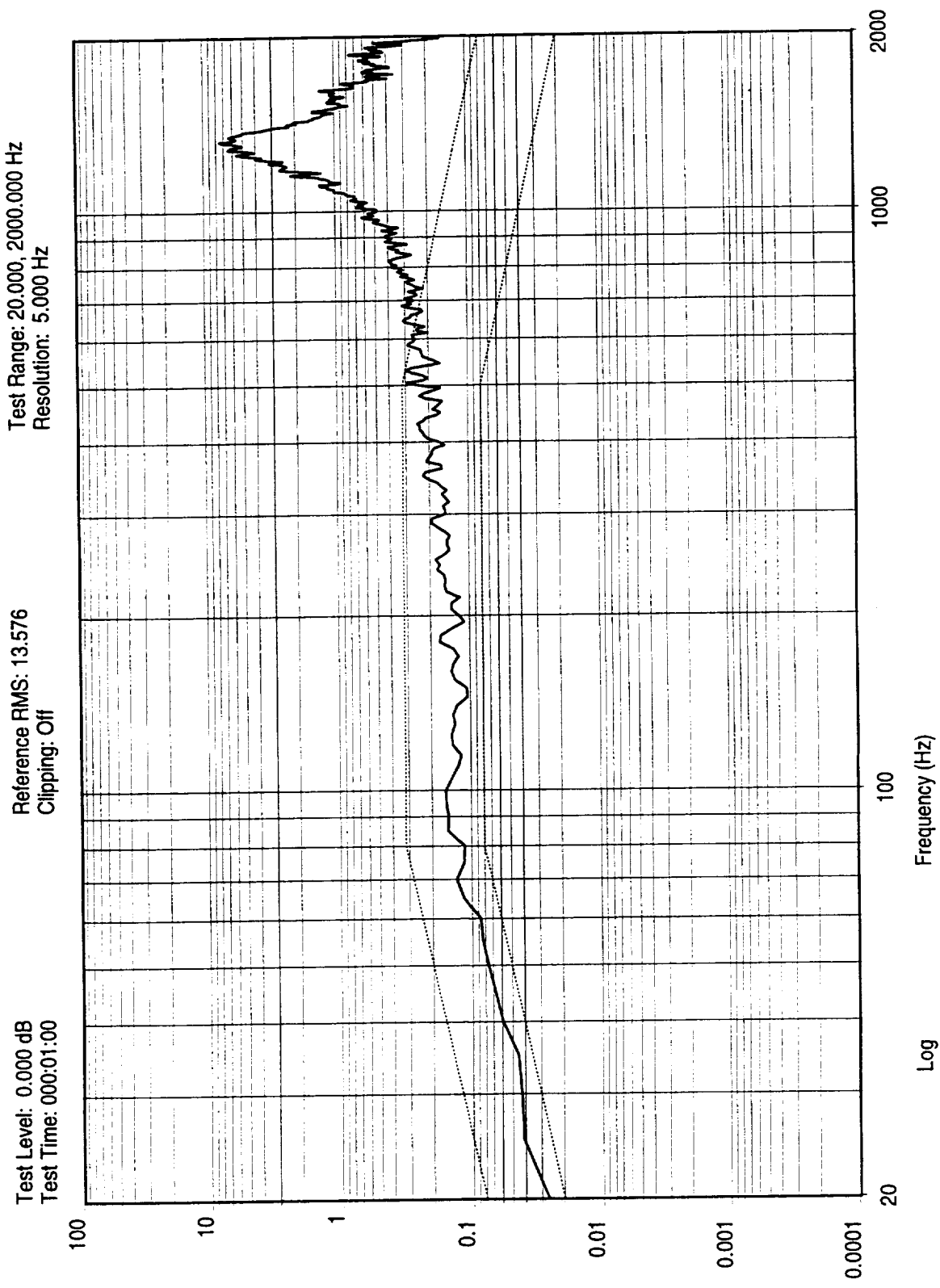
16:46:20
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
Z AXIS TEST P/N 1348360-1 S/N ,F09

Test Name: PLO.tmp

UNIT X AXIS
11-12-78





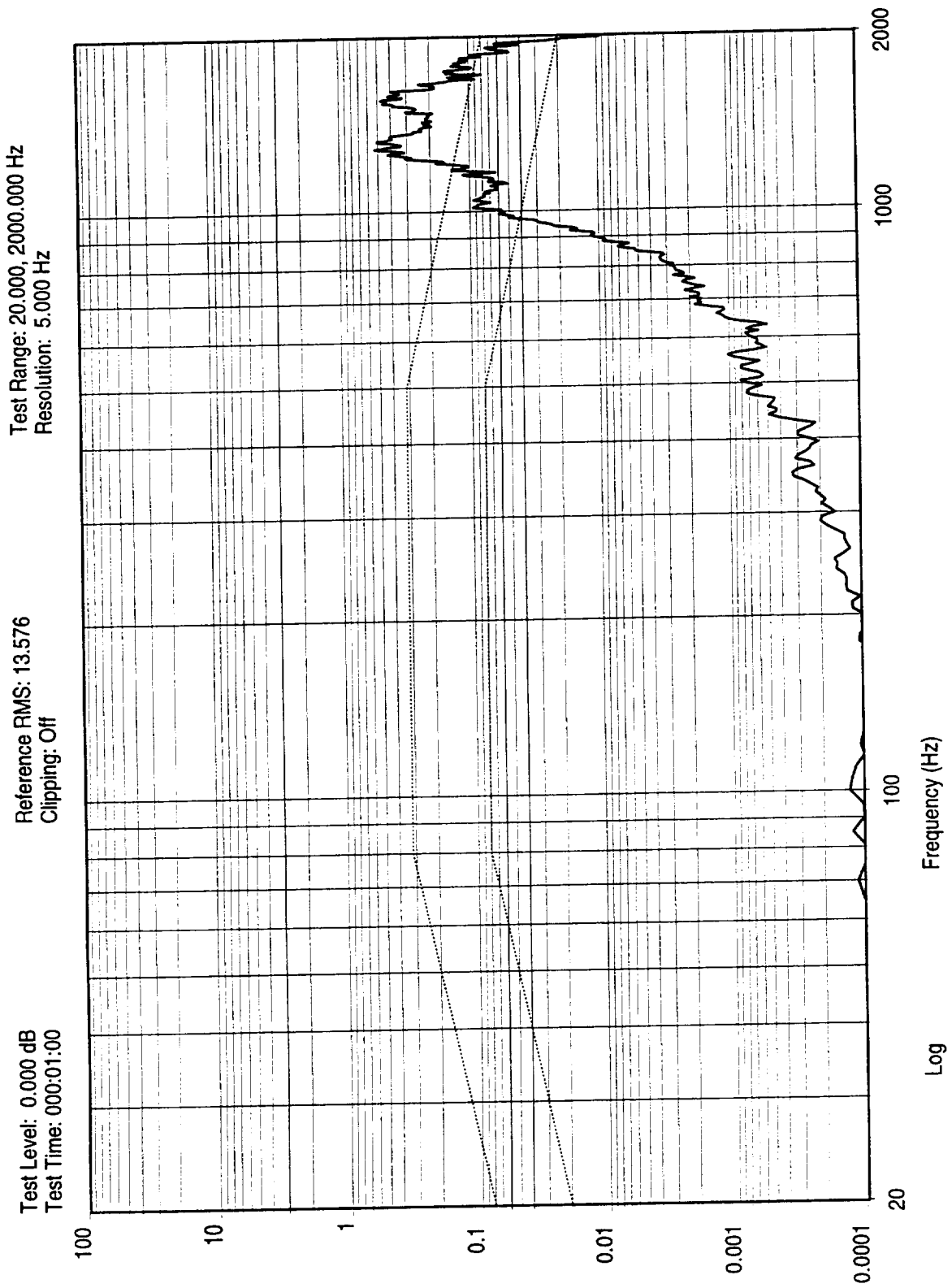
UNIT Z AXIS
11-12-98



AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
Z AXIS TEST P/N 1348360-1 S/N ,F09

Test Name: PLO.tmp

16:46:24
12-Nov-1998



Auxiliary 4

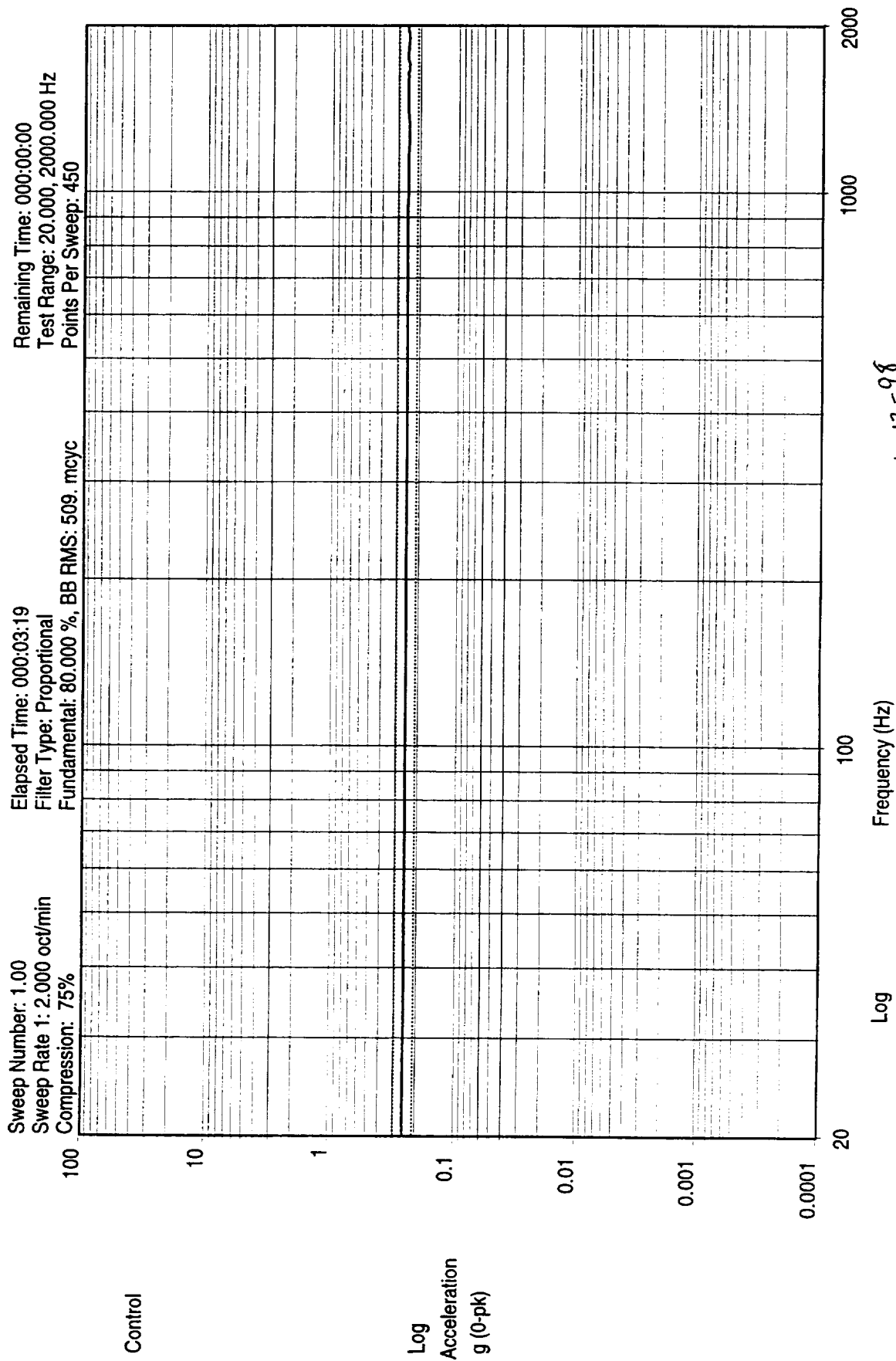
Log
g²/Hz
DOF 120
RMS:
13.797 g

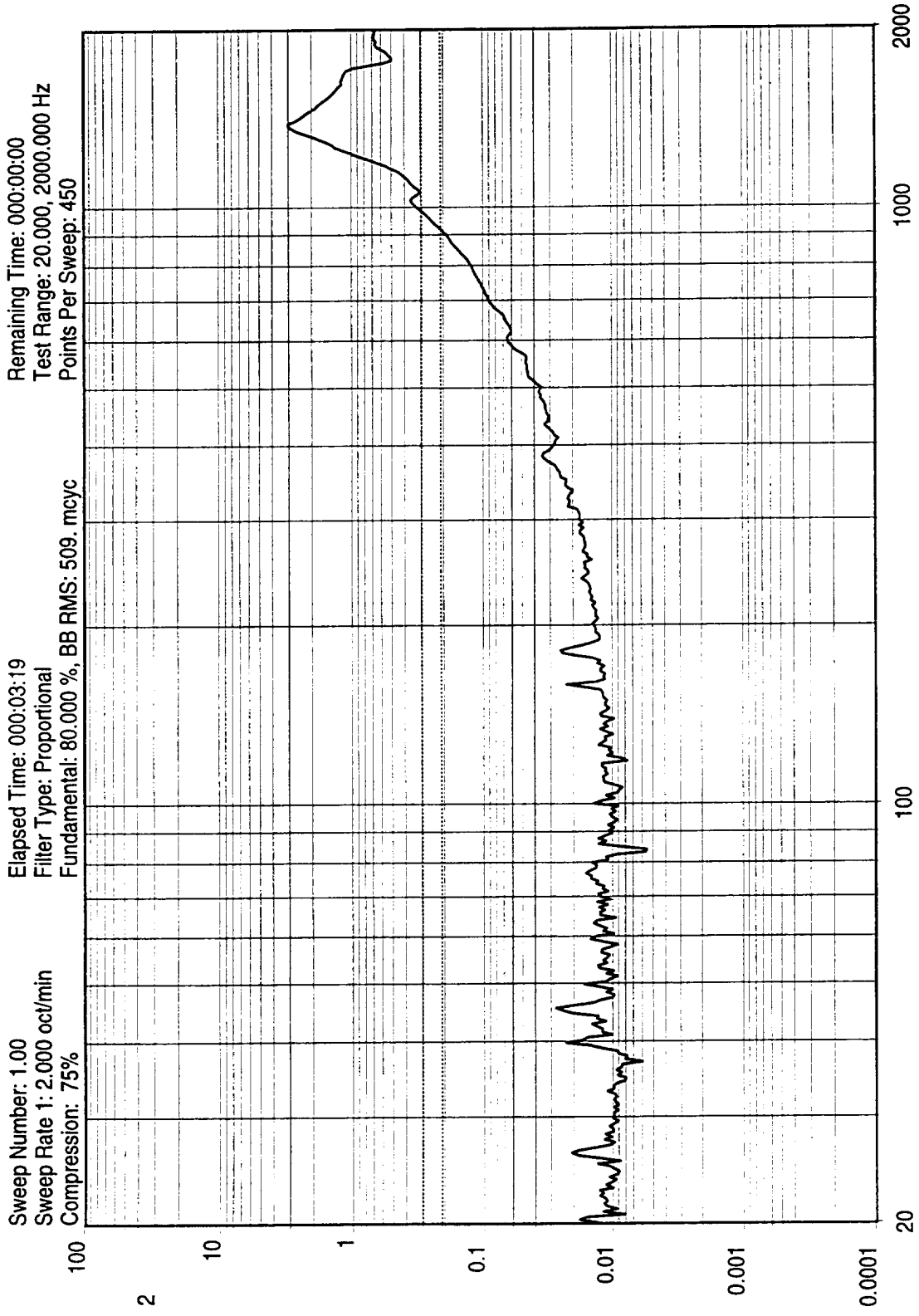
16:46:28
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT
Z AXIS TEST P/N 1348360-1 S/N F09
Test Name: PLO.tmp

UNIT Y AXIS
11-12-98







UNIT X

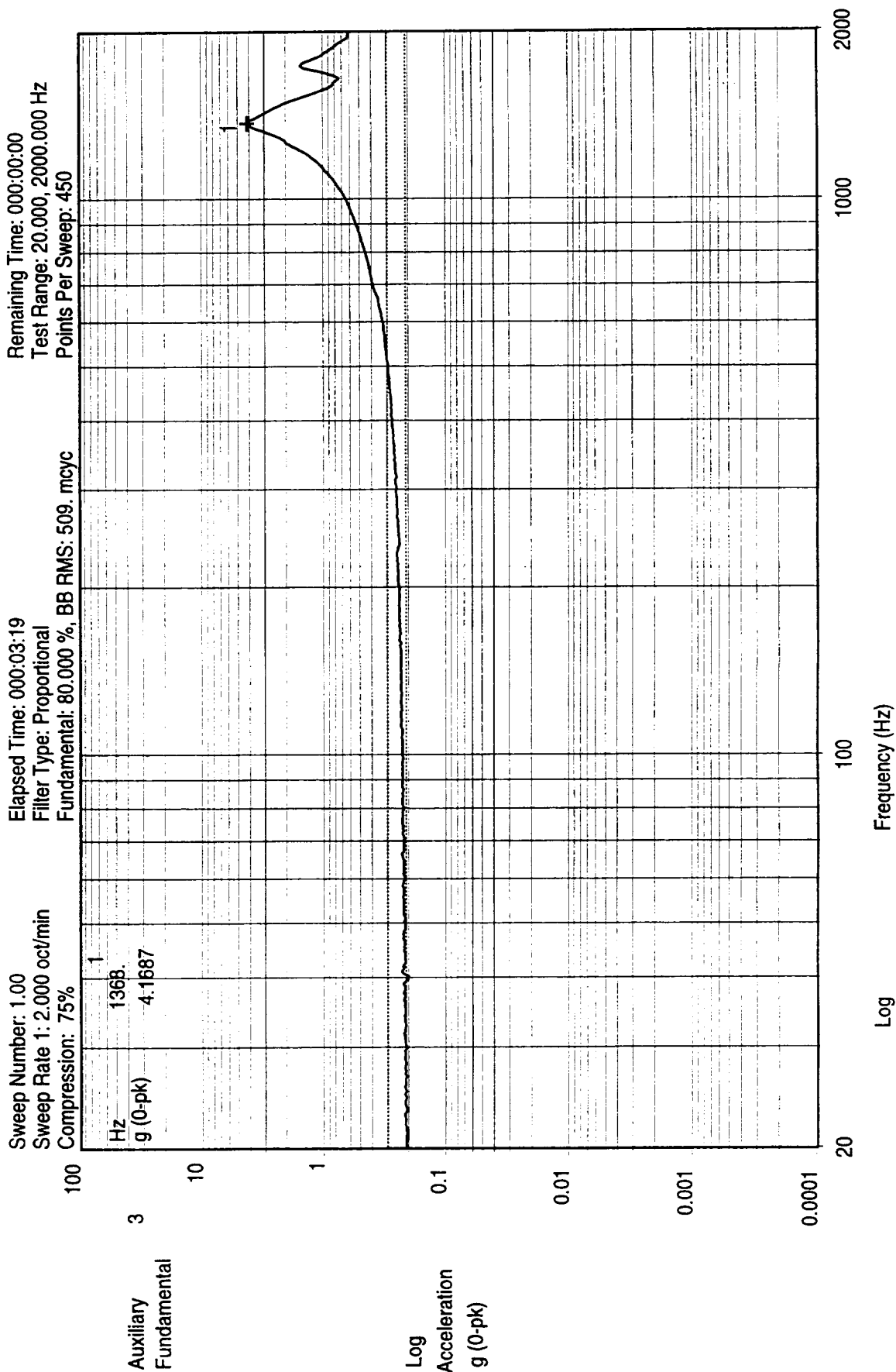
11-12-98

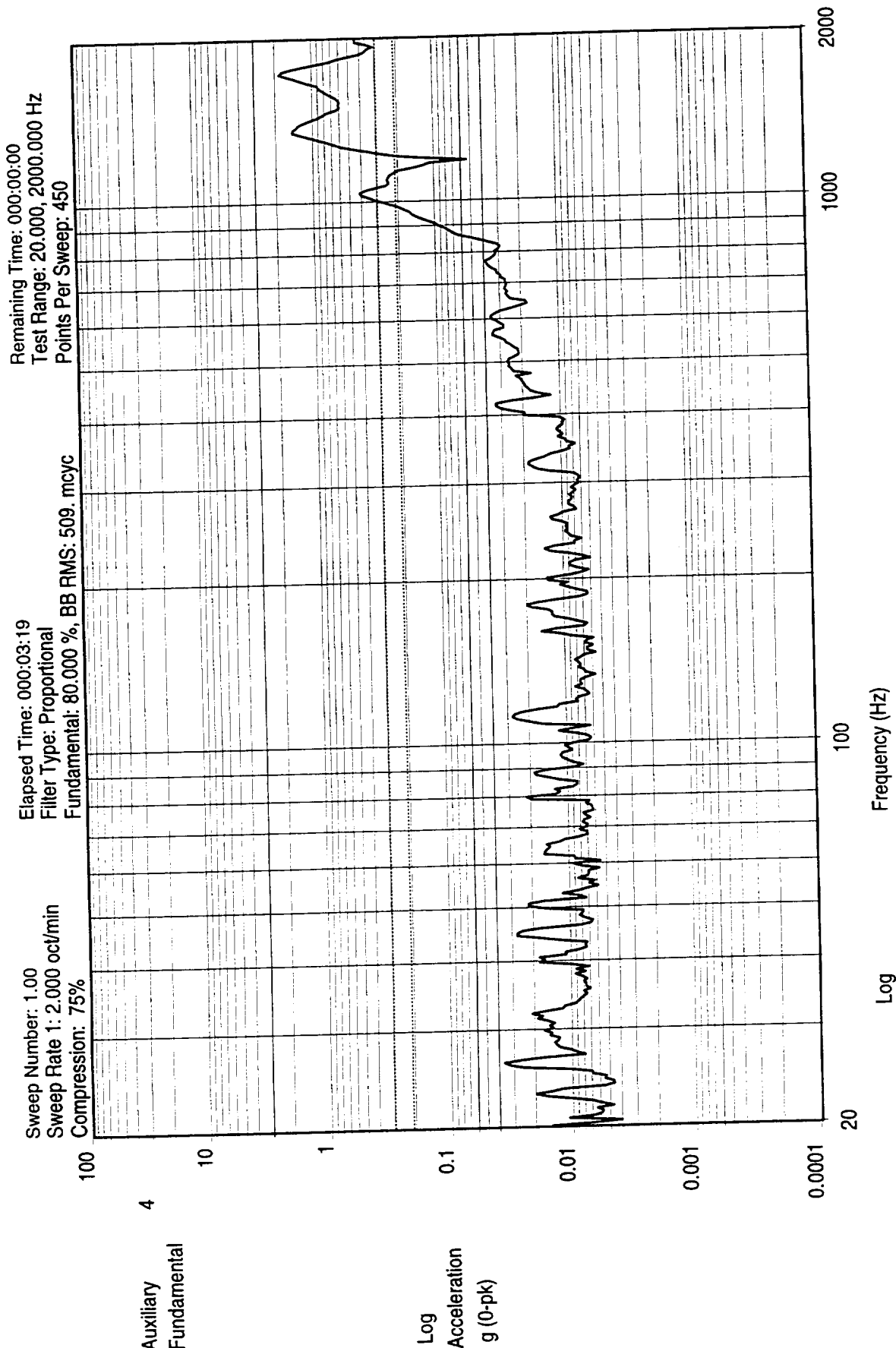
ENG 217 74 187

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
Z AXIS POST SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

16:58:21
12-Nov-1998





AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT
Z AXIS POST SINE SWEEP/N 1348360-1 S/N F09
Sine Test Name: PLO.tmp

11-12-98
ENG 217 197

Section 2B: Acceptance Level Vibration - F10

This section includes the data from the limited functional tests which take place before and throughout vibration, and the vibration-specific. The following table summarizes the results of the limited functional test.

Test	Expected Value	Post X axis	Post Y axis	Post Z axis
Output Frequency	57290344 \pm 200 kHz	57290339 kHz	57290360 kHz	57290376 kHz
Output Power	18.5 dBm \pm 1.5 dB	17.9 dBm	17.9 dBm	17.3 dBm

The following pages contain the raw data.

TEST DATA SHEET 8B
Limited Functional Test (Paragraph 4.2.3)

Post X-Axis LPT

Test Setup Verified: [Signature]
Signature

Paragraph 4.2.3.2:

Step	Test	Required	Measurement	Pass/Fail
3	Potential Difference			
	From	To		
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	1 mVac
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	1 mVac

Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.00 V	PASS
	Voltage Meter 2	-15 ± 0.1 V	-15.02 V	PASS
	Current Meter 1	600 mA max.	534 mA	PASS
	Current Meter 2	100 mA max.	-90. mA	PASS
9	Output Frequency	57.290344 ± .0001 GHz	57.290339	PASS
10	Output Power	18.5 dBm ± 1.5 dB	17.89 dBm	PASS

92 (45/T) 11/4/98

* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

Shop Order No.: 538595
Operation: 0150
Unit Serial No.: F10
Date: 11/4/98

Test Engineer: [Signature]
Quality Control: [Signature] 7A 197 11/4/98
Govt. Rep.: [Signature] 11/5/98

11/4/98
(45/T)

SHEET 82 OF 1956
ECN NO. 1956TEST DATA SHEET 8C
Limited Functional Test (Paragraph 4.2.3)

Post Y-Axis LPT

Test Setup Verified: [Signature]
Signature

Paragraph 4.2.3.2:

Step	Test		Required	Measurement	Pass/Fail
3	Potential Difference				
	From	To			
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	1 mVac	Pass
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	1 mVac	Pass

Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.00 V	Pass
	Voltage Meter 2	-15 ± 0.1 V	-15.08 V	Pass
	Current Meter 1	600 mA max.	535 mA	Pass
	Current Meter 2	100 mA max.	-70 mA	Pass
9	Output Frequency	57.290344 ± .0001 GHz	57.2903360	Pass
10	Output Power	18.5 dBm ± 1.5 dB	17.89 dBm	Pass

* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

Shop Order No.: 538595
 Operation: 0150
 Unit Serial No.: F10
 Date: 11/4/98

Test Engineer: [Signature]
 Quality Control: [Signature] 7A 197 11/4/98
 Govt. Rep.: [Signature] 11/4/98

11/4/98
45

TEST DATA SHEET 8D
Limited Functional Test (Paragraph 4.2.3)

Post Z-Axis LPT

Test Setup Verified: *[Signature]*
Signature

Paragraph 4.2.3.2:

Step	Test	Required	Measurement	Pass/Fail
3	Potential Difference			
	From	To		
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	1mVac
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	1mVac

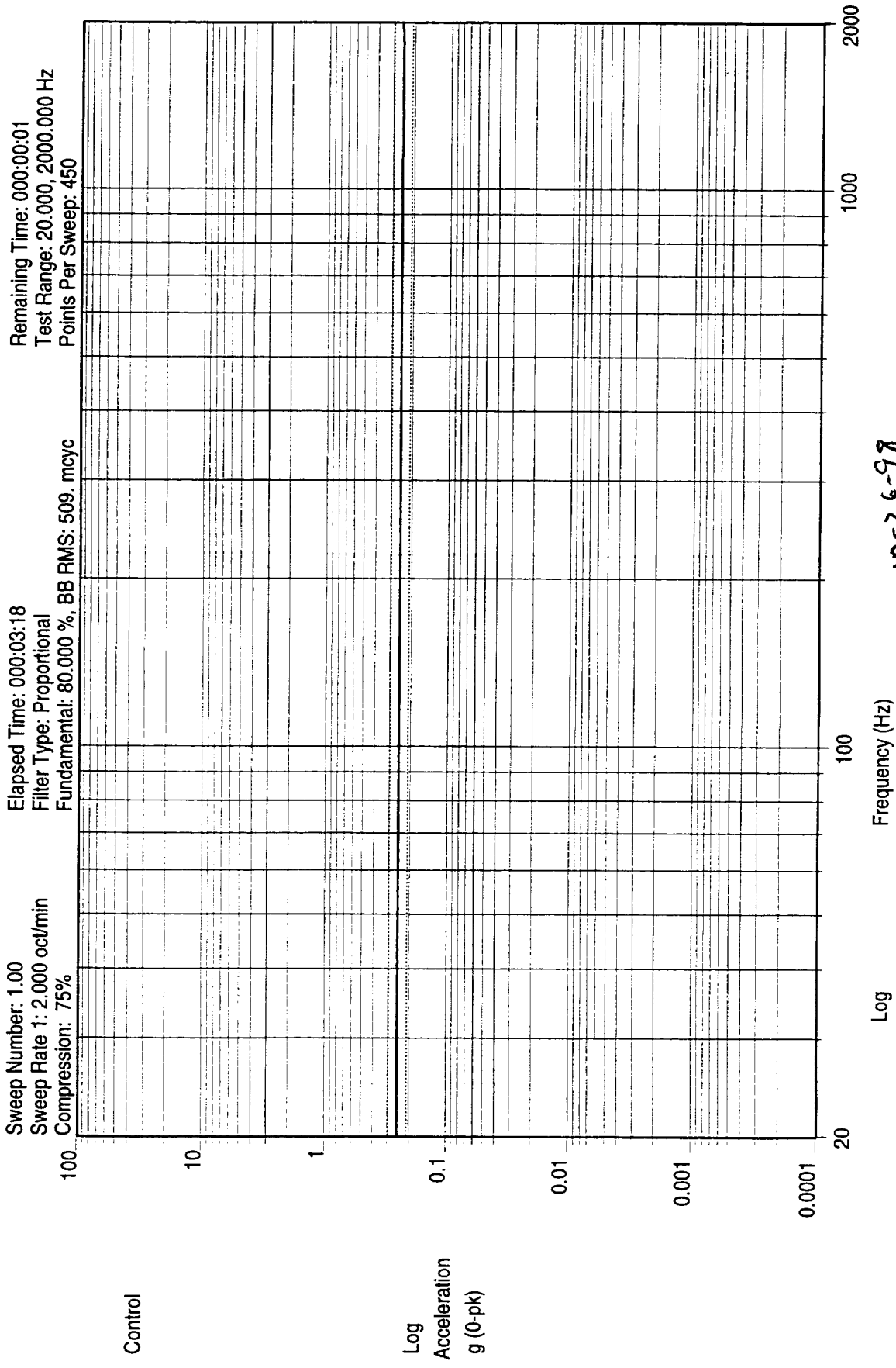
Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.01 V	PASS
	Voltage Meter 2	-15 ± 0.1 V	-15.05 V	PASS
	Current Meter 1	600 mA max.	535 mA	PASS
	Current Meter 2	100 mA max.	70 mA	PASS
9	Output Frequency	57.290344 ± .0001 GHz	57.2903376 GHz	PASS
10	Output Power	18.5 dBm ± 1.5 dB	17.26 dBm	PASS

* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

11/4/98

Shop Order No.: 538595
Operation: 0150
Unit Serial No.: F10
Date: 11/4/98

Test Engineer: *[Signature]*
Quality Control: 11/4/98
Govt. Rep.: *[Signature]* 11/5/98



10-26-98
ENG 217
EOL
24
267

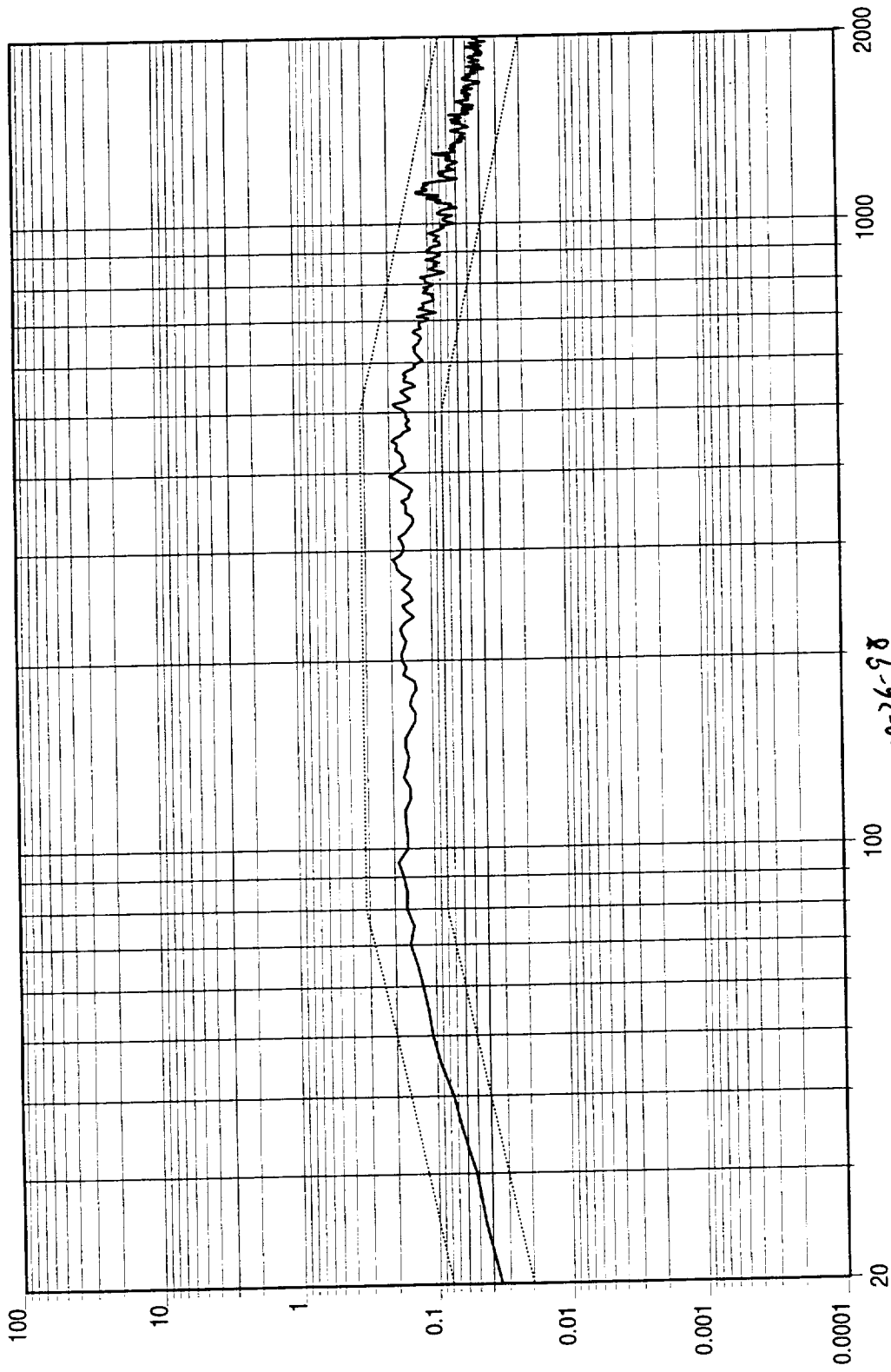
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
Y AXIS SYSTEM CHECKOUT P/N 1348360-1 S/N F10
Sine Test Name: PLO.tmp

10:09:36
26-Oct-1998

Test Level: 0.000 dB
Test Time: 000:01:13

Reference RMS: 13.576
Clipping: Off

Test Range: 20.000, 2000.000 Hz
Resolution: 5.000 Hz



09:59:42
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O534921-534922
Y AXIS SYSTEM CHECKOUT P/N 1348360-1 9NF08 ,F10

Test Name: PLO.tmp

10-26-98

ENG
217

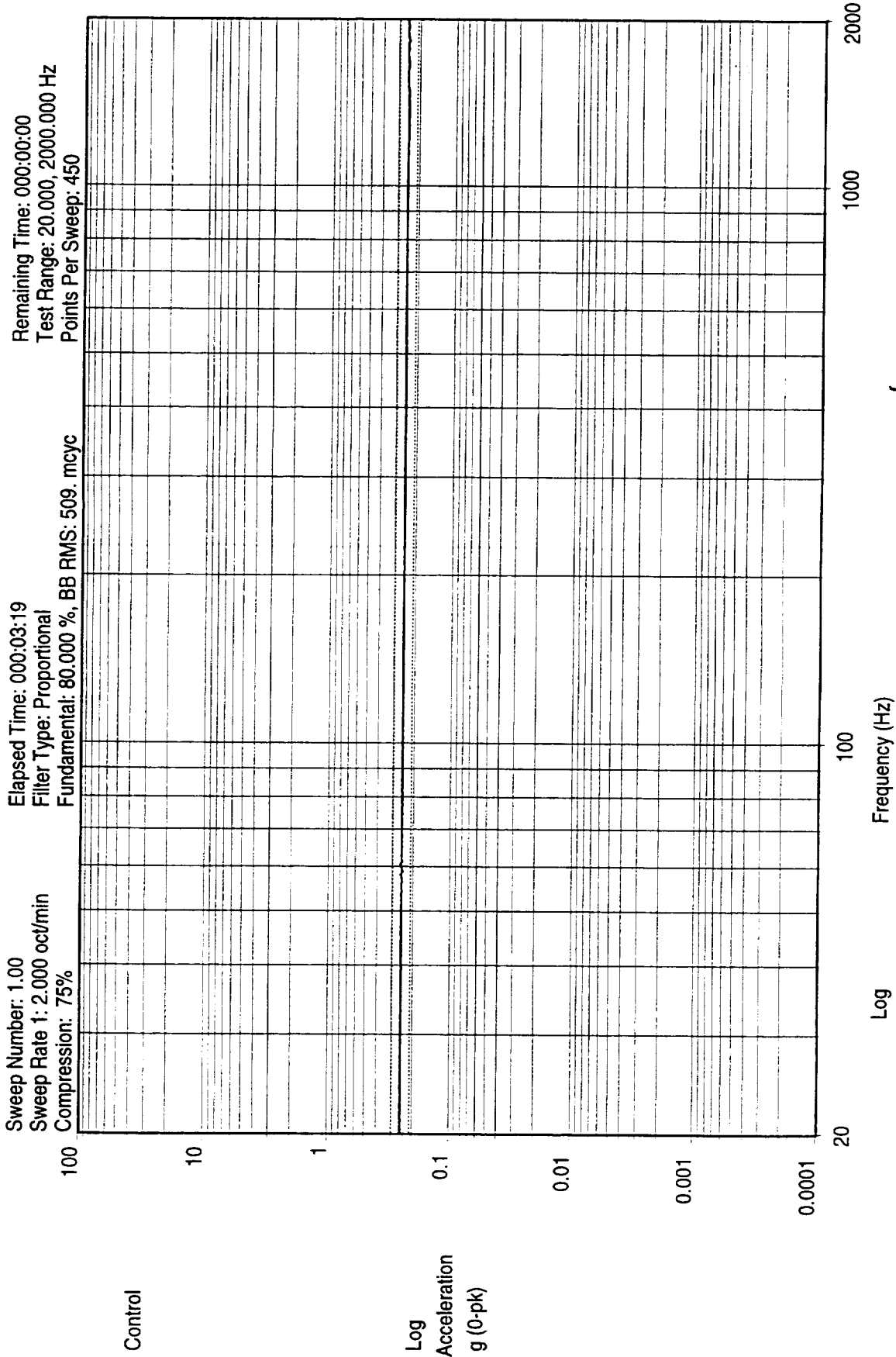
FOI

PA
P67

10-26-98

ENG
217

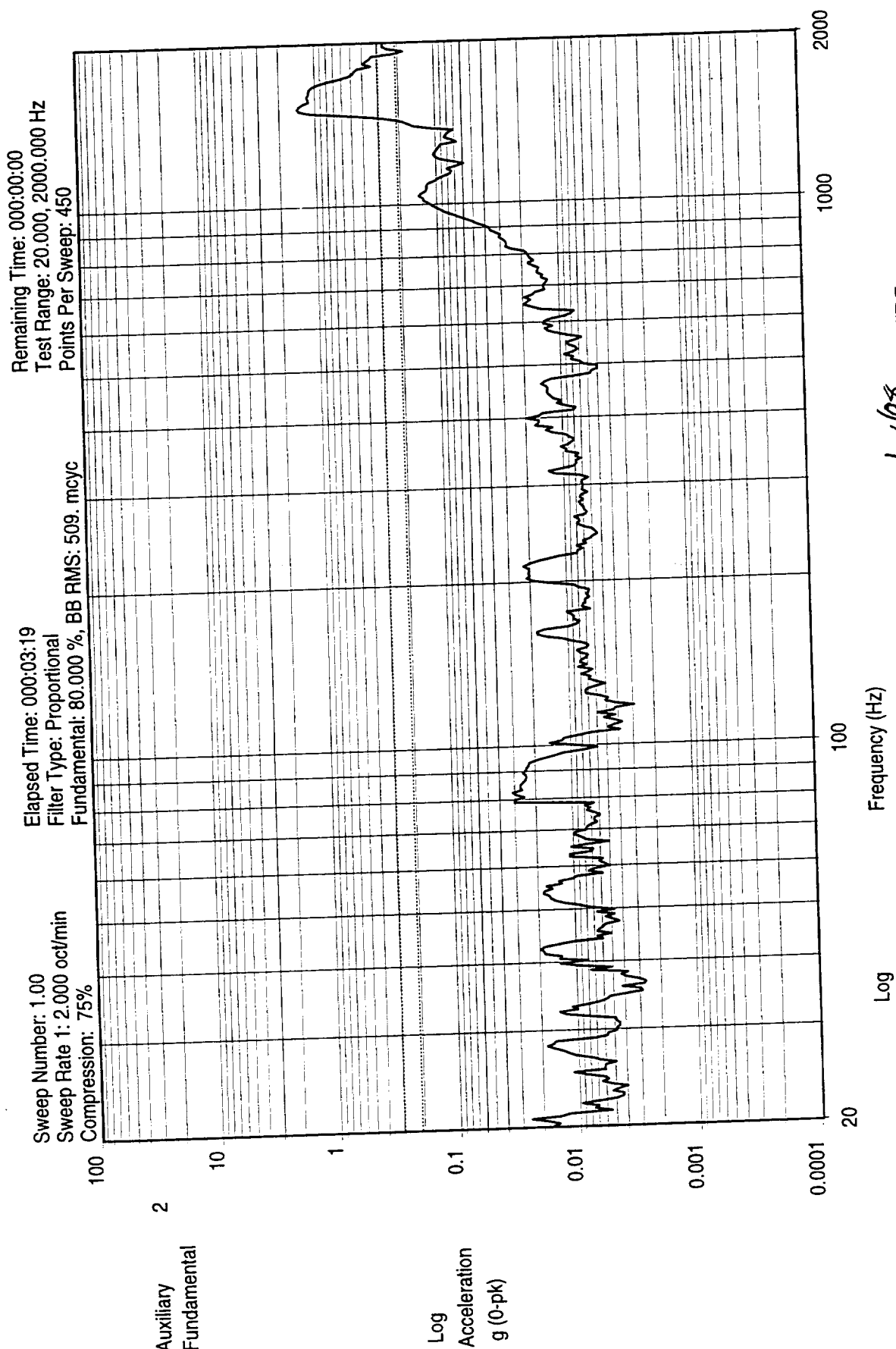
538595



11:32:04
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
PRE Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10
Sine Test Name: PLO.tmp

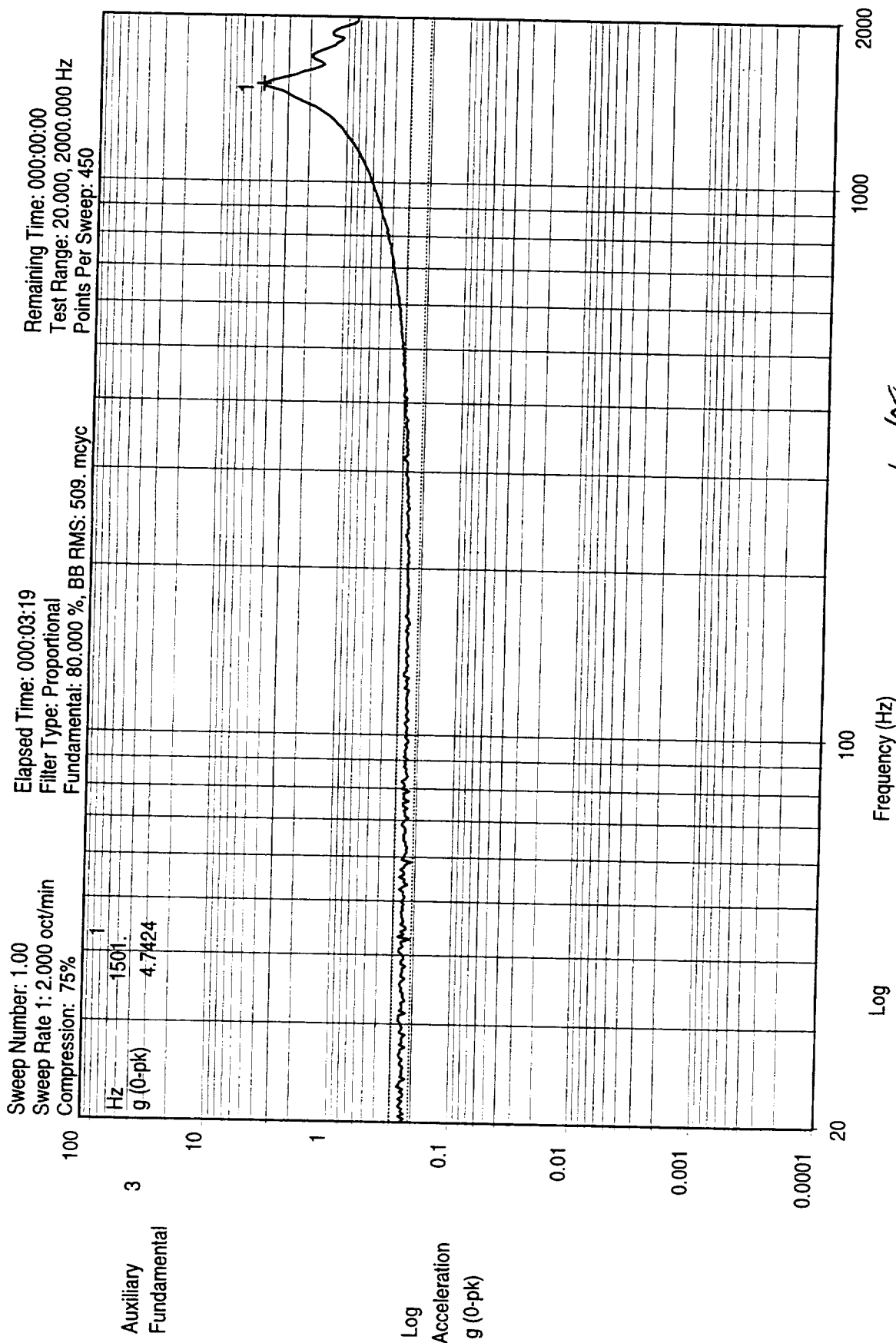
10/26/98
ENG 217
E.O.Z
492
K2



10/26/98 UNIT Z
ENG 217
EOL
7A
267

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
PRE Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10
Sine Test Name: PLO.tmp

11:32:09
26-Oct-1998

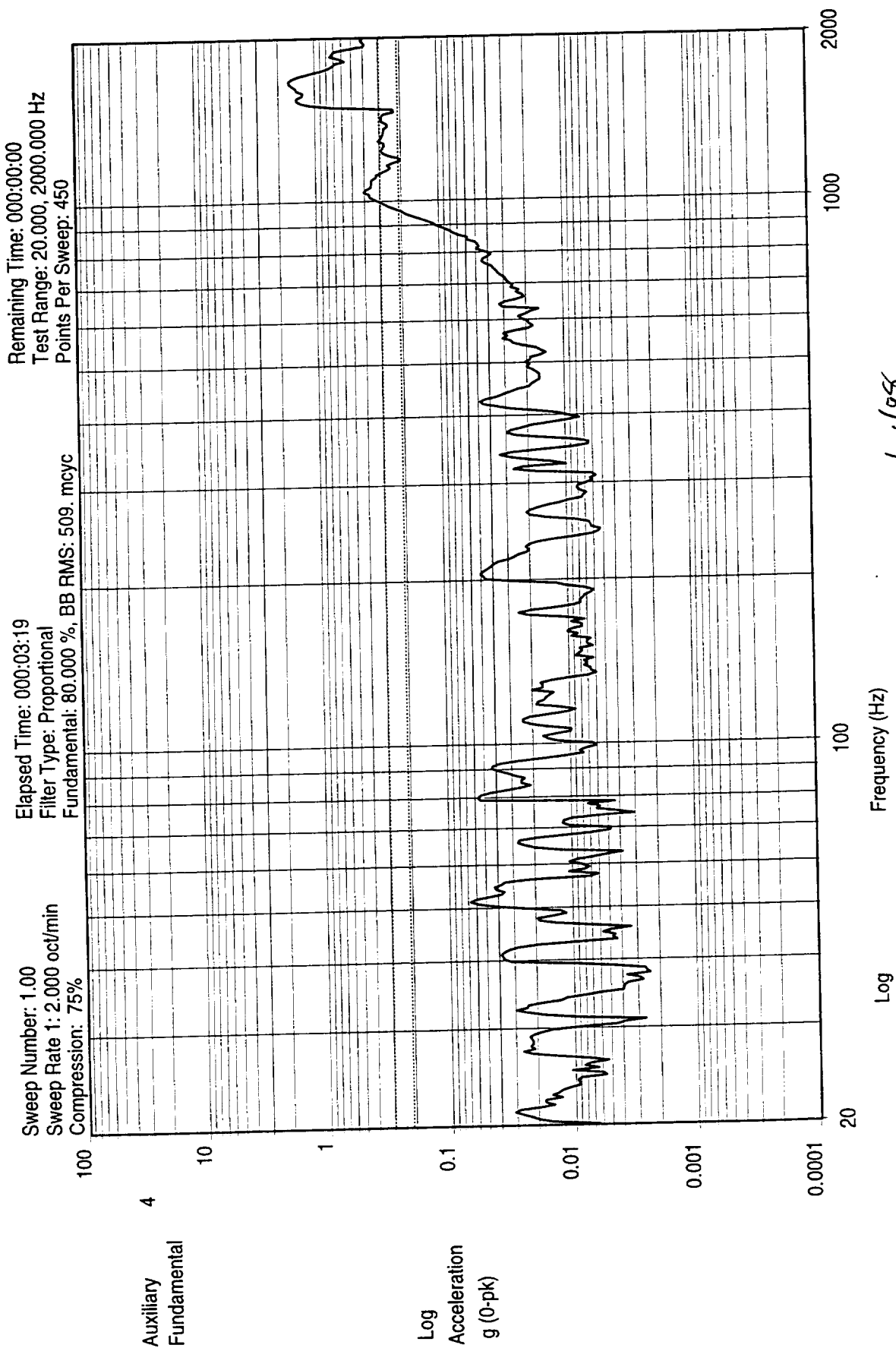


UNIT Y

10/26/98
 ENG 217
 EOI 74 267

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 PRE Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10
 Sine Test Name: PLO.tmp

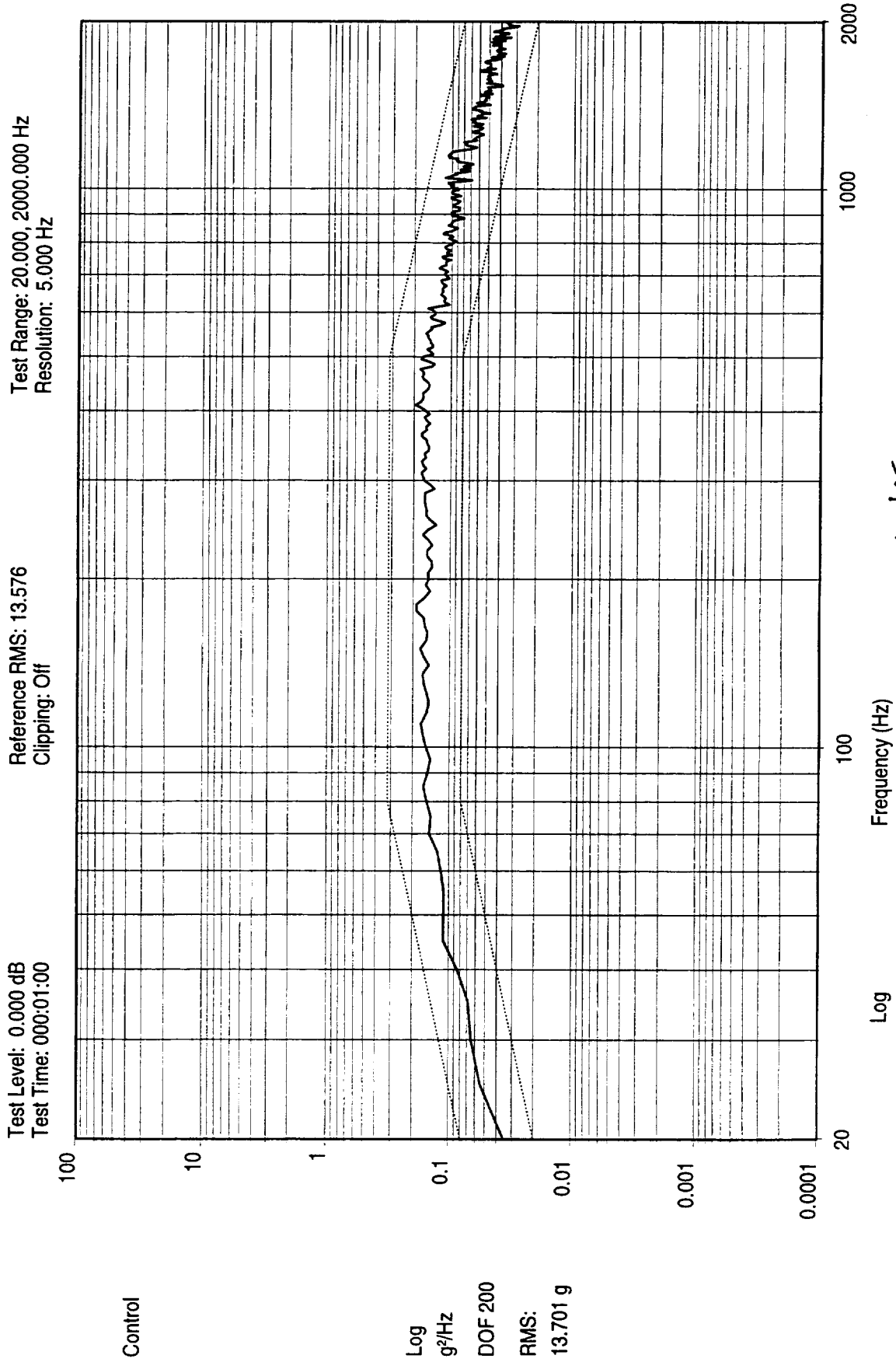
11:34:15
 26-Oct-1998



11:32:54
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
PRE Y AXIS SINE SWEEP TEST P/N 1348360-1 SIN F10
Sine Test Name: PLO.tmp

10/26/98 UNIT X
ENG 217
EOL 24 267



11:45:44
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O538595
Y AXIS TEST P/N 1348360-1 S/N,F10
Test Name: PLO.tmp

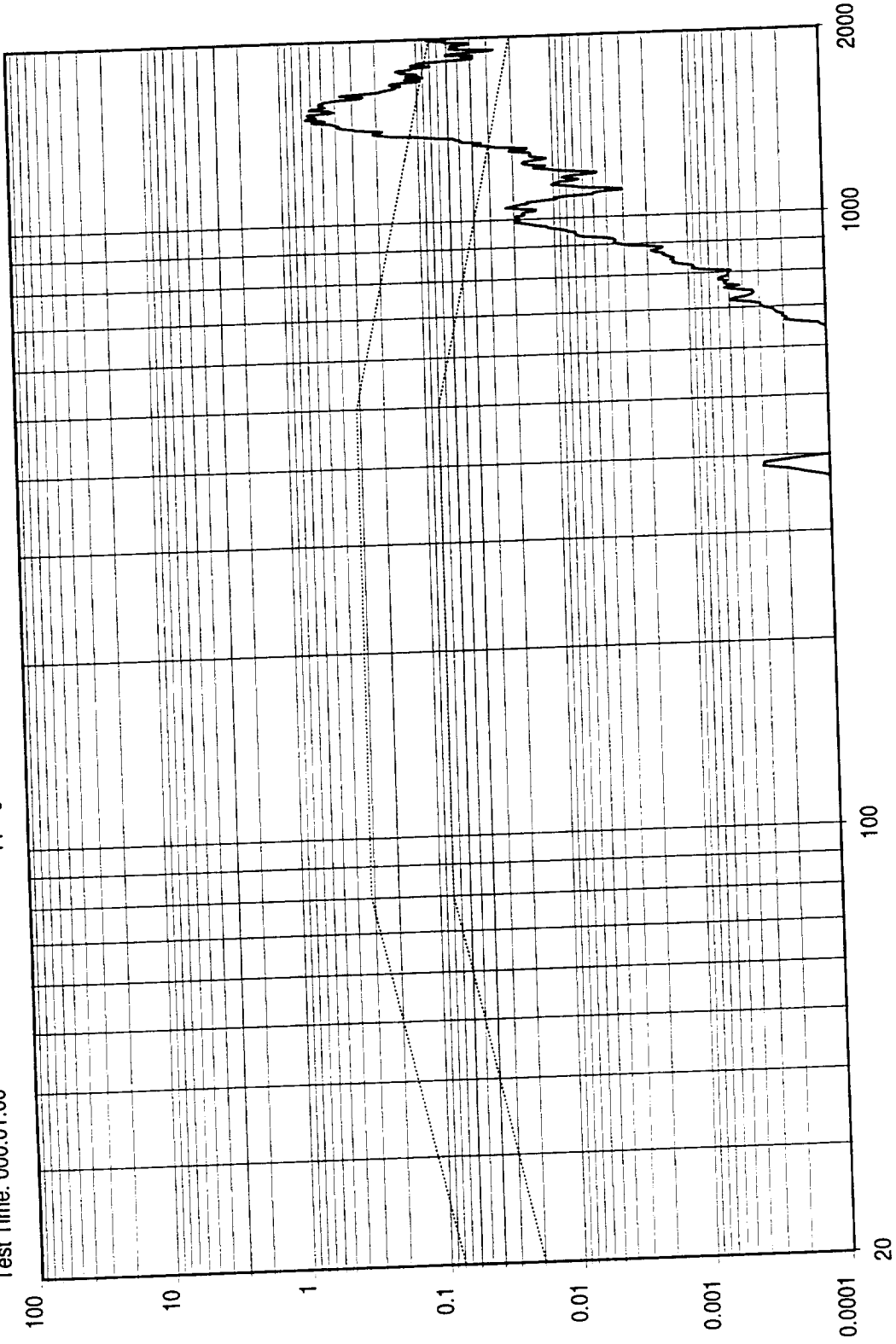
ENG
217

10/26/98
EOT
7A
267

Test Range: 20.000, 2000.000 Hz
Resolution: 5.000 Hz

Reference RMS: 13.576
Clipping: Off

Test Level: 0.000 dB
Test Time: 000:01:00



Auxiliary 2

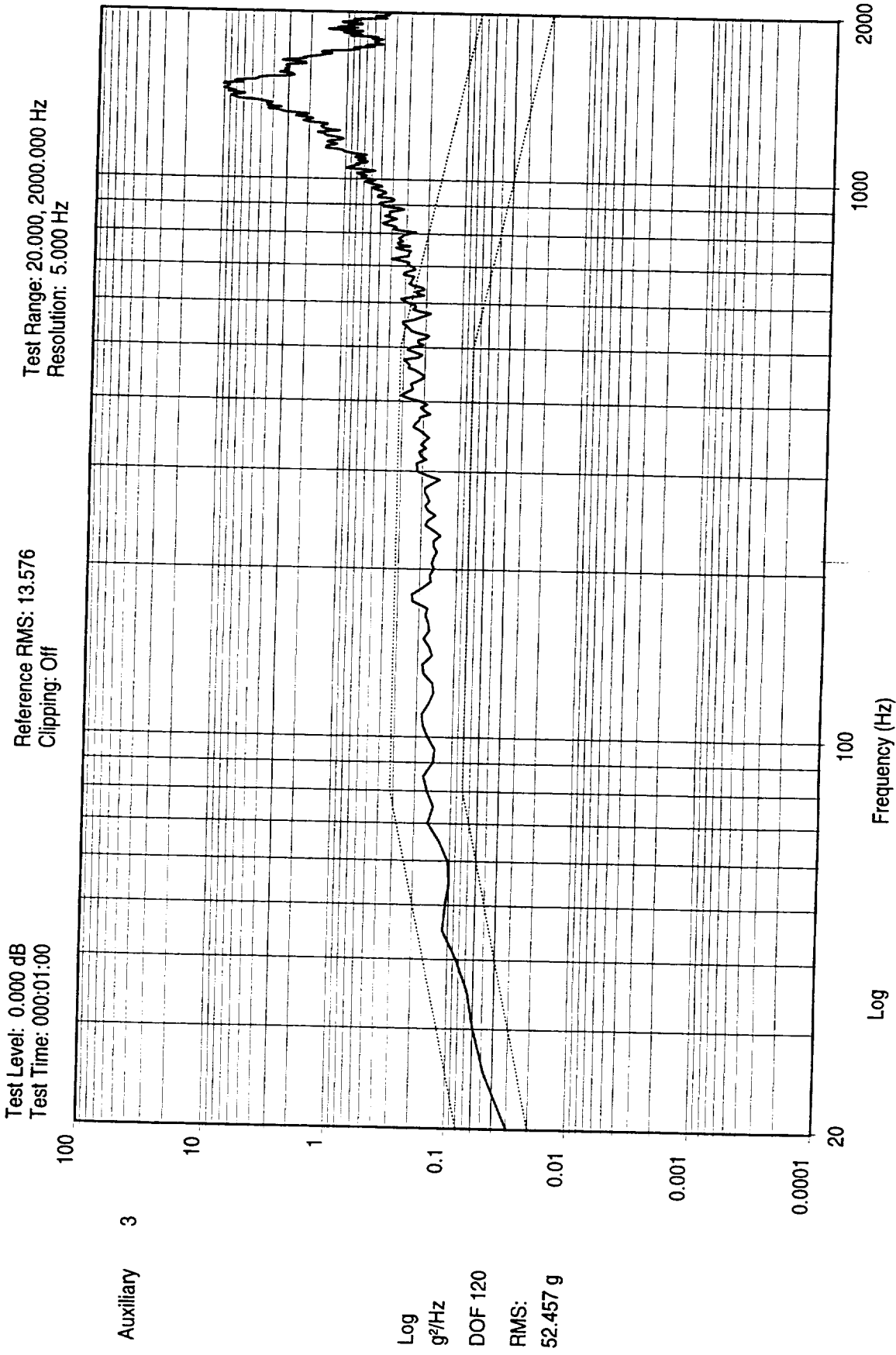
Log
g²/Hz
DOF 120
RMS:
12.066 g

Log
Frequency (Hz)

10/26/98
ENG 217
24 OCT

AMSU PHASE LOCK OSCILLATOR S/O538595
Y AXIS TEST P/N 1348360-1 S/N,F10
Test Name: PLO.tmp

11:45:49
26-Oct-1998

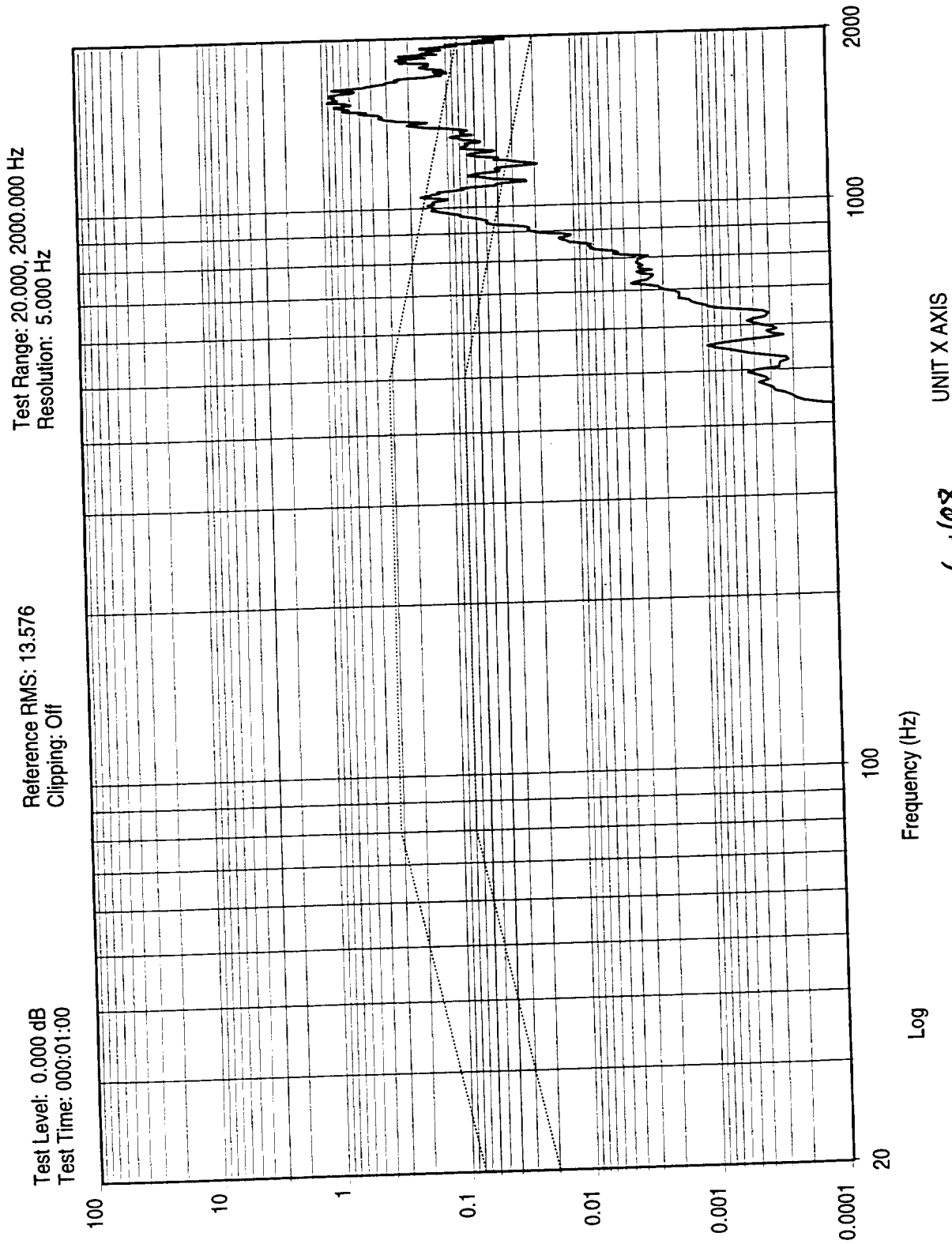


UNIT Y AXIS

10/26/98
ENG 217
EOL
287

AMSU PHASE LOCK OSCILLATOR S/O538595
Y AXIS TEST P/N 1348360-1 S/N ,F10
Test Name: PLO.tmp

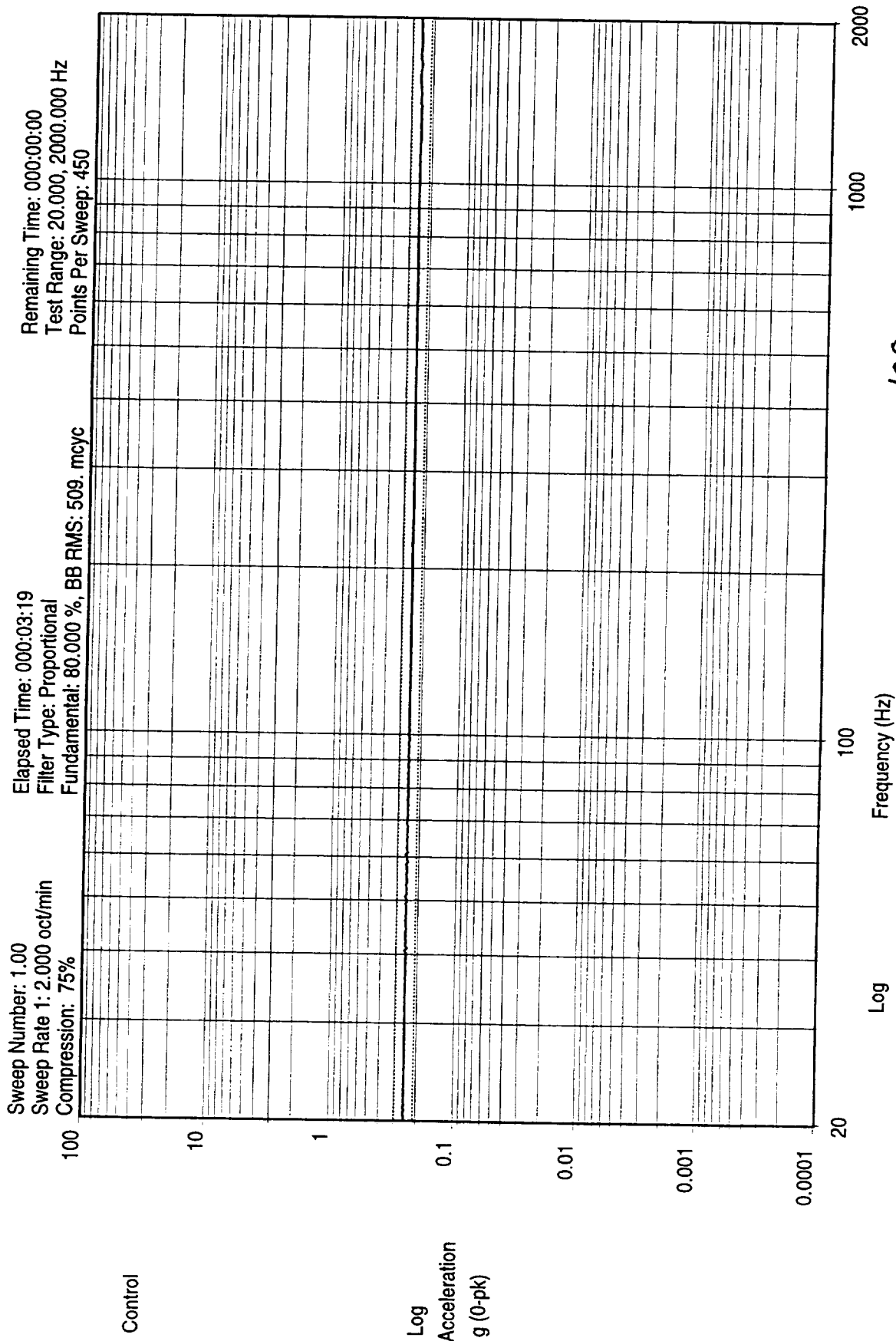
11:45:53
26-Oct-1998



11:45:57
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O538595
Y AXIS TEST P/N 1348360-1 S/N ,F10
Test Name: PLO.tmp

10/26/98
ENG 217
EOT
7A
262



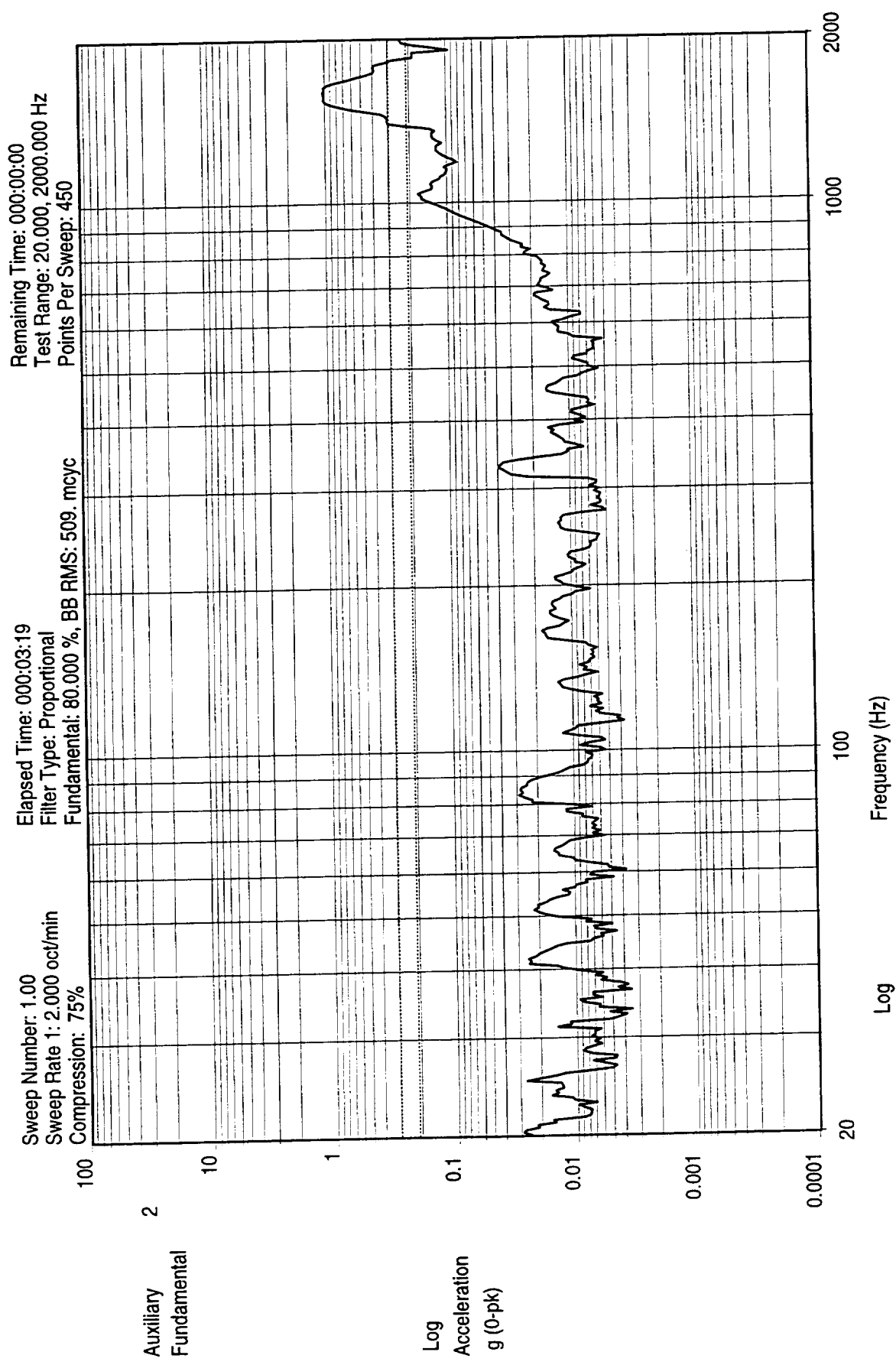
11:55:30
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
POST Y AXIS SINE SWEEP TEST P/N 1348360-1 SIN F10
Sine Test Name: PLO.tmp

ENG 217
217

10/26/98

267



UNIT Z

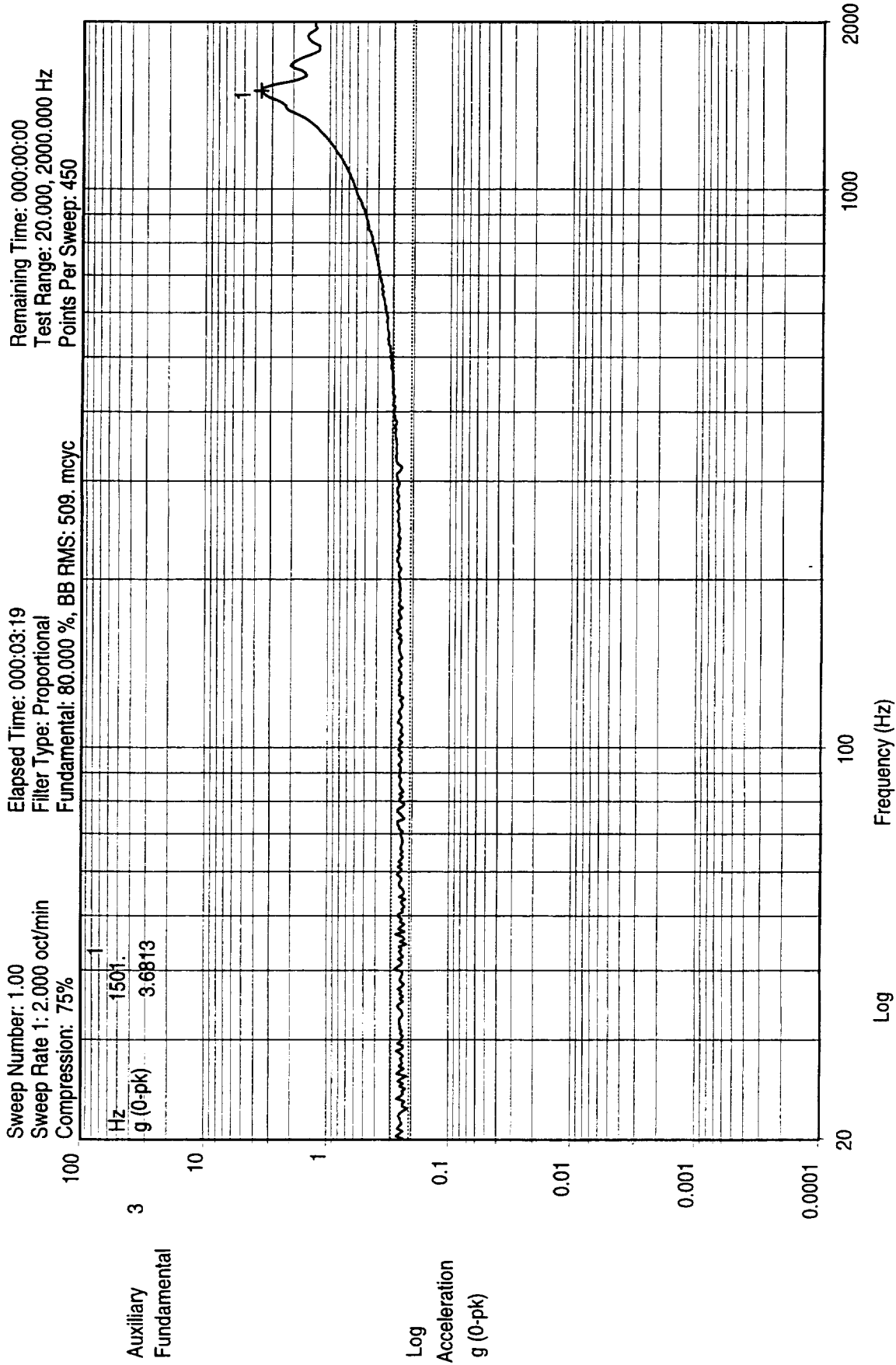
10/26/98

ENG 217
EOT 267

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
POST Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

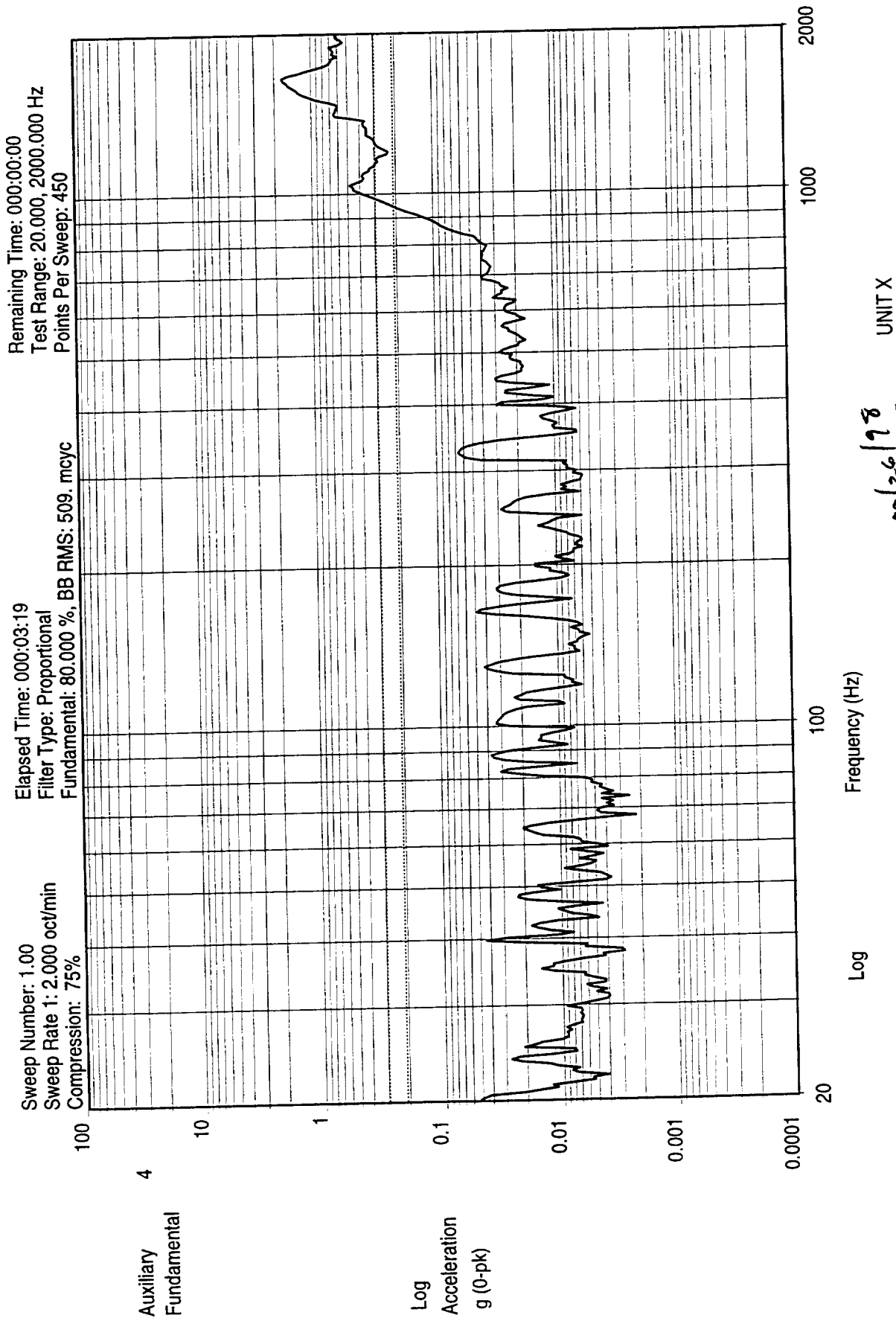
11:55:34
26-Oct-1998



11:57:50
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 POST Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10
 Sine Test Name: PLO.tmp

10/26/98
 ENG 217
 EOI
 2A
 267
 UNIT Y



11:55:42
26-Oct-1998

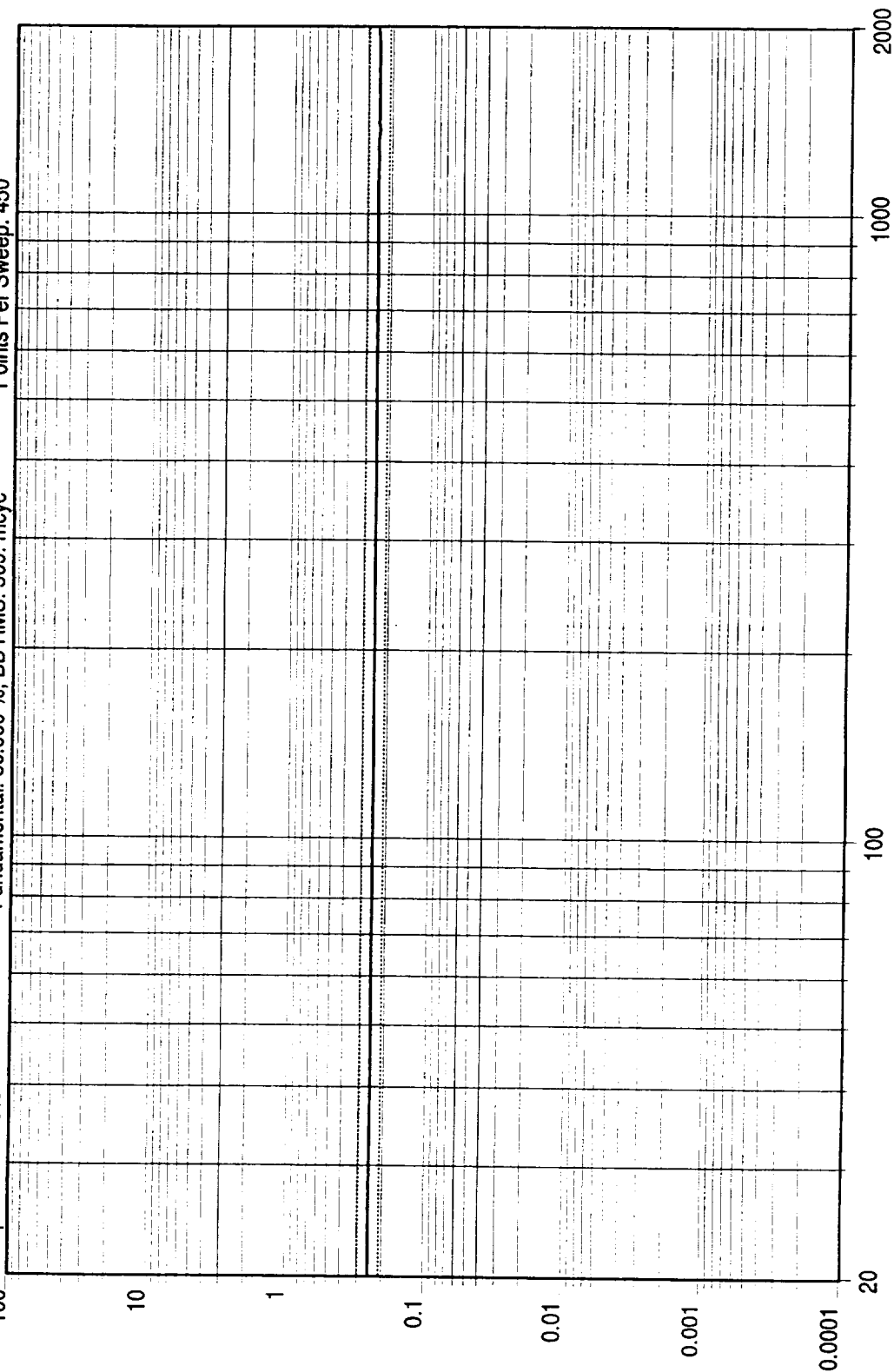
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
POST Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10
Sine Test Name: PLO.tmp

10/26/98
EOT
ENG 217
FA 257

Sweep Number: 1.00
Sweep Rate 1: 2.000 oct/min
Compression: 75%

Elapsed Time: 000:03:19
Filter Type: Proportional
Fundamental: 80.000 %, BB RMS: 509. mcyc

Remaining Time: 000:00:00
Test Range: 20.000, 2000.000 Hz
Points Per Sweep: 450

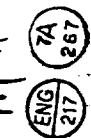


Control

Log
Acceleration
g (0-pk)

Log
Frequency (Hz)

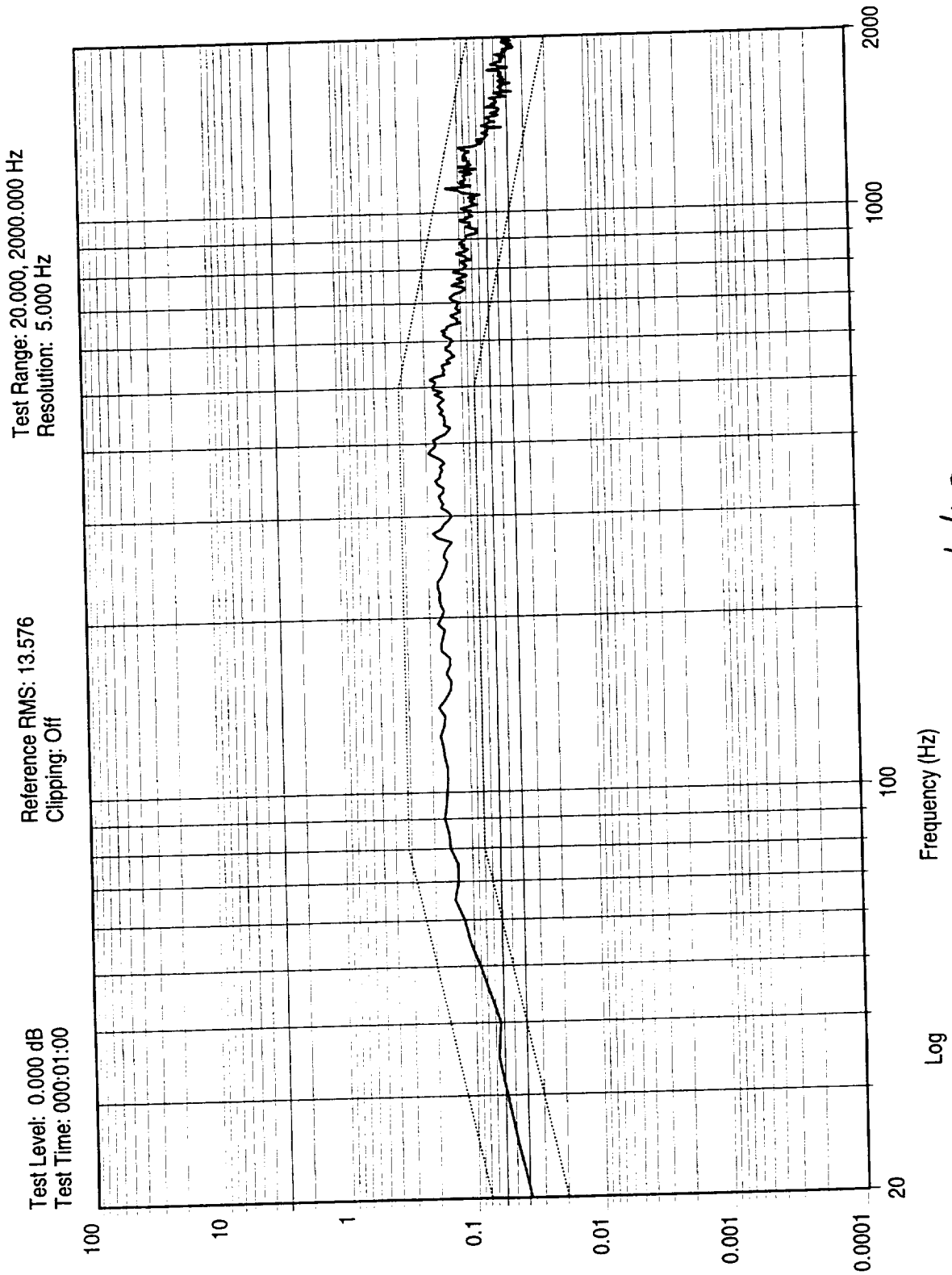
11/4/98



AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
Y AXIS SYSTEM CHECKOUT P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

10:47:55
04-Nov-1998



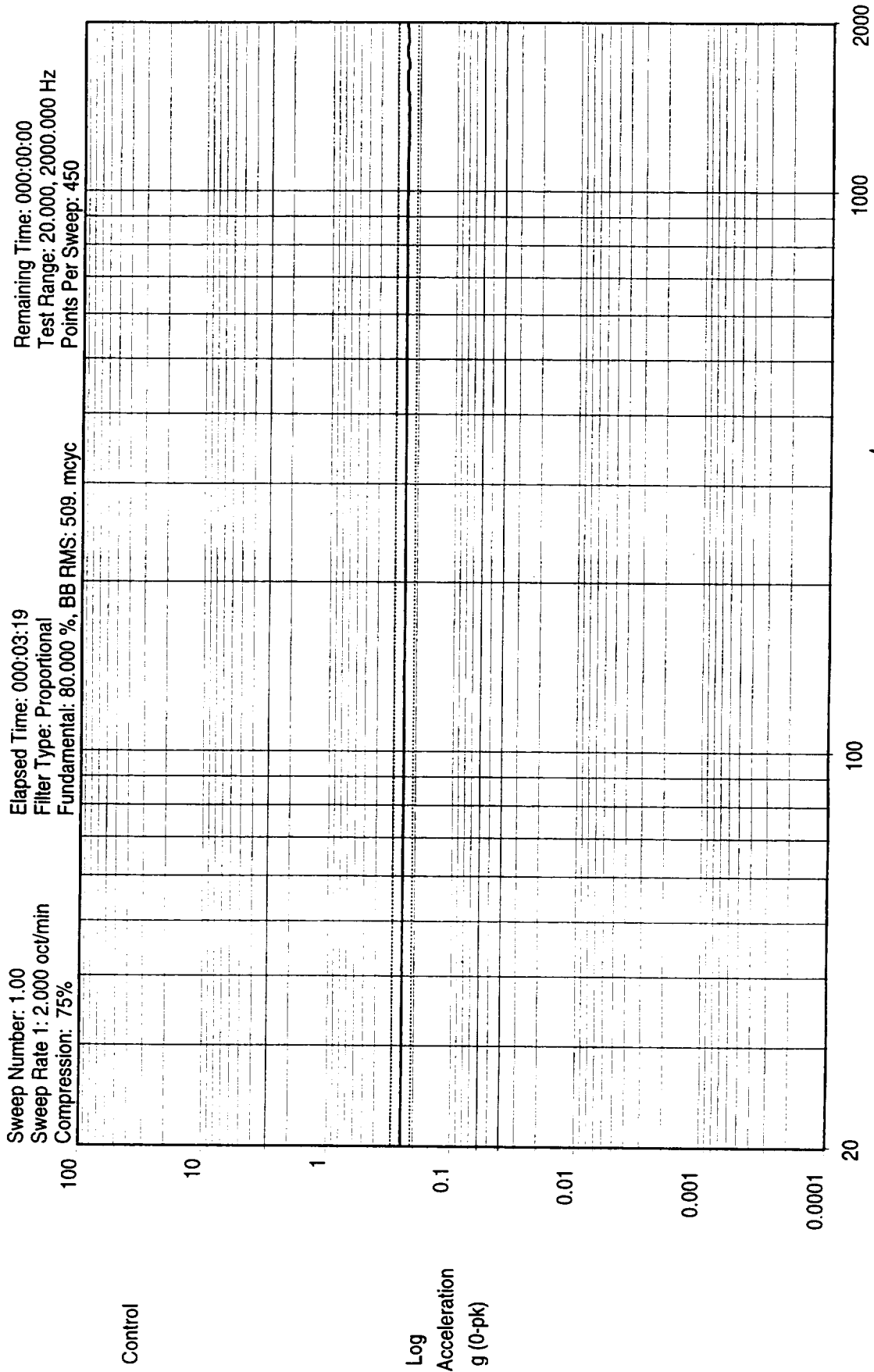
11/4/98

ENG 217

1A 261

AMSU PHASE LOCK OSCILLATOR S/O538595
Y AXIS SYSTEM CHECKOUT P/N 1348360-1 S/N, F10
Test Name: PLO.tmp

10:56:02
04-Nov-1998



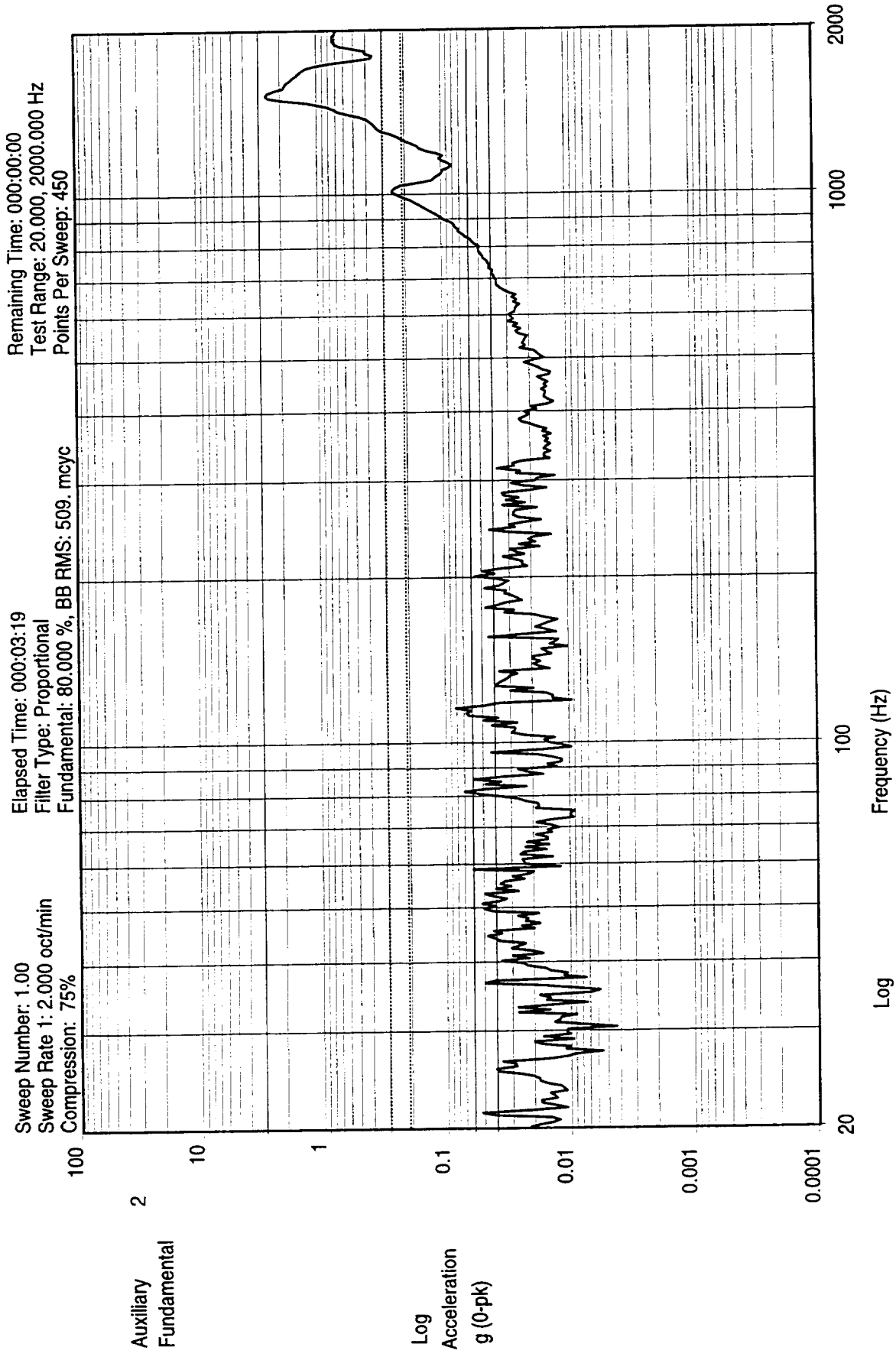
11/4/98

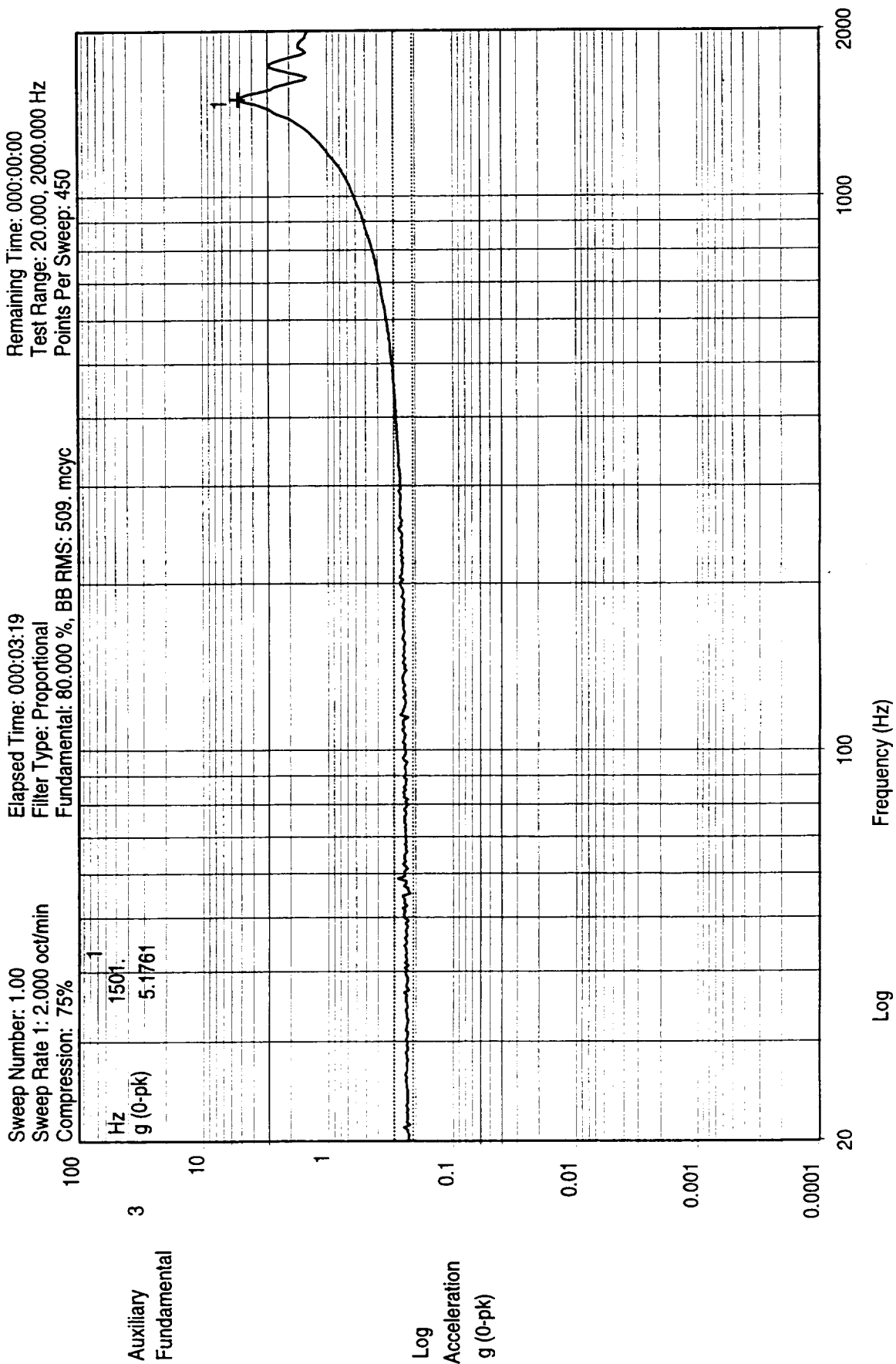
ENG 217

1A 261

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
Y AXIS TEST P/N 1348360-1 S/N F10
Sine Test Name: PLO.tmp

14:22:27
04-Nov-1998





UNIT Y

11-4-98



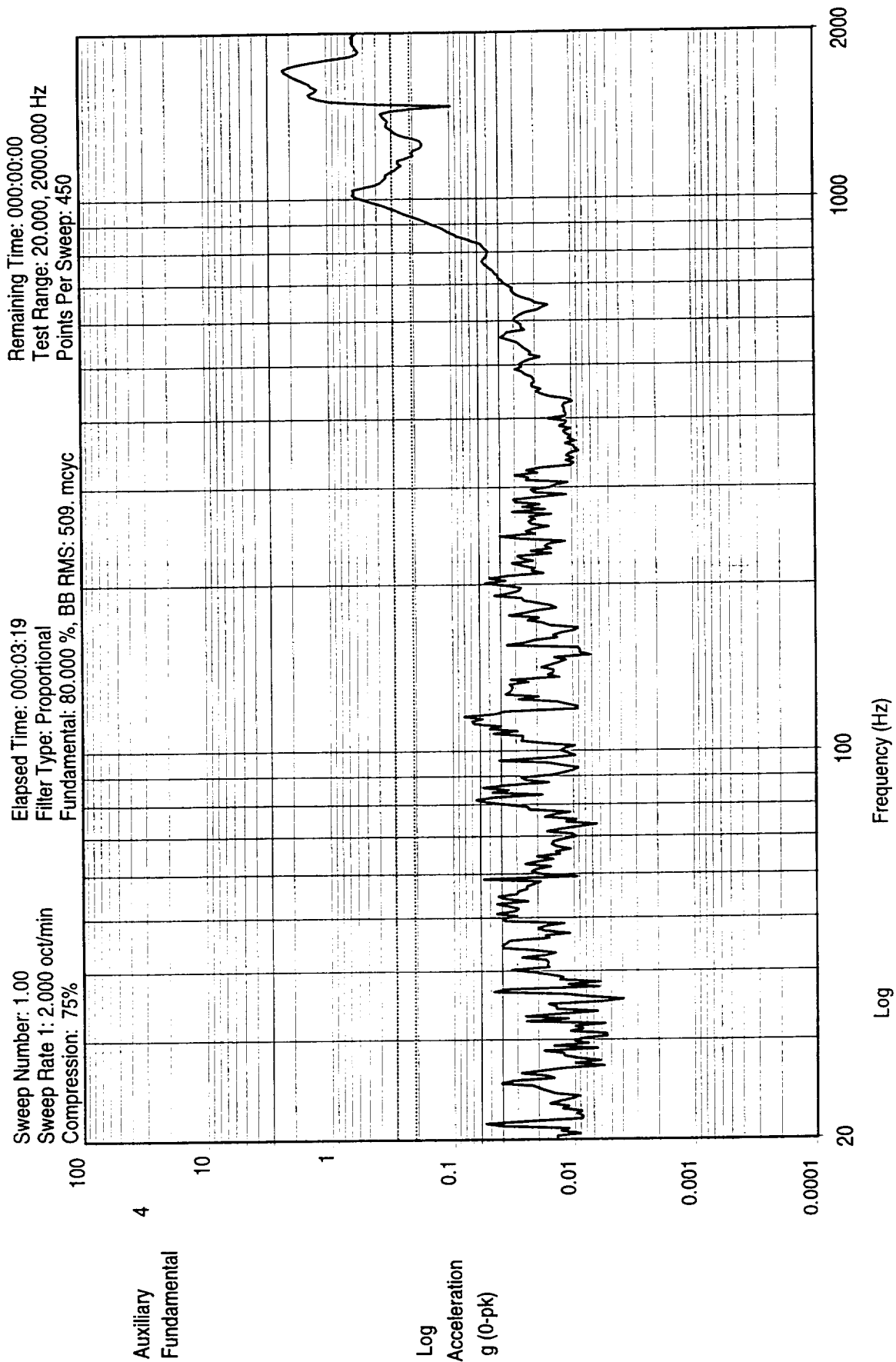
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10

Y AXIS TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

14:22:41

04-Nov-1998



UNIT X

11-4-98

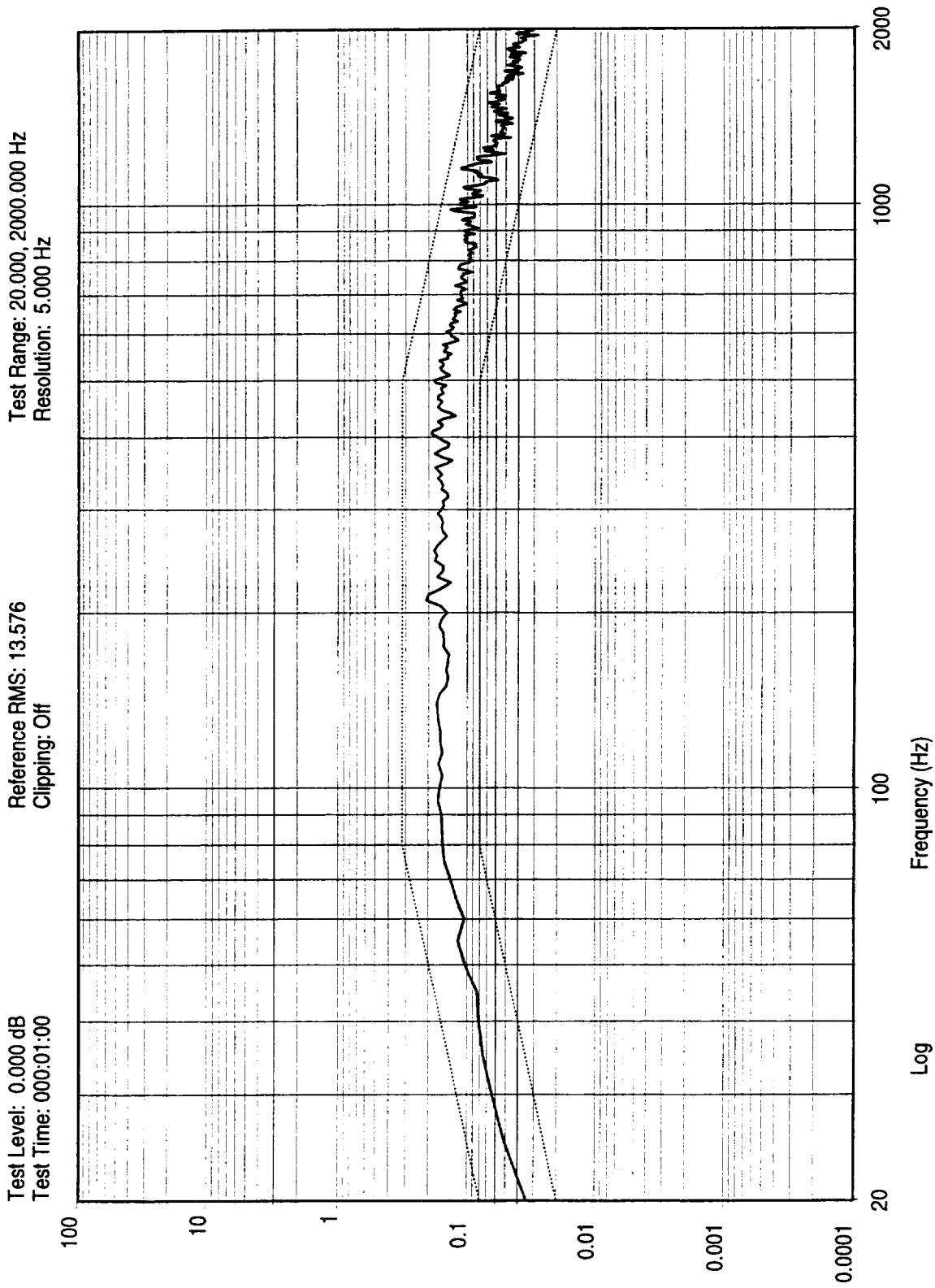
ENG
217

TA
267

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 Y AXIS TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

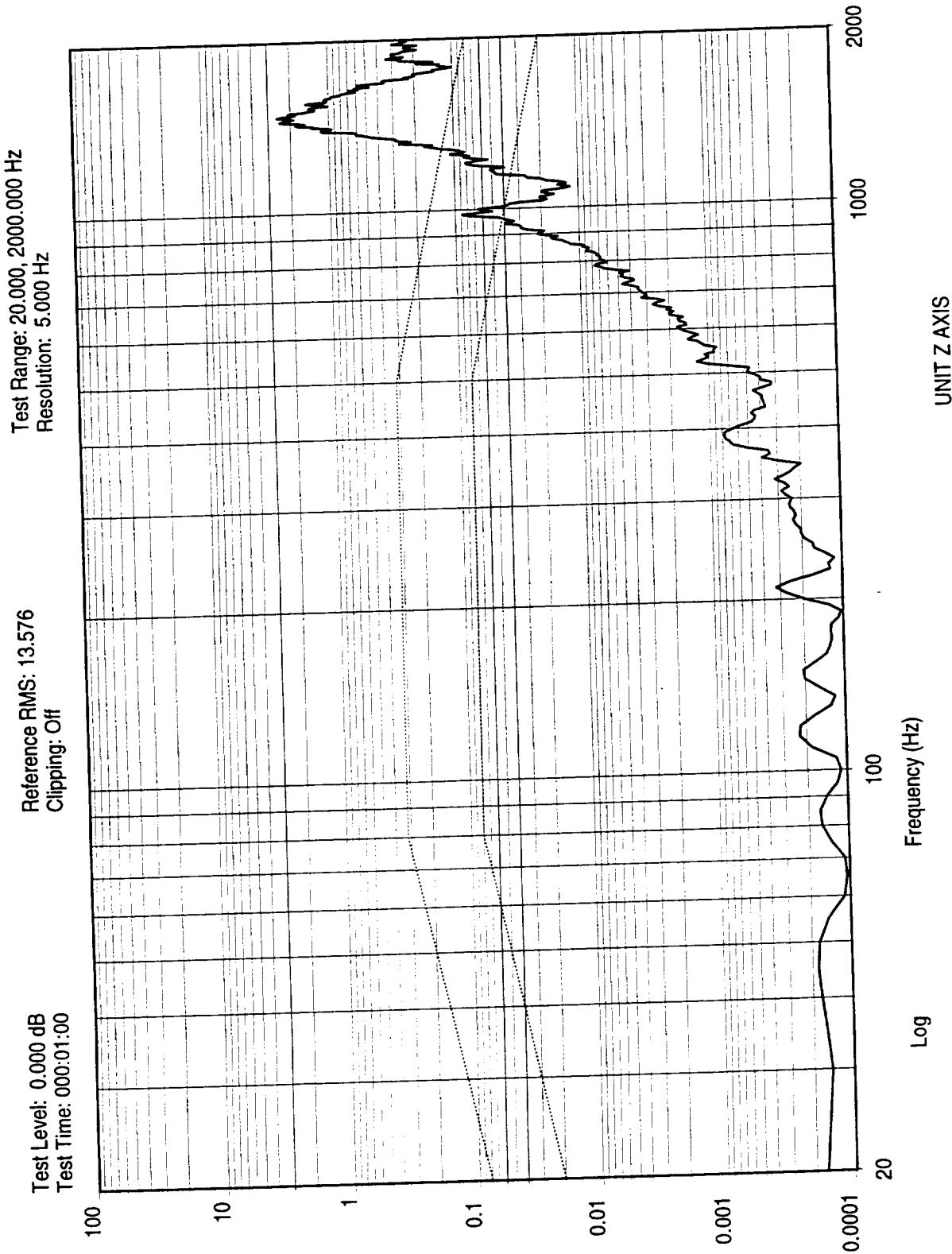
14:22:45
 04-Nov-1998



14:41:59
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538595
Y AXIS TEST P/N 1348360-1 S/N ,F10
Test Name: PLO.tmp

11-4-98
ENG 217
7A 267



AMSU PHASE LOCK OSCILLATOR S/O538595
Y AXIS TEST P/N 1348360-1 S/N,F10

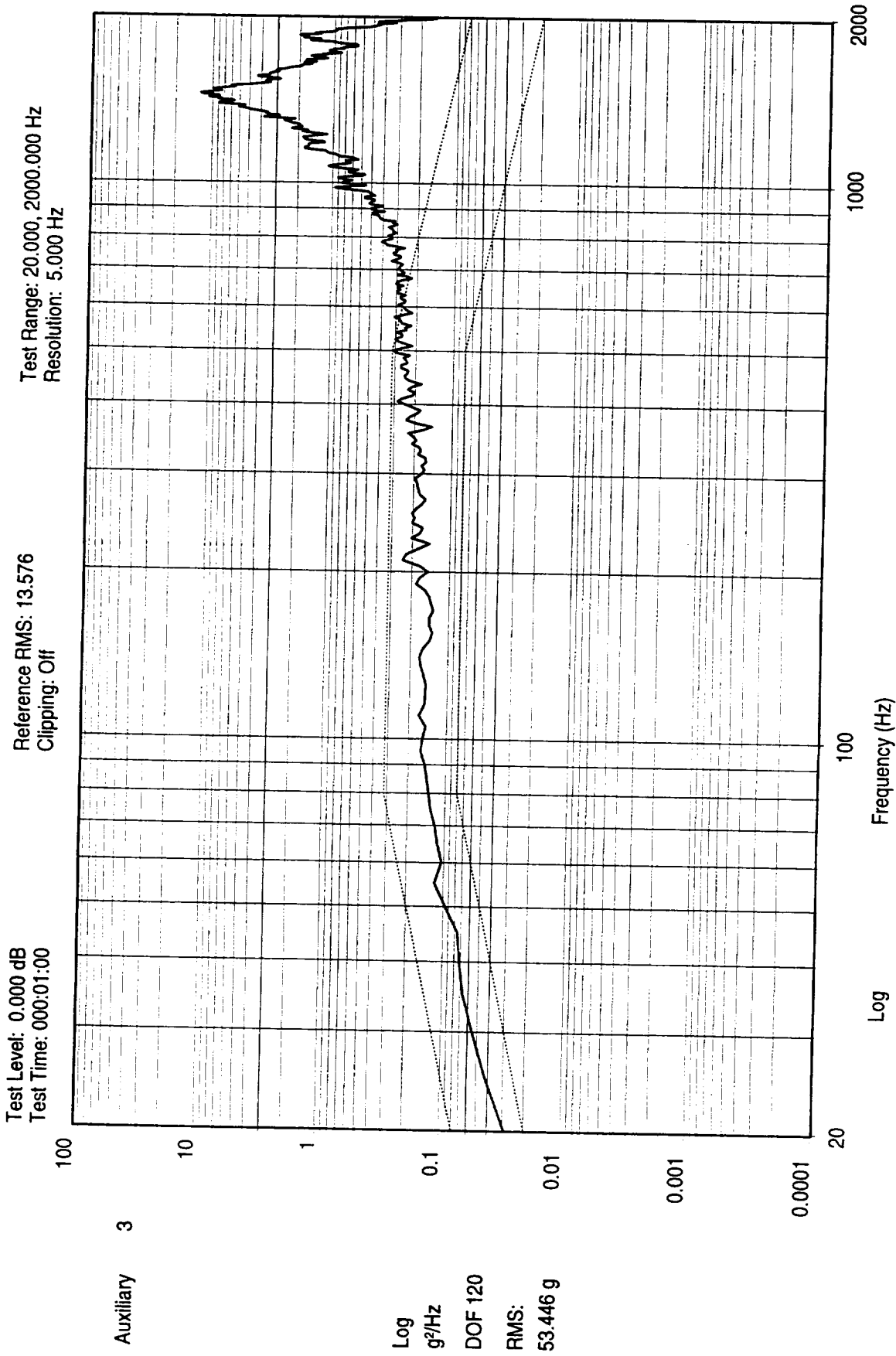
Test Name: PLO.tmp

14:42:04
04-Nov-1998

11-4-98
ENG 217
11A 251

Auxiliary 2

Log
g²/Hz
DOF 120
RMS:
22.412 g



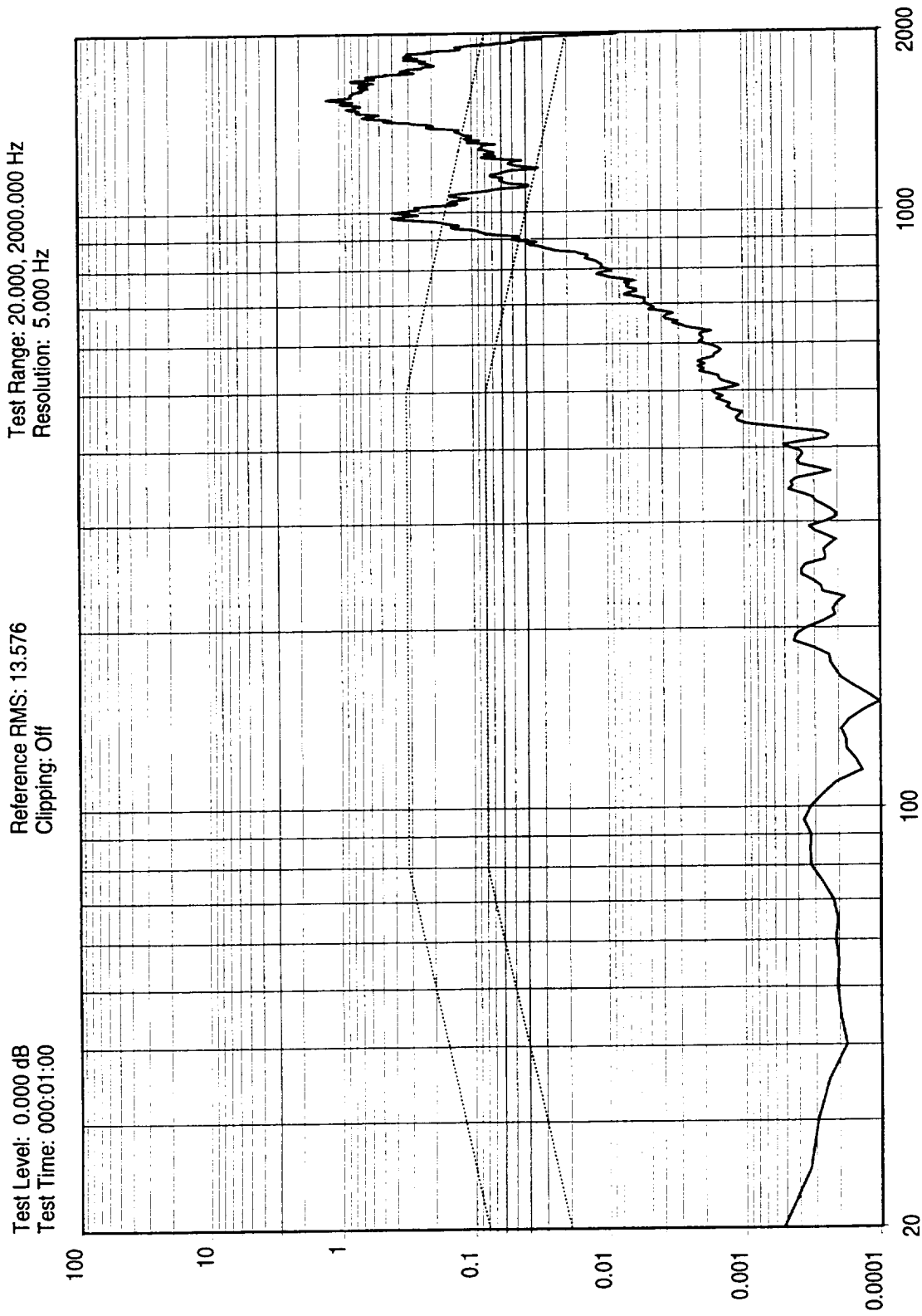
UNIT Y AXIS

AMSU PHASE LOCK OSCILLATOR S/O538595
 Y AXIS TEST P/N 1348360-1 S/N F10
 Test Name: PLO.tmp

11-4-98

ENG
 217
 (1A)
 (2.63)

14:42:08
 04-Nov-1998



Auxiliary 4

Log
g²/Hz
DOF 120
RMS:
17.974 g

14:42:12
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538595
Y AXIS TEST P/N 1348360-1 S/N F10
Test Name: PLO.tmp

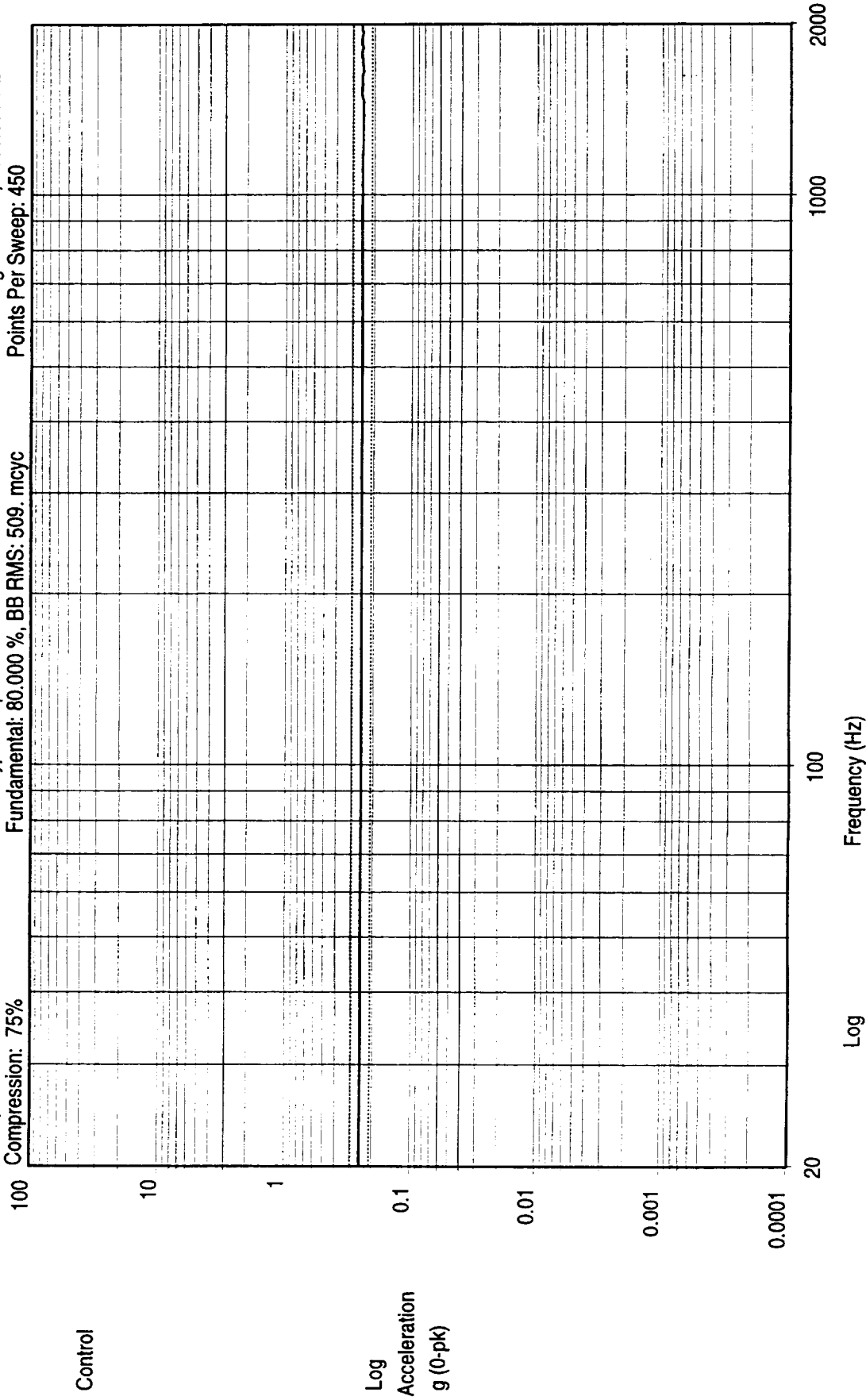
UNIT X AXIS

11-4-98
ENG 217
1A 283

Sweep Number: 1.00
Sweep Rate 1: 2.000 oct/min
Compression: 75%

Elapsed Time: 000:03:19
Filter Type: Proportional
Fundamental: 80.000 %, BB RMS: 509. mcyc

Remaining Time: 000:00:00
Test Range: 20.000, 2000.000 Hz
Points Per Sweep: 450

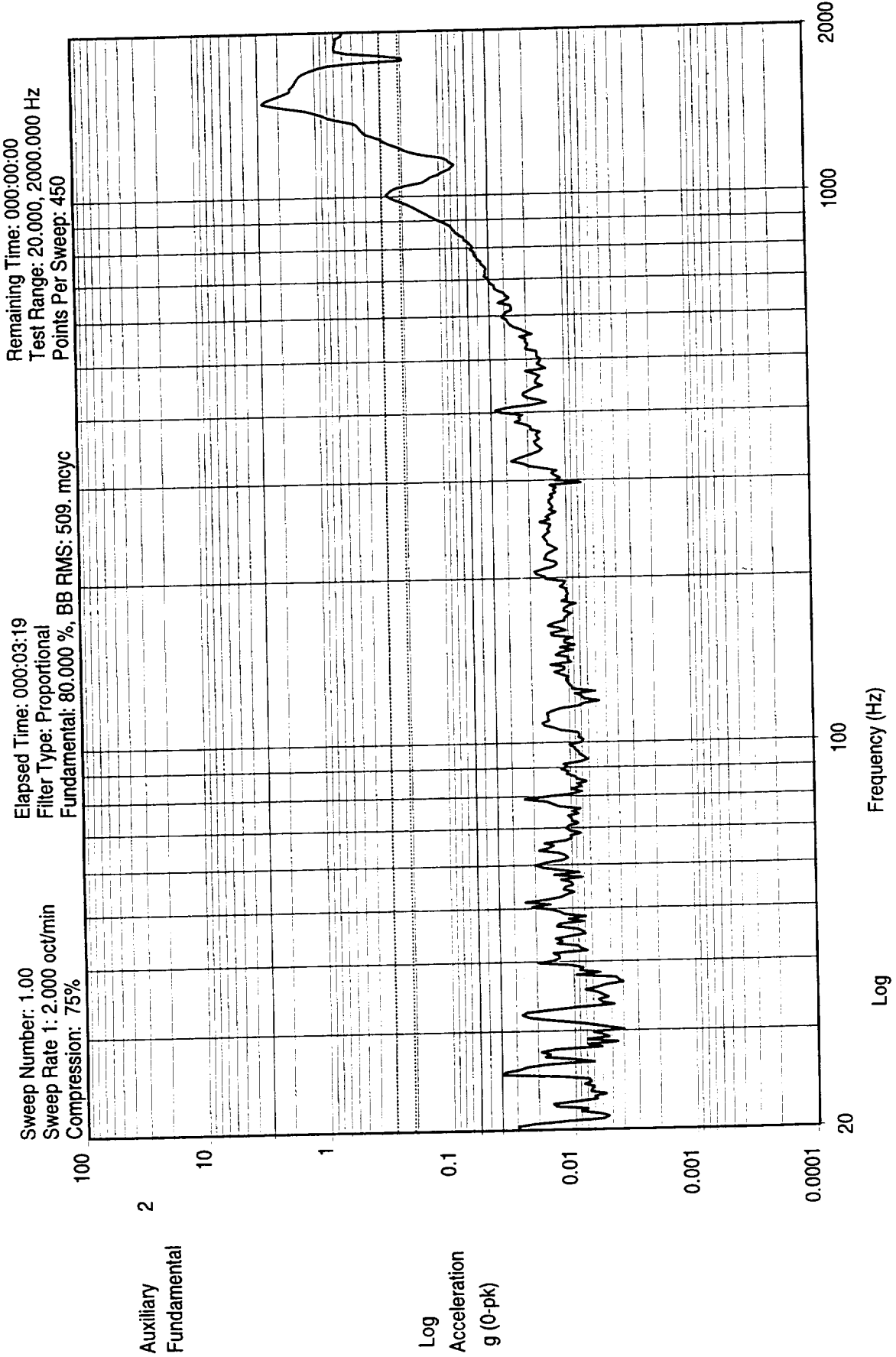


14:55:56
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
Y AXIS POST SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

11-4-98
ENG 217
11-4-98



UNIT Z

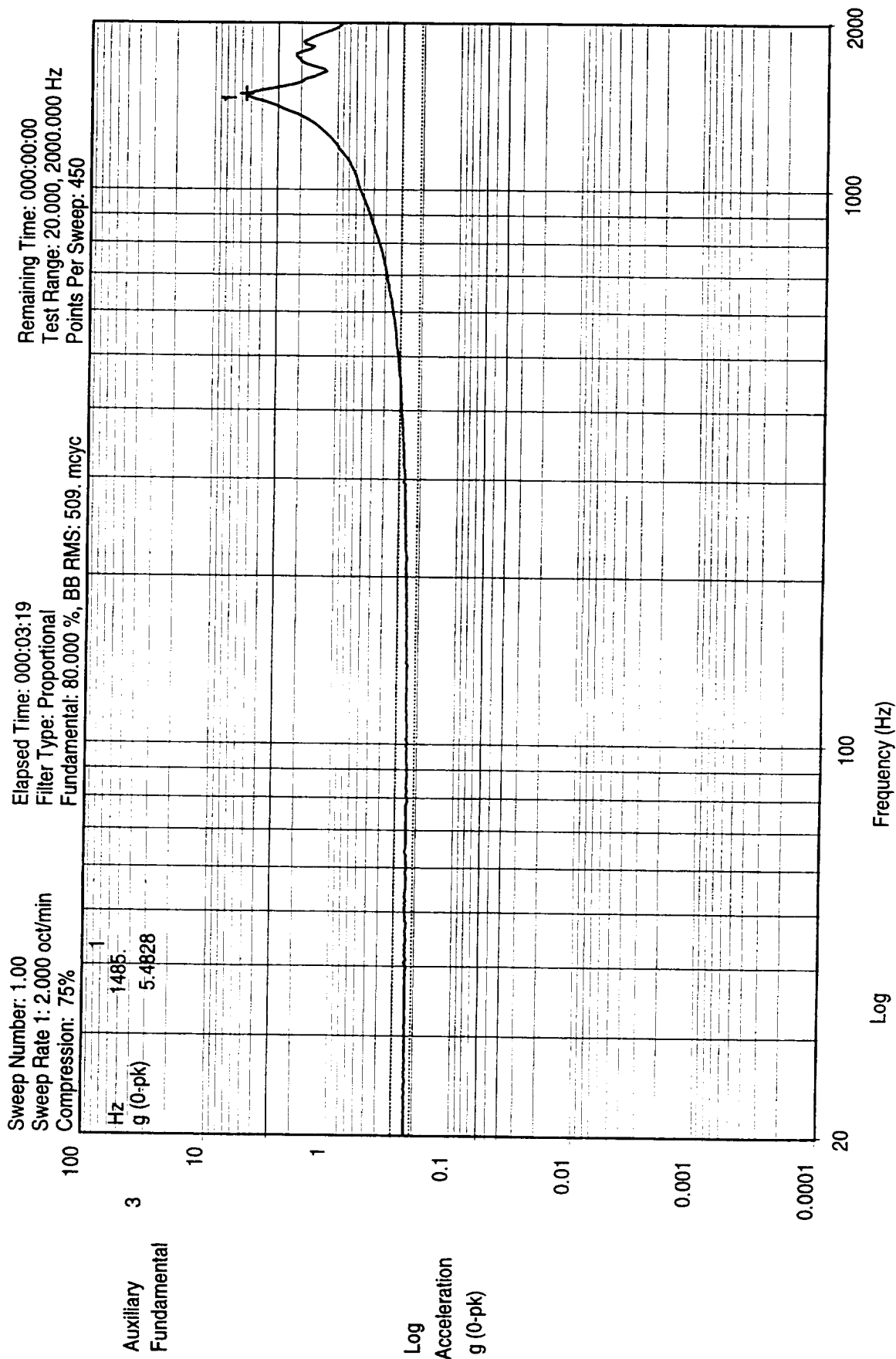
11-4-98

ENG 217
1A 267

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
Y AXIS POST SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

14:56:02
04-Nov-1998



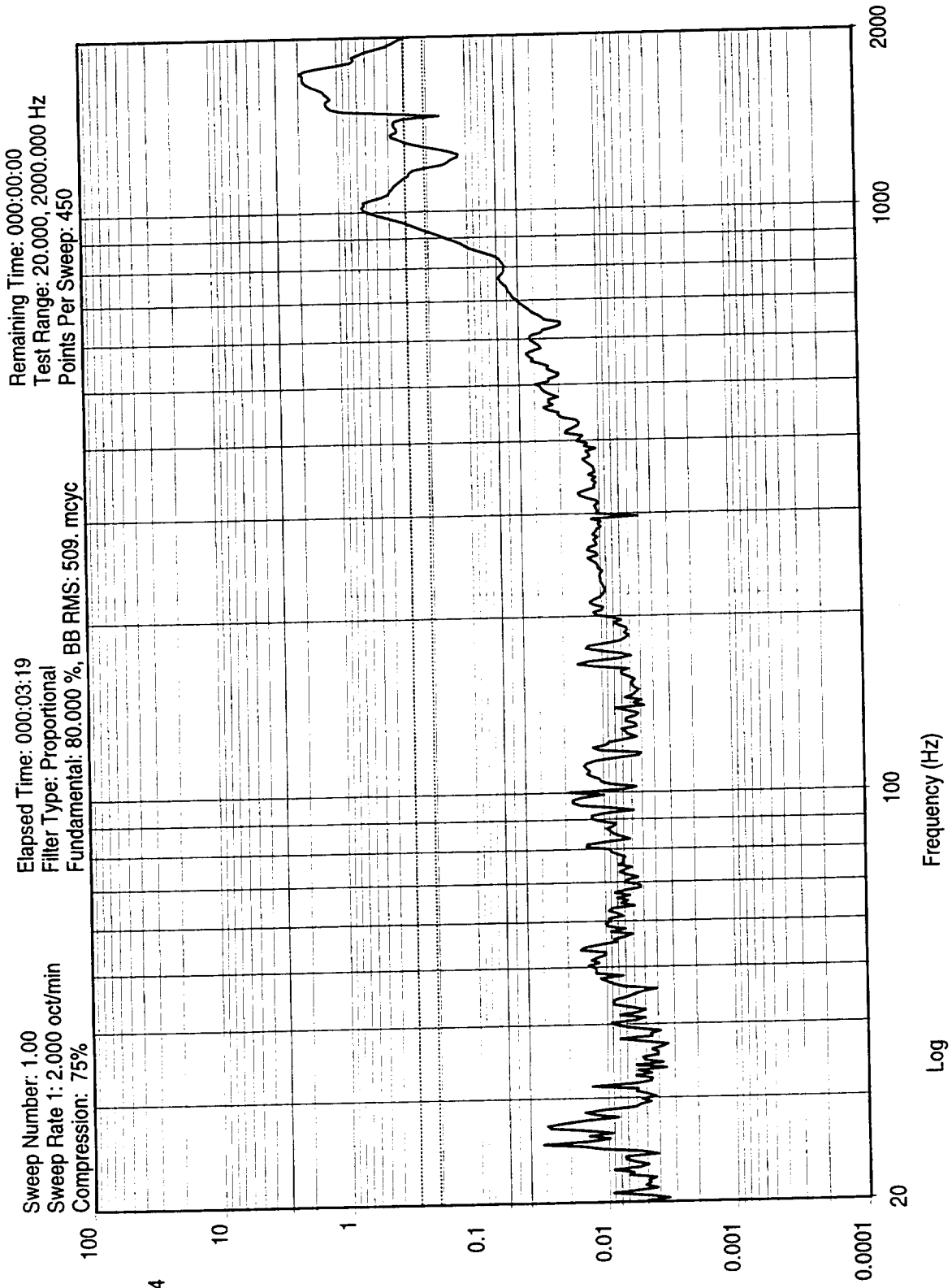
UNITY

11-4-98
 ENG 217
 1A 261

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 Y AXIS POST SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

14:56:17
 04-Nov-1998



Auxiliary
 Fundamental

Log
 Acceleration
 g (0-pk)

Log
 Frequency (Hz)

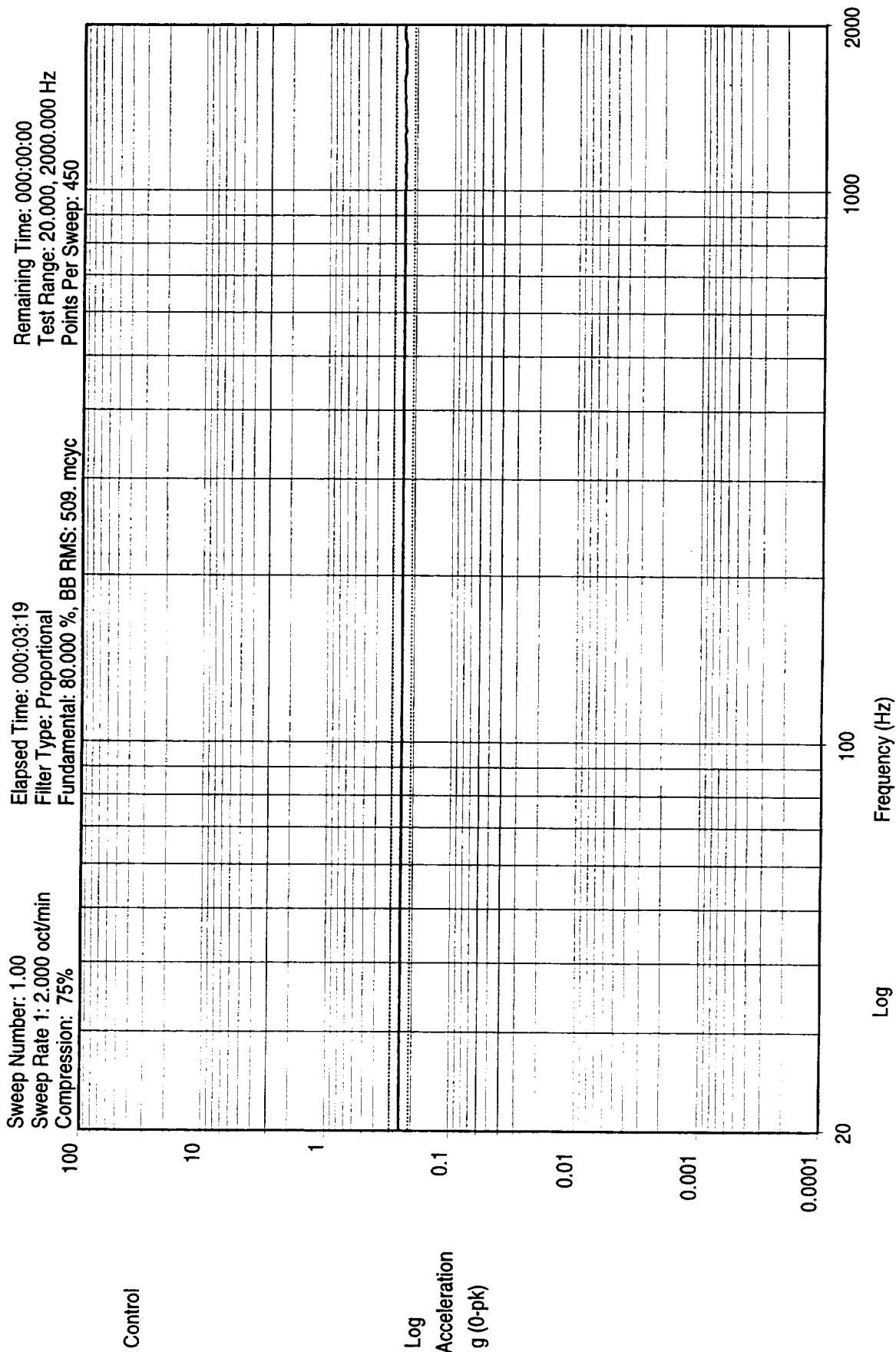
UNIT X

11-4-98
 (17/25)
 ENG
 217

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 Y AXIS POST SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

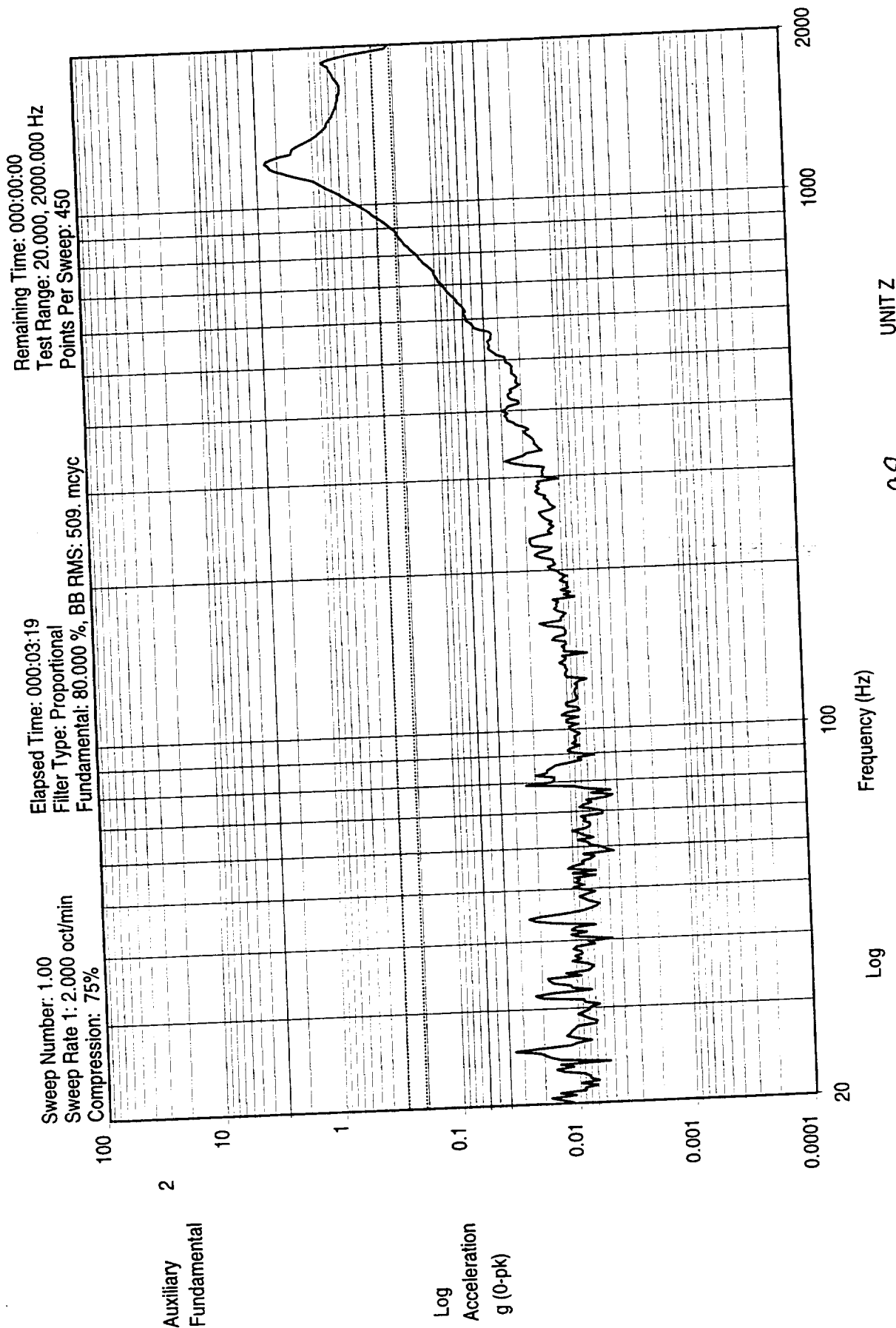
14:56:21
 04-Nov-1998



15:37:11
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
X AXIS SINE TEST P/N 1348360-1 S/N F10
Sine Test Name: PLO.tmp

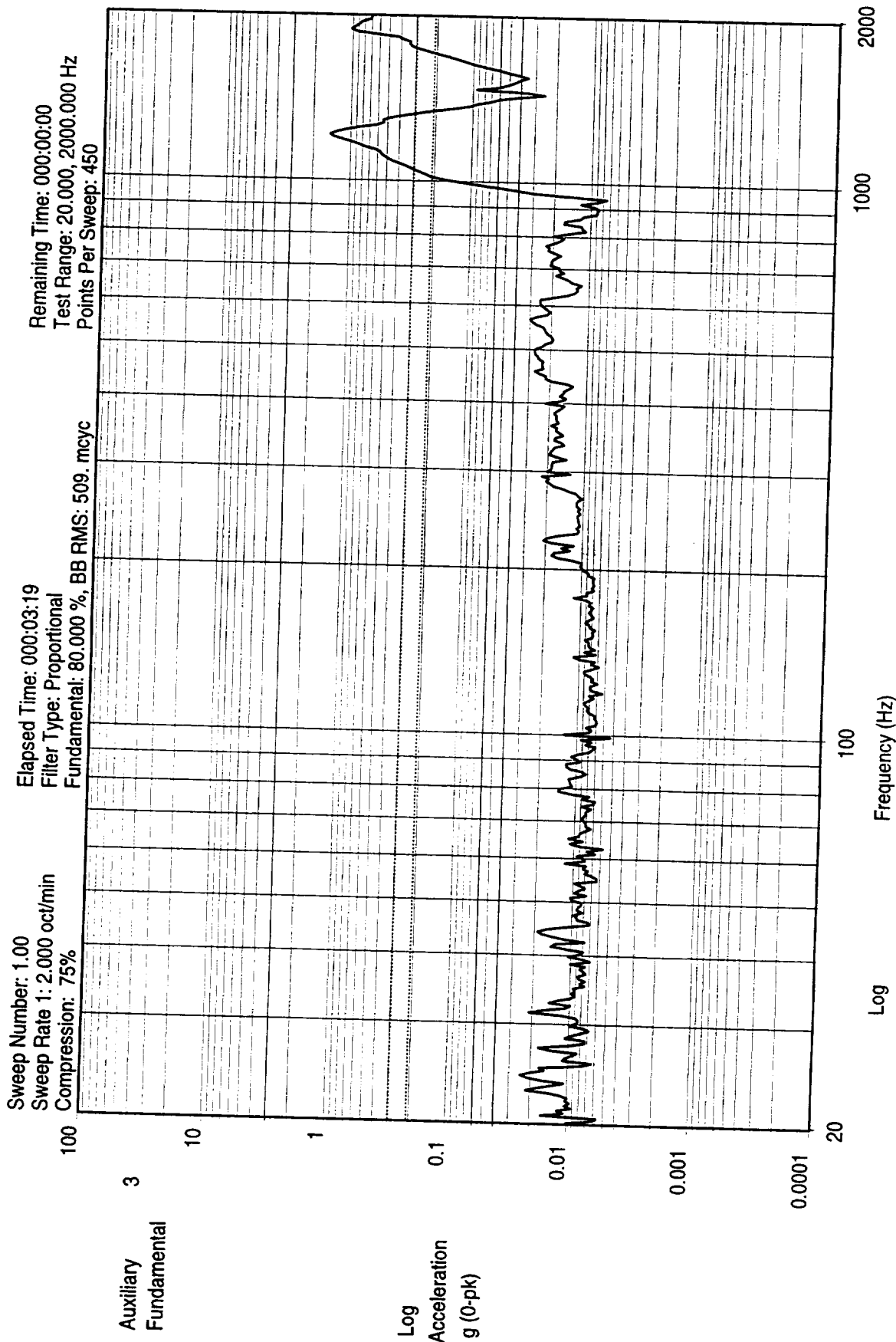
11-4-98
1A
267
ENG
217



11-4-99
 ENG 217
 1A 267

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 X AXIS SINE TEST P/N 1348360-1 S/N F10
 Sine Test Name: PLO.tmp

15:37:15
 04-Nov-1998



UNIT Y

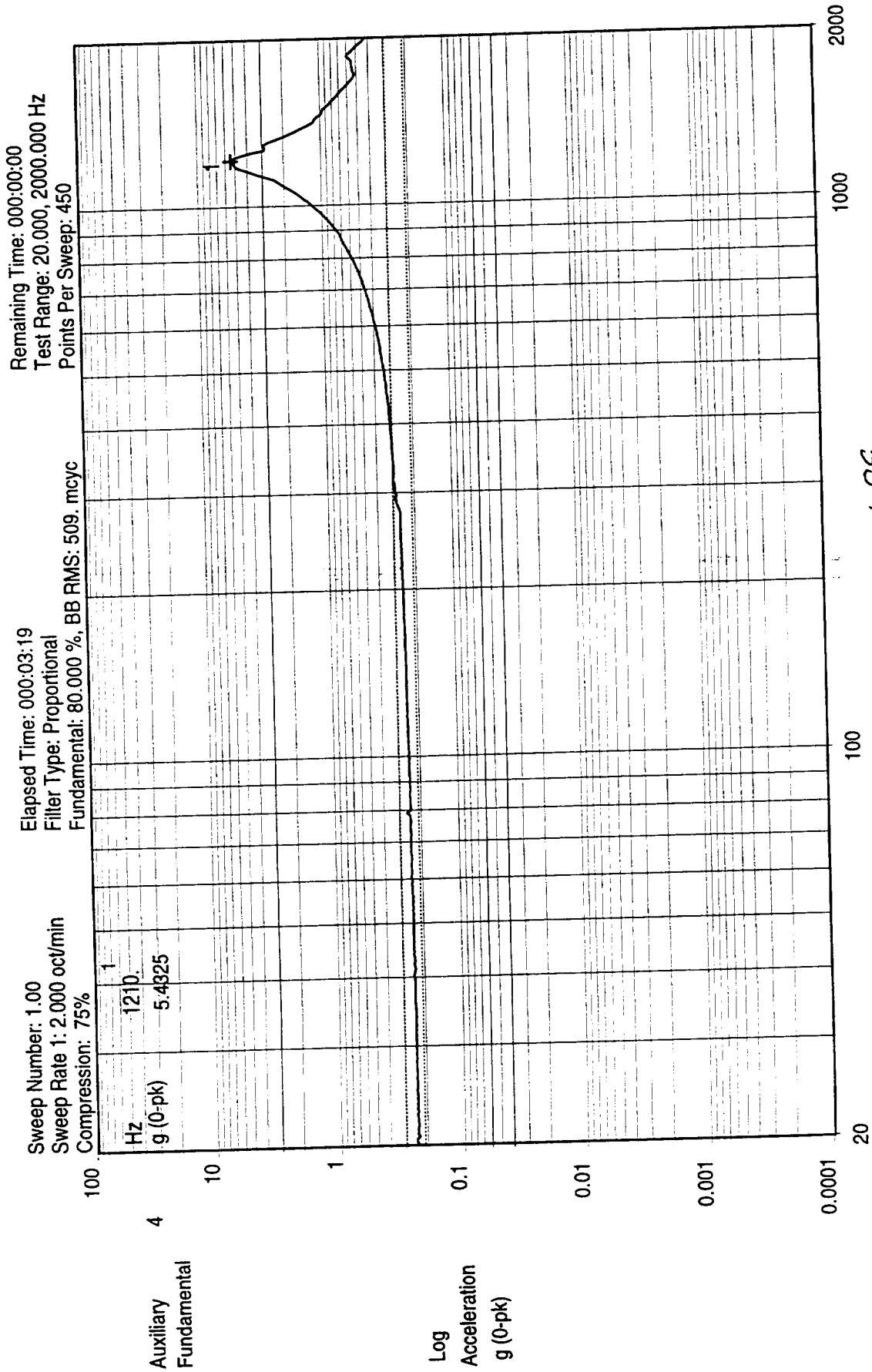
11-4-98



AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
X AXIS SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

15:37:19
04-Nov-1998



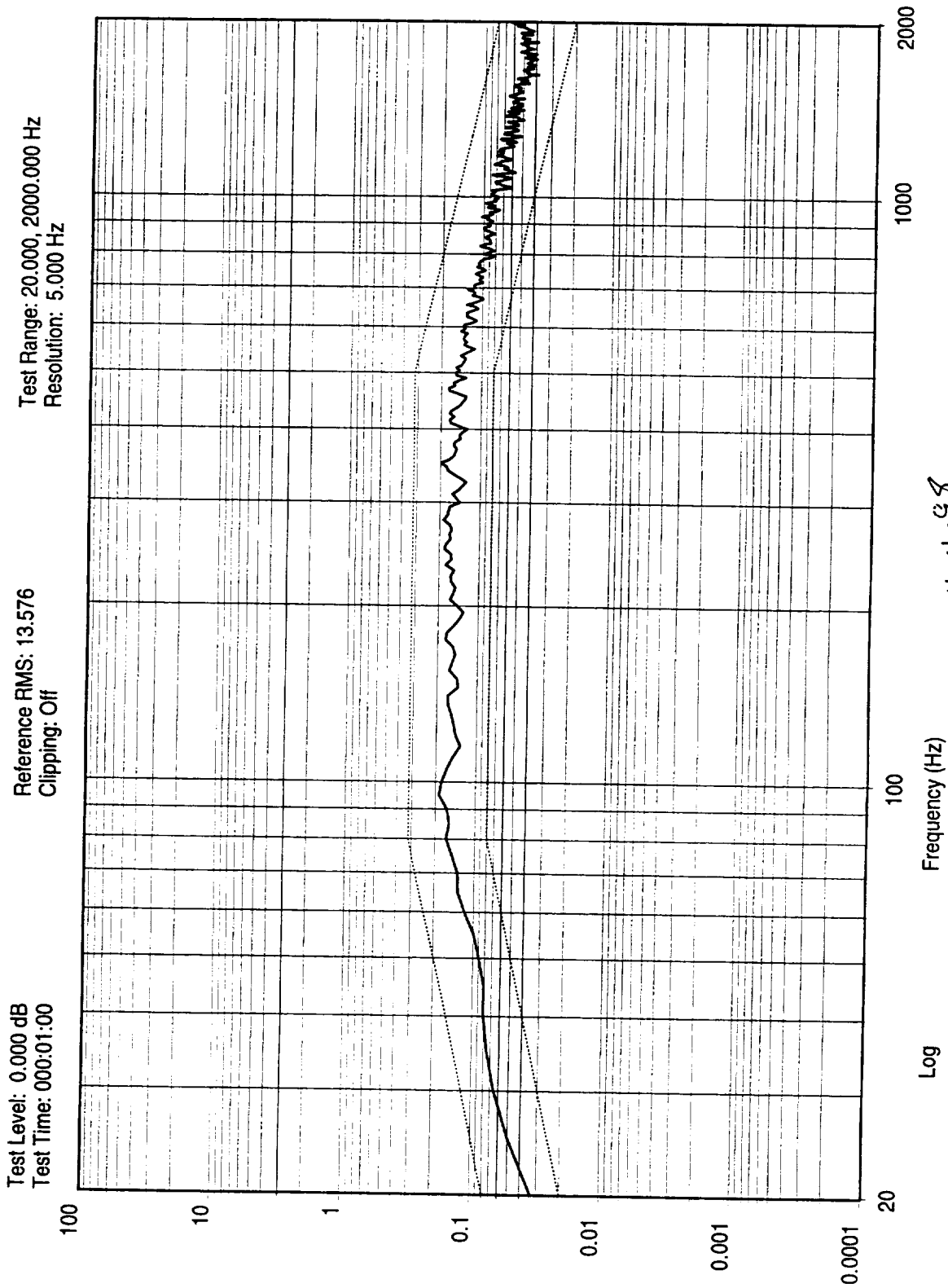
11-4-98

ENG 277

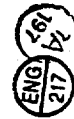
11-4-98

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 X AXIS SINE TEST P/N 1348360-1 S/N F10
 Sine Test Name: PLO.tmp

15:37:36
 04-Nov-1998



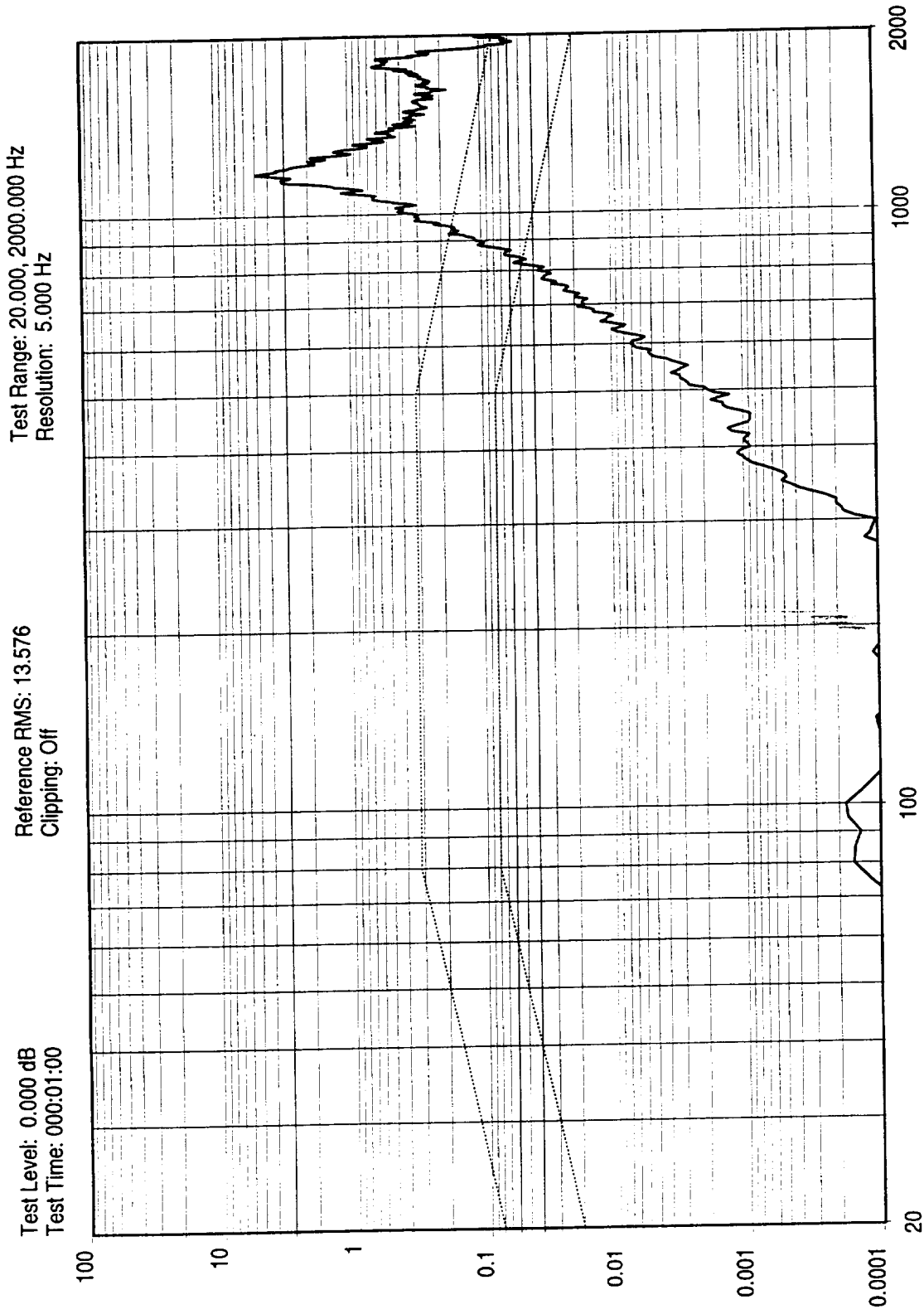
11-4-98



AMSU PHASE LOCK OSCILLATOR S/O538595
X AXIS TEST P/N 1348360-1 S/N ,F10

Test Name: PLO.tmp

15:51:48
04-Nov-1998



Auxiliary 2

Log
g²/Hz
DOF 120
RMS:
27.488 g

Log Frequency (Hz)

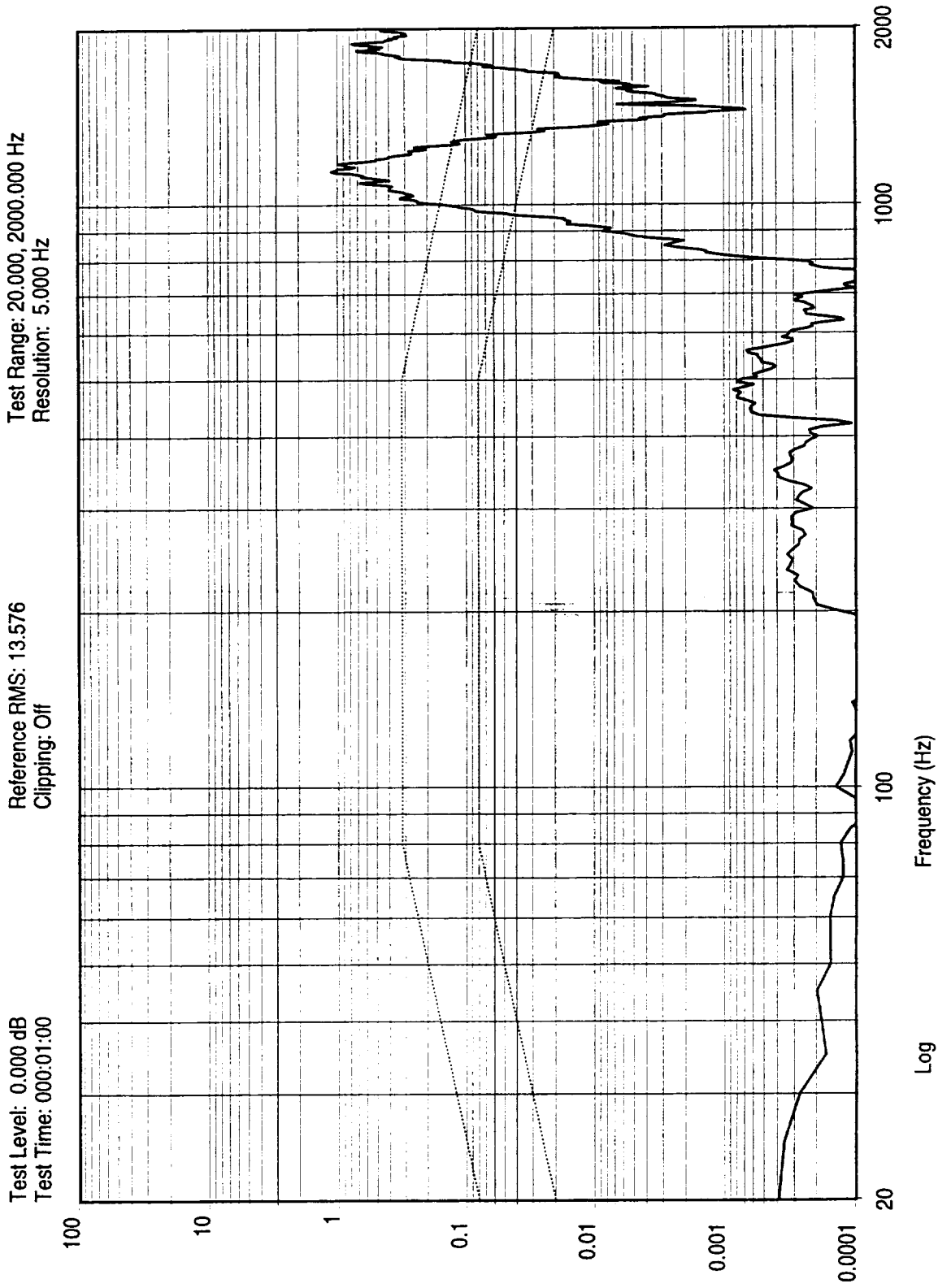
UNIT Z AXIS

11-4-98



AMSU PHASE LOCK OSCILLATOR S/O538595
X AXIS TEST P/N 1348360-1 S/N,F10
Test Name: PLO.tmp

15:51:55
04-Nov-1998



Auxiliary 3

Log
 g^2/Hz
 DOF 120
 RMS:
 15.924 g

15:51:59
 04-Nov-1998

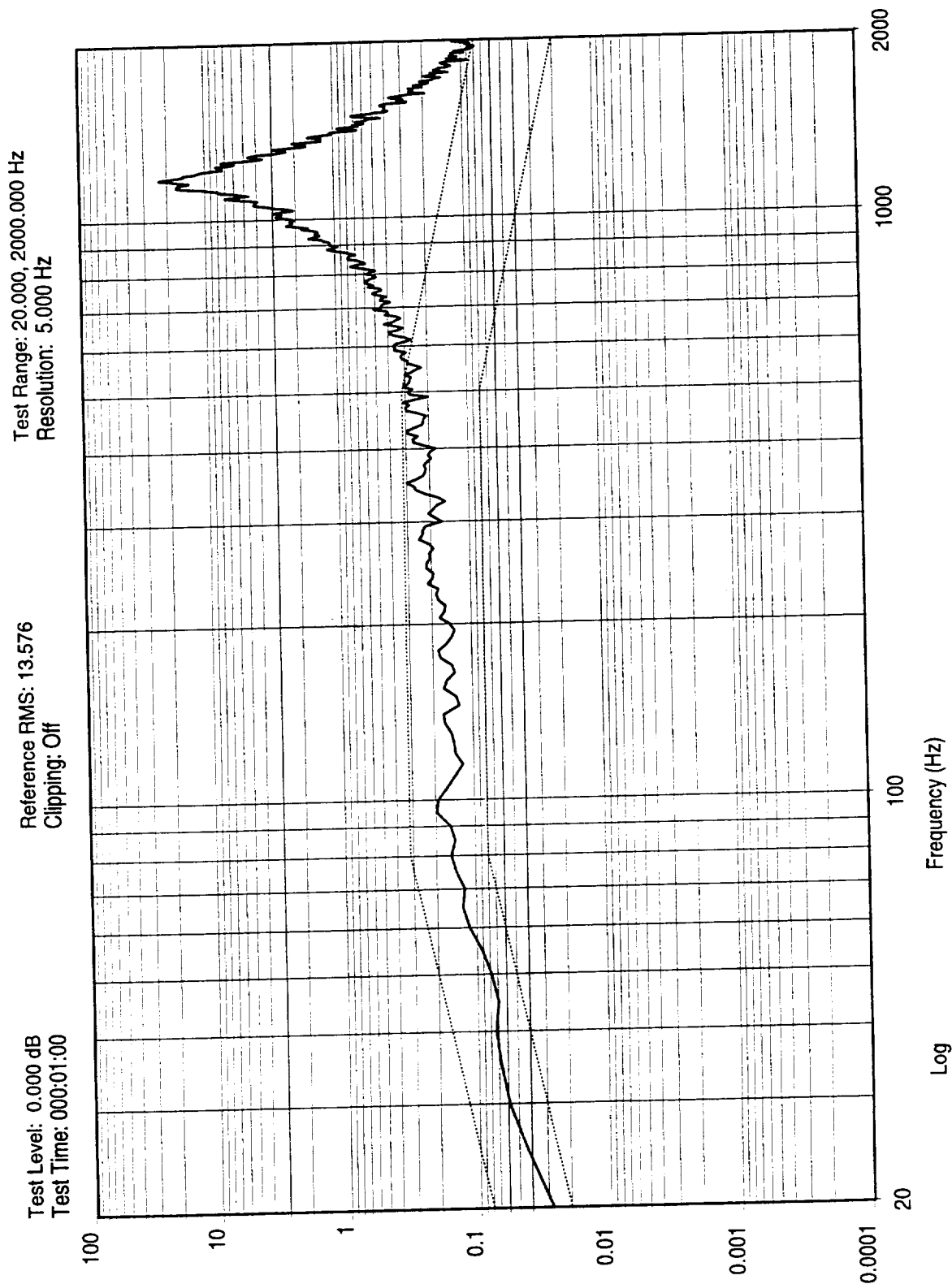
AMSU PHASE LOCK OSCILLATOR S/O538595
 X AXIS TEST P/N 1348360-1 S/N ,F10

Test Name: PLO.tmp

UNIT Y AXIS

11-4-98





Auxiliary 4

Log
g²/Hz

DOF 120

RMS:
56.174 g

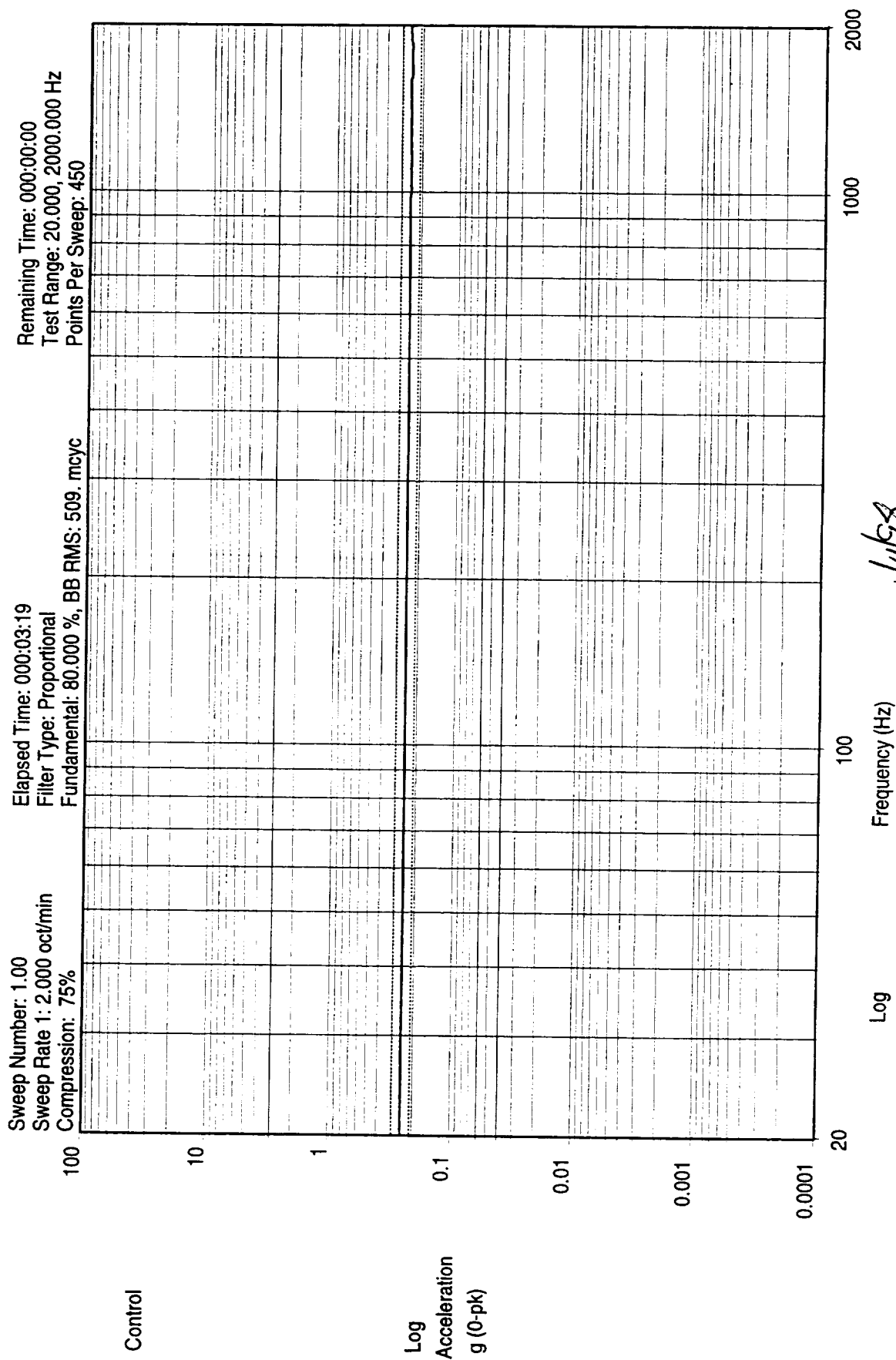
11-4-98



AMSU PHASE LOCK OSCILLATOR S/O538595
X AXIS TEST P/N 1348360-1 S/N, F10

Test Name: PLO.tmp

15:52:05
04-Nov-1998



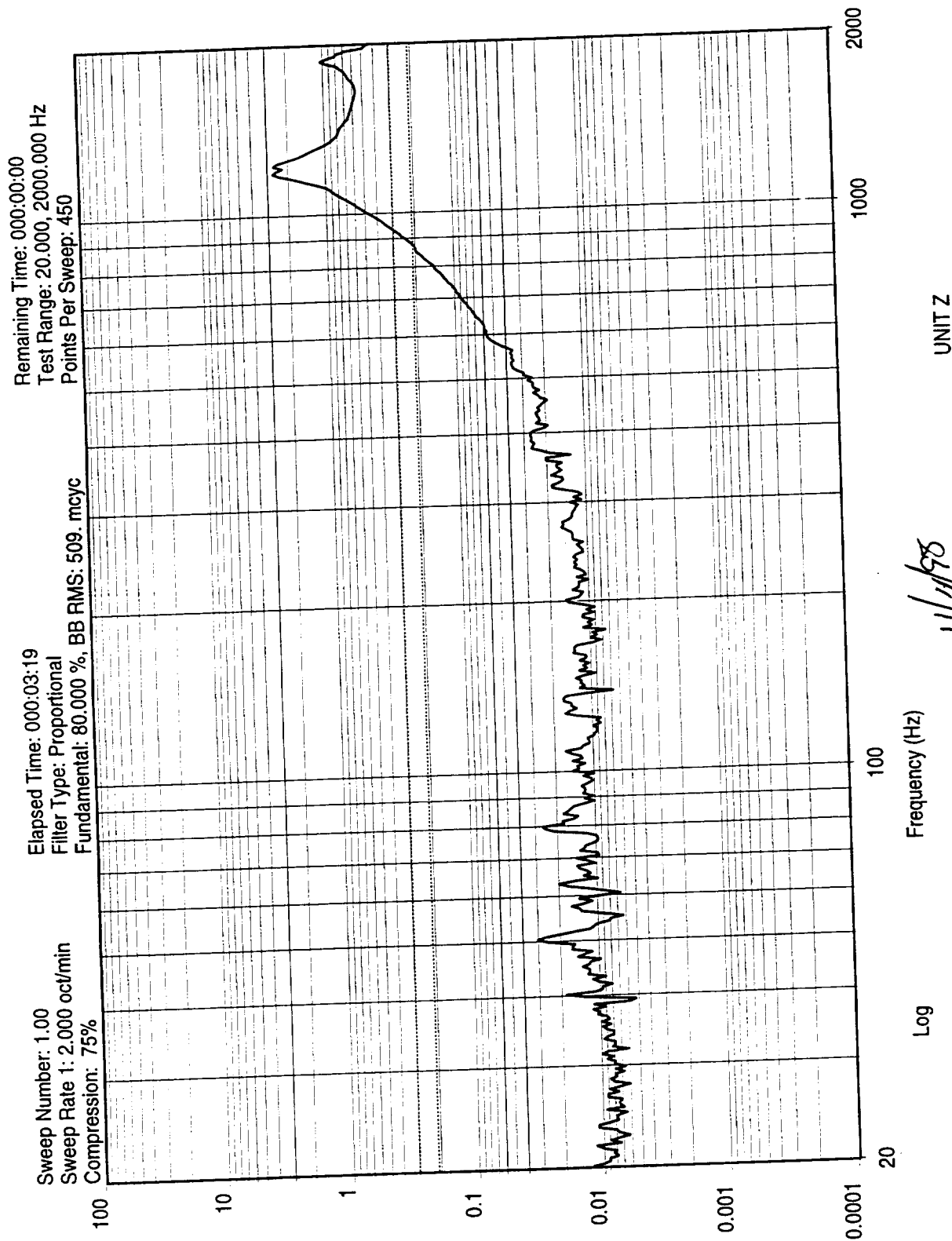
11/4/98

ENG 217
 251

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 X AXIS POST SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

16:01:18
 04-Nov-1998



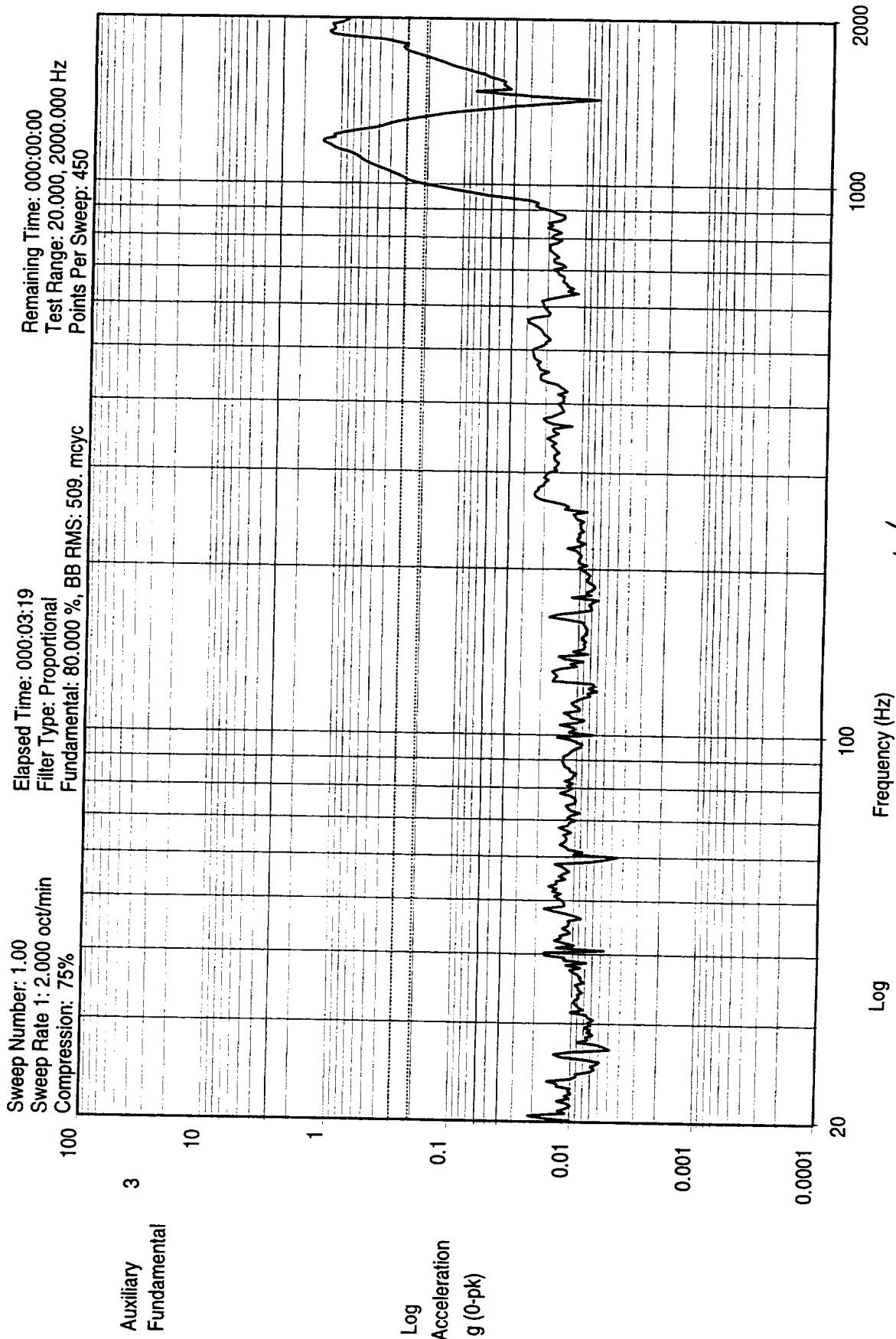
11/11/98



AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 X AXIS POST SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

16:01:23
 04-Nov-1998



UNIT Y

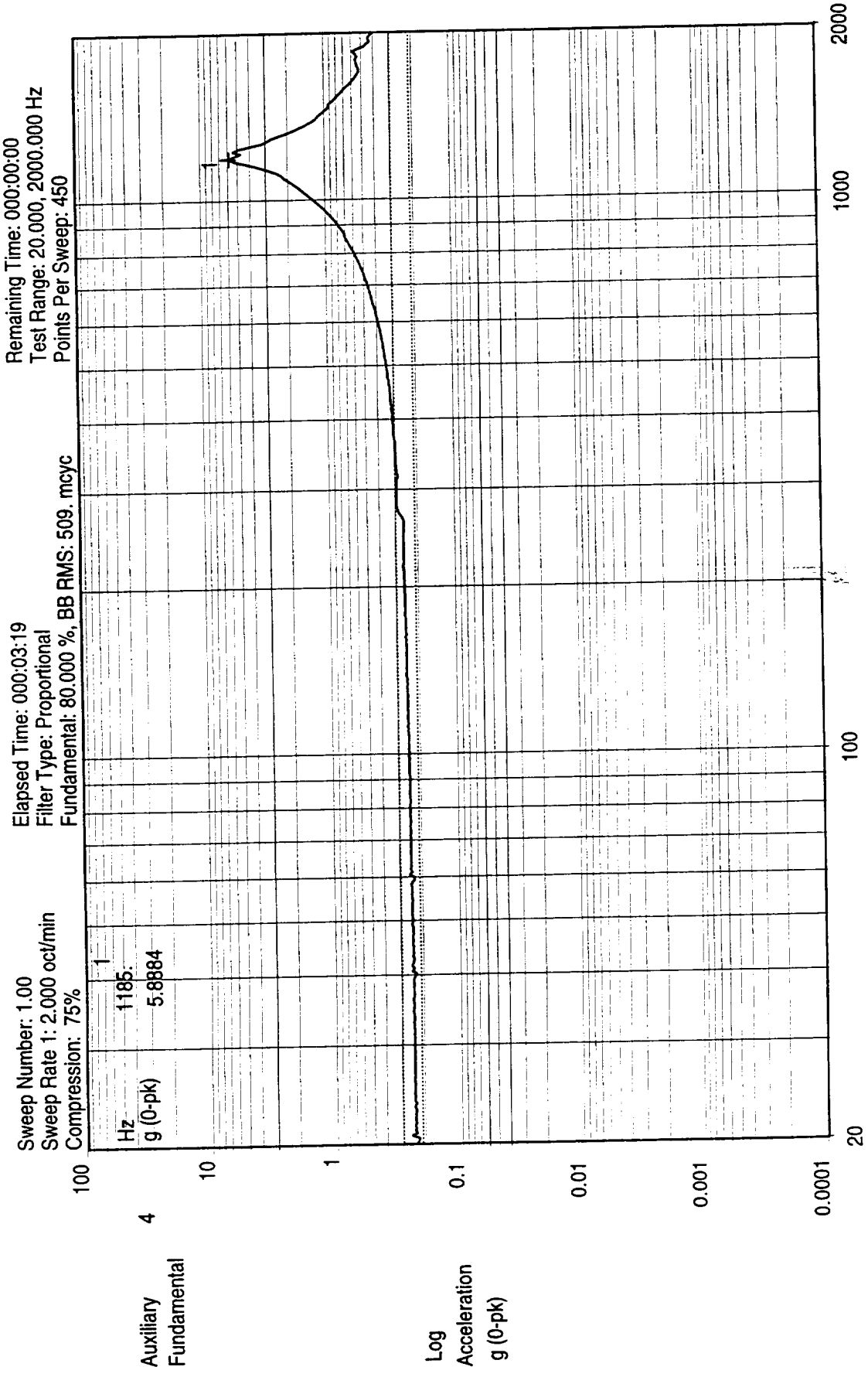
11/4/98



AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 X AXIS POST SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

16:01:27
 04-Nov-1998



UNIT X

11-4-98



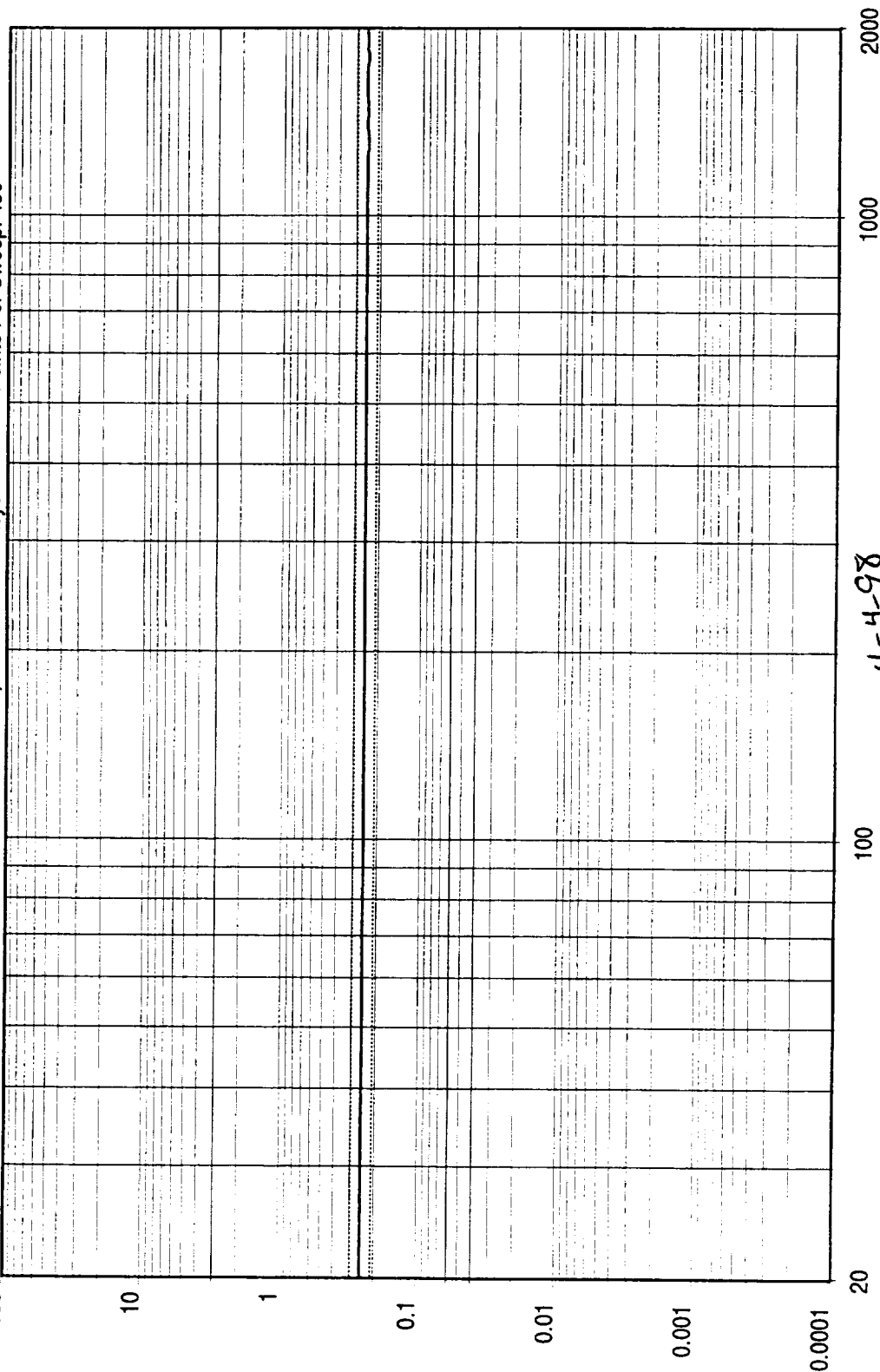
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 X AXIS POST SINE TEST P/N 1348360-1 S/N F10
 Sine Test Name: PLO.tmp

16:01:36
 04-Nov-1998

Sweep Number: 1.00
Sweep Rate 1: 2.000 oct/min
Compression: 75%

Elapsed Time: 000:03:19
Filter Type: Proportional
Fundamental: 80.000 %, BB RMS: 509. mcyc

Remaining Time: 000:00:00
Test Range: 20.000, 2000.000 Hz
Points Per Sweep: 450

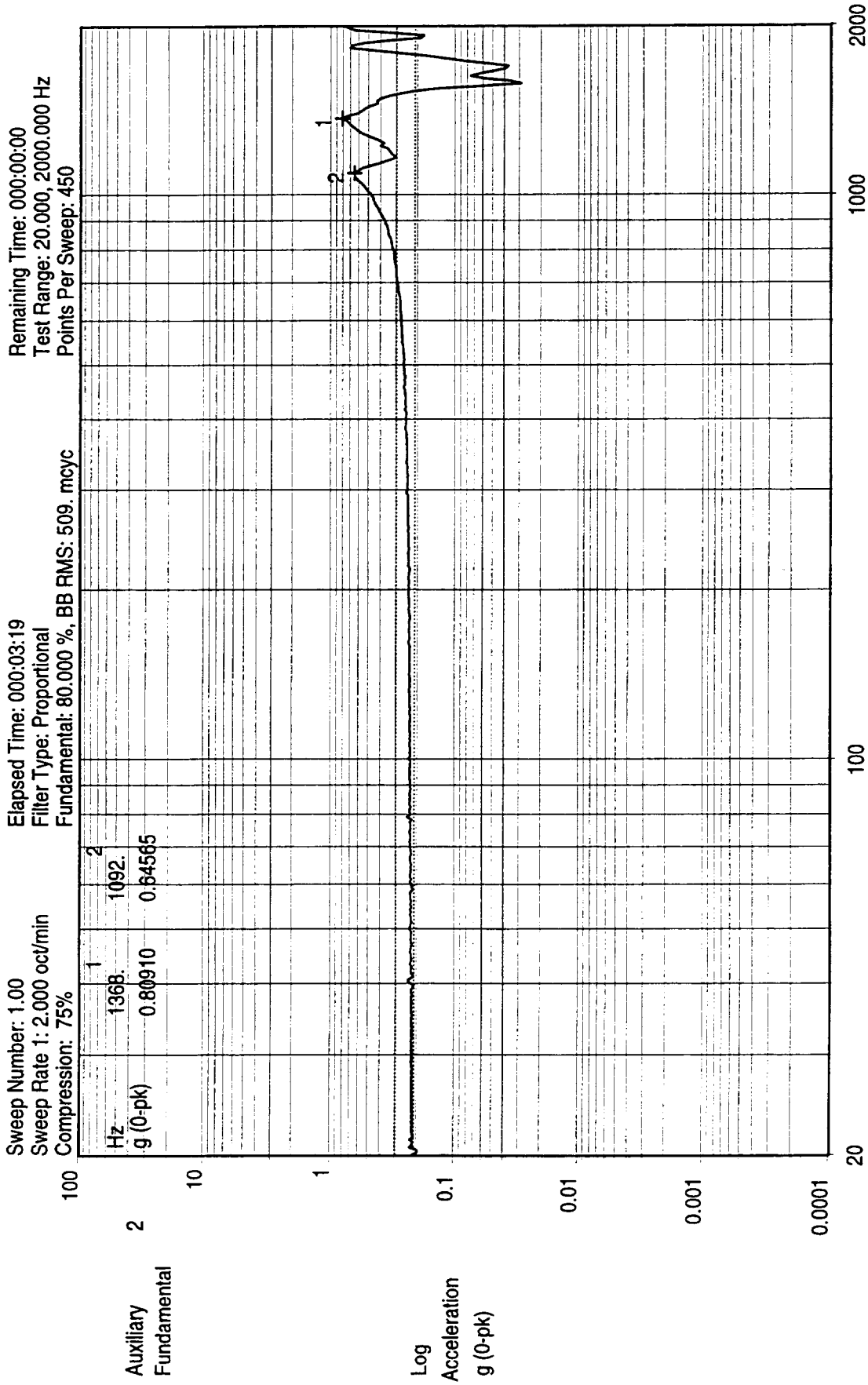


ENG
2/2
19/1

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
Z AXIS SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

16:34:04
04-Nov-1998



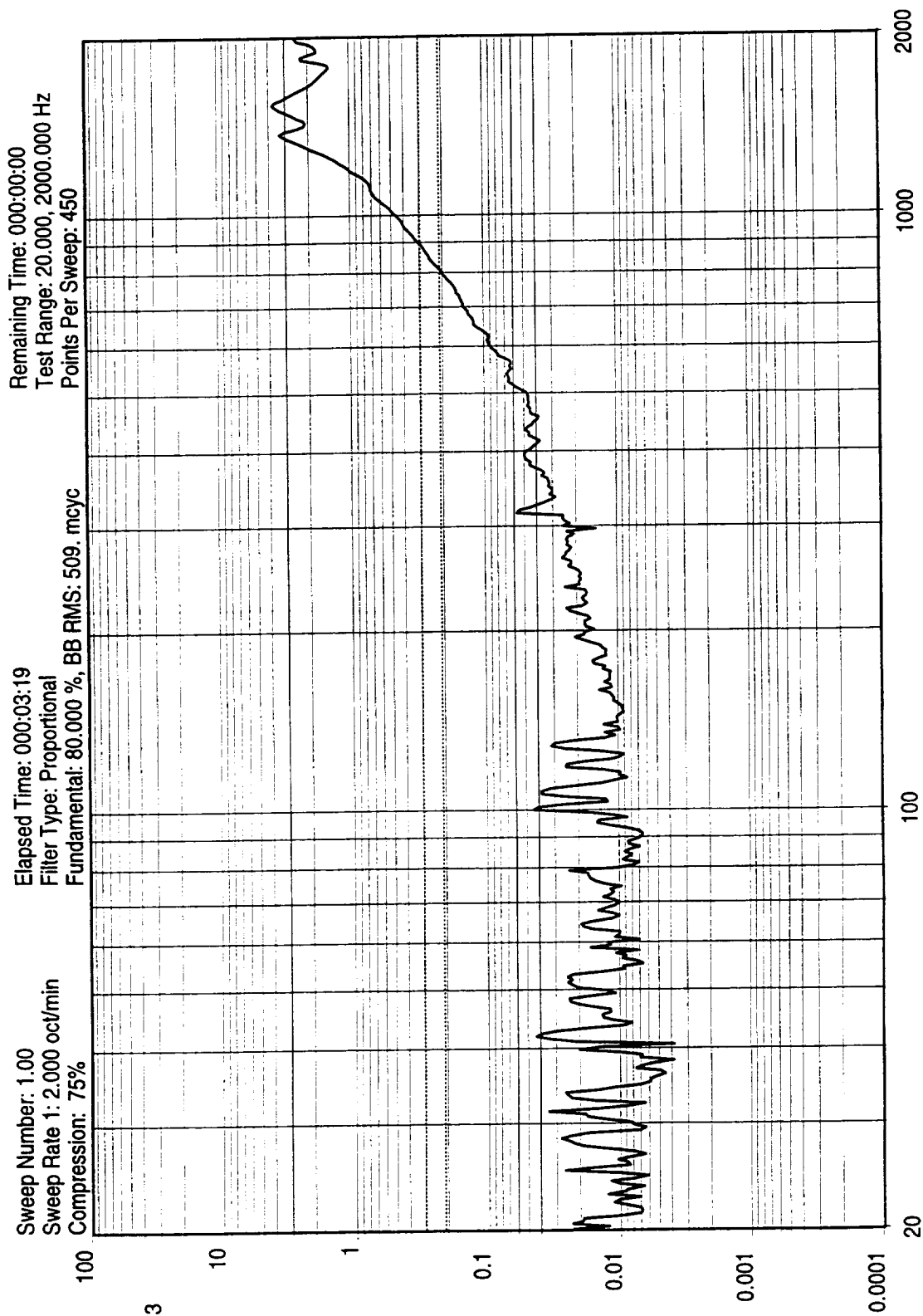
UNIT Z

11-4-98

ENG 217
 197

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 Z AXIS SINE TEST P/N 1348360-1 S/N F10
 Sine Test Name: PLO.tmp

16:51:45
 04-Nov-1998



UNITY

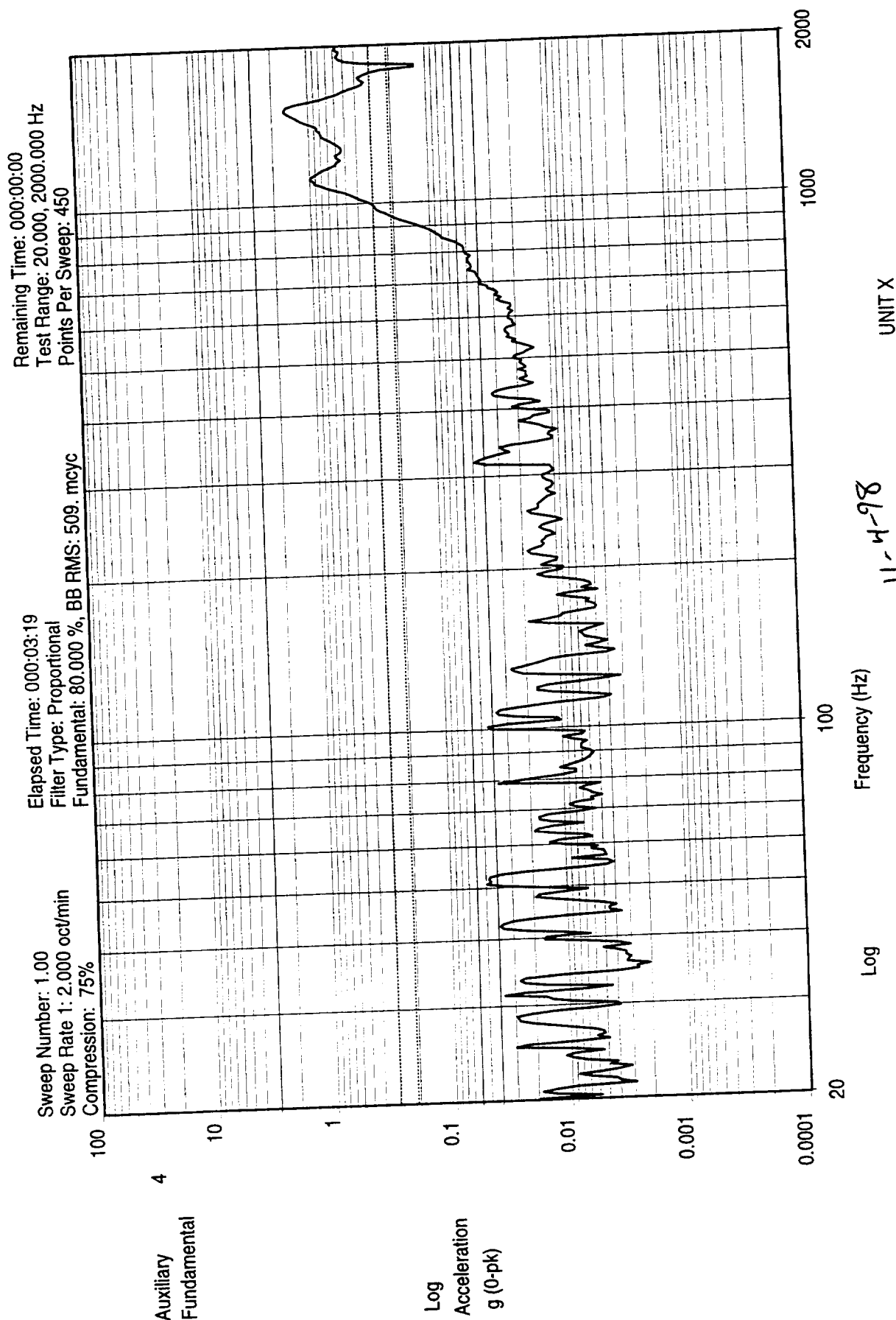
11-4-98



AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 Z AXIS SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

16:34:12
 04-Nov-1998

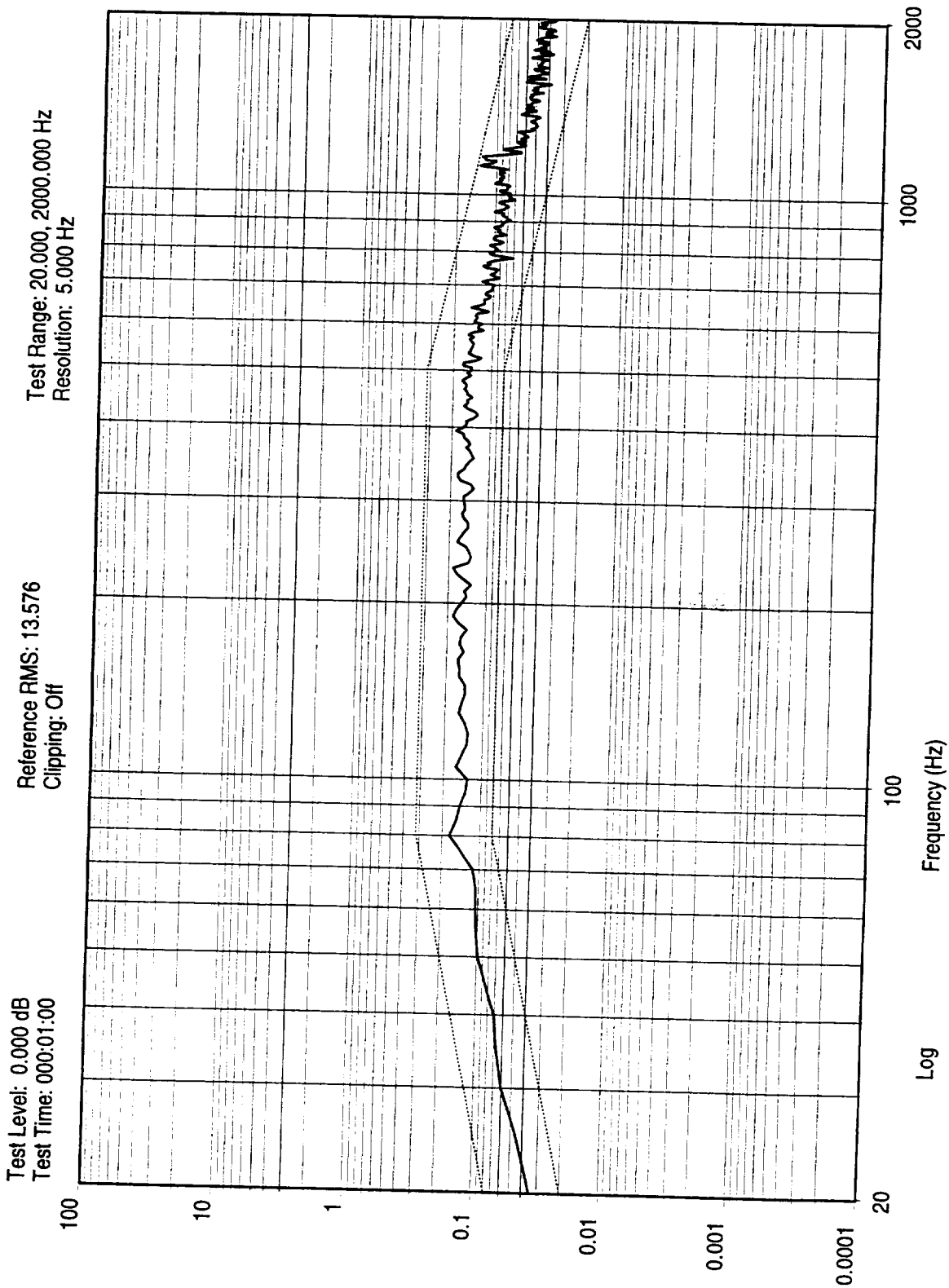


11-4-98



AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 Z AXIS SINE TEST P/N 1348360-1 S/N F10
 Sine Test Name: PLO tmp

16:34:17
 04-Nov-1998

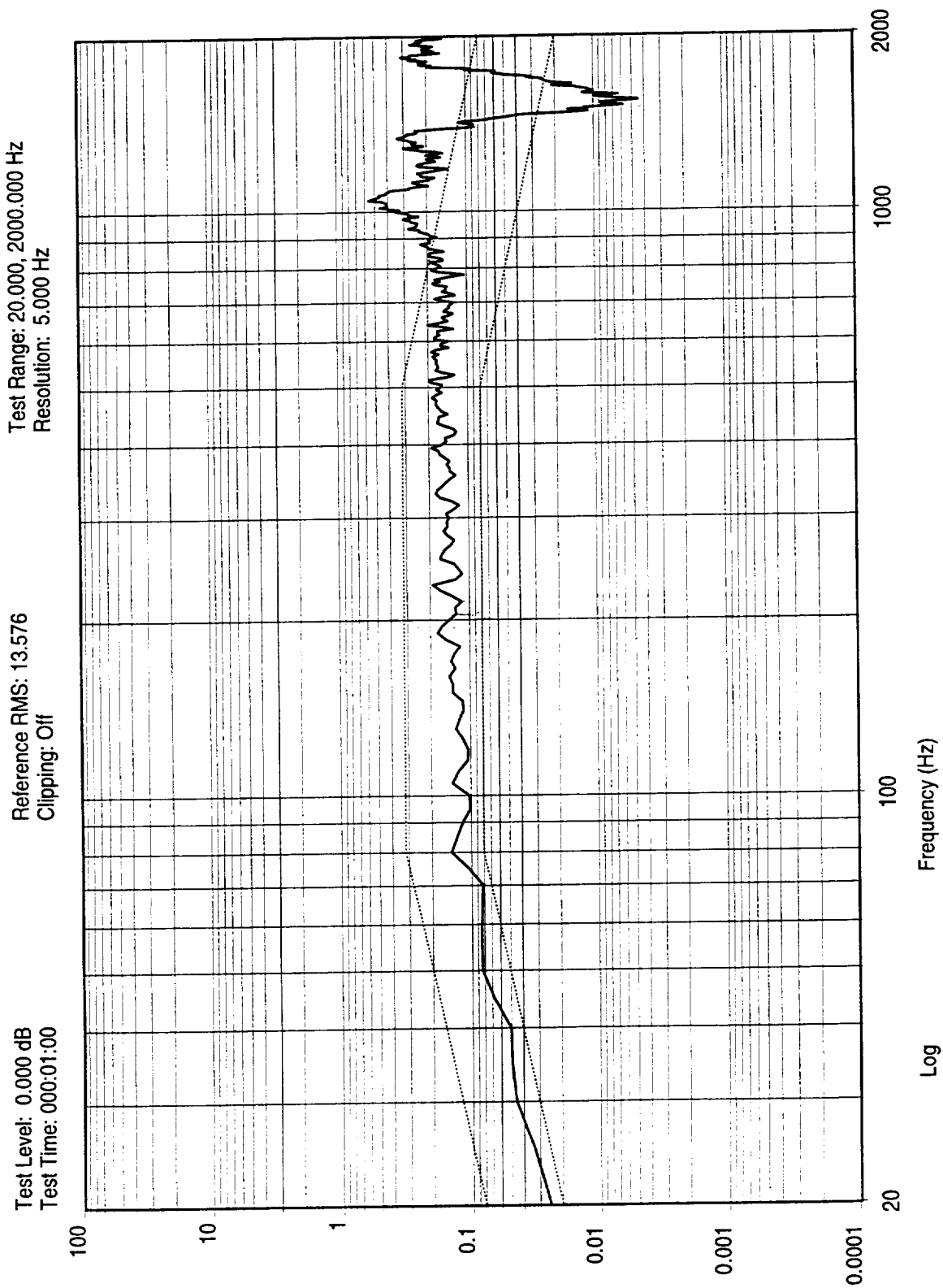


17:13:00
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538595
Z AXIS TEST P/N 1348360-1 S/N F10

Test Name: PLO.tmp

ENG
217
7A
137
11-48



Auxiliary 2

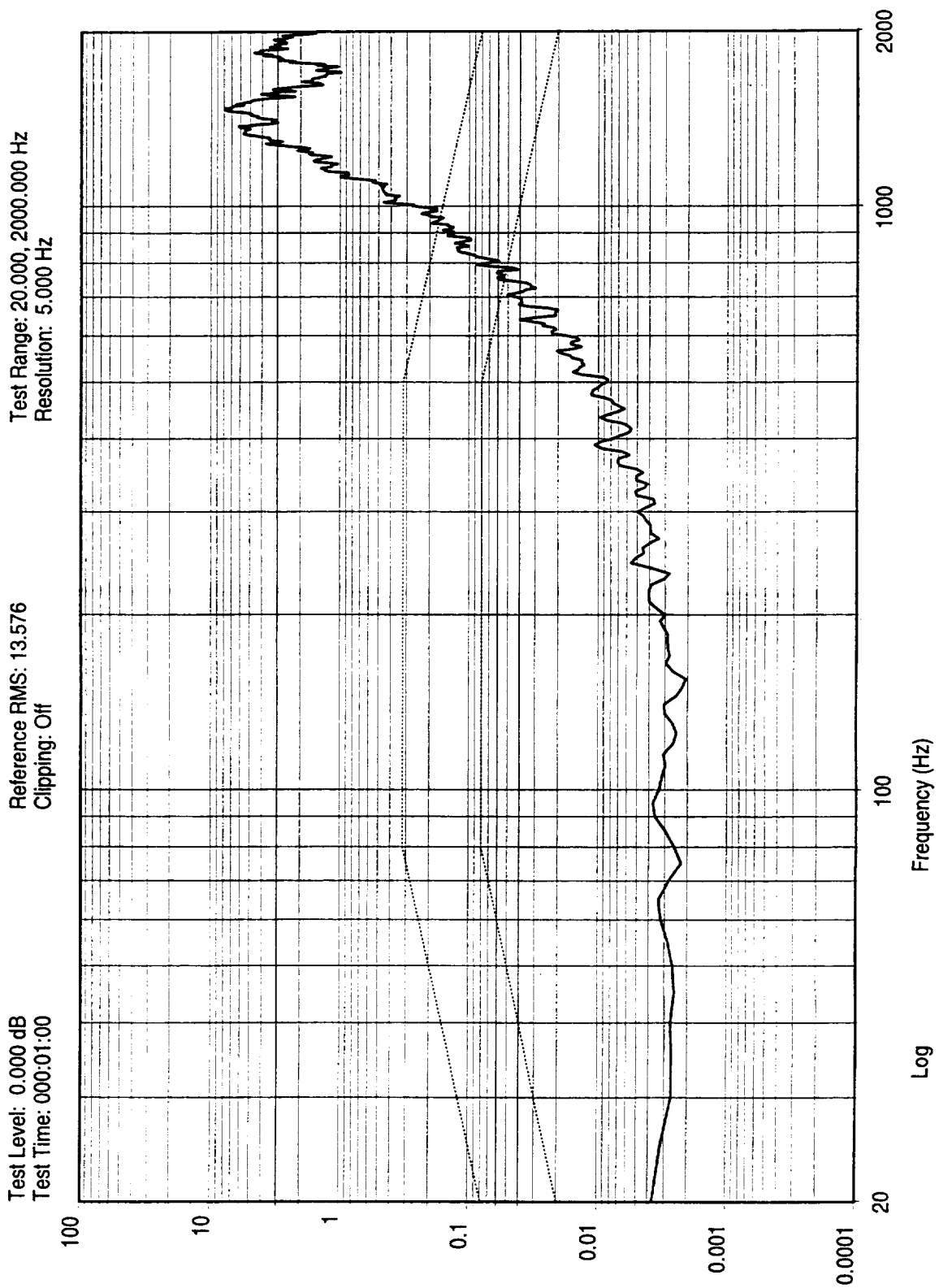
Log
g²/Hz
DOF 120
RMS:
18.051 g

17:13:07
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538595
Z AXIS TEST P/N 1348360-1 S/N F10
Test Name: PLO.tmp



11-00



Auxiliary 3

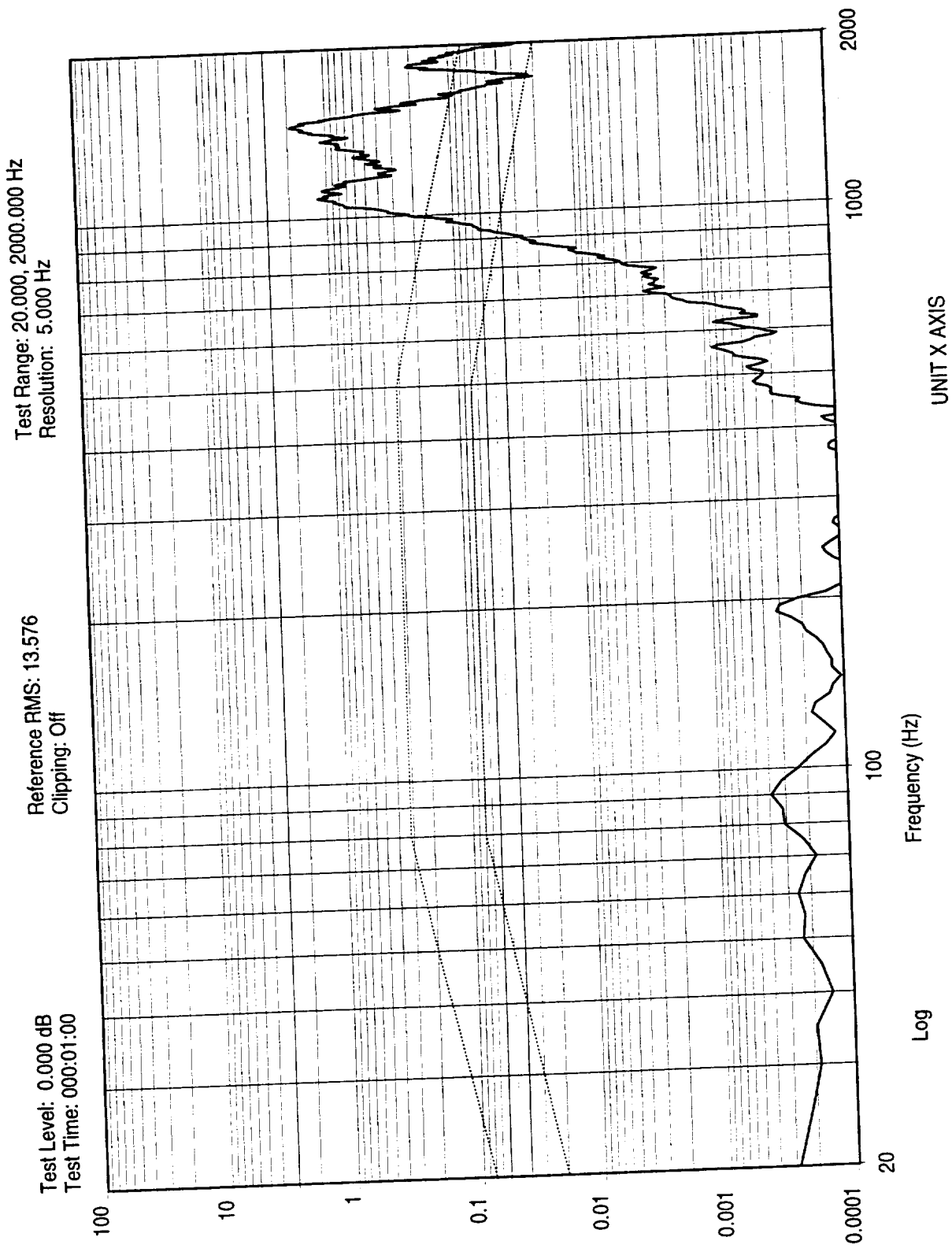
Log
g²/Hz
DOF 120
RMS:
52.164 g

UNIT Y AXIS

AMSU PHASE LOCK OSCILLATOR S/O538595
Z AXIS TEST P/N 1348360-1 S/N ,F10
Test Name: PLO.tmp

17:13:11
04-Nov-1998

ENG 27 197 74
11-1-98



Auxiliary 4

Log
g²/Hz
DOF 120
RMS:
21.995 g

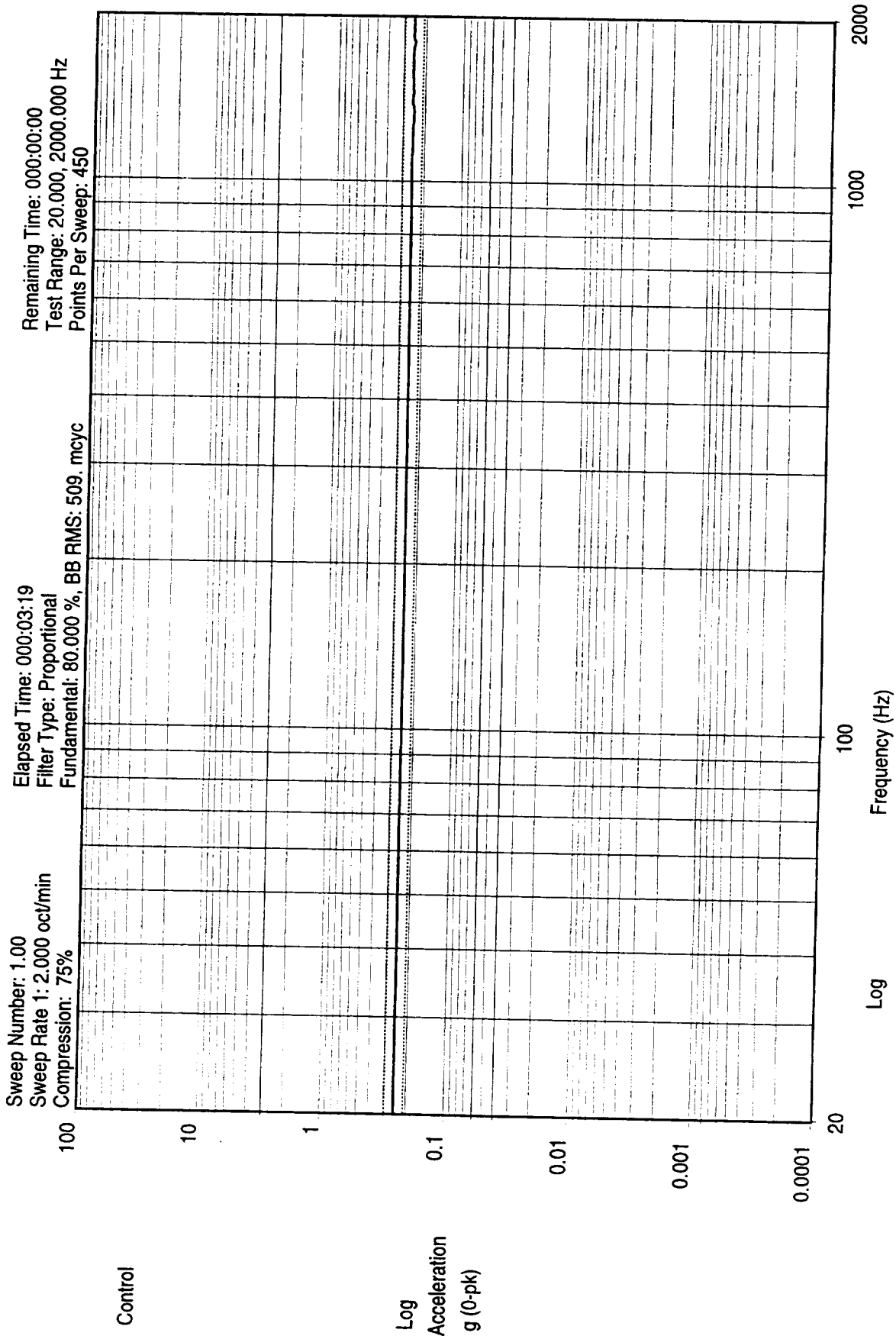
17:13:15
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538595
Z AXIS TEST P/N 1348360-1 S/N F10

Test Name: PLO.tmp



11-1-98

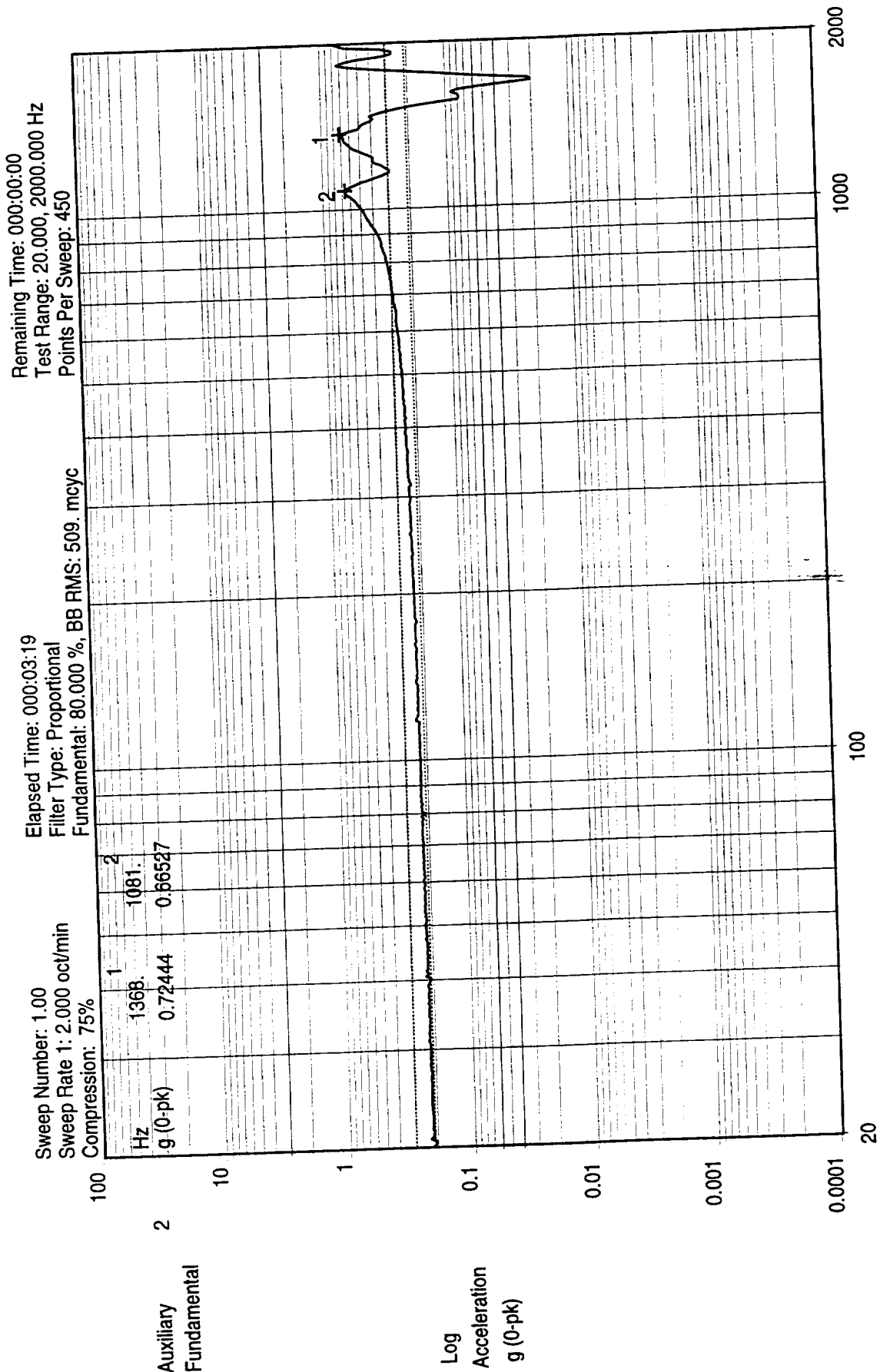


11-4-98

ENG 217

197

17:23:25
04-Nov-1998



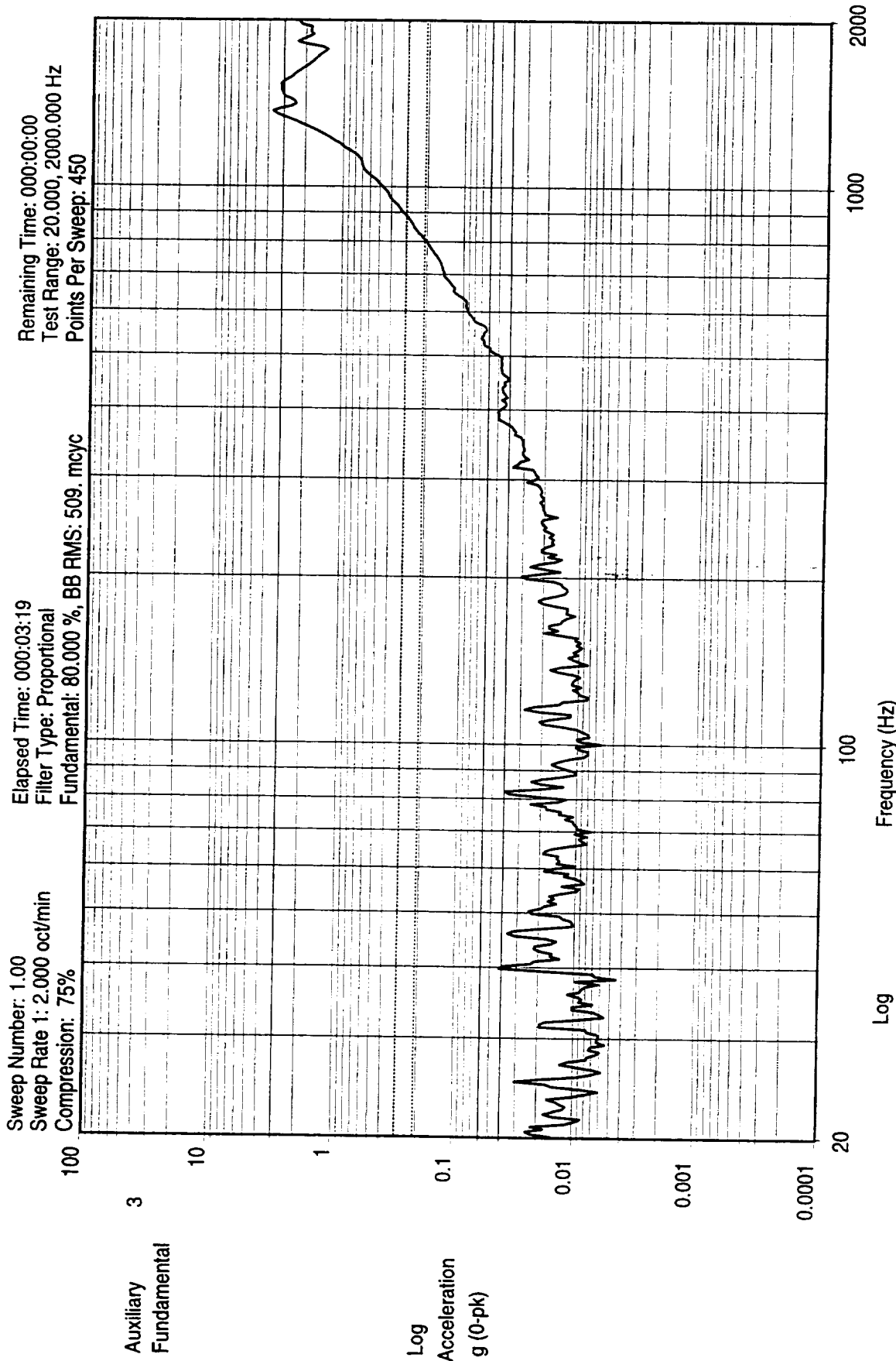
UNIT Z

11-4-98



AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 Z AXIS POST SINE TEST P/N 1348360-1 S/N F10
 Sine Test Name: PLO.tmp

17:24:01
 04-Nov-1998



UNIT Y

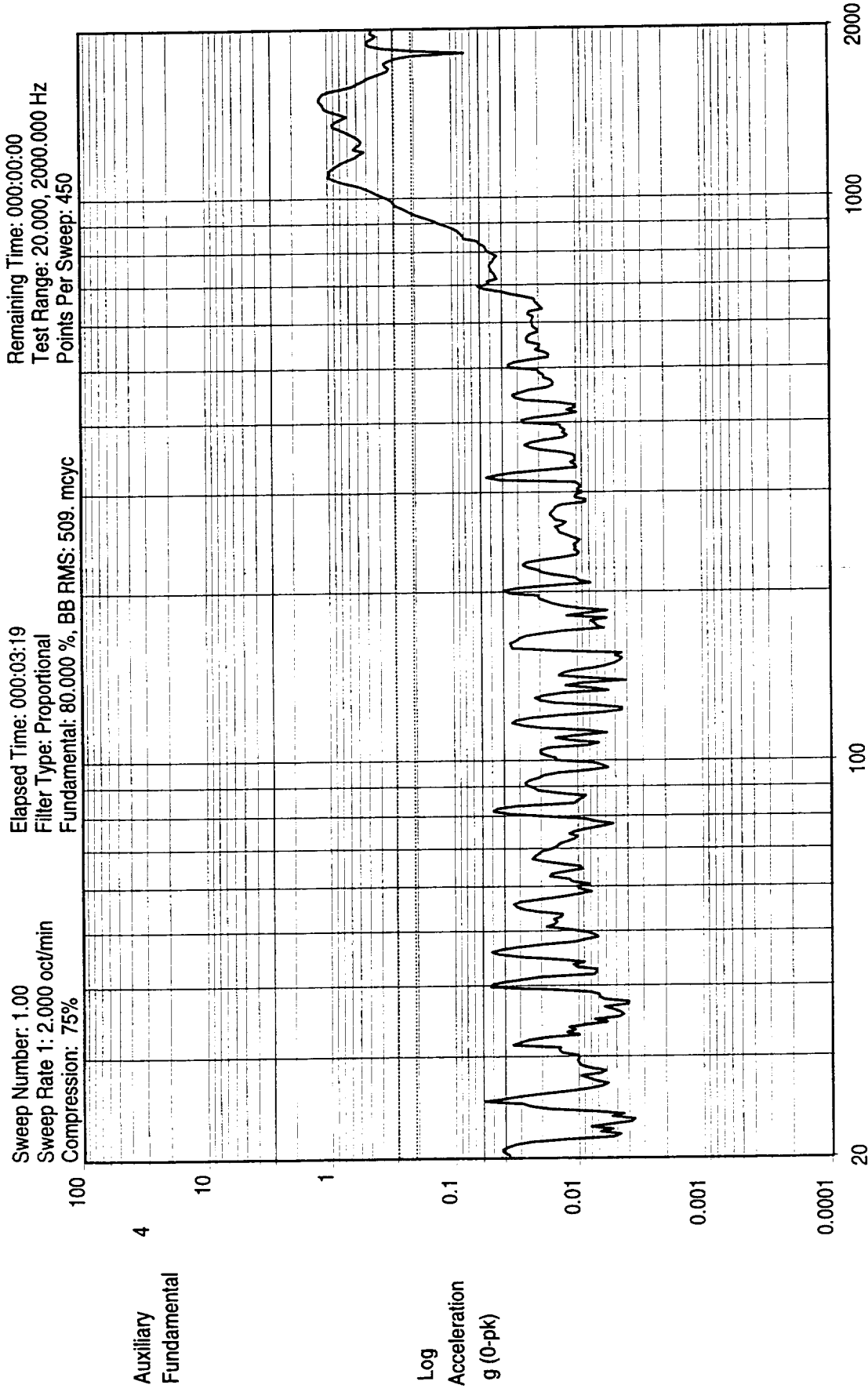
11-4-98



AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
 Z AXIS POST SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

17:24:05
 04-Nov-1998



UNIT X

11-4-98

ENG
217

7A
197

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10
Z AXIS POST SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

17:24:09
04-Nov-1998

Section 3A: Frequency and Power Hysteresis - F09

Worst case frequency and power hysteresis at 22°C for S/N F09 are 11 kHz and approximately 0.4 dBm, respectively.

TEST DATA SHEET 7 (Sheet 1 of 3)
Temperature Cycling (Paragraph 4.2.2)

Test Setup Verified: [Signature]
Signature

Temperature Cycle	Cycle 1	Cycle 2	Cycle 3	Cycle 4	Cycle 5	Cycle 6
Frequency 57.290344 GHz ±200 kHz	57.290327 490 GHz	57.290328 285 GHz	57.290330 856 GHz		N	
Output Power 17 to 20 dBm	17.95 dBm	17.8 dBm	17.59 dBm		A	
Frequency 57.290344 GHz ±200 kHz	57.290335 074 GHz	57.290335 877 GHz	57.290338 062 GHz			
Output Power 17 to 20 dBm	18.03 dBm	18.05 dBm	17.85 dBm			

ambient →

Beginning of cycle 3
f _{req} = 57.290330050 GHz
P ₀ = 17.7 dBm

ambient →

f _{req} = 57.290338062
P ₀ = 17.85 dBm

Shop Order No.: 538596
Operation: 0170
Unit Serial No.: F09
Date: 11-13-98

Test Engineer: [Signature]
Quality Control: [Stamp] NOV 18 '98
Govt. Rep.: U. Shin done 11/18/98

Section 3B: Frequency and Power Hysteresis - F10

Worst case frequency and power hysteresis at 22°C for S/N F10 are 12 kHz and approximately 0.1 dBm, respectively.

TEST DATA SHEET 7 (Sheet 1 of 3)
Temperature Cycling (Paragraph 4.2.2)

Test Setup Verified: [Signature]
Signature

Temperature Cycle	Cycle 1	Cycle 2	Cycle 3	Cycle 4	Cycle 5	Cycle 6
Frequency 57.290344 GHz ±200 kHz	57.290 338 986 GHz	57.290336 775 GHz	57.290343 942 GHz		<u>[Signature]</u> 11-5-98	
Output Power 17 to 20 dBm	17.85 dBm	17.8 dBm	17.8 dBm			
Frequency 57.290344 GHz ±200 kHz	57.290343 GHz	57.290347 GHz	57.290348 725 GHz			
Output Power 17 to 20 dBm	17.80 dBm	17.83 dBm	17.9 dBm			

Shop Order No.: 538595

Operation: 0170

Unit Serial No.: F10

Date: 11-5-98

Test Engineer: [Signature]

Quality Control: [Stamp: 74 268] NOV 10 '98

Govt. Rep.: [Stamp: 74 268] 11/11/98

Section 4A: EMI/RE02 - F09

Not required. Qualification Testing done on S/N's F01, F02.

Section 4B: EMI/RE02 - F10

Not required. Qualification Testing done on S/N's F01, F02.

Section 5A: Final Functional Testing - F09

This section contains the results of a full functional test over temperature taken after PLO F09 endured thermal cycling. All tests passed.

TEST DATA SHEET 6C (Sheet 1 of 4)
Functional Testing (Paragraph 4.2.1)

Test Setup Verified: [Signature] Post-Thermal Cycling CPT
Signature

Paragraph 4.2.1.3, Functional Testing:

Step	Test	Expected	Measured	Pass/ Fail
1	Potential Difference from ± 15 V RTN to:			
	PLO Base Plate	< 1.0 Vac	0.03 Vac	Pass
	Spectrum Analyzer	< 1.0 Vac	0.02 Vac	Pass
	Frequency Counter Chassis	< 1.0 Vac	0.1 Vac	Pass
	Power Meter Chassis	< 1.0 Vac	0.07 Vac	Pass
4	Evacuate vacuum chamber and record pressure	$< 10^{-2}$ torr	Pressure = <u>N/A</u>	*
5	Thermal couple readings	TC1 = 22 ± 2 °C	TC1 = <u>24.0</u> °C	Pass
			TC2 = <u>23.9</u> °C	N/A
			TC3 = <u>23.1</u> °C	N/A
6	DRO L/A	0 to 1V	DRO L/A = <u>87 mV</u>	Pass
	PLO L/A	S/N: F06, F08 = 14.6 ± 0.4 V S/N: F07 = 0 to 1V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.53</u> V	Pass
	Is PLO locked?	Yes	Yes <u>yes</u> No _____	Pass
7	PLO Frequency	$57.290344 \pm .0002$ GHz	Freq. = <u>57.29033910</u> GHz	
	PLO Power	17 to 20 dBm	P = <u>18.11</u> dBm	Pass
8	Input Voltage and Current			
	VM1 Voltage	$+15 \pm 0.1$ V	VM1 = <u>15.19</u> V	Pass
	VM2 Voltage	-15 ± 0.1 V	VM2 = <u>-15.14</u> V	Pass
	IM1 Current	600 mA max.	IM1 = <u>522</u> mA	Pass
	IM2 Current	100 mA max.	IM2 = <u>-63.9</u> mA	Pass
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>86.6 mV</u>	Pass
	PLO L/A Voltage	S/N: F06, F07, F08 = 14.6 ± 0.4 V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.53</u> V	Pass
12	RF Output Power and Frequency	17 to 20 dBm	P = <u>18.11</u> dBm	Pass
		$57.290344 \pm .0002$ GHz	Freq. = <u>57.29033910</u> GHz	Pass
	Baseplate Temp. (TC1)	TC1 = 22 ± 2 °C	TC1 = <u>23.4</u> °C	Pass

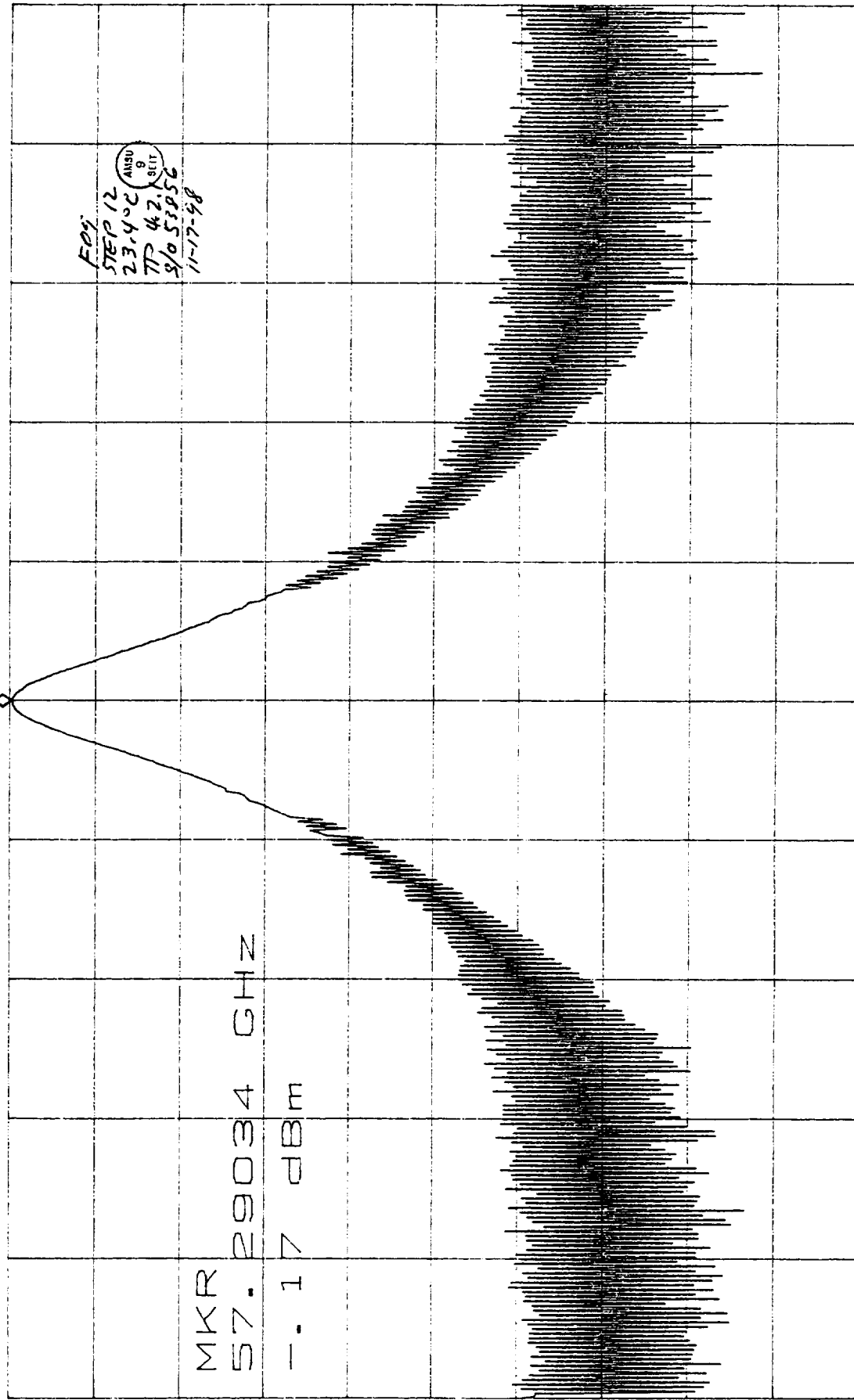
*Record data only if performing test under vacuum

CL 30.0dB
RL 0dBm

MKR -.17dBm
57.29034GHz

10dB/

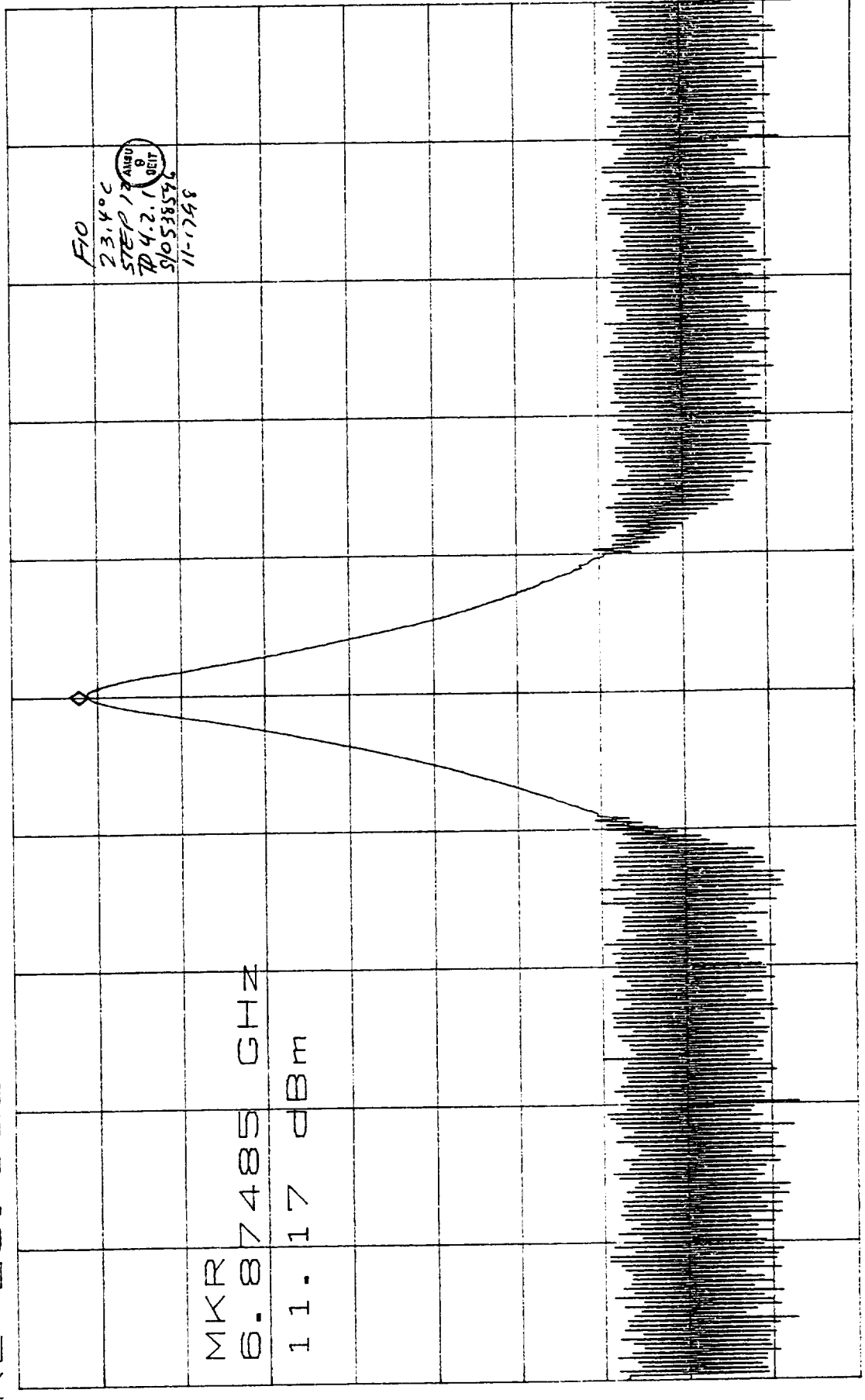
MKR
57.29034 GHz
-.17 dBm



CENTER 57.29034GHz SPAN 10.00MHz
*RBW 300kHz VBW 300kHz *SWP 50.0ms

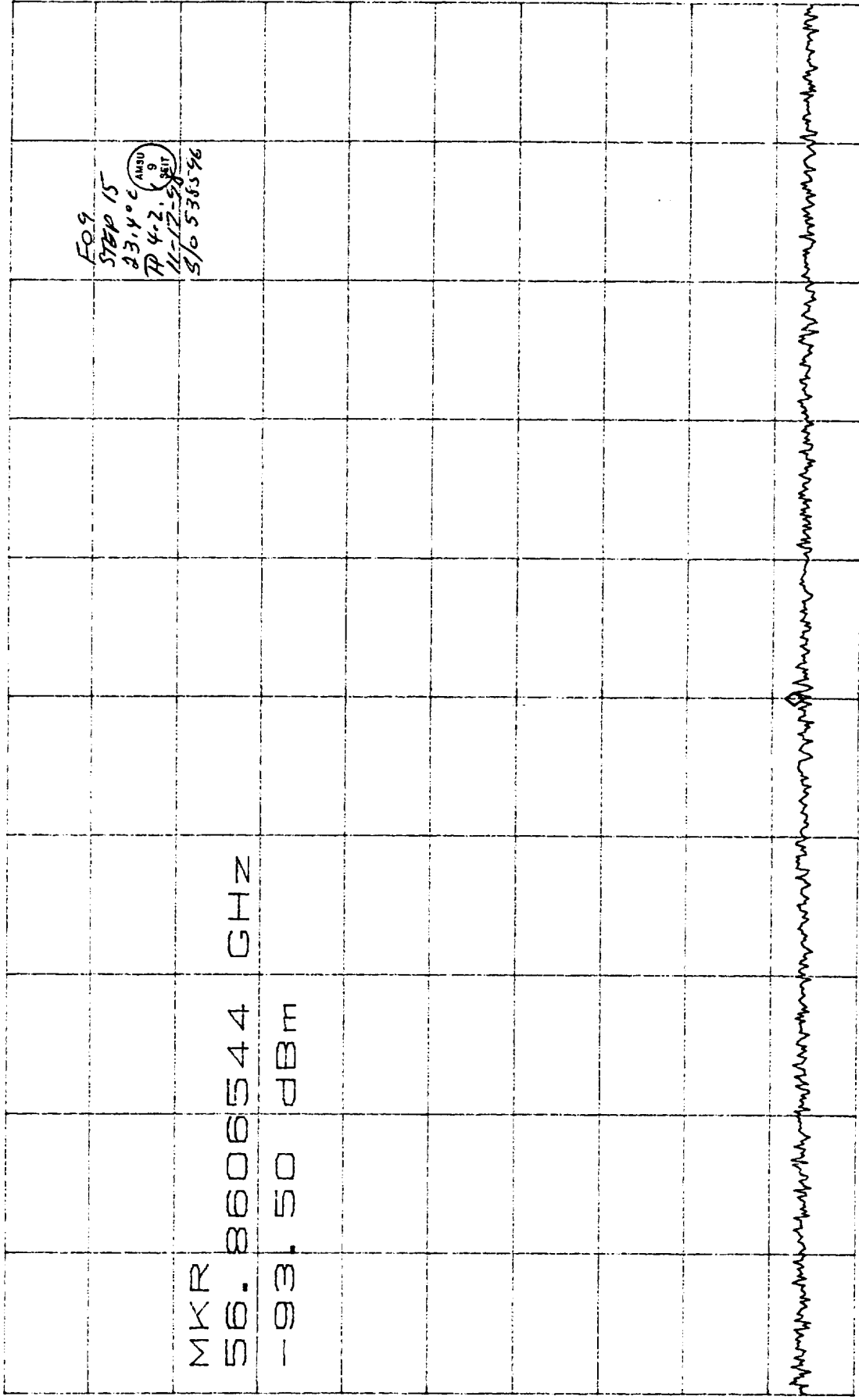
*ATTEN 30dB
RL 20.00dB

MKR 11.17dBm
6.87485GHz



CENTER 6.87485GHz SPAN 20.00MHz
*RBW 300kHz VBW 300kHz SWP 50.0ms

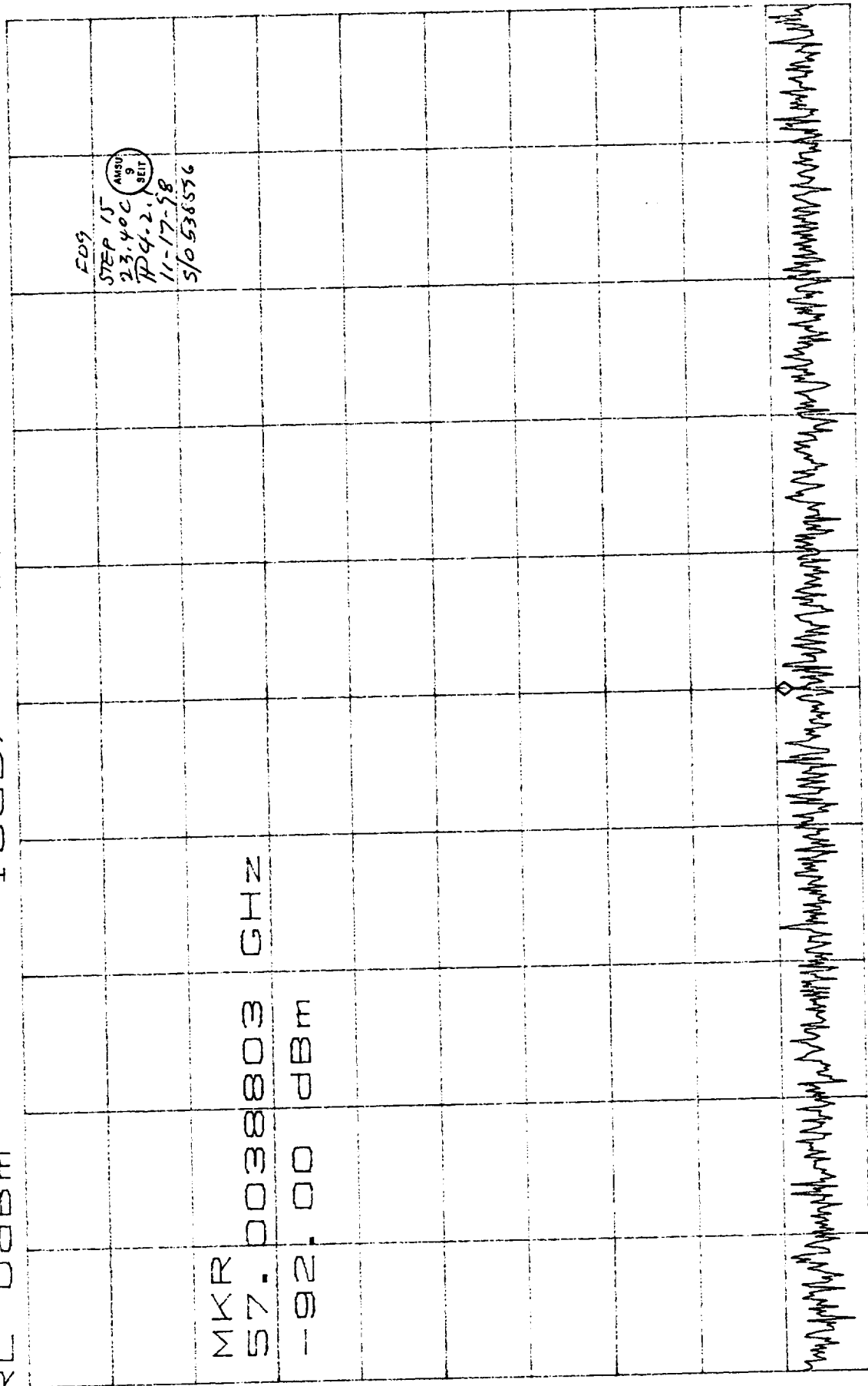
CL 30.0dB VAVG 10 MKR -93.50dBm
RL 0dBm 10dB/ 56.8606544GHz



D

CENTER 56.8606544GHz SPAN 500.0kHz
RBW 3.0kHz *VBW 1.0kHz *SWP 2.00sec

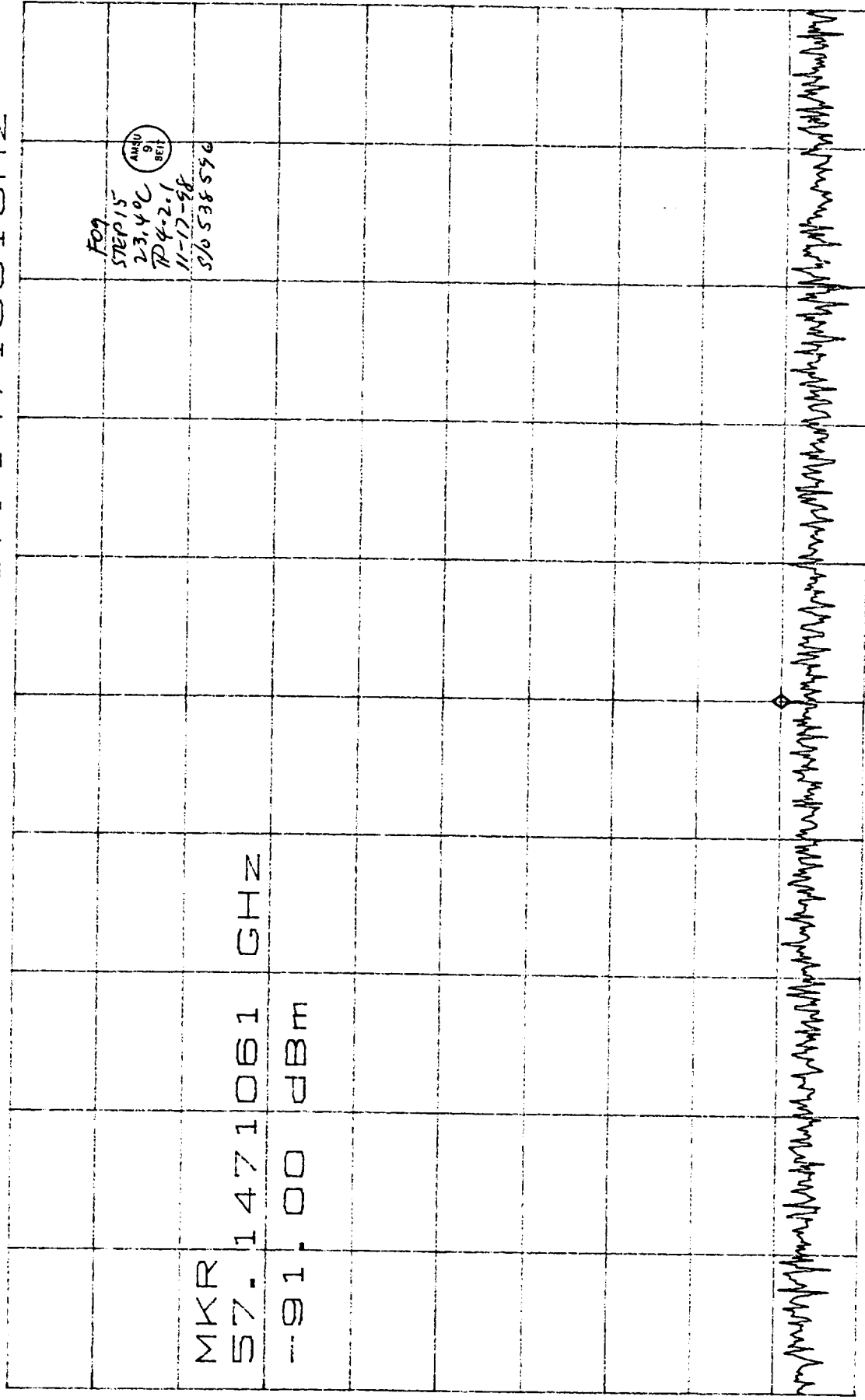
CL 30.0dB VAVG 1 MKR -92.00dBm
 RL 0dBm 10dB/ 57.0038803GHz



MKR
 57.0038803 GHz
 -92.00 dBm

CENTER 57.0038803GHz SPAN 500.0KHz
 RBW 3.0KHz *VBW 1.0KHz *SWP 2.00sec

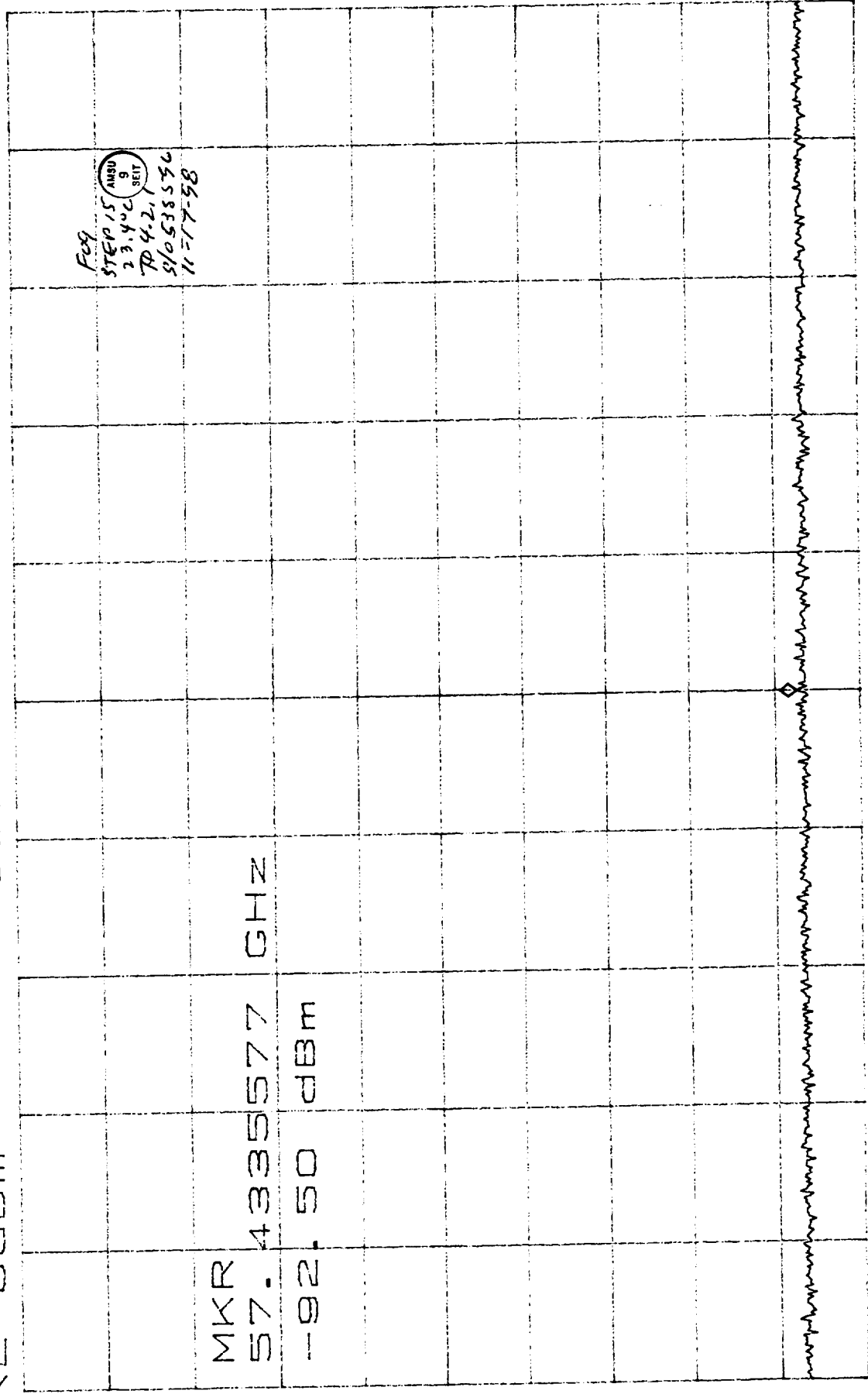
CL 30.0dB VAVG 1 MKR -91.00dBm
RL 0dBm 10dB/ 57.1471061GHz



D

CENTER 57.1471061GHz SPAN 500.0KHz
RBW 3.0KHz *VBW 1.0KHz *SWP 2.00sec

CL 30.0dB VAVG 0 MKR -92.50dBm
RL 0dBm 10dB/ 57.4335577GHz

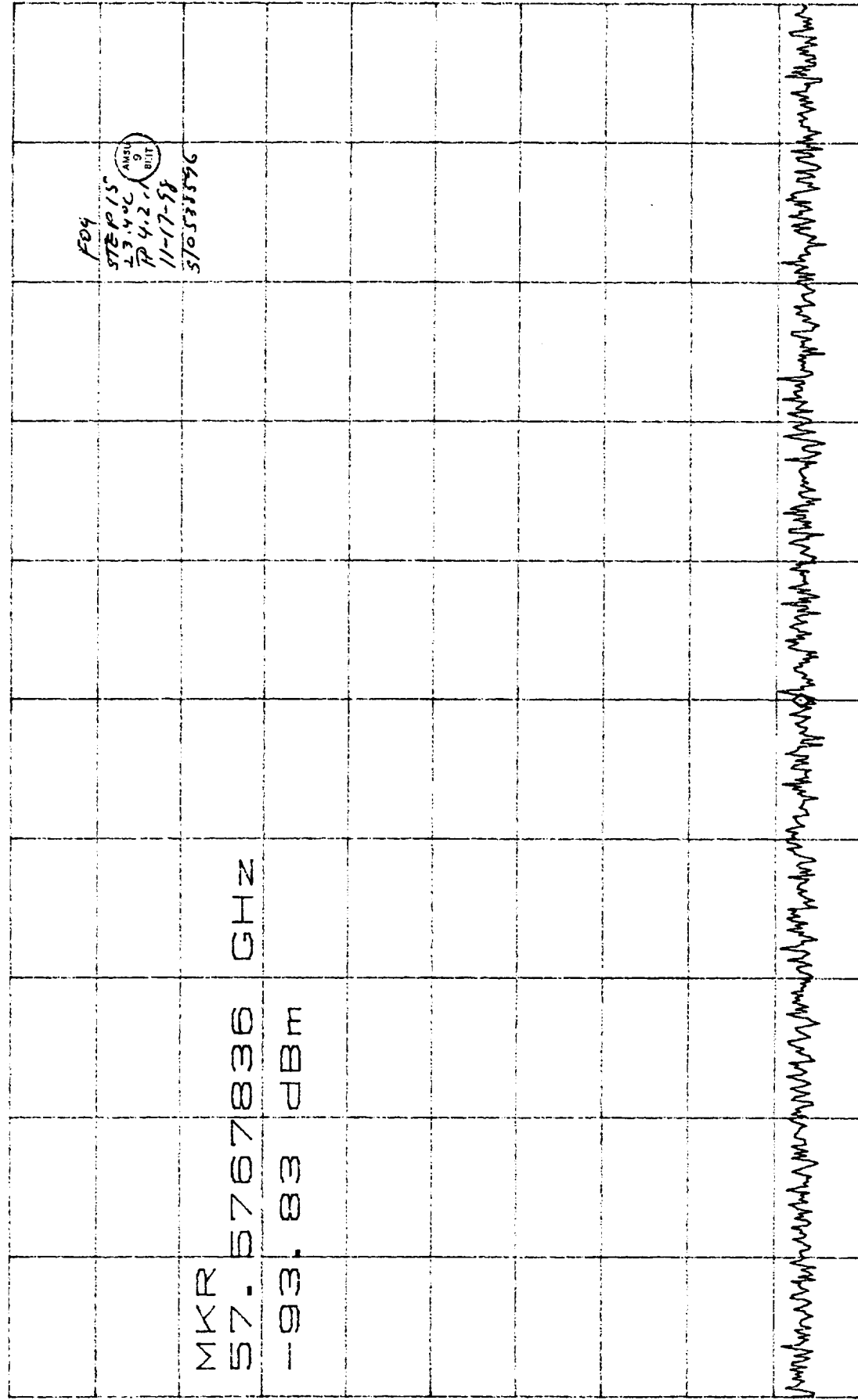


MKR
57.4335577 GHz
-92.50 dBm

D

CENTER 57.4335577GHz SPAN 500.0KHz
RBW 3.0KHz *VBW 1.0KHz *SWP 2.00sec

CL 30.0dB VAVG 3 MKR -93.83dBm
 RL 0dBm 10dB/ 57.5767836GHz



D

CENTER 57.5767836GHz SPAN 500.0KHz
 RBW 3.0KHz *VBW 1.0KHz *SWP 2.00Sec

CL 30.0dB VAVG 2 MKR -94.50dBm
RL 0dBm 10dB/ 57.7200094GHZ

MKR
57.7200094 GHZ
-94.50 dBm

FORM
STEP 15
23.40C
74.2.1
11-17-55
S/O 538556



57.7200094GHZ

CENTER 57.7200094GHZ SPAN 500.0KHZ
RBW 3.0KHZ *VBW 1.0KHZ *SWP 2.00sec

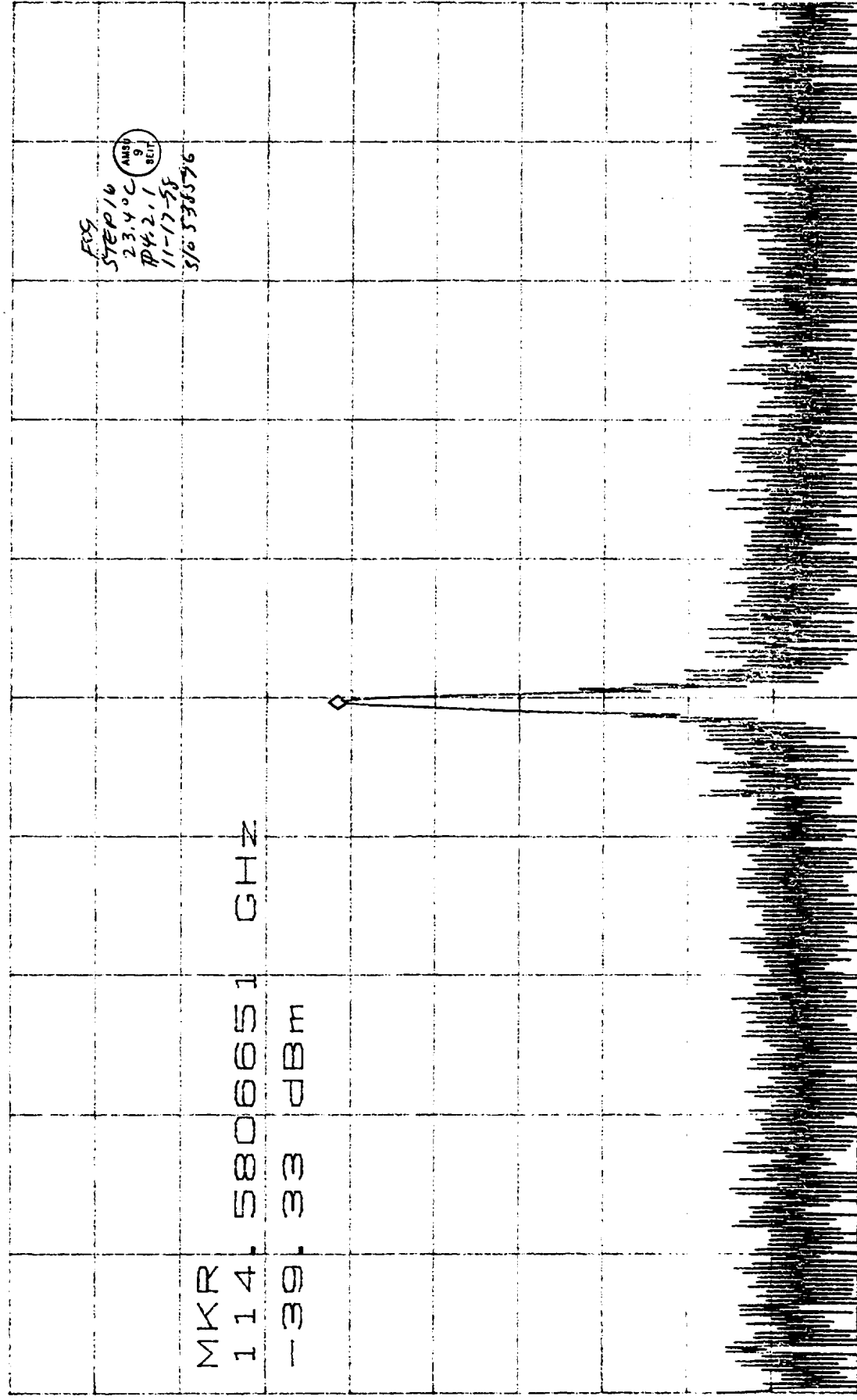
CL 30.0dB

RL 0dBm

MKR -39.33dBm

114.5806651GHz

10dB/



MKR

114.5806651 GHz

-39.33 dBm

CENTER 114.5806655GHz SPAN 100.0KHz
*RBW 300Hz *VBW 1.0KHz *SWP 2.800000

TEST DATA SHEET 6C (Sheet 2 of 4)
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/ Fail
13	Frequency vs. Voltage			Pass
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>15.2</u> V	N/A
		-15.2 ± 0.05 V	-Voltage = <u>-15.2</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.29033214</u> GHz	
		17 to 20 dBm	P = <u>18.15</u> dBm	
14	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	N/A
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290332156</u> GHz	
		17 to 20 dBm	P = <u>18.18</u> dBm	
15	Spurious and Sub	-200 to -90 dBc	<u>see plots</u> <u>-39.33</u> dBm	Pass
16	Power level of 114.58 GHz signal	<-10 dBm		Pass
17	Load VSWR and Frequency Pulling			N/A
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>7 mHz</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>1.0</u> dB Peak	N/A
18	Operating Temperature @ 1°C baseplate	TC1 = 1 ± 2°C	TC1 = <u>2.7°C</u>	Pass
			TC2 = <u>2.8°C</u>	N/A
			TC3 = <u>1.9°C</u>	N/A
		0 - 1V	DRO L/A = <u>71.8 mV</u>	Pass
		S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.53</u> V	Pass
19	Input Voltage and Current			
	VM1 Voltage	+15 ± 0.1 V	VM1 = <u>15.0</u> V	Pass
	VM2 Voltage	-15 ± 0.1 V	VM2 = <u>-15.0</u> V	
	IM1 Current	600 mA max.	IM1 = <u>508</u> mA	
	IM2 Current	100 mA max.	IM2 = <u>62</u> mA	
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>71.8 mV</u>	
	PLO L/A Voltage	S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.53</u> V	
	RF Output Power	17 to 20 dBm	Power = <u>19.09</u> dBm	
	Frequency	57.290344 ± .0002 GHz	Freq. = <u>57.290324398</u> GHz	

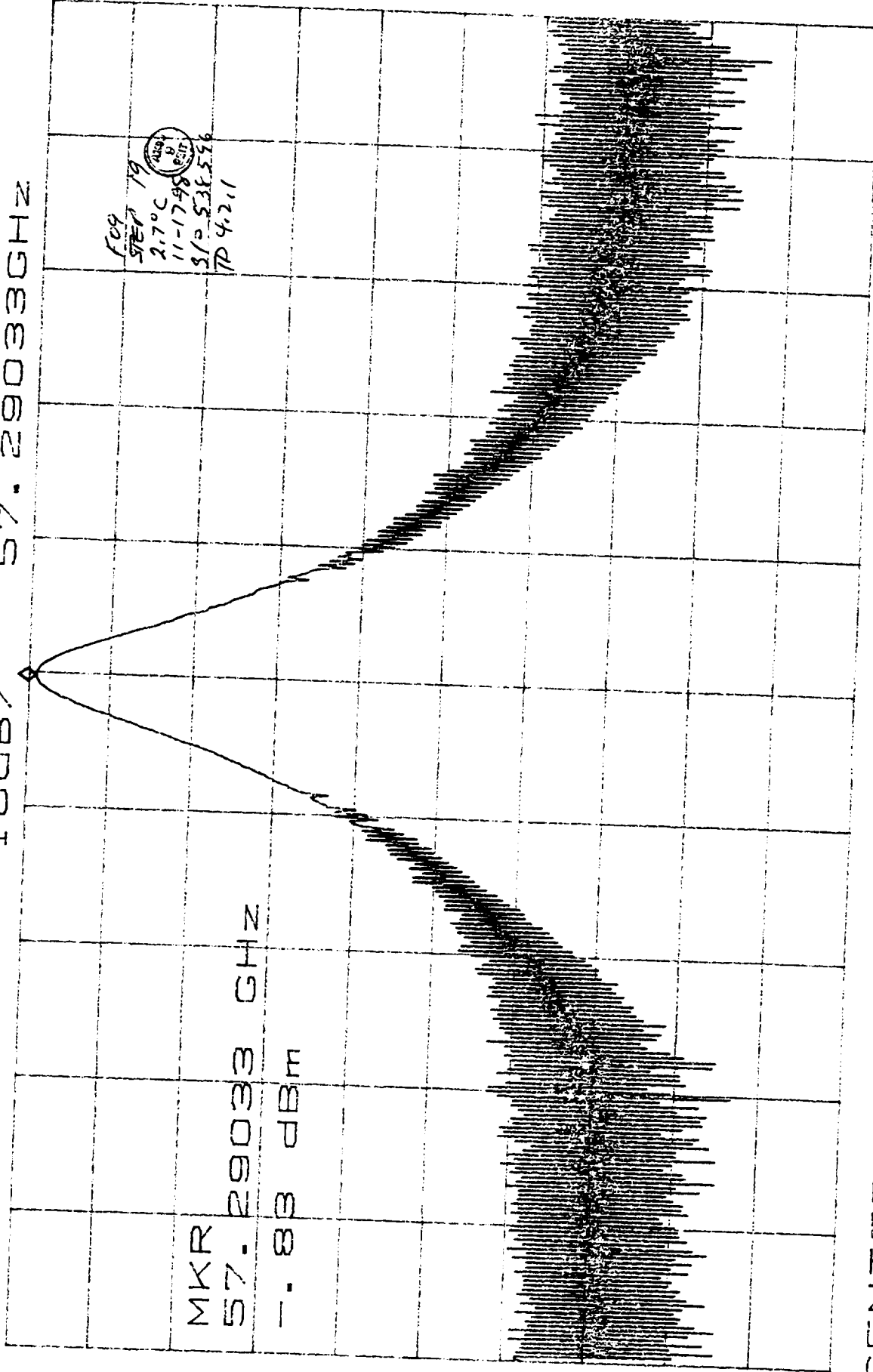
CL 30.0dB
RL 0dBm

MKR --.83dBm
57.29033GHz

10dB/

MKR
57.29033 GHz
--.83 dBm

FC9
SEP 19
2.7°C
11-1748
3/0.536536
TP 42.1

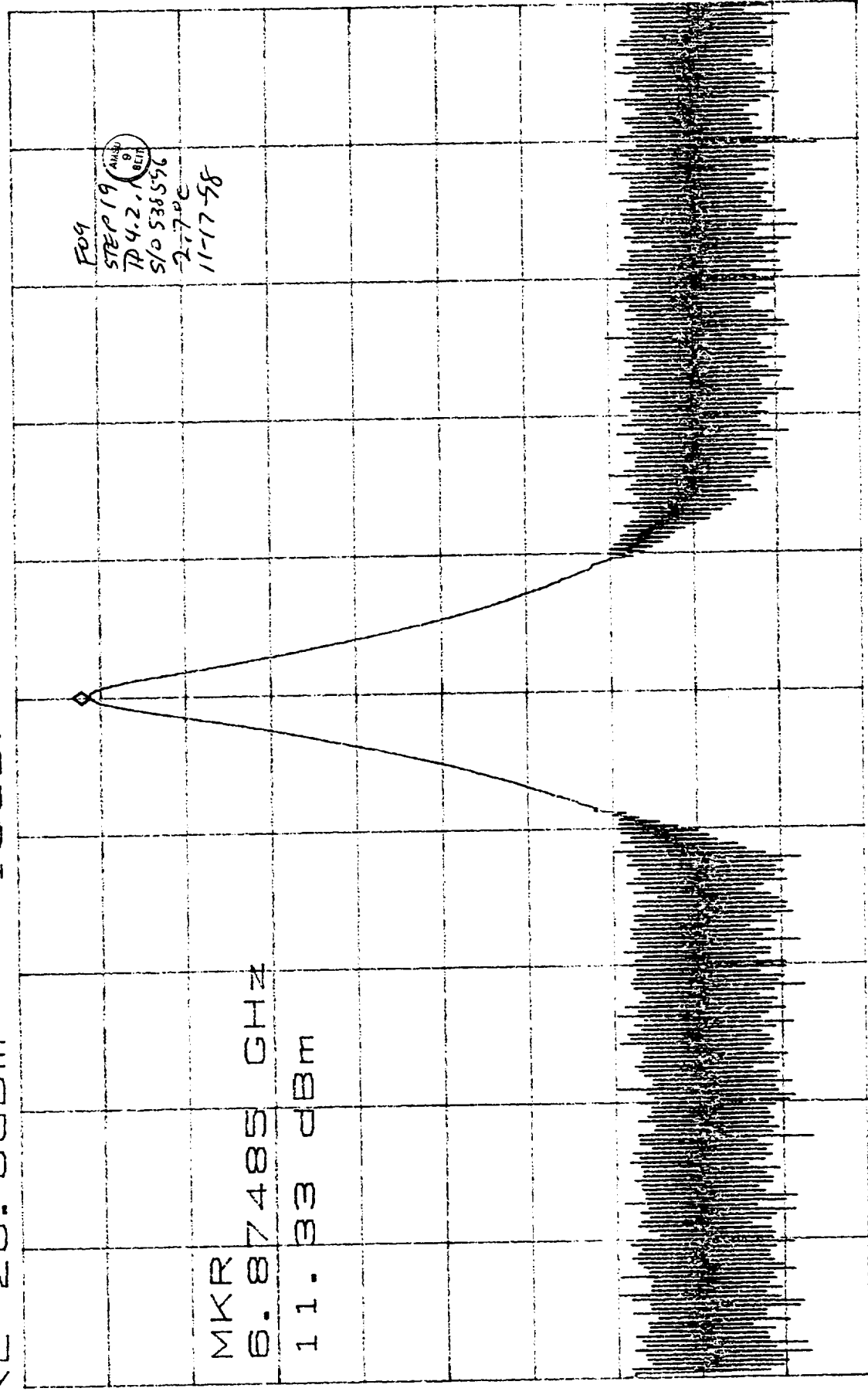


CENTER 57.29034GHz

SPAN 10.00MHz
*SWP 50.0ms

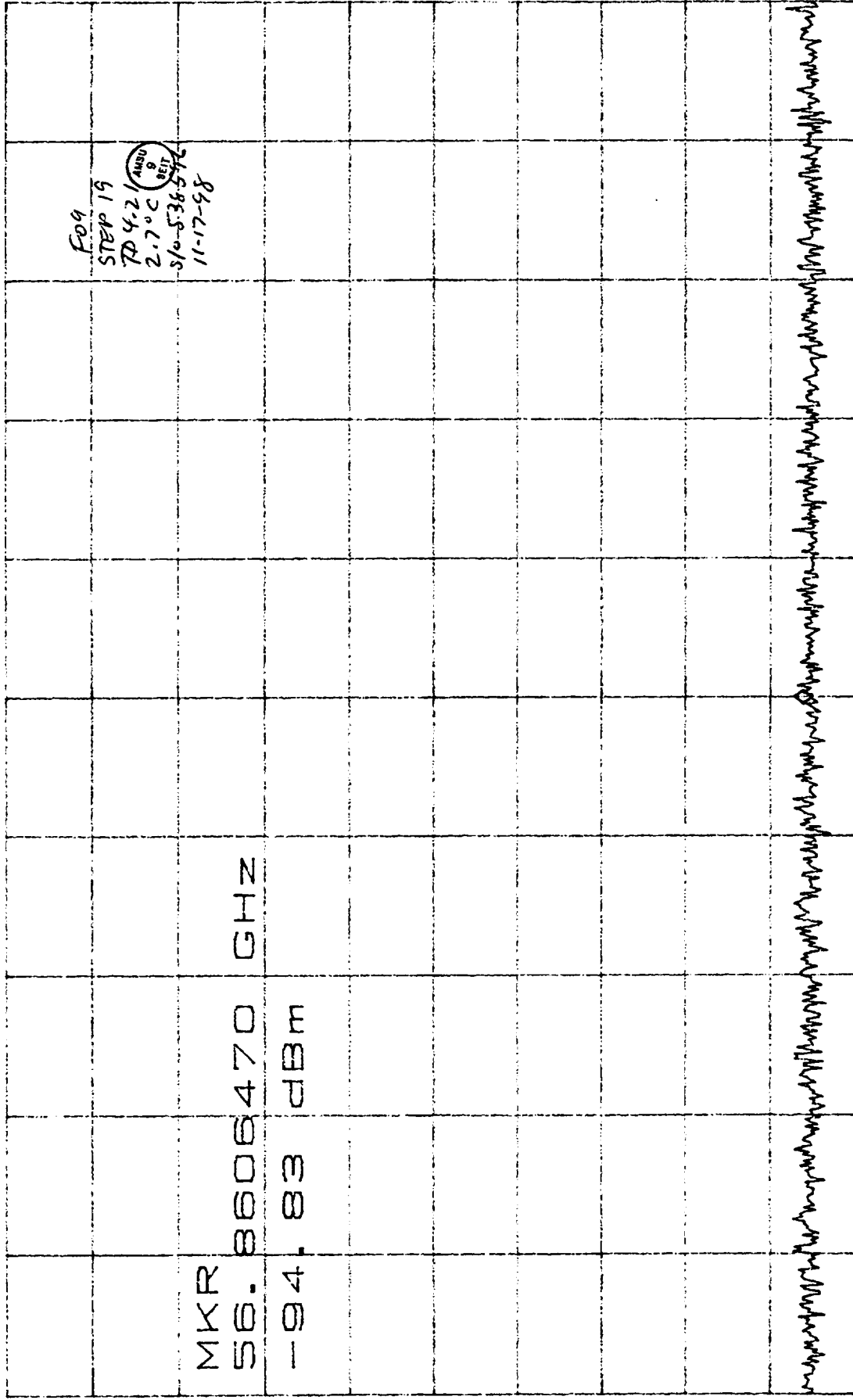
*RBW 300kHz *VBW 300kHz

ATTEN 30dB MKR 11.33dBm
RL 20.0dBm 6.87485GHz 10dB/



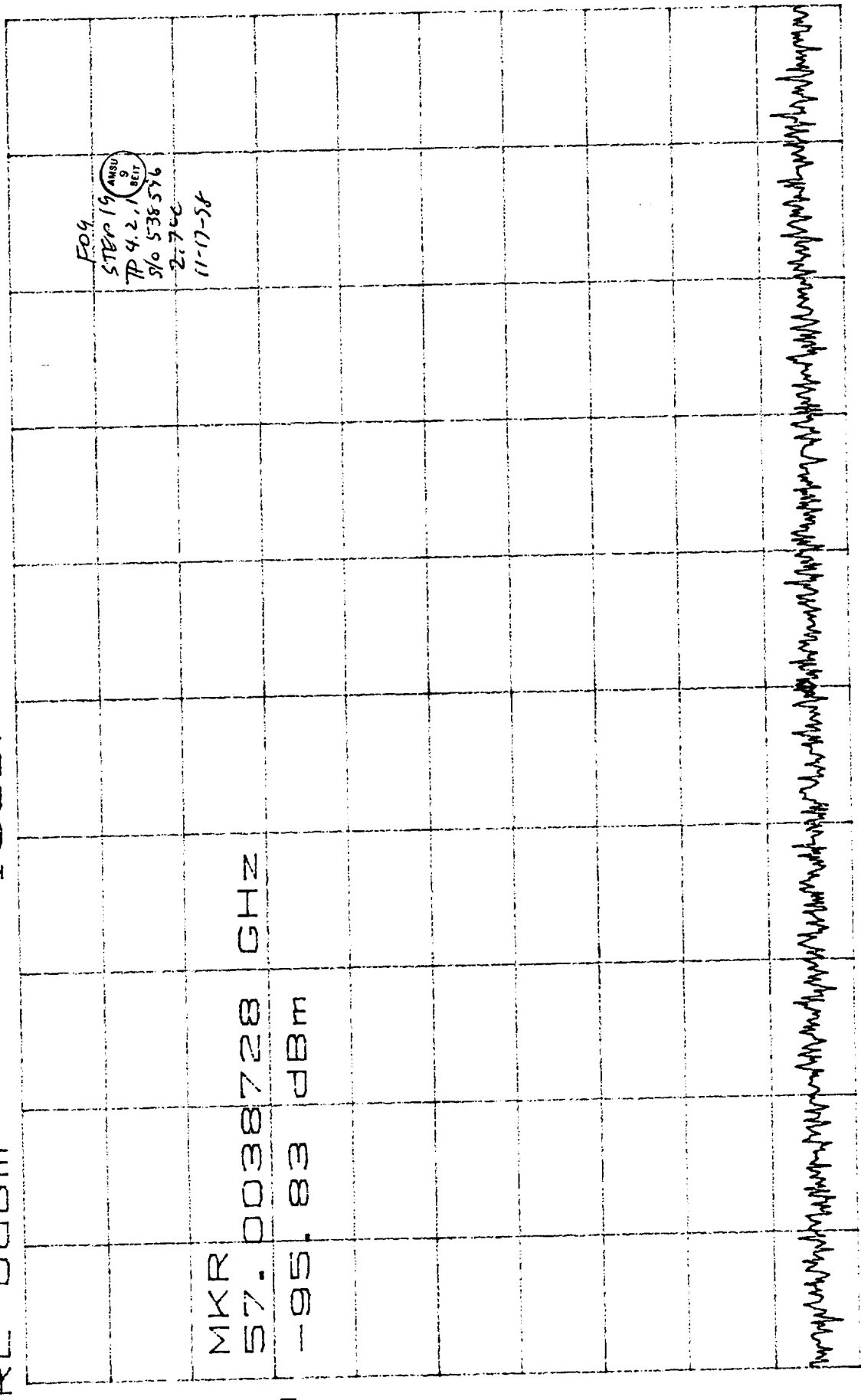
CENTER 6.87485GHz SPAN 20.00MHz
*RBW 300kHz VBW 300kHz SWP 50.0MHz

CL 30.0dB VAVG 3 MKR -94.83dBm
RL 0dBm 10dB/ 56.8606470GHZ



CENTER 56.8606470GHZ SPAN 500.0KHZ
*RBW 3.0KHZ *VBW 1.0KHZ *SWP 2.00sec

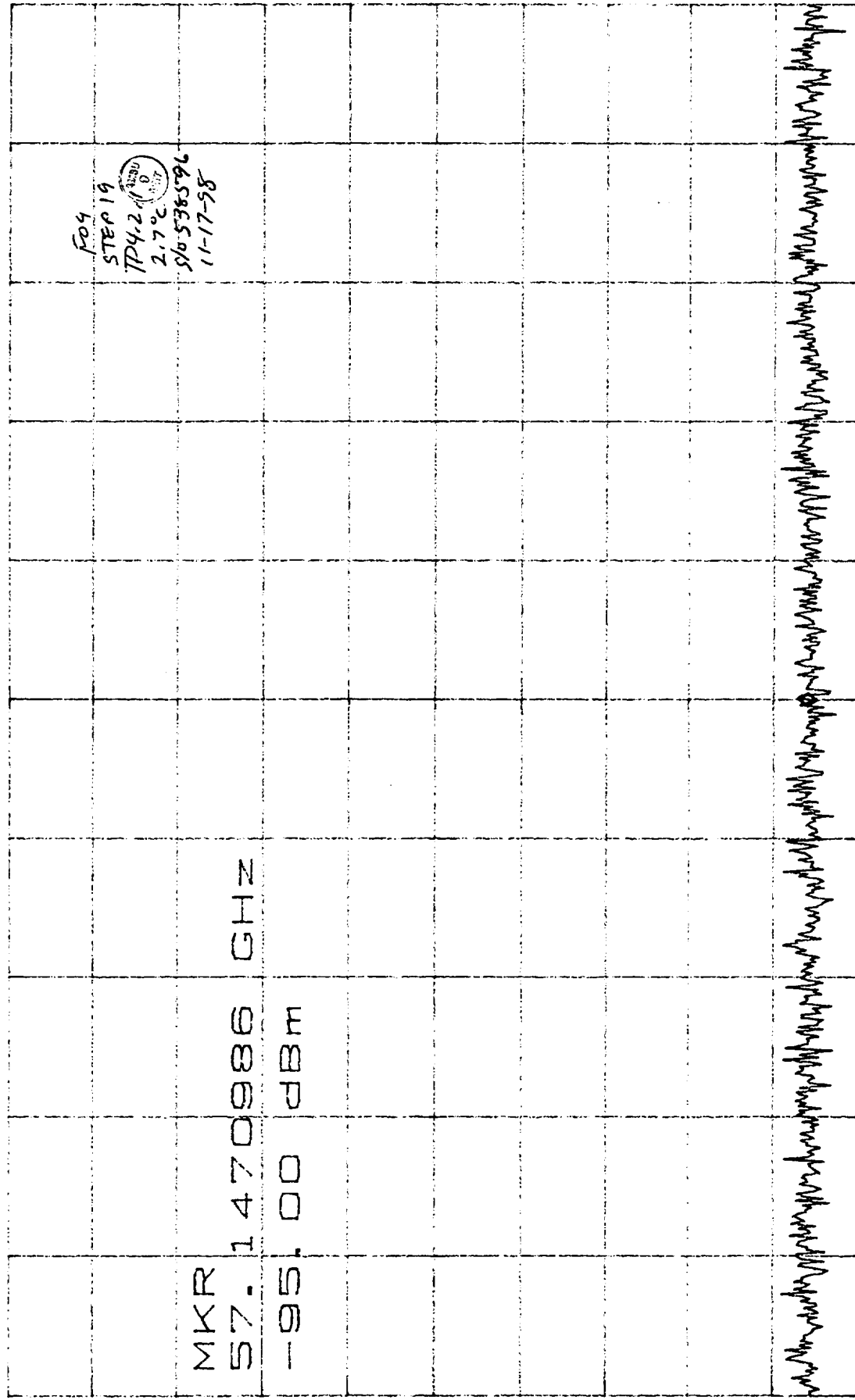
CL 30.0dB VAVG 2 MKR -95.83dBm
 RL 0dBm 10dB/ 57.0038728GHz



MKR
 57.0038728 GHz
 -95.83 dBm

CENTER 57.0038728GHz SPAN 500.0KHz
 *RBW 3.0KHz *VBW 1.0KHz *SWP 2.00sec

CL 30.0dB VAVG 2 MKR -95.00dBm
RL 0dBm 10dB/ 57.1470986GHZ



CENTER 57.1470986GHZ SPAN 500.0KHZ
*RBW 3.0KHZ *VBW 1.0KHZ *SWP 2.00sec

CL 30.0dB VAVG 3 MKR -93.33dBm
RL 0dBm 10dB/ 57.4335502GHZ

MKR 57.4335502 GHZ
-93.33 dBm

Feb
STEP 19
2.70C
S/O 538596
P4216
11-17-98



CENTER 57.4335502GHZ SPAN 500.0KHZ
*RBW 3.0KHZ *VBW 1.0KHZ *SWP 2.00sec

CL 30.0dB
RL 0dBm

VAVG 2
10dB/

MKR -94.17dBm
57.5767760GHz

209
STE 19
2.7°C
P4.2.1
5/0.538556
11-17-98

MKR
57.5767760 GHz
-94.17 dBm

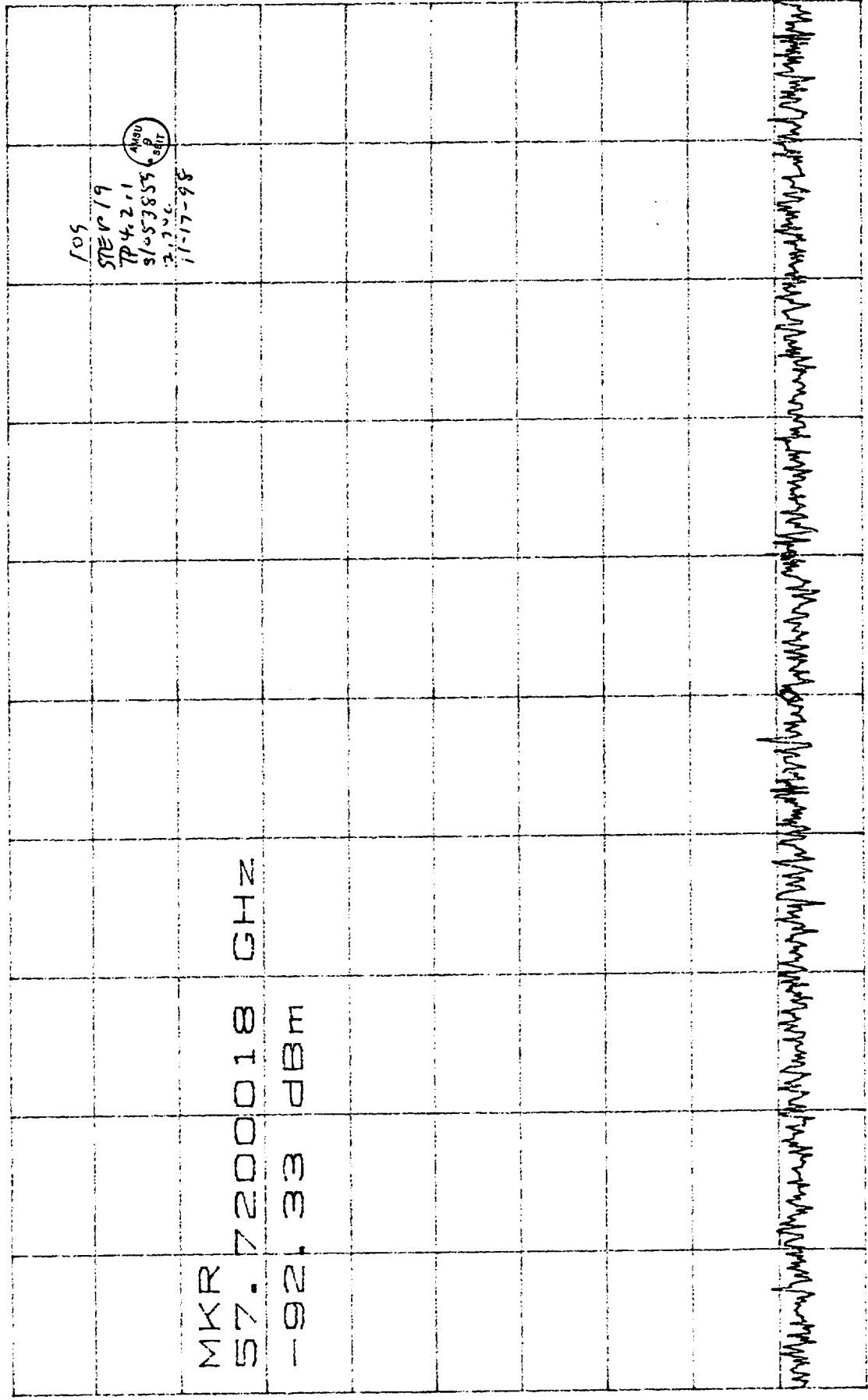
D



CENTER 57.5767760GHz

*RBW 3.0KHz *VBW 1.0KHz SPAN 500.0KHz
*SWP 2.00sec

CL 30.0dB VAVG 2 MKR -92.33dBm
 RL 0dBm 10dB/ 57.7200018GHz

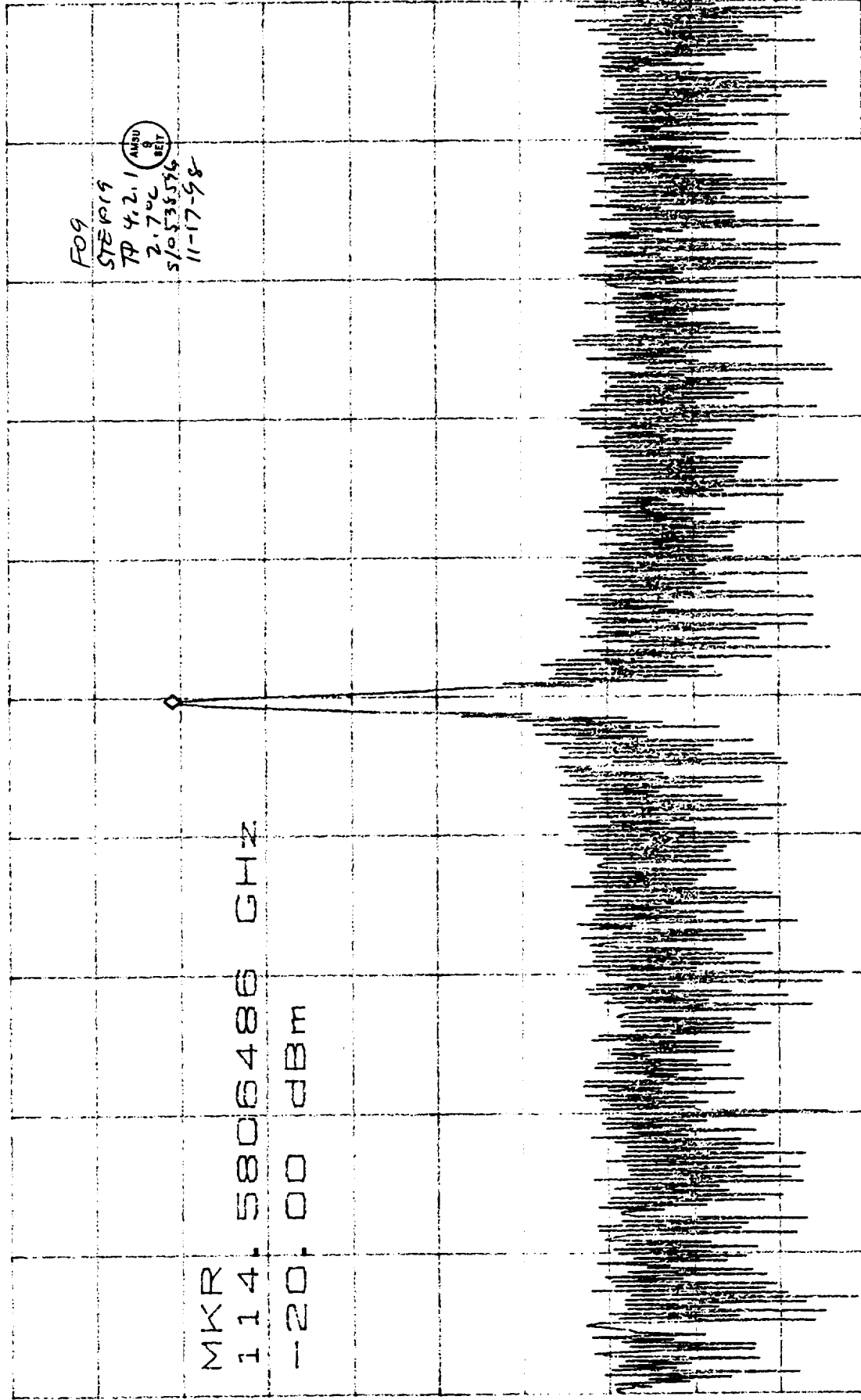


CENTER 57.7200018GHz SPAN 500.0KHz
 *RBW 3.0KHz *VBW 1.0KHz
 *SWP 2.000000

CL 30.0dB
RL 0dBm

MKR -20.00dBm
114.5806486GHz

10dB/



CENTER 114.5806486GHz SPAN 100.0KHz
*RBW 300Hz *VBW 1.0KHz *SWP 2.800000

TEST DATA SHEET 6C (Sheet 3 of 4)
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

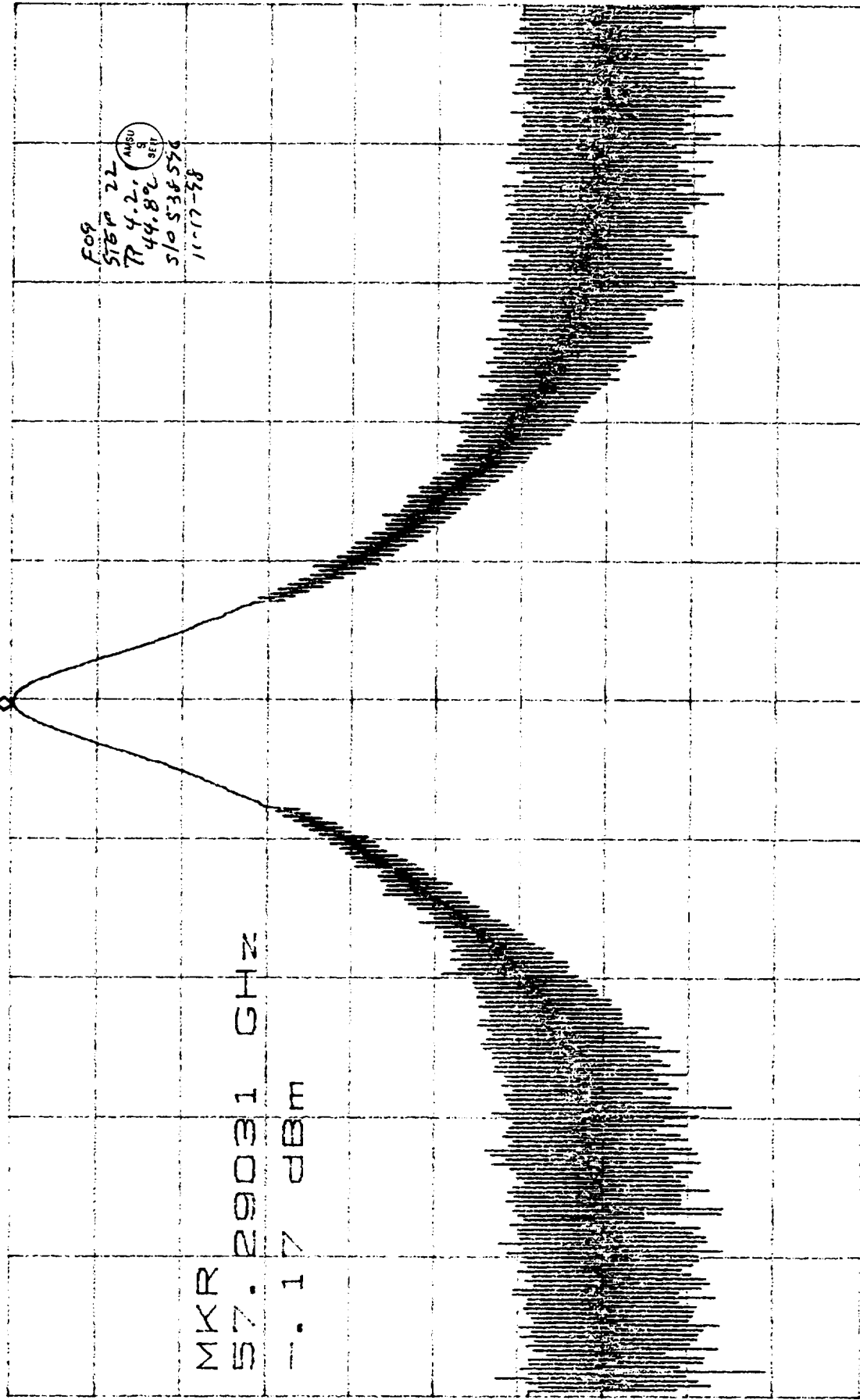
Paragraph 4.2.1.3 (Cont):				
Step	Test	Expected	Measured	Pass/ Fail
19 (Cont)	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>+15.2</u> V	Pass
		-15.2 ± 0.05 V	-Voltage = <u>-15.2</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290344394</u> GHz	
		17 to 20 dBm	Power = <u>18.62</u> dBm	
	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>+14.8</u> V	
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290344236</u> GHz	
		17 to 20 dBm	Power = <u>18.62</u> dBm	
	Spurious and Sub	-200 to -90 dBc	<u>See plots</u>	Pass
	Power level of 114.58 GHz signal	<-10 dBm	<u>-20</u> dBm	
	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>6 Hz</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>0.7</u> dB	N/A
21	Operating Temperature @ +44°C Baseplate	TC1 = 44 ± 2°C	TC1 = <u>44°C</u>	Pass
			TC2 = <u>43.9°C</u>	N/A
			TC3 = <u>43.8°C</u>	N/A
		0 - 1V	DRO L/A = <u>139m</u> V	Pass
		S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.54</u> V	
22	Input Voltage and Current			
	VM1 Voltage	+15 ± 0.1 V	VM1 = <u>15.0</u> V	
	VM2 Voltage	-15 ± 0.1 V	VM2 = <u>-15.0</u> V	
	IM1 Current	600 mA max.	IM1 = <u>534</u> mA	
	IM2 Current	100 mA max.	IM2 = <u>-65</u> mA	
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>140 m</u> V	
	PLO L/A Voltage	S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.54</u> V	
	RF Output Power and	17 to 20 dBm	Power = <u>17.66</u> dBm	
	Frequency	57.290344 ± .0002 GHz	Freq. = <u>57.290344503</u> GHz	
		Pass		

CL 30.0dB
RL 0dBm

MKR --.17dBm
57.29031GHz

10dB/

MKR
57.29031 GHz
--.17 dBm



CENTER 57.29034GHz

SPAN 10.00MHz

* RBW 300kHz

VBW 300kHz

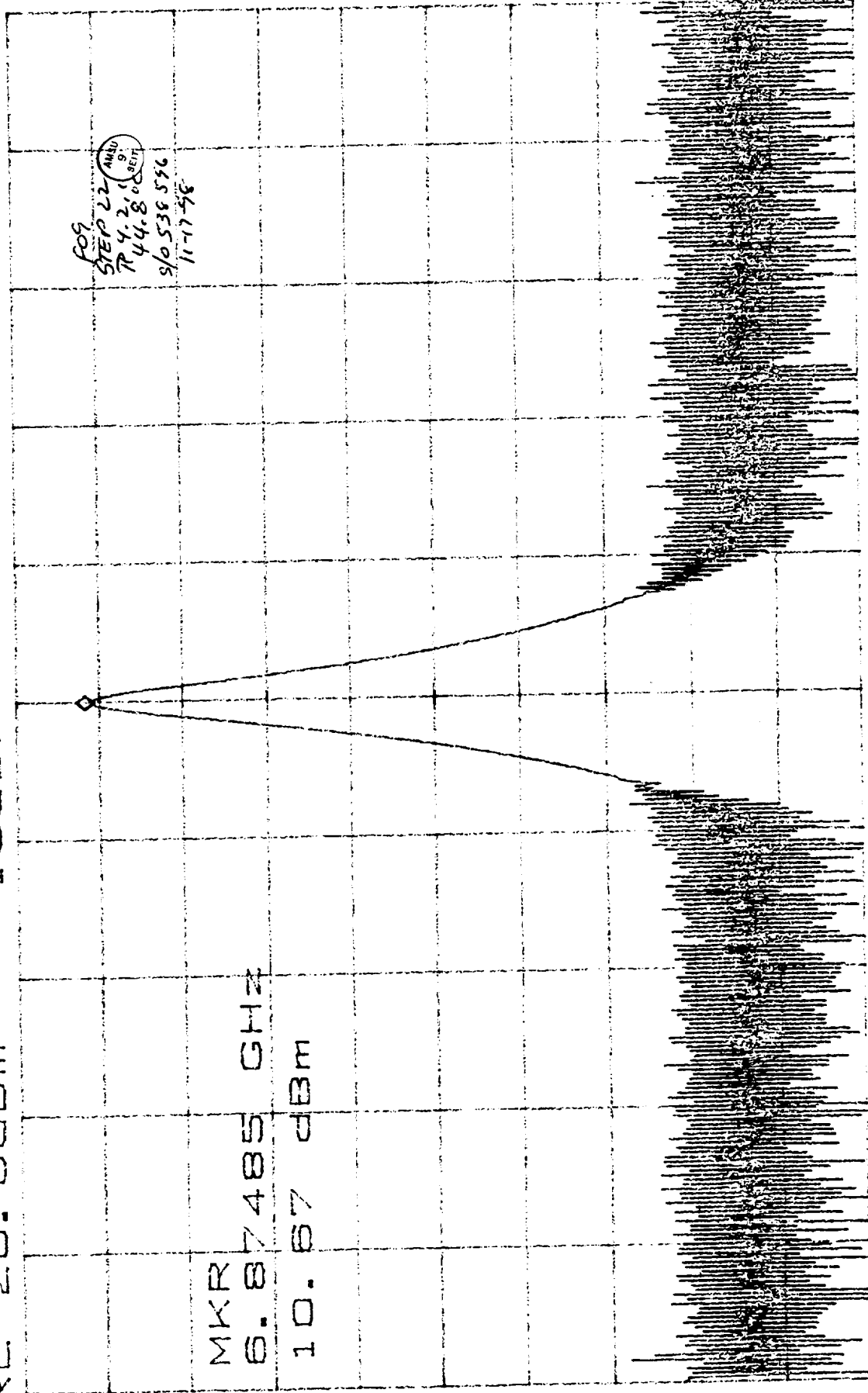
* SWP 50.0ms

*ATTEN 30dB
RL 20.0dBm

MKR 10.67dBm
6.87485GHz

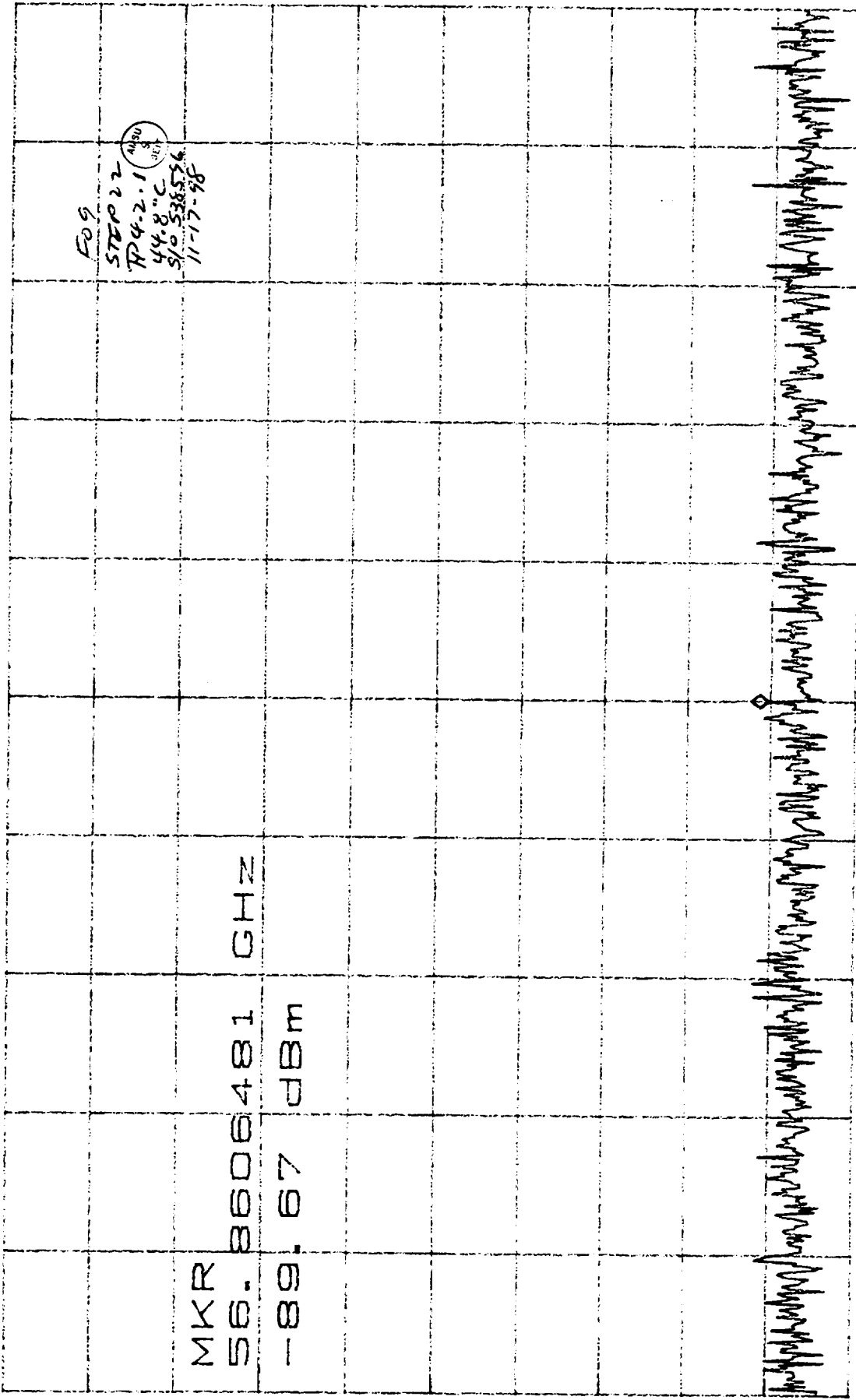
10dB/

MKR
6.87485 GHz
10.67 dBm



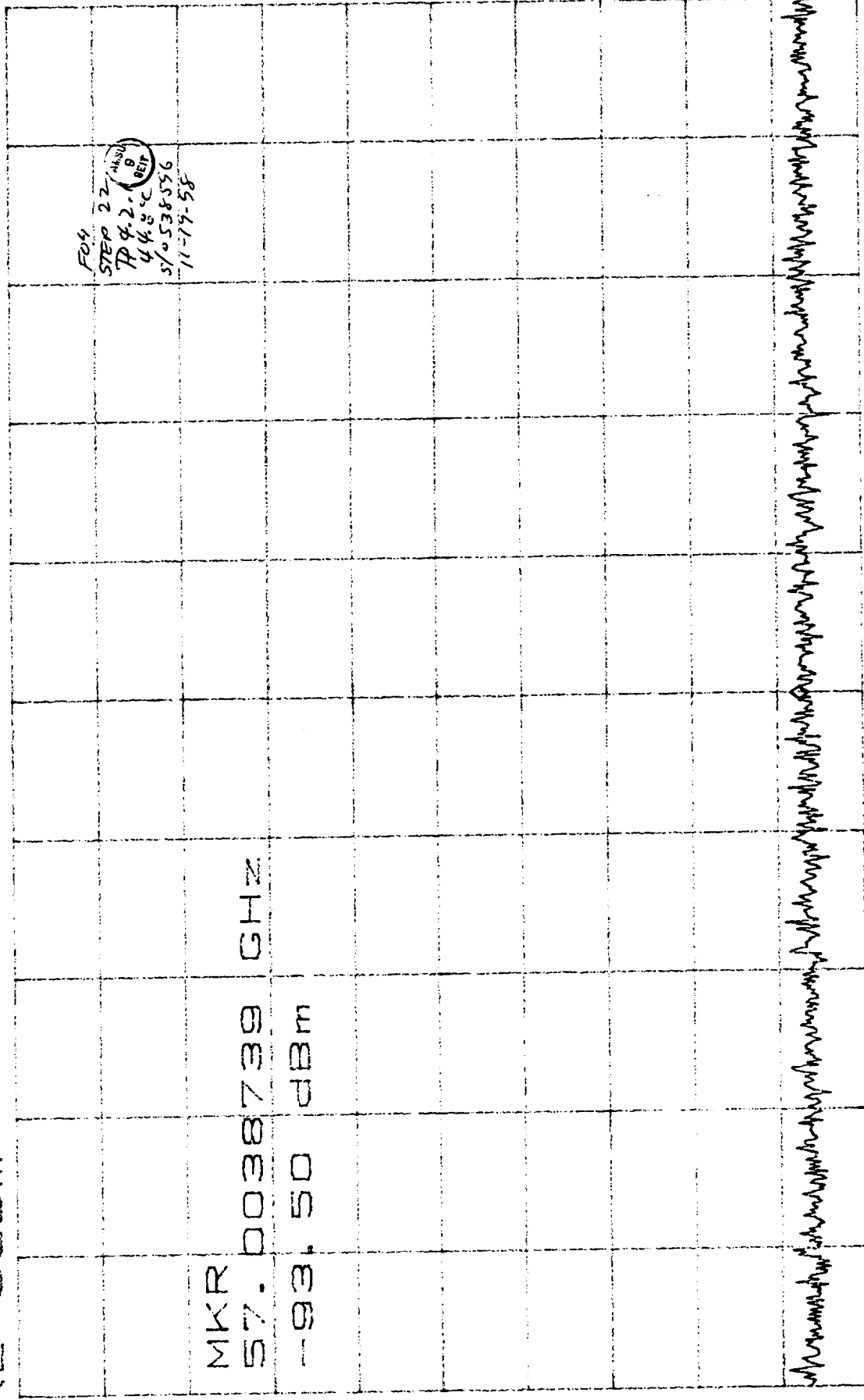
CENTER 6.87485GHz
RBW 100kHz
SPAN 10.00MHz
VSW 50.0ms

CL 30.0dB VAVG 1 MKR --89.67dBm
RL 0dBm 10dB/ 56.8606481GHz



CENTER 56.8606481GHz SPAN 500.0KHZ
RBW 3.0KHZ *VBW 1.0KHZ *SWP 2.00Sec

CL 30.0dB VAVG 3 MKR --93.50dBm
 RL 0dBm 10dB/ 57.0038739GHz

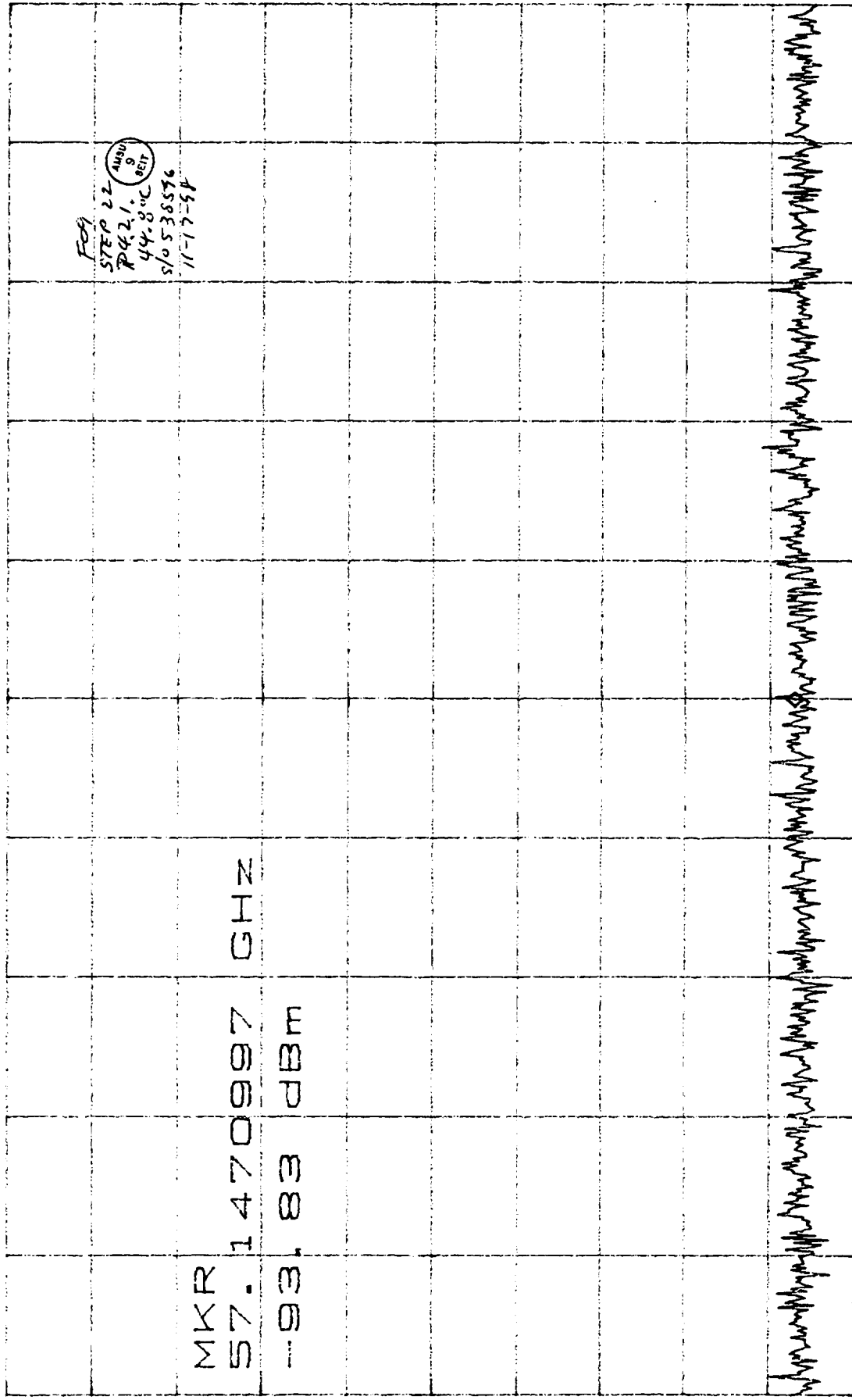


MKR
 57.0038739 GHz
 --93.50 dBm

CENTER 57.0038739GHz SPAN 500.0KHz
 RBW 3.0KHz *VBW 1.0KHz *SWP 2.00sec

D

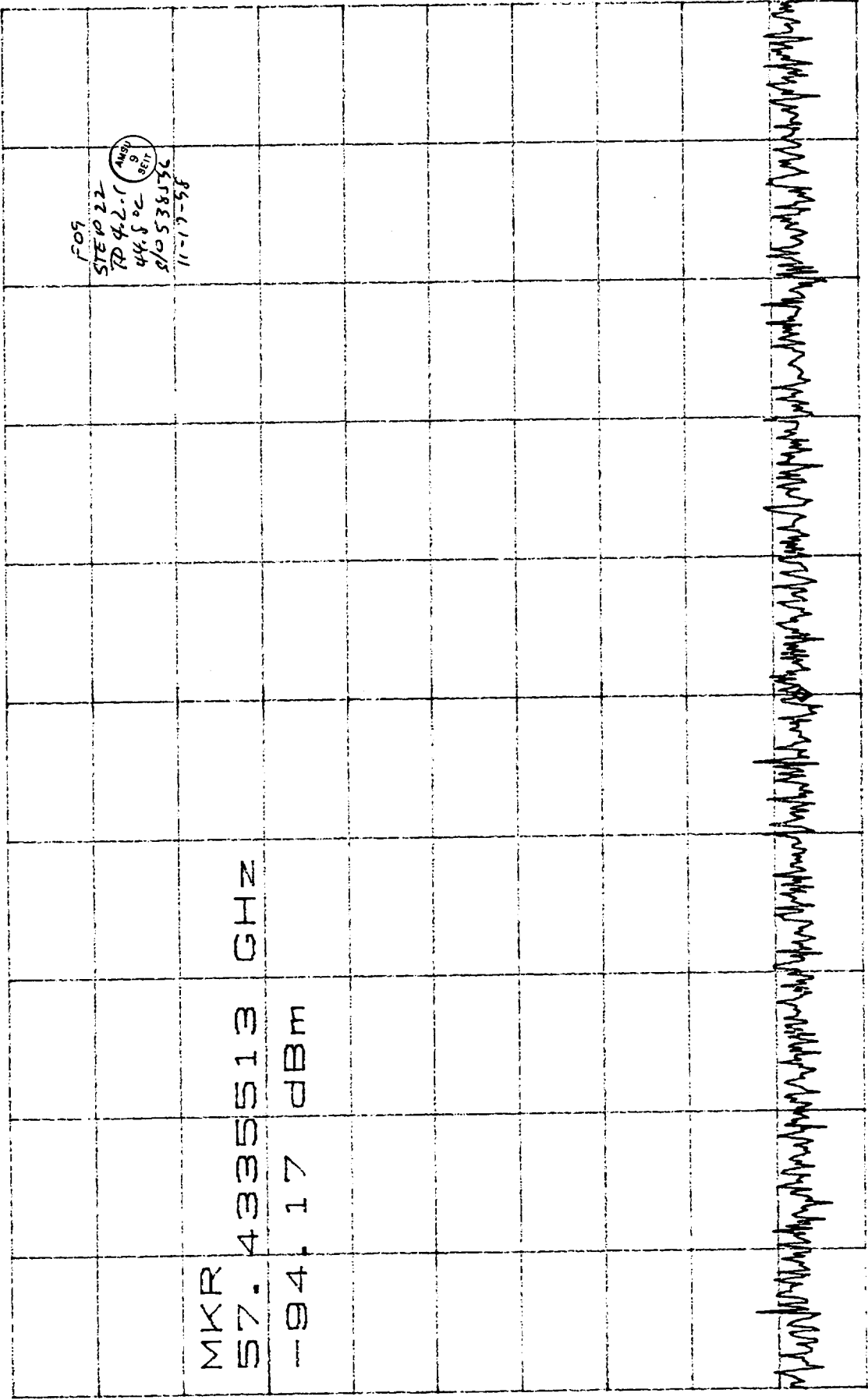
CL 30.0dB VAVG 2 MKR -93.83dBm
RL 0dBm 10dB/ 57.1470997GHz



D

CENTER 57.1470997GHz SPAN 500.0KHz
RBW 3.0KHz *VBW 1.0KHz *SWP 2.00sec

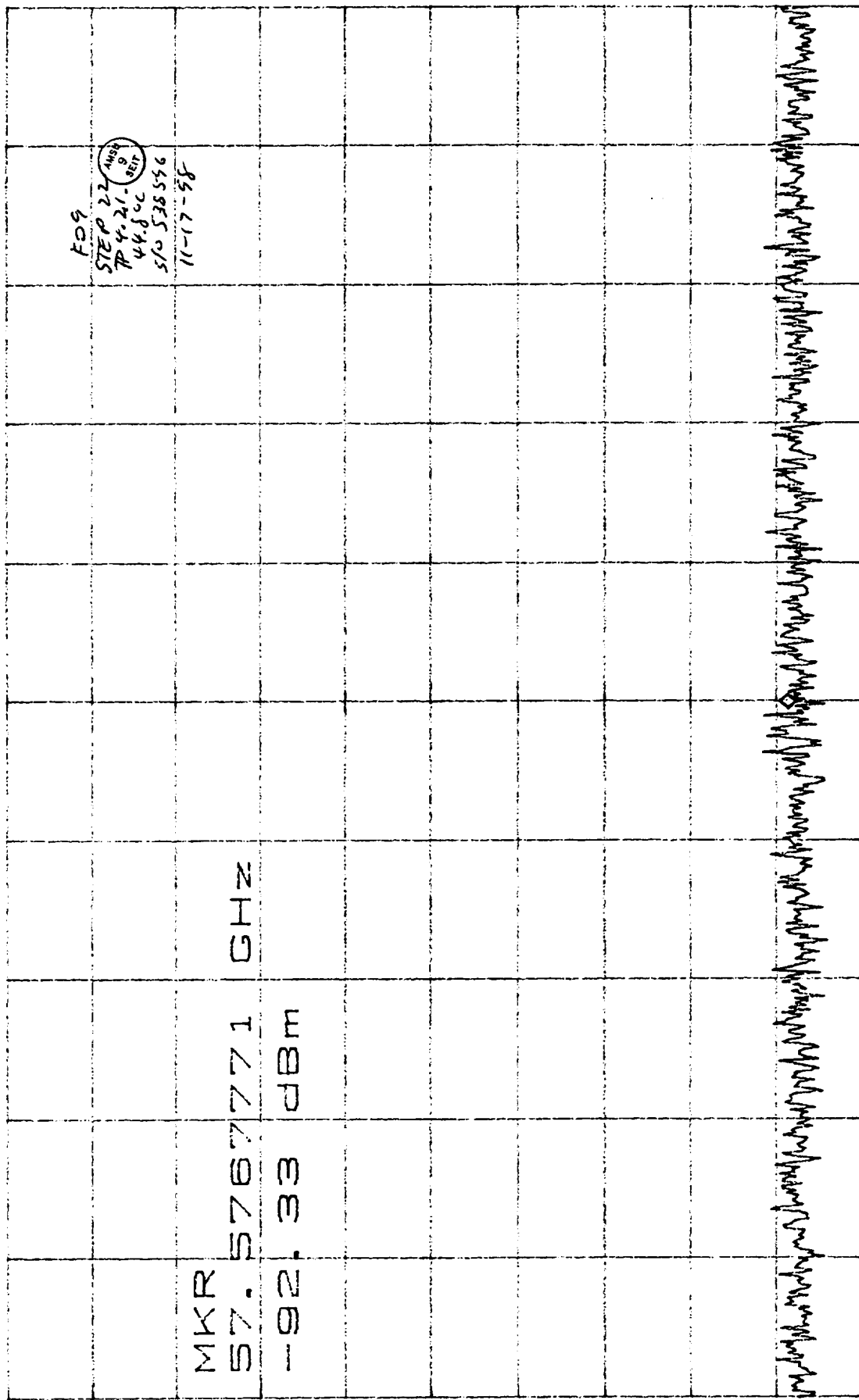
CL 30.0dB VAVG 2 MKR -94.17dBm
 RL 0dBm 10dB/ 57.4335513GHz



D

CENTER 57.4335513GHz SPAN 500.0KHz
 RBW 3.0KHz *VBW 1.0KHz *SWP 2.00sec

CL 30.0dB VAVG 2 MKR -92.33dBm
 RL 0dBm 10dB/ 57.5767771GHz



D

CENTER 57.5767771GHz SPAN 500.0kHz
 RBW 3.0kHz *VBW 1.0kHz *SWP 2.00sec

CL 30.0dB VAVG 3 MKR --93.67dBm
RL 0dBm 10dB/ 57.7200029GHz

F05
STEP 12
7P4.2.1
44.8°C
S/O 138576
11-17-98

MKR
57.7200029 GHz
--93.67 dBm

D

57.7200029GHz

CENTER 57.7200029GHz SPAN 500.0KHz
RBW 3.0KHz *VBW 1.0KHz *SWP 2.00000

CL 30.0dB
RL 0dBm

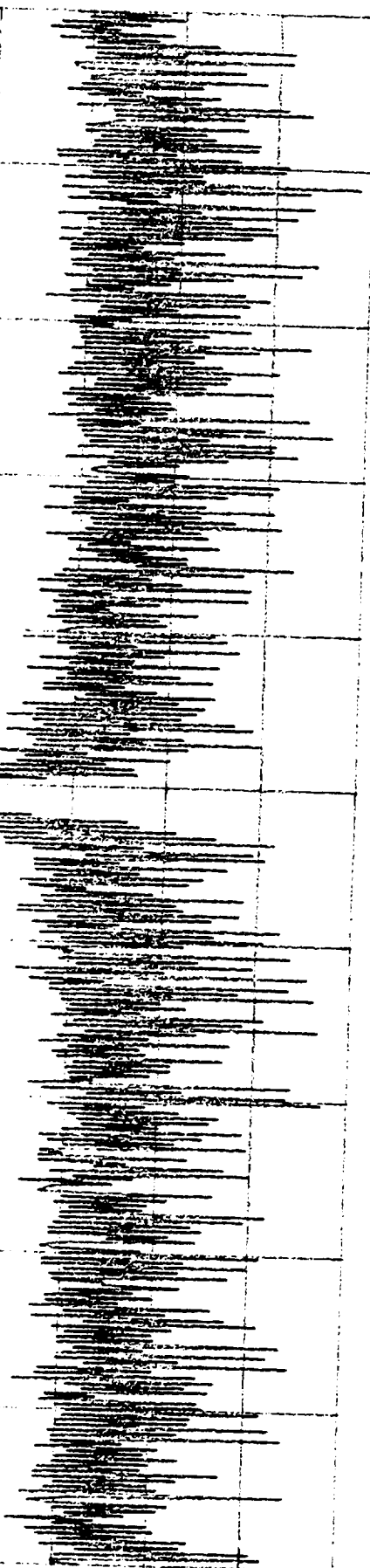
MKR -19.00dBm
114.5806531GHz

10dB/

MKR
114.5806531 GHz
-19.00 dBm

F09
STEP 22
R42,1
44.8
5/0.53554
11-17-58

◇



CENTER 114.5806538GHz
RBW 300Hz
* VBW 1.0kHz
SPAN 100.0kHz
* SWP 2.80000

TEST DATA SHEET 6C (Sheet 4 of 4)
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
22 (Cont)	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>15.2</u> V	Pass
		-15.2 ± 0.05 V	-Voltage = <u>-15.2</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290325594</u> GHz	
		17 to 20 dBm	Power = <u>17.36</u> dBm	
	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290325594</u> GHz	
		17 to 20 dBm	Power = <u>17.58</u> dBm	
	Spurious and Sub	-200 to -90 dBc	<u>see plots</u>	
	Power level of 114.58 GHz signal	<-10 dBm	<u>-19</u> dBm	Pass
	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>7 Hz</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>1.0</u> dB	N/A

Shop Order No.: 538596
Operation: 0170
Unit Serial No.: F09
Date: 11-17-98

Test Engineer: AMSU 9 SEIT
Quality Control: Ref 2002 100704
Govt. Rep.: W. D. DMC 11/18/98

Section 5B: Final Functional Testing - F10

This section contains the results of a full functional test over temperature taken after PLO F10 endured thermal cycling. All tests passed.

TEST DATA SHEET 6C (Sheet 1 of 4)
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Test Setup Verified: *[Signature]*

Signature

Paragraph 4.2.1.3, Functional Testing:

Step	Test	Expected	Measured	Pass/ Fail
1	Potential Difference from ± 15 V RTN to:			
	PLO Base Plate	< 1.0 Vac	0.01 V	Pass
	Spectrum Analyzer	< 1.0 Vac	0.02 V	Pass
	Frequency Counter Chassis	< 1.0 Vac	0.06 V	Pass
	Power Meter Chassis	< 1.0 Vac	0.02 V	Pass
4	Evacuate vacuum chamber and record pressure	< 10^{-2} torr	Pressure = _____ torr	*
5	Thermal couple readings	TC1 = 22 ± 2 °C	TC1 = <u>23.4</u> °C	
			TC2 = <u>24.0</u> °C	N/A
			TC3 = <u>22.9</u> °C	N/A
6	DRO L/A	0 to 1V	DRO L/A = <u>73 m</u> V	Pass
	PLO L/A	S/N: F06, F08 = 14.6 ± 0.4 V S/N: F07 = 0 to 1V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.54</u> V	Pass
	Is PLO locked?	Yes	Yes <input checked="" type="checkbox"/> No _____	Pass
7	PLO Frequency	$57.290344 \pm .0002$ GHz	Freq. = <u>57.290346129</u> GHz	Pass
	PLO Power	17 to 20 dBm	P = <u>17.9</u> dBm	Pass
8	Input Voltage and Current			
	VM1 Voltage	$+15 \pm 0.1$ V	VM1 = <u>+15.18</u> V	Pass
	VM2 Voltage	-15 ± 0.1 V	VM2 = <u>-15.20</u> V	Pass
	IM1 Current	600 mA max.	IM1 = <u>533</u> mA	Pass
	IM2 Current	100 mA max.	IM2 = <u>-70.2</u> mA	Pass
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>73 m</u> V	Pass
	PLO L/A Voltage	S/N: F06, F07, F08 = 14.6 ± 0.4 V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.54</u> V	Pass
			P = <u>17.9</u> dBm	Pass
12	RF Output Power and Frequency	17 to 20 dBm	Freq. = <u>57.290346129</u> GHz	Pass
	Baseplate Temp. (TC1)	TC1 = 22 ± 2 °C	TC1 = <u>23.6</u> °C	Pass

*Record data only if performing test under vacuum

30.0000
RL 0000

NR 3.3300E
57.290340HN

10000

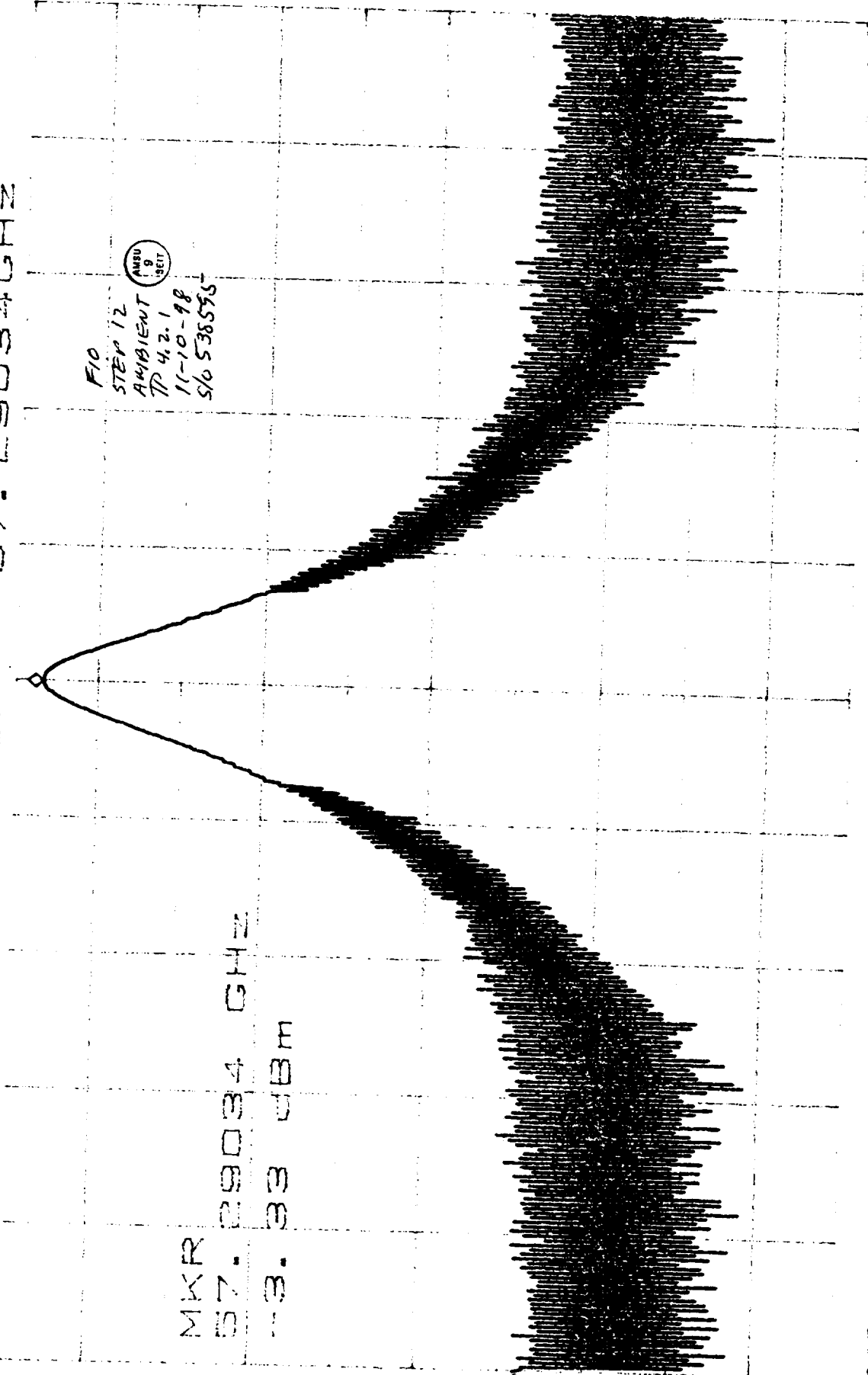
NR 3.3300E
57.290340HN

F10
STEP 12
AMBIENT
TP 4.2.1
11-10-98
SLO 538555

ANNU
9
SET

CENTER 57.290340HN
* RBW 3000HN * VBW 1.00HN

SPAN 10.00HN
SWP 50.00

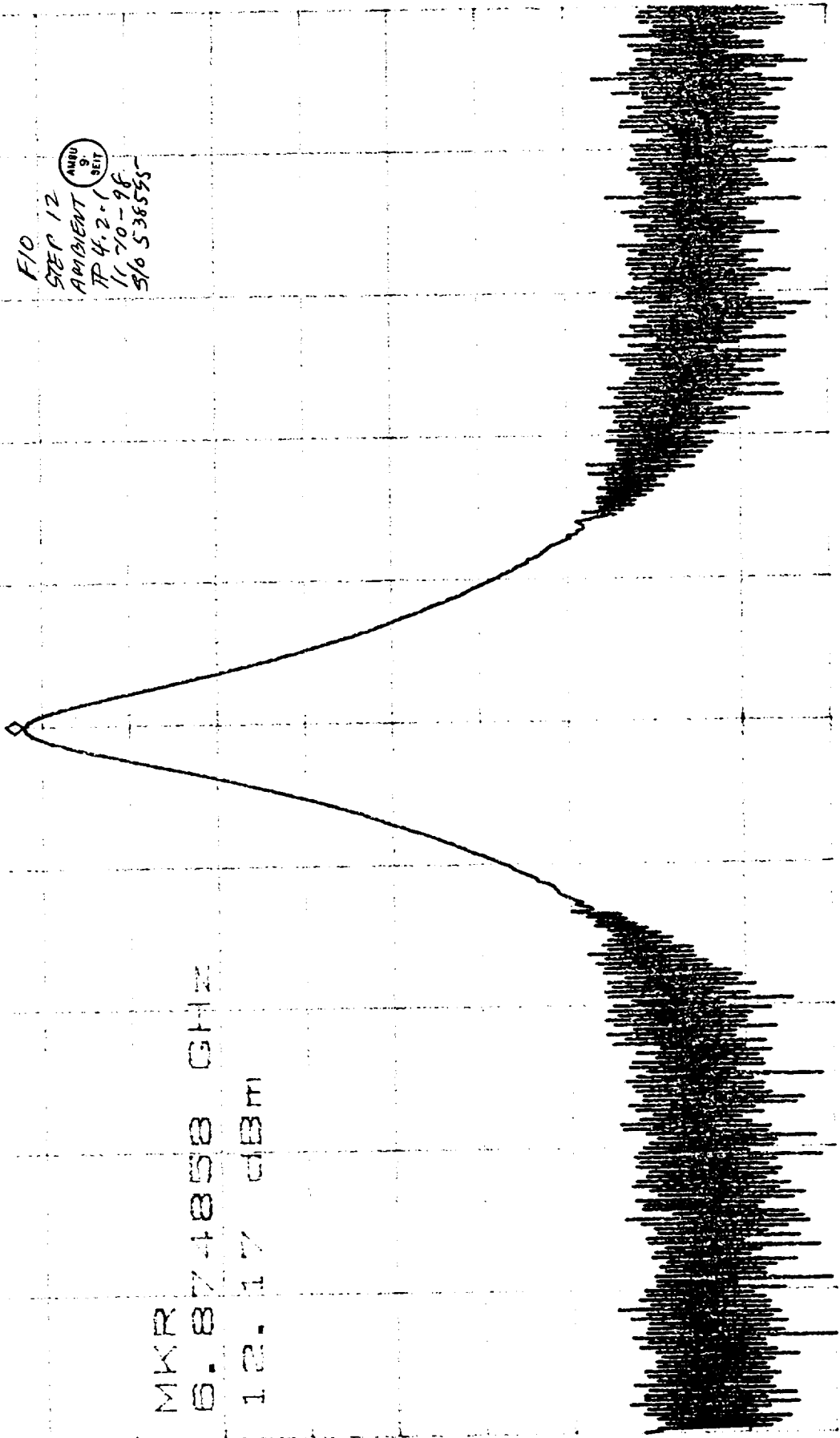


ATTEN 30dB
RL 20.0dB

MR 12.17dB
S. 874858GHz

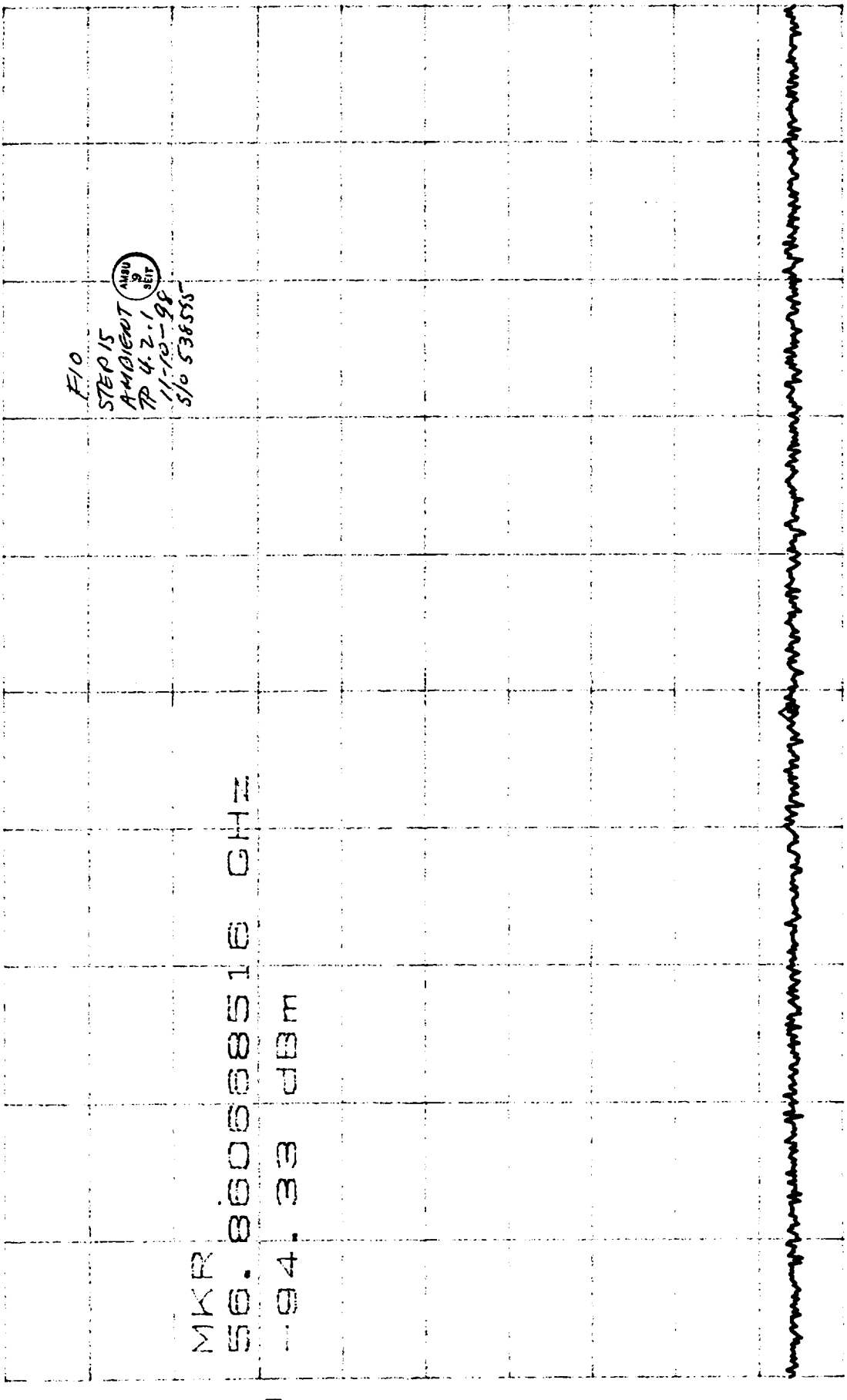
MR 0.07dB
S. 874858GHz
12.17dB

F10
SEP 12
AMBIENT
TP 4.2-1
11-10-98
S/0 538555



SPAN 5.000MHz
S. 874858GHz
VSW 100kHz
S. 874858GHz
VSW 100kHz
S. 874858GHz
VSW 100kHz

CL 30.0JBE VAVG 53 MKR - 94.33JBE
 RL 0JBE 10JBE/ 56.860668516GHE



MKR
 56.860668516
 - 94.33JBE

CENTER 56.860668516GHE SPAN 1.000KHE
 ORW 3.0KHE *VBW 3.0KHE
 * SWP 67.0HE

CL 30.0dB
RL 0dBm

VAVG 50
10dB/

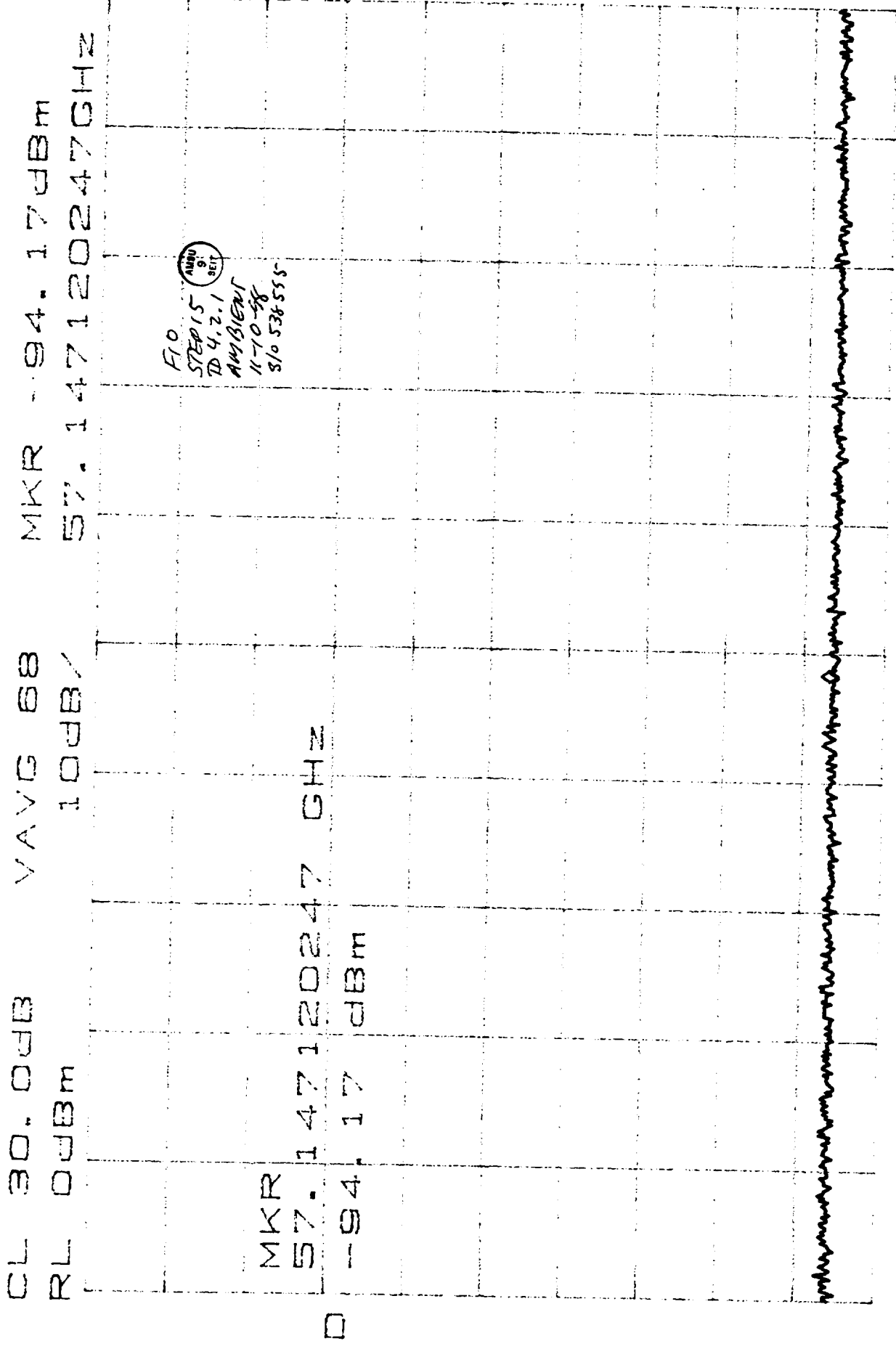
MKR -93.67dBm
57.003894381GHz

MKR
57.003894381 GHz
-93.67 dBm

F10
STEP 15
AMBIENT
TP 4.2.1
11-10-98
S/O 536595



CENTER 57.0038943898GHz
RBW 3.0KHz * VBW 3.0KHz
SPAN 1.000KHz
SWP 67.0ms



CENTER 57.147120264GHz SPAN 1.000kHz
 *RBW 3.0kHz *VBW 3.0kHz
 SWP 67.0ms

CL 30.0dB

VAVG 26

MKR -94.67dBm

RL 0dBm

10dB/

57.433571977GHz

MKR

57.433571977 GHz

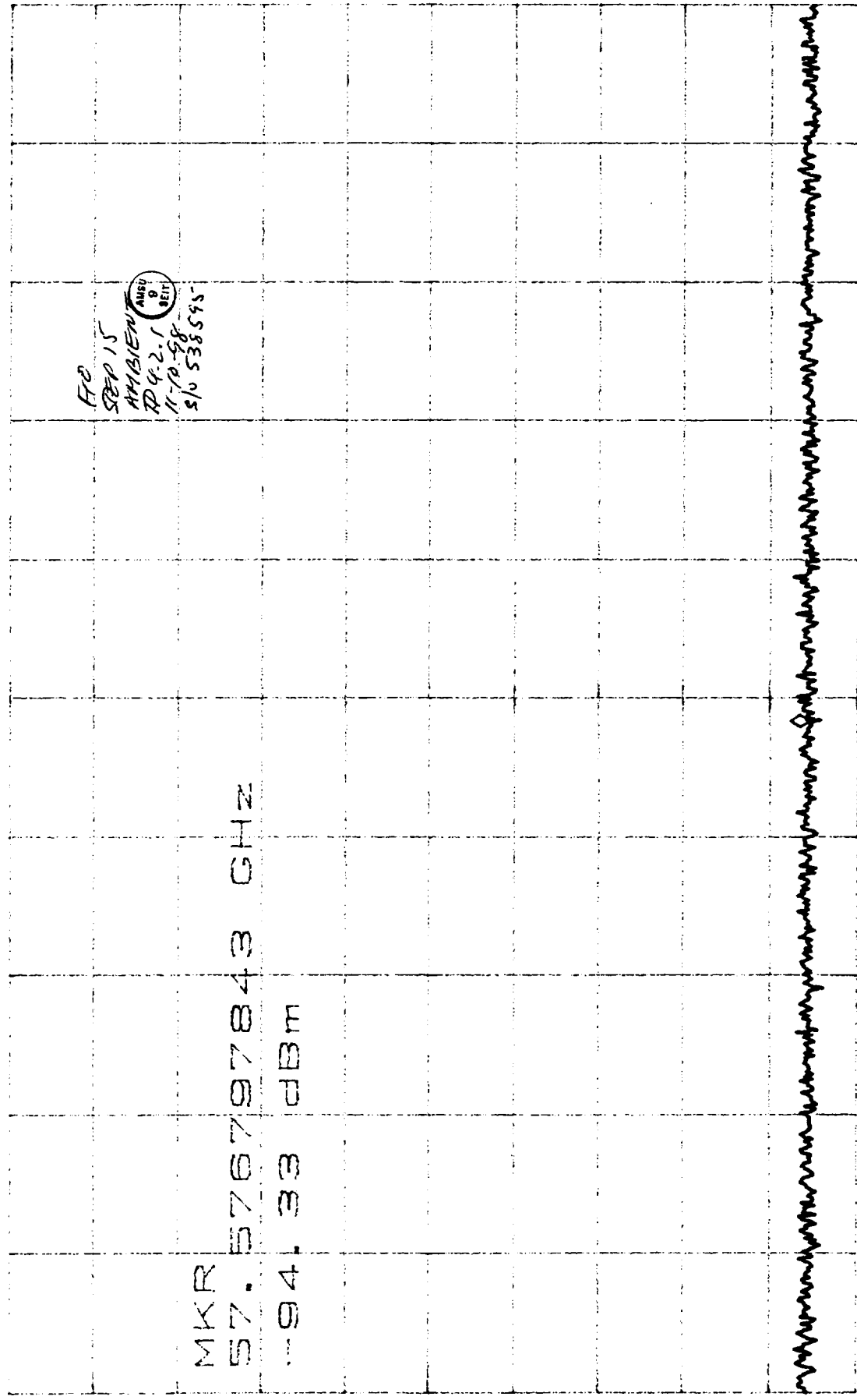
-94.67 dBm

F10
STEP 15
AMBU/ENT
P 4.2.1
11-10-58
310538595



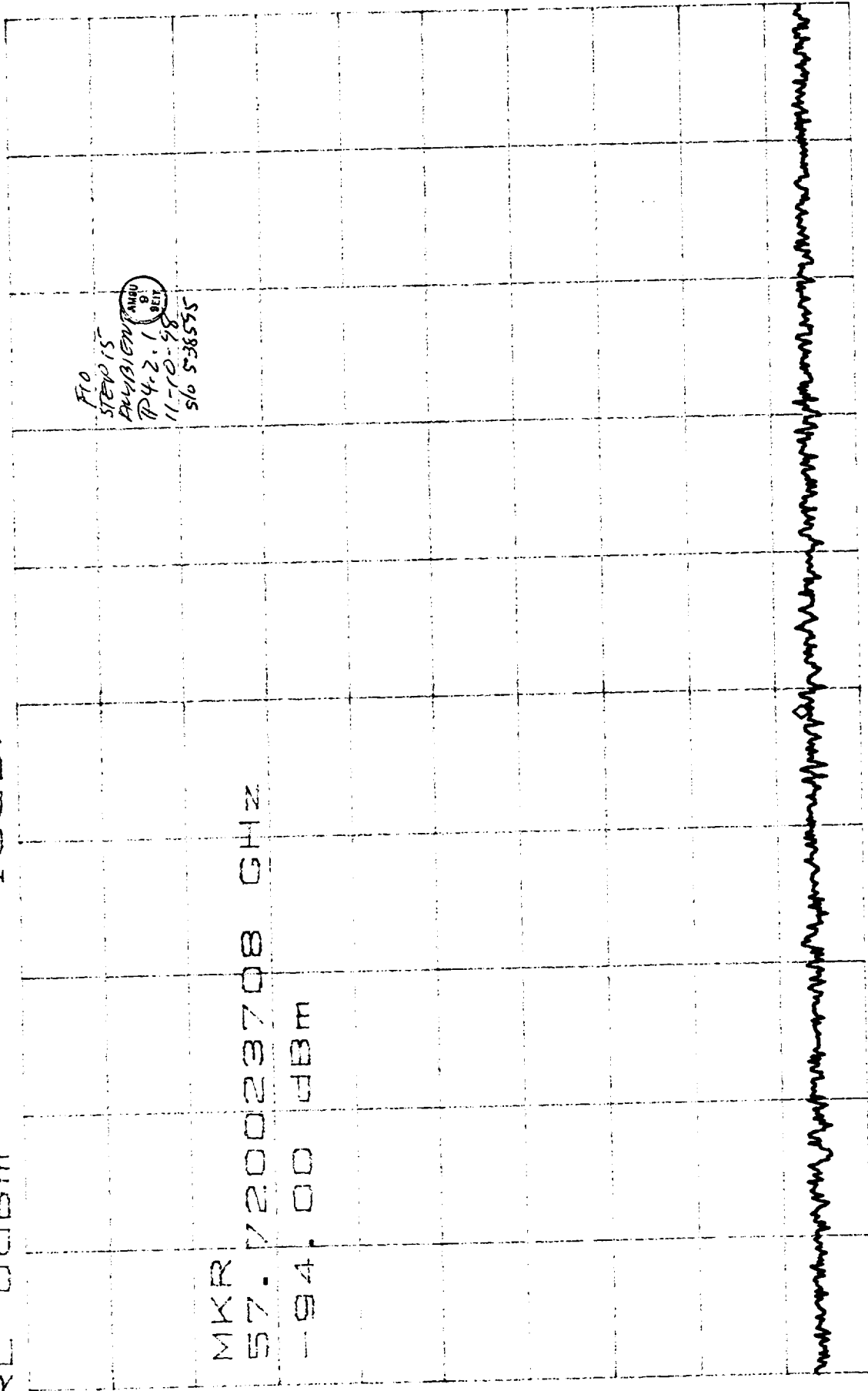
CENTER 57.433571994GHz SPAN 1.000kHz
*RBW 3.0kHz *VBW 3.0kHz SWP 67.0ms

CL 30.0dB VAVG 15 MKR -94.33dBm
RL 0dBm 10dB/ 57.576797843GHz



CENTER 57.576797860GHz SPAN 1.000kHz
*RBW 3.0kHz *VBW 3.0kHz SWP 67.0ms

CL 30.0dB VAVG 10 MKR -94.00dBm
RL 0dBm 10dB/ 57.720023708GHz



CENTER 57.720023725GHz SPAN 1.000kHz
*RBW 3.0kHz *VBW 3.0kHz SWP 67.0ms

CL 30.0J3
RL 00BE

MKR -70.33J3E
114.580596GH

10J3/

MKR 114.580596GH
114.580596GH
114.580596GH

F10
STEP 16
P 4.2.1
AMBIGUITY
11-10-50
S/0538595

AMBI
9
SEP

CENTER 114.580596GH SPAN 1.000MHz
CRW 1.0KHz * VBW 1.0KHz
* SWP 2.50000

TEST DATA SHEET 6C (Sheet 2 of 4)
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

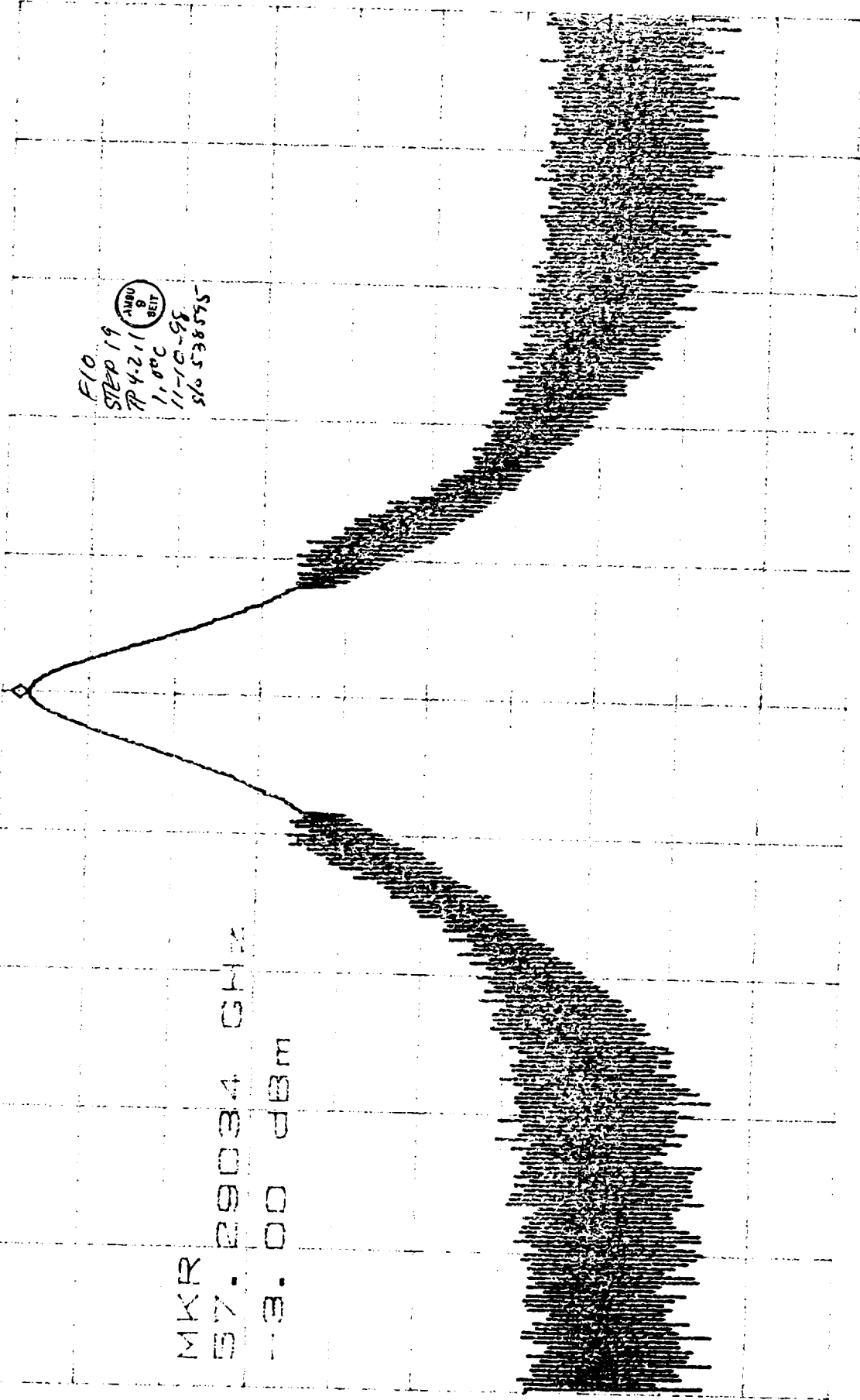
Step	Test	Expected	Measured	Pass/ Fail
13	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>+15.20 V</u>	Pass
		-15.2 ± 0.05 V	-Voltage = <u>-15.20 V</u>	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.29034667 GHz</u>	Pass
		17 to 20 dBm	P = <u>17.83 dBm</u>	Pass
14	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.80 V</u>	Pass
		-14.8 ± 0.05 V	-Voltage = <u>-14.80 V</u>	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.290354969 GHz</u>	Pass
		17 to 20 dBm	P = <u>17.81 dBm</u>	Pass
15	Spurious and Sub	-200 to -90 dBc	<u>See Plots</u> <u>-70.33 dBm</u>	Pass
16	Power level of 114.58 GHz signal	<-10 dBm		Pass
17	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>6 Hz</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>0.7 dB Peak</u>	N/A
	Operating Temperature @ 1°C baseplate	TC1 = 1 ± 2°C	TC1 = <u>1.7°C</u>	N/A
			TC2 = <u>2.4°C</u>	N/A
			TC3 = <u>1.1°C</u>	N/A
18	Operating Temperature @ 1°C baseplate	0 - 1V	DRO L/A = <u>1.00 mV</u>	Pass
		S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.55 V</u>	Pass
19	Input Voltage and Current			
	VM1 Voltage	+15 ± 0.1 V	VM1 = <u>+15.0 V</u>	Pass
	VM2 Voltage	-15 ± 0.1 V	VM2 = <u>-15.0 V</u>	Pass
	IM1 Current	600 mA max.	IM1 = <u>520 mA</u>	Pass
	IM2 Current	100 mA max.	IM2 = <u>-65.7 mA</u>	Pass
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>60 mV</u>	Pass
	PLO L/A Voltage	S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.55 V</u>	Pass
	RF Output Power	17 to 20 dBm	Power = <u>18.75 dBm</u>	Pass
	Frequency	57.290344 ± .0002 GHz	Freq. = <u>57.290339351 GHz</u>	Pass

30.00dB
RL 0.00dBm

NKR -3.000JBE
57.20034GHZ

20034 GHz
3.00 0.00 0.00

F10
STEP 19
P42.11
1.00C
11-10-95
SLO 538555



CENTER 57.20034GHZ
*RBW 300KHz

SPAN 10.00MHz
SWP 50.00MHz

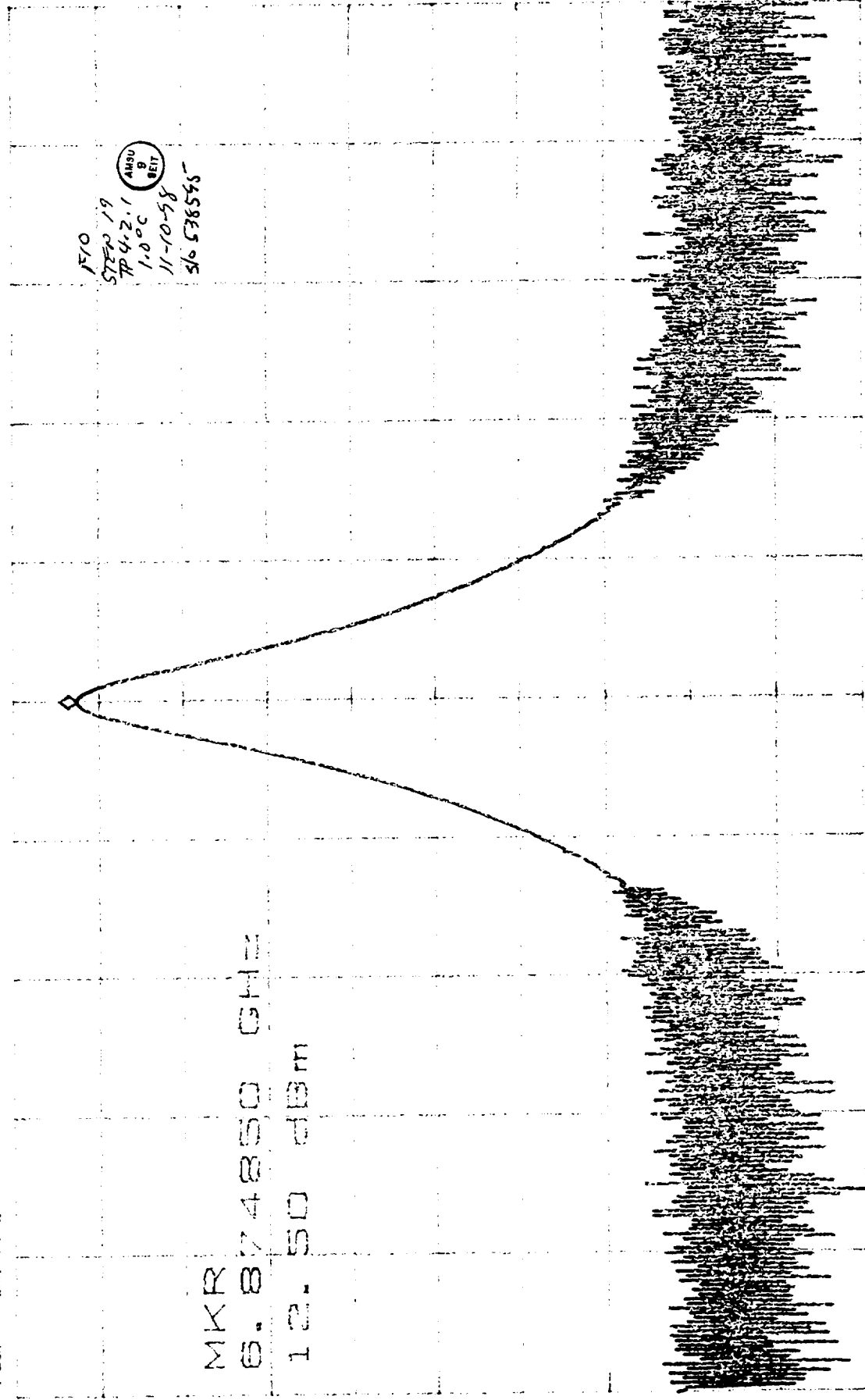
ATTEN 30dB
RL 20.0dBm

MKR 12.50GHz
6.874850GHz

10dB/

MKR
6.874850 GHz
12.50 GHz

F10
STEP 19
TP42.1
1.0°C
11-10-58
56538545



CENTER 6.874850GHz

*RBW 100kHz

VBW 100kHz

SPAN 5.000MHz

SWP 50.0dB

CL 30.0JEB VAVG 16 MKR -94.00JEB
 RL 0JEB 10JEB/ 55.860661789GHZ

F10
 10C
 24.2.1
 SEP 13
 11-10-98
 S/O 53555

MKR
 55.860661789 GHZ
 -94.00 JEB

0

CENTER 55.860661806GHZ SPAN 1.000KHz
 * RBW 3.0KHz * VBW 3.0KHz
 SWP 67.0MHz

CL 30.0dB

VAVG 37

MKR -92.50dBm

RL 0dBm

10dB/

57.003888154GHz

MKR

57.003888154 GHz

-92.50 dBm

F10
STEP 19
79.2.1
100
11-10-58
3/0536555



CENTER 57.003888154GHz

SPAN 1.000kHz

*RBW 3.0kHz

*VBW 3.0kHz

SWP 67.0m

CL 30.0dB
RL 0dBm

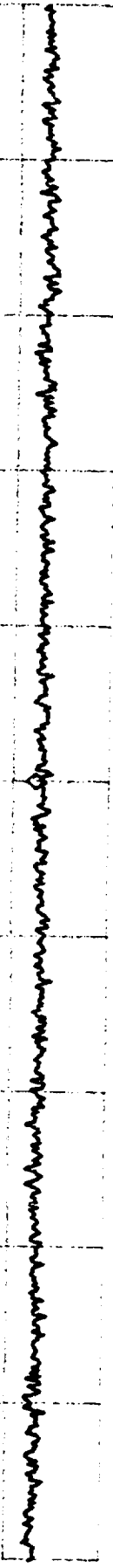
VAVG 25
10dB/

MKR --93.33dBm
57.147113503GHz

MAX
57.147113503 GHz
--93.33 dBm

F10
STEP 19
TP 4.2.1
10C
11-10-58
S5595
1/10 53655

0



CENTER 57.147113503GHz SPAN 1.000kHz
* RBW 3.0kHz * VBW 3.0kHz SWP 67.0ms

CL 30.0dB VAVG 13 MKR -94.67dBm
RL 0dBm 10dB/

MKR 433505199 CH1
ES -94.67 dBm

F10
10C
STEP 19
742.1
11-10-98
S/N 538535



CENTER 57.433505199 CH1 SPAN 1.000KHz
*REBW 3.0KHz *VBW 3.0KHz SWP 67.0ms

30.0dB MKR 93.67dBm
0dB 10dB/ 57.720016896GHz



MKR 720016896 GHz
57.720016896dBm

CENTER 57.720016896GHz SPAN 1.000kHz
*RBW 3.0kHz *VBW 3.0kHz SWP 67.0ms

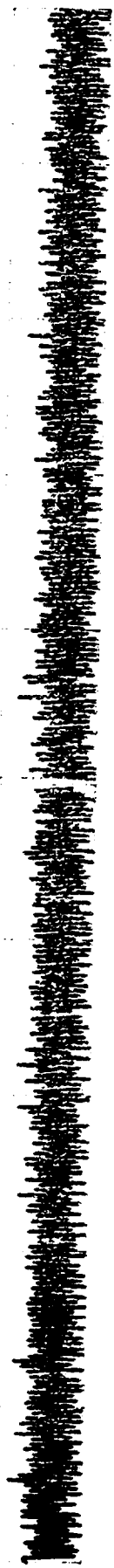
CL 30.00B
RL 0000E

MKR 100.00B
114.580676GHZ

1000B/

MKR 114.580676GHZ
114.580676GHZ
114.580676GHZ

F10
STEP 19
TP 4.2.
1.0C
11-10-98
816596595



CENTER 114.580676GHZ SPAN 1.000MHz
* RBW 1.0KHz * VBW 1.0KHz SWP 2.50000

TEST DATA SHEET 6C (Sheet 3 of 4)
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/ Fail
19 (Cont)	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>+15.23</u> V	Pass
		-15.2 ± 0.05 V	-Voltage = <u>-15.23</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.29037429</u> GHz	Pass
		17 to 20 dBm	Power = <u>18.2</u> dBm	Pass
	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>+14.85</u> V	Pass
		-14.8 ± 0.05 V	-Voltage = <u>-14.85</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.290333111</u> GHz	Pass
		17 to 20 dBm	Power = <u>18.6</u> dBm	Pass
	Spurious and Sub	-200 to -90 dBc	<u>See plot</u>	Pass
	Power level of 114.58 GHz signal	<-10 dBm	<u>-69</u> dBm	Pass
	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>5 Hz</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>0.7</u> dB	N/A
21	Operating Temperature @ +44°C Baseplate	TC1 = 44 ± 2°C	TC1 = <u>43.3</u>	
			TC2 = <u>43.2</u>	N/A
			TC3 = <u>42.8</u>	N/A
		0 - 1V	DRO L/A = <u>110 mV</u>	Pass
		S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.55</u> V	Pass
22	Input Voltage and Current			
	VM1 Voltage	+15 ± 0.1 V	VM1 = <u>+15.0</u> V	Pass
	VM2 Voltage	-15 ± 0.1 V	VM2 = <u>-15.0</u> V	Pass
	IM1 Current	600 mA max.	IM1 = <u>343</u> mA	Pass
	IM2 Current	100 mA max.	IM2 = <u>71.3</u> mA	Pass
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>110 mV</u>	Pass
	PLO L/A Voltage	S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.55</u> V	Pass
	RF Output Power and	17 to 20 dBm	Power = <u>17.1</u> dBm	Pass
	Frequency	57.290344 ± .0002 GHz	Freq. = <u>57.290341590</u> GHz	Pass

CL 30.0000

VAVG 20

MKR 104.007 JEM

RL 0000

100000

56.8800004011 GHz

MKR

56.8800004011 GHz

104.007 JEM

F10
STEP 22
74.2.1
440C
11-10-98
S10538595

10

CENTER 56.8800004000 GHz

SPAN 1.0000 Hz

* RBW 3.0000 Hz

* VBW 3.0000 Hz

SWP 67.0000

CL. 30.0dB

VAVG 8

MKR -94.67dBm

RL 0dBm

10dB/

57.003889885GHz

MKR

57.003889885 GHz

-94.67 dBm

File
STEP 22
P4.2.1
4402
11-10-58
S/0538595

4402
11-10-58
S/0538595

CENTER 57.003889882GHz

SPAN 1.000kHz

* RBW 3.0kHz

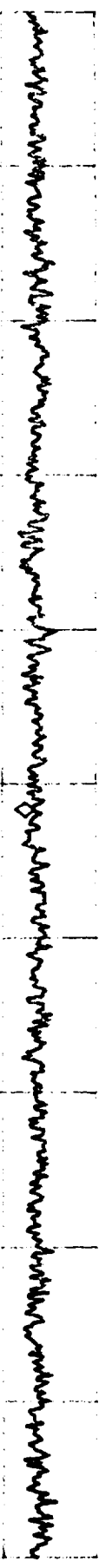
* VBW 3.0kHz

SWP 67.0ms

CL 30.0dB VAVG 7 MKR -93.33dBm
 RL 0dBm 10dB/ 57.147115719GHz

MX
 57.147115719 GHz
 33.33 dBm

F10
 STEP 22
 R4.2.
 440C
 11-10-98
 SLO 536545



CENTER 57.147115736GHz SPAN 1.000kHz
 * RBW 3.0kHz * VBW 3.0kHz SWP 67.0ms

CL 30.0dB

VAVG 10

MKR -94.50dBm

RL 0dBm

10dB/

57.433567427GHz

MKR

57.433567427 GHz

-94.50 dBm

F10
STEP 22
RP 4.2.1
44%
11-10-98
S/O 538595

ASD
SET

Handwritten notes and a large scribble across the bottom of the grid.

CENTER 57.433567444GHz

SPAN 1.000kHz

*RBW 3.0kHz

*VBW 3.0kHz

SWP 67.0dB

CL 30.0dB

RL 0dBm

NKR 100.50dBm

114.5806900GHz

10dB

NKR

114.5806900GHz

100.50dB

F10
STEP 22
TP 4.2.1
44°C
11-10-98
51053595

ANSU
9
SET

CENTER 114.5806900GHz

SPAN 1.000MHz

*RBW 1.0KHz

*VBW 1.0KHz

SWP 2.50000




TEST DATA SHEET 6C (Sheet 4 of 4)
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
22	Frequency vs. Voltage			
(Cont)	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>+15.24</u> V	Pass
		-15.2 ± 0.05 V	-Voltage = <u>-15.26</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.290342419</u> GHz	Pass
		17 to 20 dBm	Power = <u>17.1</u> dBm	Pass
	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>+14.85</u> V	Pass
		-14.8 ± 0.05 V	-Voltage = <u>-14.84</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.290342793</u> GHz	Pass
		17 to 20 dBm	Power = <u>17.1</u> dBm	Pass
	Spurious and Sub	-200 to -90 dBc	<u>See plots</u>	Pass
	Power level of 114.58 GHz signal	<-10 dBm	<u>-69</u> dBm	Pass
	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>0.5 Hz</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>0.6</u> dB	N/A

Shop Order No.: 538595
Operation: 0170
Unit Serial No.: F10
Date: 11-10-98

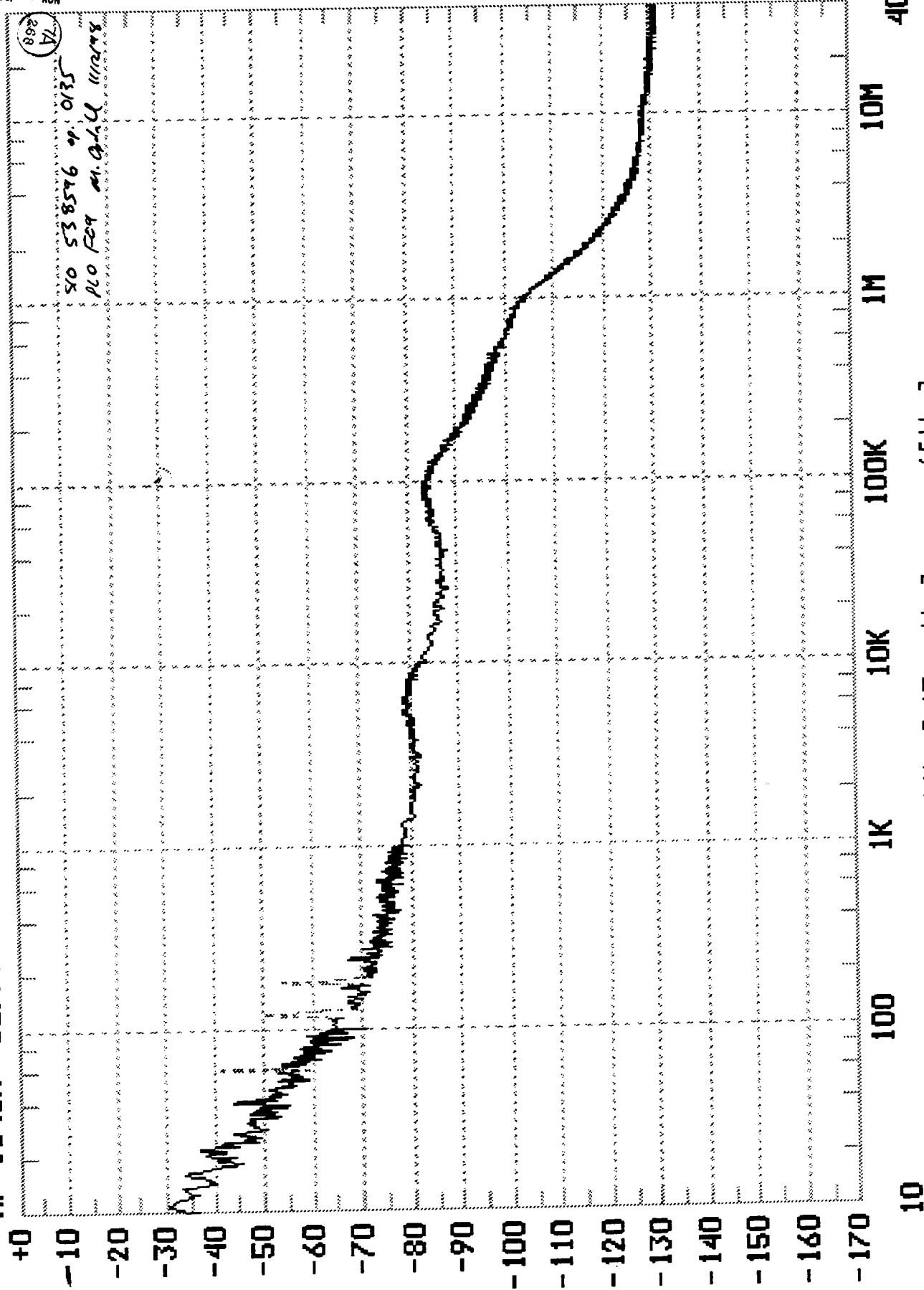
Test Engineer: 
Quality Control:  NOV 10 '98
Govt. Rep.:  11/11/98

Section 6A: AM/FM Testing - F09

The following section contains the raw data from the AM/FM Noise Tests. Requirements are that the FM Noise level be less than -100 dBc/Hz for frequencies greater than 1 MHz. Requirements are that the AM Noise level be less than 130 dBc/Hz for all frequencies greater than 1 MHz. Both Tests Pass.

FM Noise Test, F09

HP 3048A Carrier: 57.29E+9 Hz 11/12/98 10:42:17 - 10:45:52



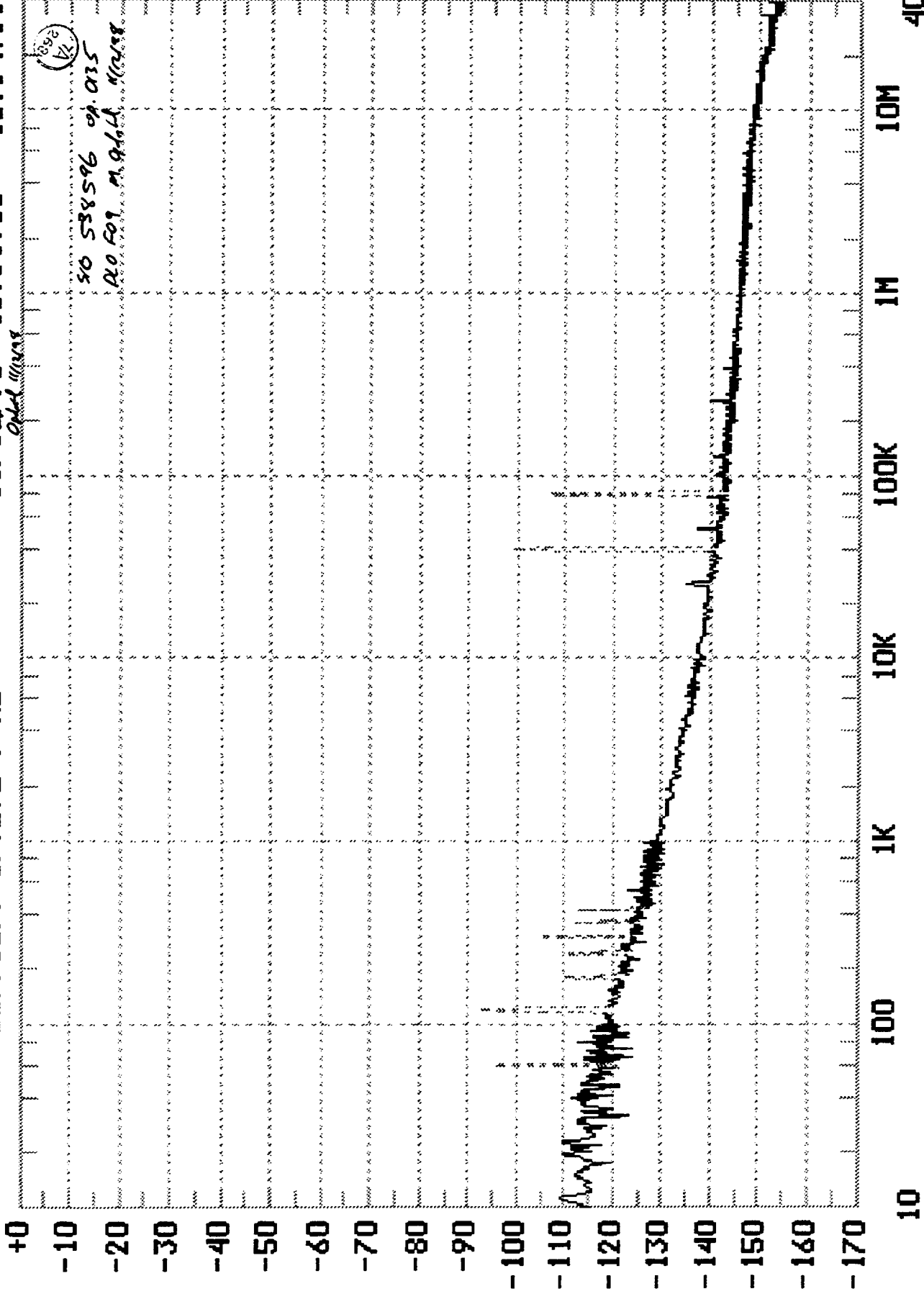
$L(f)$ [dBc/Hz] vs. f [Hz]

AM Note, F09

HP 3048A Carrier: 57.29E+9 Hz

11/12/98 10:31:00 - 10:34:31

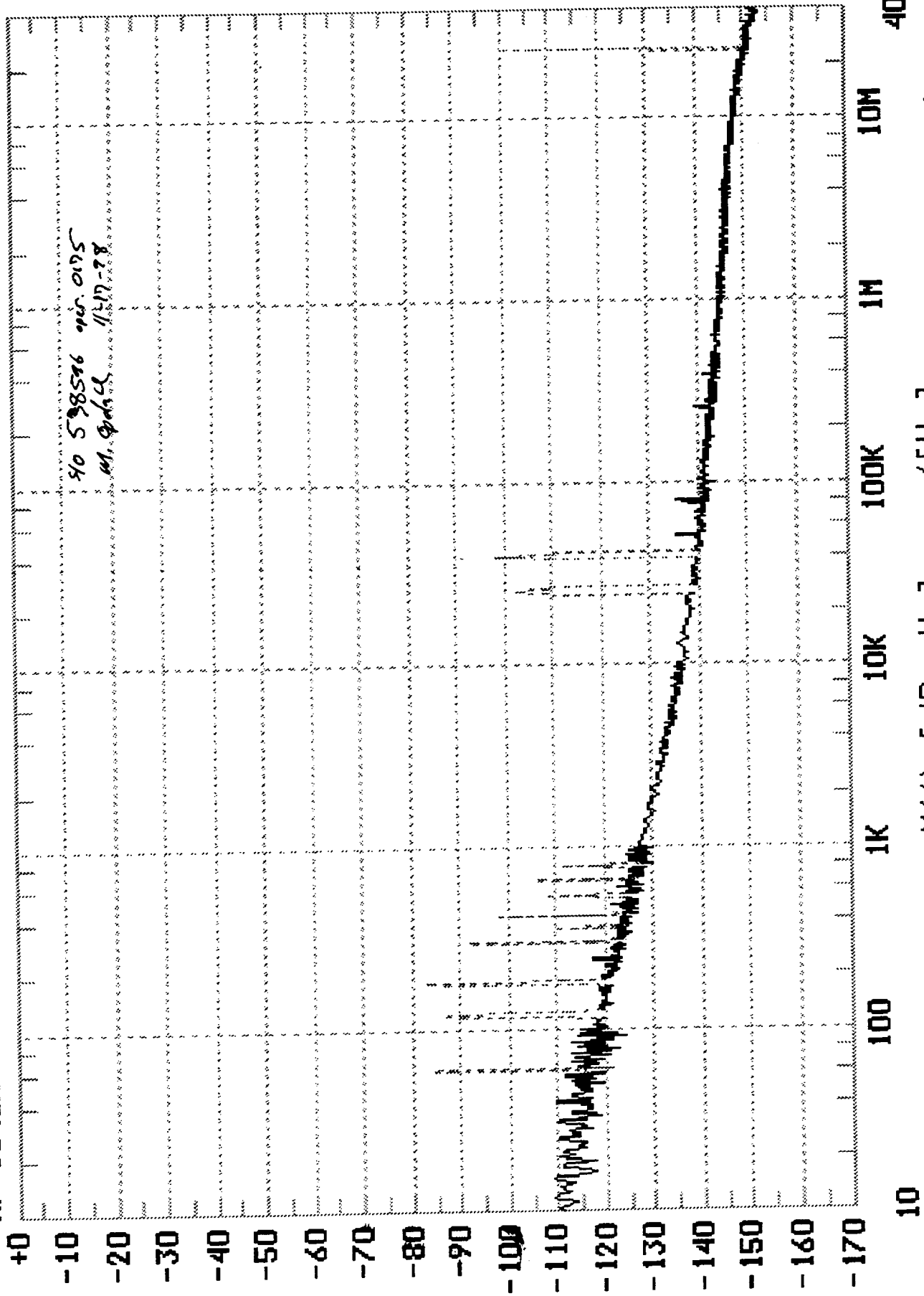
Optical "112298"


$$M(f) [dBc/Hz] \quad \text{vs.} \quad f [Hz]$$

AM Noise, PLO F09

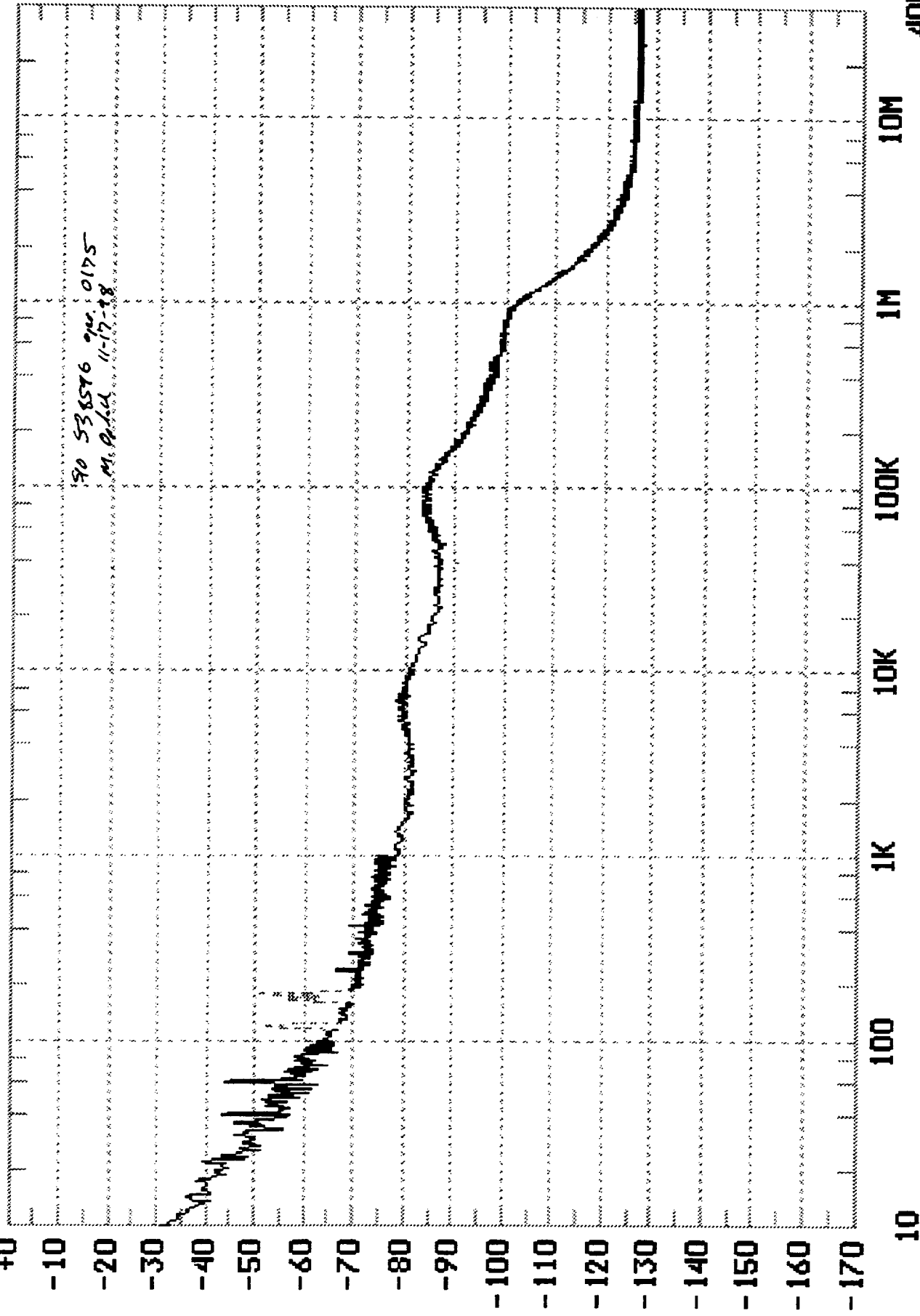
HP 3048A Carrier: 57.29E+9 Hz

11/17/98 16:18:25 - 16:21:54



FM Noise T_{Lt}t, PLO F09

HP 3048A Carrier: 57.29E+9 Hz 11/17/98 16:05:40 - 16:09:15



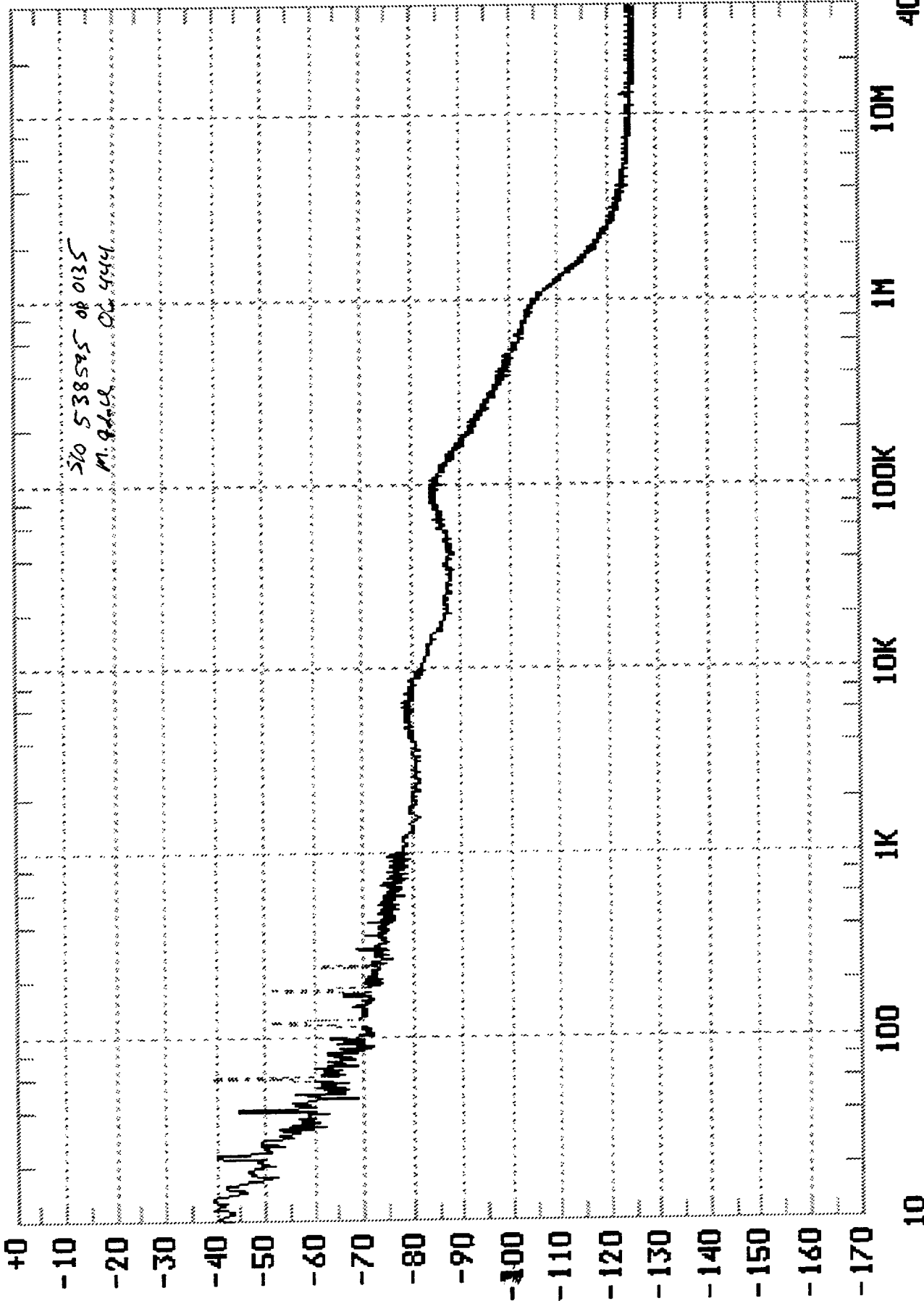
$L(f)$ [dBc/Hz] vs. f [Hz]

Section 6B: AM/FM - F10

The following section contains the raw data from the AM/FM Noise Tests. Requirements are that the FM Noise level be less than -100 dBc/Hz for frequencies greater than 1 MHz. Requirements are that the AM Noise level be less than 130 dBc/Hz for all frequencies greater than 1 MHz. Both Tests pass.

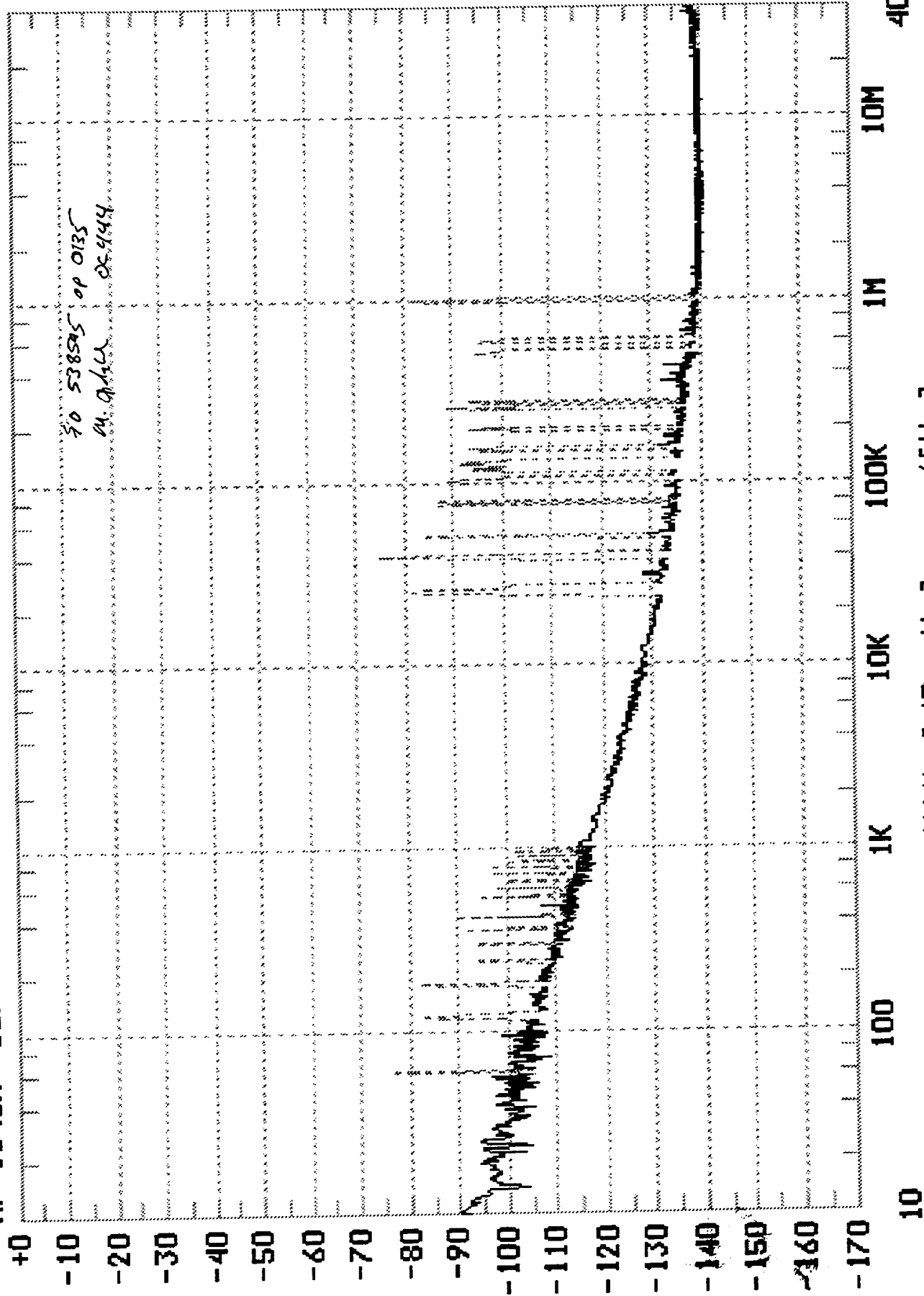
FM Noise, PLO F10

HP 3048A Carrier: 57.29E+9 Hz 10/05/98 15:22:26 - 15:26:01



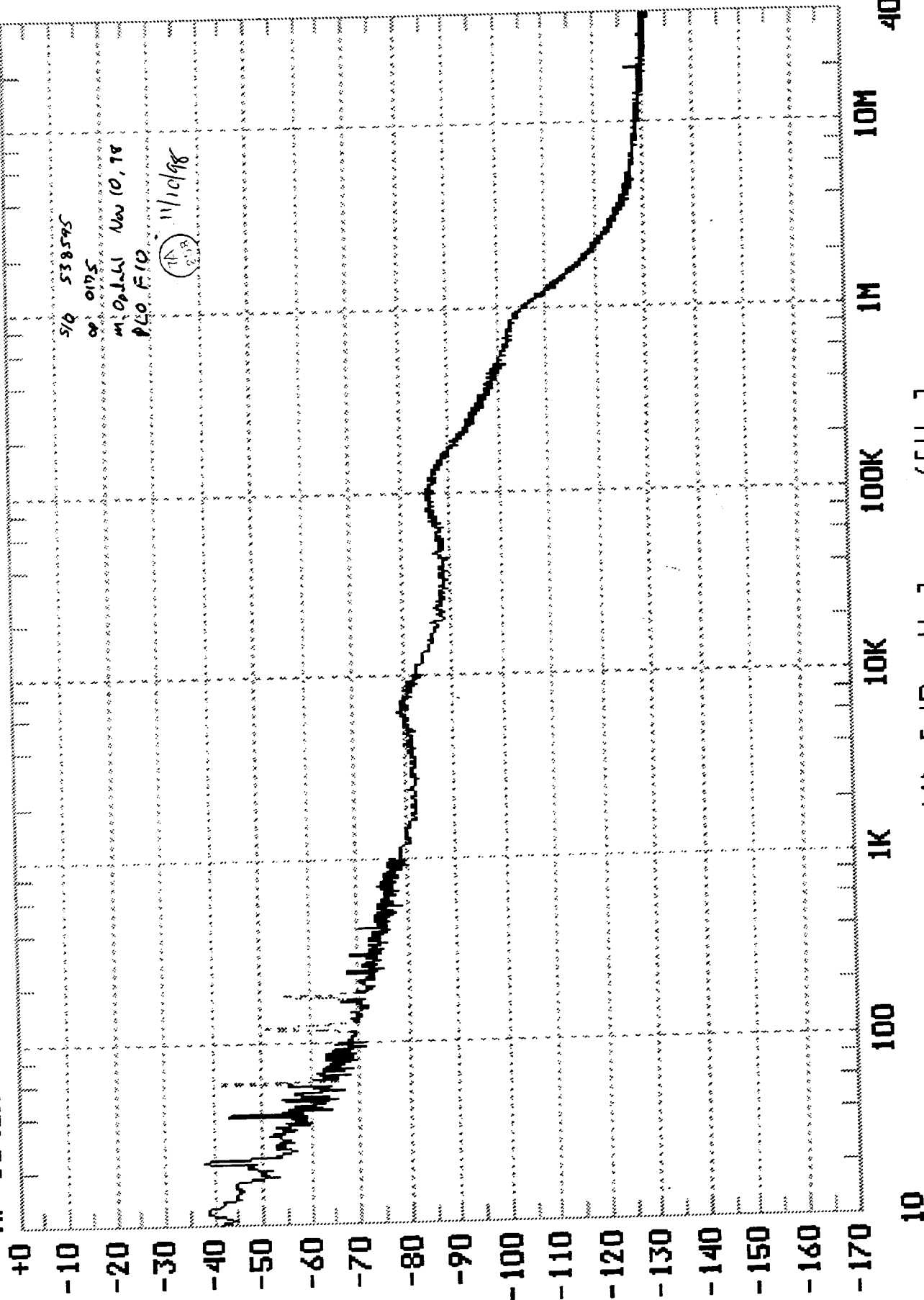
AM noi 2, F10

HP 3048A Carrier: 57.29E+9 Hz 10/25/98 15:46:20 - 15:49:49



F11 NOISE, PLU F1U

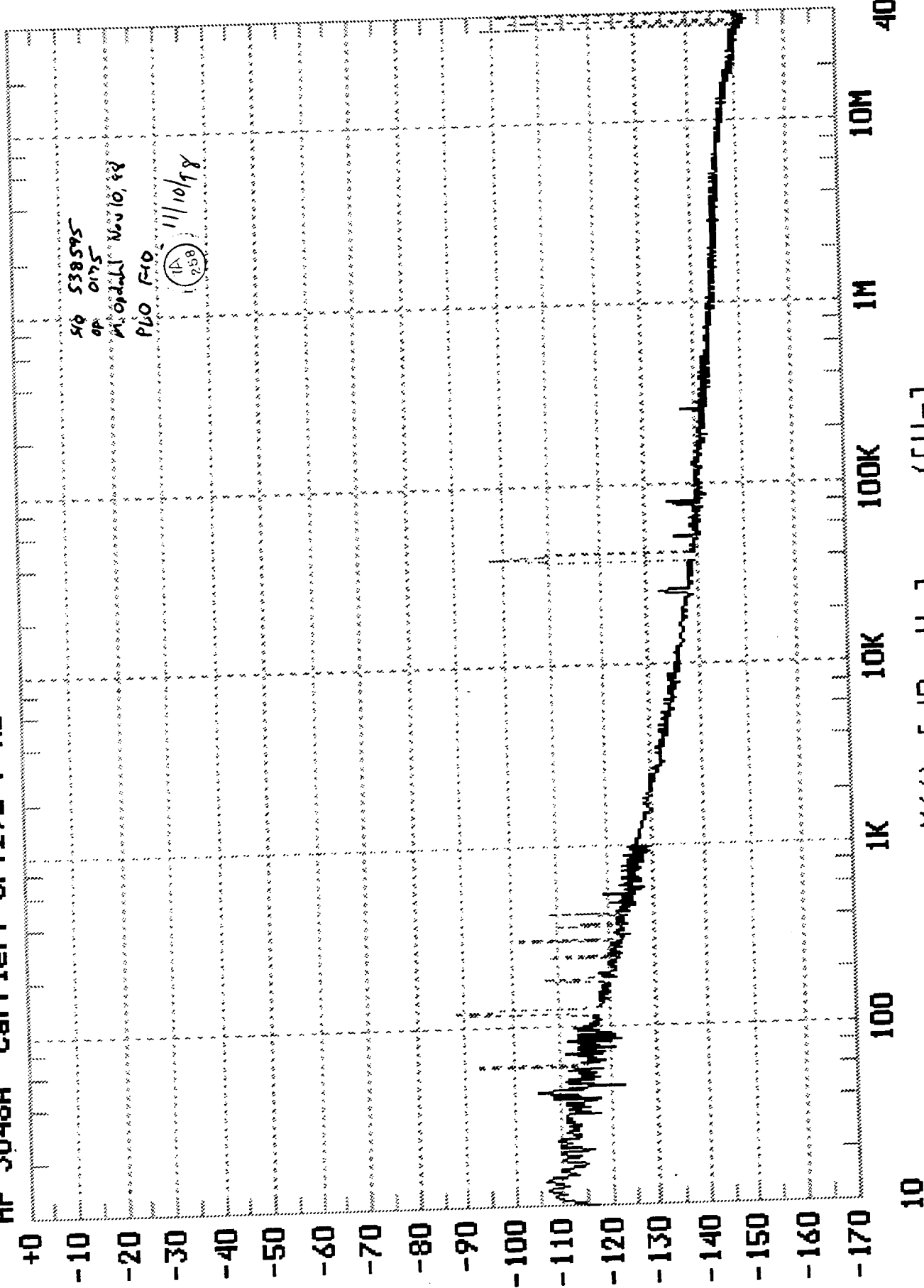
HP 3048A Carrier: 57.29E+9 Hz 11/10/98 17:50:03 - 17:53:39



$\epsilon(f)$ [dBc/Hz] vs. f [Hz]

HP 3048A, PLU 1 10

HP 3048A Carrier: 57.29E+9 Hz 11/10/98 17:36:01 - 17:39:30

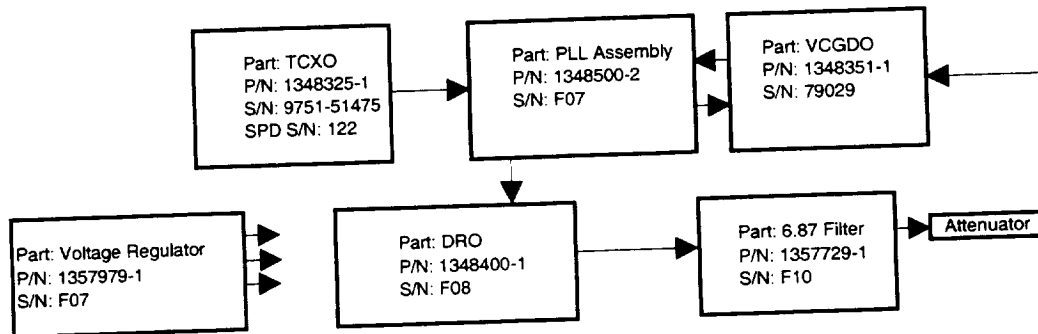


$M(f)$ [dBc/Hz] vs. f [Hz]

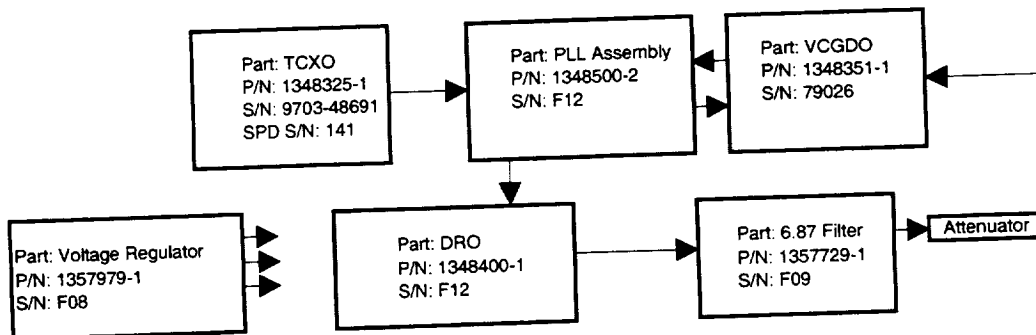
PLO As-Built Configuration


Part Name	Part Number	Serial Number	
		F09	F10
TCXO	1348325-1	51475	48691
VCGDO	1348351-1	79029	79026
PLL Assembly	1348500-2	F07	F10
DRO Assembly	1348400-1	F08	F12
Voltage Regulator	1357979-1	F07	F08

PLO F09



PLO F10



 NASA National Aeronautics and Space Administration				Report Documentation Page			
1. Report No. ---		2. Government Accession No. ---		3. Recipient's Catalog No. ---			
4. Title and Subtitle Integrated Advanced Microwave Sounding Unit-A (AMSU-A), Performance Verification Report				5. Report Date January 1999			
				6. Performing Organization Code ---			
7. Author(s) D. Pines				8. Performing Organization Report No. 11384			
9. Performing Organization Name and Address Aerojet 1100 W. Hollyvale Azusa, CA 91702				10. Work Unit No. ---			
				11. Contract or Grant No. NAS 5-32314			
12. Sponsoring Agency Name and Address NASA Goddard Space Flight Center Greenbelt, Maryland 20771				13. Type of Report and Period Covered Final			
				14. Sponsoring Agency Code ---			
15. Supplementary Notes ---							
16. ABSTRACT (Maximum 200 words) This is the Performance Verification Report, METSAT Phase Locked Oscillator Assembly, P/N 1348360-1, S/N F09 and F10, for the Integrated Advanced Microwave Sounding Unit-A (AMSU-A).							
17. Key Words (Suggested by Author(s)) EOS Microwave System			18. Distribution Statement Unclassified --- Unlimited				
19. Security Classif. (of this report) Unclassified		20. Security Classif. (of this page) Unclassified		21. No. of pages ---			
				22. Price ---			

NASA FORM 1626 OCT 86

PREPARATION OF THE REPORT DOCUMENTATION PAGE

The last page of a report facing the third cover is the Report Documentation Page, RDP. Information presented on this page is used in announcing and cataloging reports as well as preparing the cover and title page. Thus, it is important that the information be correct. Instructions for filling in each block of the form are as follows:

Block 1. Report No. NASA report series number, if preassigned.

Block 2. Government Accession No. Leave blank.

Block 3. Recipient's Catalog No. Reserved for use by each report recipient.

Block 4. Title and Subtitle. Typed in caps and lower case with dash or period separating subtitle from title.

Block 5. Report Date. Approximate month and year the report will be published.

Block 6. Performing Organization Code. Leave blank.

Block 7. Authors. Provide full names exactly as they are to appear on the title page. If applicable, the word editor should follow a name.

Block 8. Performing Organization Report No. NASA installation report control number and, if desired, the non-NASA performing organization report control number.

Block 9. Performing Organization Name and Address. Provide affiliation (NASA program office, NASA installation, or contractor name) of authors.

Block 10. Work Unit No. Provide Research and Technology Objectives and Plants (RTOP) number.

Block 11. Contract or Grant No. Provide when applicable.

Block 12. Sponsoring Agency Name and Address. National Aeronautics and Space Administration, Washington, D.C. 20546-0001. If contractor report, add NASA installation or HQ program office.

Block 13. Type of Report and Period Covered. NASA formal report series; for Contractor Report also list type (interim, final) and period covered when applicable.

Block 14. Sponsoring Agency Code. Leave blank.

Block 15. Supplementary Notes. Information not included

elsewhere: affiliation of authors if additional space is required for Block 9, notice of work sponsored by another agency, monitor of contract, information about supplements (file, data tapes, etc.) meeting site and date for presented papers, journal to which an article has been submitted, note of a report made from a thesis, appendix by author other than shown in Block 7.

Block 16. Abstract. The abstract should be informative rather than descriptive and should state the objectives of the investigation, the methods employed (e.g., simulation, experiment, or remote sensing), the results obtained, and the conclusions reached.

Block 17. Key Words. Identifying words or phrases to be used in cataloging the report.

Block 18. Distribution Statement. Indicate whether report is available to public or not. If not to be controlled, use "Unclassified-Unlimited." If controlled availability is required, list the category approved on the Document Availability Authorization Form (see NHB 2200.2, Form FF427). Also specify subject category (see "Table of Contents" in a current issue of STAR) in which report is to be distributed.

Block 19. Security Classification (of the report). Self-explanatory.

Block 20. Security Classification (of this page). Self-explanatory.

Block 21. No. of Pages. Count front matter pages beginning with iii, text pages including internal blank pages, and the RDP, but not the title page or the back of the title page.

Block 22. Price Code. If Block 18 shows "Unclassified-Unlimited," provide the NTIS price code (see "NTIS Price Schedules" in a current issue of STAR) and at the bottom of the form add either "For sale by the National Technical Information Service, Springfield, VA 22161-2171" or "For sale by the Superintendent of Documents, U.S. Government Printing Office, Washington, D.C. 20402-0001," whichever is appropriate.

REPORT DOCUMENTATION PAGE			<i>Form Approved OMB No. 0704-0188</i>	
<small>Public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden to Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302, and to the Office of Management and Budget, Paperwork Reduction Project (0704-0188), Washington, DC 20503.</small>				
1. AGENCY USE ONLY (Leave blank)		2. REPORT DATE		3. REPORT TYPE AND DATES COVERED
4. TITLE AND SUBTITLE Integrated Advanced Microwave Sounding Unit-A (AMSU-A), Performance Verification Report			5. FUNDING NUMBERS NAS 5-32314	
6. AUTHOR(S) D. Pines				
7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES) Aerojet 1100 W. Hollyvale Azusa, CA 91702			8. PERFORMING ORGANIZATION REPORT NUMBER 11384 January 1999	
9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS(ES) NASA Goddard Space Flight Center Greenbelt, Maryland 20771			10. SPONSORING/MONITORING AGENCY REPORT NUMBER ---	
11. SUPPLEMENTARY NOTES ---				
12a. DISTRIBUTION/AVAILABILITY STATEMENT ---			12b. DISTRIBUTION CODE ---	
13. ABSTRACT (Maximum 200 words) This is the Performance Verification Report, METSAT Phase Locked Oscillator Assembly, P/N 1348360-1, S/N F09 and F10, for the Integrated Advanced Microwave Sounding Unit-A (AMSU-A).				
14. SUBJECT TERMS EOS Microwave System			15. NUMBER OF PAGES 16. PRICE CODE ---	
17. SECURITY CLASSIFICATION OF REPORT Unclassified	18. SECURITY CLASSIFICATION OF THIS PAGE Unclassified	19. SECURITY CLASSIFICATION OF ABSTRACT Unclassified	20. LIMITATION OF ABSTRACT SAR	

GENERAL INSTRUCTIONS FOR COMPLETING SF 298

The Report Documentation Page (RDP) is used in announcing and cataloging reports. It is important that this information be consistent with the rest of the report, particularly the cover and title page. Instructions for filing in each block of the form follow. It is important to stay within the lines to meet optical scanning requirements.

Block 1. Agency Use Only/Leave blank

Block 2. Report Date Full publication date including day, month, and year, if available (e.g., 1 Jan 88). Must cite at least the year.

Block 3. Type of Report and Dates Covered State whether report is interim, final, etc. If applicable, enter inclusive report dates (e.g., 10 Jun 87 - 30 Jun 88).

Block 4. Title and Subtitle A title is taken from the part of the report that provides the most meaningful and complete information. When a report is prepared in more than one volume report the primary title, add volume number, and include subtitle for the specific volume. On classified documents enter the title classification in parentheses.

Block 5. Funding Numbers To include contract and grant numbers; may include program element number(s), project number(s), task number(s), and work unit number(s). Use the following labels:

C	-	Contract	PR	-	Project
G	-	Grant	TA	-	Task
PE	-	Program Element	WU	-	Work Unit Accession No.

Block 6. Author(s) Name(s) of person(s) responsible for writing the report, performing the research, or credited with the content of the report. If editor or compiler, this should follow the name(s).

Block 7. Performing Organization Name(s) and Address(es) Self-explanatory.

Block 8. Performing Organization Report Number Enter the unique alphanumeric report number(s) assigned by the organization performing the report.

Block 9. Sponsoring/Monitoring Agency Name(s) and Address(es) Self-explanatory.

Block 10. Sponsoring/Monitoring Agency Reports Number (if known).

Block 11. Supplementary Notes Enter information not included elsewhere such as: Prepared in cooperation with ...; Trans. of ...; To be published in ... When a report is revised, include a statement whether the new report supersedes or supplements the older report.

Block 12.a Distribution/Availability Statement Denotes public availability or limitations. Cite any availability to the public. Enter additional limitations or special markings in all capitals (e.g., NOFORN, REL, ITAR).

DOD - See DoDD 5230.24 *Distribution Statement on Technical Documents*

DOE - See authorities.

NASA - See Handbook NHB 2200.2.

NTIS - Leave blank.

Block 12.b Distribution Code.

DOD - Leave blank.

DOE - Enter DOE distribution categories from the standard Distribution for Unclassified Scientific and Technical Reports.

NASA - Leave blank.

NTIS - Leave blank.

Block 13. Abstract Include a brief *Maximum 200 words* factual summary of the most significant information contained in the report.

Block 14. Subject Terms Keywords or phrases identifying major subjects in the report.

Block 15. Number of Pages Enter the total number of pages.

Block 16. Price Code Enter appropriate price code (NTIS only).

Block 17 - 19. Security Classifications Self-explanatory. Enter U.S. Security Classification in accordance with U.S. Security Regulations (i.e., UNCLASSIFIED). If form contains classified information, stamp classification on the top and bottom of the page.

Block 20. Limitation of Abstract This block must be completed to assign a limitation to the abstract. Enter either UL (unlimited) or SAR (same as report). An entry in this block is necessary if the abstract is to be limited. If blank, the abstract is assumed to be unlimited.



DOCUMENT APPROVAL SHEET

TITLE Performance Verification Report METSAT Phase Locked Oscillator Assembly, P/N 1348360-1, S/N F09 and F10		DOCUMENT NO. Report 11384 January 1999	
INPUT FROM: D. Pines	CDRL: 208	SPECIFICATION ENGINEER: N/A	DATE
CHECKED BY: N/A	DATE	JOB NUMBER: N/A	DATE
APPROVED SIGNATURES		DEPT. NO.	DATE
Product Team Leader (D. Pines) <u><i>D. Pines</i></u>		8661	1/29/99
Systems Engineer (R. Platt) <u><i>Robert H Platt</i></u>		8341	2/1/99
Design Assurance (E. Lorenz) <u><i>A. Salinas for</i></u>		8331	2/1/99
Quality Assurance (R. Taylor) <u><i>Neil Goldsmith for</i></u>		7831	2/2/99
Technical Director/PMO (R. Hauerwaas) <u><i>R. Hauerwaas</i></u>		4001	1/29/99
Released: Configuration Management (J. Cavanaugh) <u><i>J. Cavanaugh</i></u>		8361	2/2/98
By my signature, I certify the above document has been reviewed by me and concurs with the technical requirements related to my area of responsibility.			
(Data Center) FINAL			

Please return this sheet and the reproducible master to Jim Kirk (Bldg. 1/Dept. 8631), ext. 2081.

